STM32H725xE/G



32-bit Arm[®] Cortex[®]-M7 550 MHz MCU, up to 1 MB Flash memory, 564 KB RAM, 35 comms peripherals and analog interfaces

Datasheet - production data

Features

Core

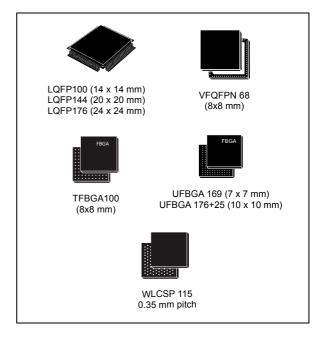
32-bit Arm[®] Cortex[®]-M7 CPU with DP-FPU, L1 cache: 32-Kbyte data cache and 32-Kbyte instruction cache allowing 0-wait state execution from embedded Flash memory and external memories, frequency up to 550 MHz, MPU, 1177 DMIPS/2.14 DMIPS/MHz (Dhrystone 2.1), and DSP instructions

Memories

- Up to 1 Mbyte of embedded Flash memory with ECC
- SRAM: total 564 Kbytes all with ECC, including 128 Kbytes of data TCM RAM for critical realtime data + 432 Kbytes of system RAM (up to 256 Kbytes can remap on instruction TCM RAM for critical real time instructions) + 4 Kbytes of backup SRAM (available in the lowest-power modes)
- Flexible external memory controller with up to 24-bit data bus: SRAM, PSRAM, SDRAM/LPSDR SDRAM, NOR/NAND memories
- 2 x Octo-SPI interface with XiP
- 2 x SD/SDIO/MMC interface
- Bootloader

Graphics

- Chrom-ART Accelerator graphical hardware accelerator enabling enhanced graphical user interface to reduce CPU load
- LCD-TFT controller supporting up to XGA resolution



Clock, reset and supply management

- 1.62 V to 3.6 V application supply and I/O
- POR, PDR, PVD and BOR
- Dedicated USB power
- Embedded DCDC and LDO regulator (*)VFQFPN68 variant is DCDC only
- Internal oscillators: 64 MHz HSI, 48 MHz HSI48, 4 MHz CSI, 32 kHz LSI
- External oscillators: 4-50 MHz HSE, 32.768 kHz LSE

Low power

- Sleep, Stop and Standby modes
- V_{BAT} supply for RTC, 32×32-bit backup registers

Analog

 2×16-bit ADC, up to 3.6 MSPS in 16-bit: up to 22 channels and 7.2 MSPS in doubleinterleaved mode

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- 1 x 12-bit ADC, up to 5 MSPS in 12-bit, up to 12 channels
- · 2 x comparators
- 2 x operational amplifier GBW = 8 MHz
- 2× 12-bit D/A converters

Digital filters for sigma delta modulator (DFSDM)

• 8 channels/4 filters

4 DMA controllers to offload the CPU

- 1 × MDMA with linked list support
- 2 × dual-port DMAs with FIFO
- 1 × basic DMA with request router capabilities

24 timers

- Seventeen 16-bit (including 5 x low power 16-bit timer available in stop mode) and four 32-bit timers, each with up to 4 IC/OC/PWM or pulse counter and quadrature (incremental) encoder input
- 2x watchdogs, 1x SysTick timer

Debug mode

- · SWD and JTAG interfaces
- · 2-Kbyte embedded trace buffer

Up to 128 I/O ports with interrupt capability

Up to 35 communication interfaces

- Up to 5 × I2C FM+ interfaces (SMBus/PMBus™)
- Up to 5 USARTs/5 UARTs (ISO7816 interface, LIN, IrDA, modem control) and 1 x LPUART
- Up to 6 SPIs with 4 with muxed duplex I2S for audio class accuracy via internal audio PLL or

external clock and up to 5 x SPI (from 5 x USART when configured in synchronous mode)

- 2x SAI (serial audio interface)
- 1× FD/TT-CAN and 2xFD-CAN
- 8- to 14-bit camera interface
- 16-bit parallel slave synchronous interface
- SPDIF-IN interface
- HDMI-CEC
- Ethernet MAC interface with DMA controller
- USB 2.0 high-speed/full-speed device/host/OTG controller with dedicated DMA, on-chip FS PHY and ULPI for external HS PHY
- SWPMI single-wire protocol master I/F
- MDIO slave interface

Mathematical acceleration

- CORDIC for trigonometric functions acceleration
- FMAC: Filter mathematical accelerator

Digital temperature sensor

True random number generator

CRC calculation unit

RTC with sub-second accuracy and hardware calendar

ROP, PC-ROP, tamper detection

96-bit unique ID

All packages are ECOPACK2 compliant

Table 1. Device summary

Reference	Part number
STM32H725xE	STM32H725ZE, STM32H725VE, STM32H725RE, STM32H725IE, STM32H725AE
STM32H725xG	STM32H725ZG, STM32H725VG, STM32H725RG, STM32H725IG, STM32H725AG



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Introduction STM32H725xE/G

1 Introduction

This document provides information on STM32H725xE/G microcontrollers, such as description, functional overview, pin assignment and definition, packaging, and ordering information.

This document should be read in conjunction with the STM32H725xE/G reference manual (RM0468), available from the STMicroelectronics website *www.st.com*.

For information on the Arm^{®(a)} Cortex[®]-M7 core, refer to the Cortex[®]-M7 Technical Reference Manual, available from the http://www.arm.com website.



a. Arm is a registered trademark of Arm Limited (or its subsidiaries) in the US and/or elsewhere.

STM32H725xE/G Description

2 Description

STM32H725xE/G devices are based on the high-performance Arm[®] Cortex[®]-M7 32-bit RISC core operating at up to 550 MHz. The Cortex[®] -M7 core features a floating point unit (FPU) which supports Arm[®] double-precision (IEEE 754 compliant) and single-precision data-processing instructions and data types. The Cortex -M7 core includes 32 Kbytes of instruction cache and 32 Kbytes of data cache. STM32H725xE/G devices support a full set of DSP instructions and a memory protection unit (MPU) to enhance application security.

STM32H725xE/G devices incorporate high-speed embedded memories with up to 1 Mbyte of Flash memory, up to 564 Kbytes of RAM (including 192 Kbytes that can be shared between ITCM and AXI, plus 64 Kbytes exclusively ITCM, plus 128 Kbytes exclusively AXI, 128 Kbyte DTCM, 48 Kbytes AHB and 4 Kbytes of backup RAM), as well as an extensive range of enhanced I/Os and peripherals connected to APB buses, AHB buses, 2x32-bit multi-AHB bus matrix and a multi layer AXI interconnect supporting internal and external memory access. To improve application robustness, all memories feature error code correction (one error correction, two error detections).

The devices embed peripherals allowing mathematical/arithmetic function acceleration (CORDIC co-processor for trigonometric functions and FMAC unit for filter functions). All the devices offer three ADCs, two DACs, two operational amplifiers, two ultra-low power comparators, a low-power RTC, 4 general-purpose 32-bit timers, 12 general-purpose 16-bit timers including two PWM timers for motor control, five low-power timers, a true random number generator (RNG). The devices support four digital filters for external sigma-delta modulators (DFSDM). They also feature standard and advanced communication interfaces.

- Standard peripherals
 - Five I²Cs
 - Five USARTs, five UARTs and one LPUART
 - Six SPIs, four I²Ss in Half-duplex mode. To achieve audio class accuracy, the I²S peripherals can be clocked by a dedicated internal audio PLL or by an external clock to allow synchronization. (Note that the five USARTs also provide SPI slave capability.)
 - Two SAI serial audio interfaces
 - One SPDIFRX interface with four inputs
 - One SWPMI (Single Wire Protocol Master Interface)
 - Management Data Input/Output (MDIO) slaves
 - Two SDMMC interfaces
 - A USB OTG high-speed interface with full-speed capability (with the ULPI)
 - Two FDCANs plus one TT-FDCAN interface
 - An Ethernet interface
 - Chrom-ART Accelerator
 - HDMI-CEC

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Description STM32H725xE/G

- Advanced peripherals including
 - A flexible memory control (FMC) interface
 - Two Octo-SPI memory interfaces
 - A camera interface for CMOS sensors
 - An LCD-TFT display controller

Refer to *Table 2: STM32H725xE/G features and peripheral counts* for the list of peripherals available on each part number.

To reduce the power consumption the STM32H725xE/G include an optional step-down converter that can be used either for internal or external supply, or both.

STM32H725xE/G devices operate in the -40 to +125 °C ambient temperature range from a 1.62 to 3.6 V power supply. The supply voltage can drop down to 1.62 V by using an external power supervisor (see *Section 3.7.2: Power supply supervisor*) and connecting the PDR_ON pin to V_{SS}. Otherwise the supply voltage must stay above 1.71 V with the embedded power voltage detector enabled.

Dedicated supply inputs for USB are available to allow a greater power supply choice.

A comprehensive set of power-saving modes allows the design of low-power applications.

STM32H725xE/G devices are offered in several packages ranging from 68 to 176 pins/balls. The set of included peripherals changes with the device chosen.

These features make STM32H725xE/G microcontrollers suitable for a wide range of applications:

- Motor drive and application control
- Medical equipment
- Industrial applications: PLC, inverters, circuit breakers
- Printers, and scanners
- · Alarm systems, video intercom, and HVAC
- Home audio appliances
- Mobile applications, Internet of Things
- · Wearable devices: smart watches.

Figure 1 shows the device block diagram.

STM32H725xE/G Description

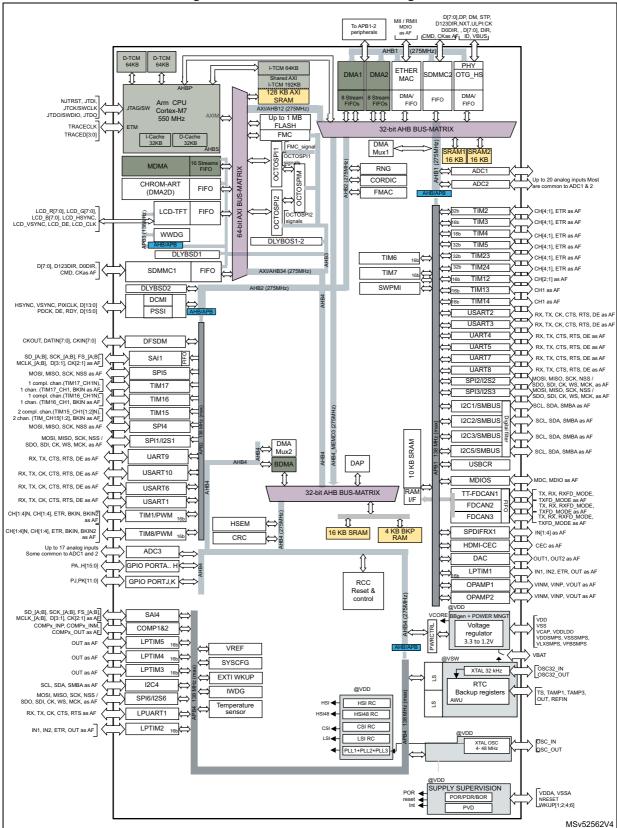


Figure 1. STM32H725xE/G block diagram

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Description STM32H725xE/G

Table 2. STM32H725xE/G features and peripheral counts

Perip	herals	STM32H 725REV/ RGV	STM32H 725VET/ VGT	STM32H 725VEH/ VGH	STM32H 725ZET/ ZGT	STM3 2H725 VGY	STM32H 725AEI/ AGI	STM32H 725IEK/ IGK	STM32H 725IET/ IGT		
Flash memory	Flash memory (Kbytes)		512/ 1024	512/ 1024	512/ 1024	1024	512/ 1024	512/ 1024	512/ 1024		
SRAM mapped onto AXI bus		128									
SRAM (Kbytes)	SRAM1 (D2 domain)		16								
(NDytes)	SRAM2 (D2 domain)				16	6					
	SRAM4 (D3 domain)				16	5					
RAM shared b and AXI (Kbyte					19	2					
TCM RAM in	ITCM RAM (instruction)	64									
Kbytes	DTCM RAM (data)	128									
Backup SRAM	(Kbytes)	4									
	Interface	1									
	NOR Flash memory/ RAM controller	-	-	-	-	-	yes	yes	yes		
FMC	Multiplexed I/O NOR Flash memory	-	yes	yes	yes	-	yes	yes	yes		
	16-bit NAND Flash memory	-	yes	yes	yes	yes	yes	yes	yes		
	16-bit SDRAM controller	-	-	-	-	-	yes	yes	yes		
	24-bit SDRAM controller ⁽¹⁾	-	-	-	-	-	-	yes	-		
GPIO	I	46	67	74	97	67	121	128	119		
OctoSPI interface		1 Quad- SPI	2 Quad- SPI	2 ⁽²⁾	2 ⁽²⁾	2 Quad- SPI	2	2	2		
OTFDEC		no									
Cordic		yes									

STM32H725xE/G Description

Table 2. STM32H725xE/G features and peripheral counts (continued)

Perip	bherals	STM32H 725REV/ RGV	STM32H 725VET/ VGT	STM32H 725VEH/ VGH	STM32H 725ZET/ ZGT	STM3 2H725 VGY	STM32H 725AEI/ AGI	STM32H 725IEK/ IGK	STM32H 725IET/ IGT			
FMAC			yes									
	General purpose 32 bits	2	2	2	2	2	2	2	2			
	General purpose 16 bits	10	10	10	10	10	10	10	10			
Timers	Advanced control (PWM)	2 ⁽³⁾	2	2 ⁽³⁾	2	2	2	2	2			
	Basic	2	2	2	2	2	2	2	2			
	Low-power	5	5	5	5	5	5	5	5			
	RTC	1	1	1	1	1	1	1	1			
	Window watchdog / independent watchdog	2	2	2	2	2	2	2	2			
Wakeup pins		3	4	4	4	4	4	4	4			
Tamper pins		1	2	2	2	2	2	2	2			
Random number generator		yes										
Cryptographic accelerator		no										

Description STM32H725xE/G

Table 2. STM32H725xE/G features and peripheral counts (continued)

Perip	herals	STM32H 725REV/ RGV	STM32H 725VET/ VGT	STM32H 725VEH/ VGH	STM32H 725ZET/ ZGT	STM3 2H725 VGY	STM32H 725AEI/ AGI	STM32H 725IEK/ IGK	STM32H 725IET/ IGT	
	SPI / I2S	4/4	5/4 ⁽³⁾	5/4	6/4	6/4	4/4	6/4	6/4	
	I2C	4	5	5	5	5	5	5	5	
	USART/ UART/ LPUART	3/4/1	4/4/1	4/6/1	5/5/1	4/4/1	5/5/1	5/5/1	5/5/1	
	SAI/PDM	1/0 ⁽³⁾	2/1 ⁽³⁾	2/1 ⁽³⁾	2/1	1/1 ⁽³⁾	2/1	2/1	2/1	
	SPDIFRX				1					
	HDMI-CEC				1					
Commu- nication	SWPMI				1					
interfaces	MDIO				1					
	SDMMC	2								
	FDCAN/ TT-FDCAN	1/1	2/1	2/1	2/1	2/1	2/1	2/1	2/1	
	USB [OTG_HS(UL PI)/ FS(PHY)]	1 [0/1]	1 [1/1]	1 [1/1]	1 [1/1]	1 [0/1]	1 [1/1]	1 [1/1]	1 [1/1]	
	Ethernet [MII/RMII]	-	1 [1/1]	1 [1/1]	1 [1/1]	1 [0/1]	1 [1/1]	1 [1/1]	1 [1/1]	
Camera interfa	ace/PSSI	yes								
LCD-TFT		yes ⁽³⁾	yes ⁽³⁾	yes ⁽³⁾	yes	yes	yes	yes	yes	
Chrom-ART Ac (DMA2D)	ccelerator	yes								
	Number of ADCs	2								
40 hit 400-	Number of Direct channels ADC1/ADC2	0	0	2/2	0	2/2	2/2	2/2	0	
16-bit ADCs	Number of Fast channels ADC1/ADC2	3/2	3/2	3/2	4/2	3/2	6/5	6/5	4/3	
	Number of Slow channels ADC1/ADC2	11/10	11/10	9/8	11/11	9/8	12/11	12/11	12/11	

STM32H725xE/G Description

Table 2. STM32H725xE/G features and peripheral counts (continued)

Perip	herals	STM32H 725REV/ RGV	STM32H 725VET/ VGT	STM32H 725VEH/ VGH	STM32H 725ZET/ ZGT	STM3 2H725 VGY	STM32H 725AEI/ AGI	STM32H 725IEK/ IGK	STM32H 725IET/ IGT
	Number of ADCs				1				
12-bit ADCs	Number of Direct channels	0	2	2	2	2	2	2	2
	Number of Fast channels	0	2	6	4	6	6	6	6
	Number of Slow channels	2	0	9	3	9	9	9	4
	Present in IC	yes							
12-bit DAC	Number of channels	2							
Comparators		2							
Operational an	nplifiers				2				
DFSDM	Present in IC	yes							
Maximum CPL	550 MHz								
USB separate supply pad USB internal regulator LDO		-	yes	yes	yes	yes	yes	yes	yes
		-	-	-	yes	yes	yes	yes	yes
		- yes yes yes							
SMPS step-down converter		yes							

Description STM32H725xE/G

Table 2. STM32H725xE/G features and peripheral counts (continued)

Perip	herals	STM32H 725REV/ RGV	STM32H 725VET/ VGT	STM32H 725VEH/ VGH	STM32H 725ZET/ ZGT	STM3 2H725 VGY	STM32H 725AEI/ AGI	STM32H 725IEK/ IGK	STM32H 725IET/ IGT
Operating voltage		1.71 to	1.71 to 3.6 V 1.62 to 3.6 V 1.62 to 3.6 V						
Operating	Ambient temperature				-40°C to	+85°C			
temperatures	Junction temperature				-40°C to	+125°C			
Extended operating	Ambient temperature				-40°C to	+125°C			
temperatures (4)	Junction temperature				-40°C to	+140°C			
Package		VFQFPN 68	LQFP 100	TFBGA 100	LQFP 144	WLCS P 115	UFBGA 169	UFBGA 176+25	LQFP17 6

^{1.} The 24-bit SDRAM controller is a 32-bit controller with only a 24-bit data bus and without NBL2-3. It can be used for graphical purposes to access aligned 32-bit words ignoring upper 8 bits.

^{2.} The two Octo-SPI/Quad-SPI interfaces are available only in Muxed mode.

^{3.} For limitations on peripheral features depending on packages, check the available pins/balls in *Table 8: STM32H725 pin and ball descriptions*.

^{4.} The extended temperature range is not available on WLCSP115 package.

STM32H725xE/G Functional overview

3 Functional overview

3.1 Arm® Cortex®-M7 with FPU

The Arm® Cortex®-M7 with double-precision FPU processor is the latest generation of Arm processors for embedded systems. It was developed to provide a low-cost platform that meets the needs of MCU implementation, with a reduced pin count and optimized power consumption, while delivering outstanding computational performance and low interrupt latency.

The Cortex®-M7 processor is a highly efficient high-performance featuring:

- Six-stage dual-issue pipeline
- Dynamic branch prediction
- Harvard architecture with L1 caches (32 Kbytes of I-cache and 32 Kbytes of D-cache)
- 64-bit AXI interface
- 64-bit ITCM interface
- 2x32-bit DTCM interfaces

The following memory interfaces are supported:

- Separate Instruction and Data buses (Harvard Architecture) to optimize CPU latency
- Tightly Coupled Memory (TCM) interface designed for fast and deterministic SRAM accesses
- AXI Bus interface to optimize Burst transfers
- Dedicated low-latency AHB-Lite peripheral bus (AHBP) to connect to peripherals.

The processor supports a set of DSP instructions which allow efficient signal processing and complex algorithm execution.

It also supports single and double precision FPU (floating point unit) speeds up software development by using metalanguage development tools, while avoiding saturation.

Figure 1 shows the general block diagram of the STM32H725xE/G family.

3.2 Memory protection unit (MPU)

generated.

The memory protection unit (MPU) manages the CPU access rights and the attributes of the system resources. It has to be programmed and enabled before use. Its main purposes are to prevent an untrusted user program to accidentally corrupt data used by the OS and/or by a privileged task, but also to protect data processes or read-protect memory regions.

The MPU defines access rules for privileged accesses and user program accesses. It allows defining up to 16 protected regions that can in turn be divided into up to 8 independent subregions, where region address, size, and attributes can be configured. The protection area ranges from 32 bytes to 4 Gbytes of addressable memory. When an unauthorized access is performed, a memory management exception is

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3.3 Memories

3.3.1 Embedded Flash memory

The STM32H725xE/G devices embed up to 1 Mbyte of Flash memory that can be used for storing programs and data.

The Flash memory is organized as 266-bit Flash words memory that can be used for storing both code and data constants. Each word consists of:

- one Flash word (8 words, 32 bytes or 256 bits)
- 10 ECC bits (single-error correction and double-error detection).

The Flash memory is organized as follows:

- up to 1 Mbyte of user Flash memory block containing eight user sectors of 128 Kbytes (4 K Flash memory words)
- 128 Kbytes of system Flash memory from which the device can boot
- 2 Kbytes (64 Flash words) of user option bytes for user configuration

3.3.2 Embedded SRAM

All devices feature:

- from 128 to 320 Kbytes of AXI-SRAM mapped onto the AXI bus on D1 domain
- SRAM1 mapped on D2 domain: 16 Kbytes
- SRAM2 mapped on D2 domain: 16 Kbytes
- SRAM4 mapped on D3 domain: 16 Kbytes
- 4 Kbytes of backup SRAM

The content of this area is protected against possible unwanted write accesses, and can be retained in Standby or V_{BAT} mode.

- RAM mapped to TCM interface (ITCM and DTCM):
 - Both ITCM and DTCM RAMs are 0 wait state memories. They can be accessed either from the CPU or the MDMA (even in Sleep mode) through a specific AHB slave of the Cortex®-M7CPU(AHBSAHBP):
 - 64 to 256 Kbytes of ITCM-RAM (instruction RAM)
 This RAM is connected to ITCM 64-bit interface designed for execution of critical real-times routines by the CPU.
 - 128 Kbytes of DTCM-RAM (2x 64-Kbyte DTCM-RAMs on 2x32-bit DTCM ports)
 The DTCM-RAM could be used for critical real-time data, such as interrupt service routines or stack/heap memory. Both DTCM-RAMs can be used in parallel (for load/store operations) thanks to the Cortex®-M7 dual issue capability.

The MDMA can be used to load code or data in ITCM or DTCM RAMs. As reflected above, 192 Kbyte of RAM can be used either for AXI SRAM or ITCM, with a 64Kbyte granularity.

STM32H725xE/G Functional overview

Error code correction (ECC)

Over the product lifetime, and/or due to external events such as radiations, invalid bits in memories may occur. They can be detected and corrected by ECC. This is an expected behavior that has to be managed at final-application software level in order to ensure data integrity through ECC algorithms implementation.

SRAM data are protected by ECC:

- 7 ECC bits are added per 32-bit word.
- 8 ECC bits are added per 64-bit word for AXI-SRAM and ITCM-RAM.

The ECC mechanism is based on the SECDED algorithm. It supports single-error correction and double-error detection.



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3.4 Boot modes

At startup, the boot memory space is selected by the BOOT pin and BOOT_ADDx option bytes, allowing to program any boot memory address from 0x0000 0000 to 0x3FFF FFFF which includes:

- All Flash address space
- All RAM address space: ITCM, DTCM RAMs and SRAMs
- The System memory bootloader

The boot loader is located in non-user System memory. It is used to reprogram the Flash memory through a serial interface (USART, I2C, SPI, FDCAN, USB-DFU). Refer to application note AN2606 "STM32 microcontroller System memory Boot mode" for details.

3.5 CORDIC co-processor (CORDIC)

The CORDIC co-processor provides hardware acceleration of certain mathematical functions, notably trigonometric, commonly used in motor control, metering, signal processing and many other applications.

It speeds up the calculation of these functions compared to a software implementation, allowing a lower operating frequency, or freeing up processor cycles in order to perform other tasks.

The filter mathematical accelerator unit performs arithmetic operations on vectors. It comprises a multiplier/accumulator (MAC) unit, together with address generation logic, which allows it to index vector elements held in local memory.

The unit includes support for circular buffers on input and output, which allows digital filters to be implemented. Both finite and infinite impulse response filters can be realized.

The unit allows frequent or lengthy filtering operations to be offloaded from the CPU, freeing up the processor for other tasks. In many cases it can accelerate such calculations compared to a software implementation, resulting in a speed-up of time critical tasks.

CORDIC features

- 24-bit CORDIC rotation engine
- Circular and Hyperbolic modes
- Rotation and Vectoring modes
- Functions: Sine, Cosine, Sinh, Cosh, Atan, Atan2, Atanh, Modulus, Square root, Natural logarithm
- Programmable precision up to 20-bit
- Fast convergence: 4 bits per clock cycle
- Supports 16-bit and 32-bit fixed point input and output formats
- Low latency AHB slave interface
- Results can be read as soon as ready without polling or interrupt
- DMA read and write channels

STM32H725xE/G Functional overview

3.6 Filter mathematical accelerator (FMAC)

The filter mathematical accelerator unit performs arithmetic operations on vectors. It comprises a multiplier/accumulator (MAC) unit, together with address generation logic, which allows it to index vector elements held in local memory.

The unit includes support for circular buffers on input and output, which allows digital filters to be implemented. Both finite and infinite impulse response filters can be realized.

The unit allows frequent or lengthy filtering operations to be offloaded from the CPU, freeing up the processor for other tasks. In many cases it can accelerate such calculations compared to a software implementation, resulting in a speed-up of time critical tasks.

FMAC features

- 16 x 16-bit multiplier
- 24+2-bit accumulator with addition and subtraction
- 16-bit input and output data
- 256 x 16-bit local memory
- Up to three areas can be defined in memory for data buffers (two input, one output), defined by programmable base address pointers and associated size registers
- · Input and output sample buffers can be circular
- Buffer "watermark" feature reduces overhead in interrupt mode
- Filter functions: FIR, IIR (direct form 1)
- AHB slave interface
- DMA read and write data channels

3.7 Power supply management

3.7.1 Power supply scheme

STM32H725xE/G power supply voltages are the following:

- V_{DD} = 1.62 to 3.6 V: external power supply for I/Os, provided externally through V_{DD} pins.
- V_{DDLDO} = 1.62 to 3.6 V: supply voltage for the internal regulator supplying V_{CORE}
- V_{DDA} = 1.62 to 3.6 V: external analog power supplies for ADC, DAC, COMP and OPAMP.
- V_{DD33USB}: allows the support of a VDD supply different from 3.3 V while powering the USB transceiver with 3.3V on V_{DD33USB}.
- V_{DD50USB} can be supplied through the USB cable to generate the V_{DD33USB} via the USB internal regulator. This allows support of a V_{DD} supply different to 3.3 V.
 The USB regulator can be bypassed to supply directly V_{DD33USB} if V_{DD} = 3.3 V.
- V_{BAT} = 1.2 to 3.6 V: power supply for the V_{SW} domain when V_{DD} is not present.
- V_{CAP}: V_{CORE} supply voltage, which values depend on voltage scaling (1.0 V, 1.1 V, 1.2 V or 1.35 V). They are configured through VOS bits in PWR_D3CR register. The

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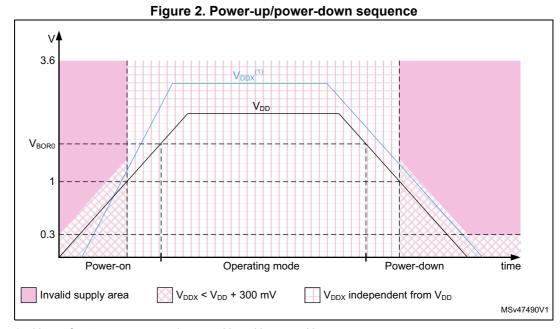
 $V_{\mbox{CORE}}$ domain is split into the following power domains that can be independently switch off.

- D1 domain containing some peripherals and the Cortex[®]-M7 core
- D2 domain containing a large part of the peripherals
- D3 domain containing some peripherals and the system control
- VDDSMPS= 1.62 V to 3.6 V: SMPS step-down converter power supply VDDSMPS must be kept at the same voltage level as VDD
- VLXSMPS = SMPS step-down converter output coupled to an inductor
- VFBSMPS = VCORE or 1.8 V or 2.5 V external SMPS step-down converter feedback voltage sense input.

During power-up and power-down phases, the following power sequence requirements must be respected (see *Figure 2*):

- When V_{DD} is below 1 V, other power supplies (V_{DDA} , $V_{DD33USB}$, $V_{DD50USB}$) must remain below V_{DD} + 300 mV.
- When V_{DD} is above 1 V, all power supplies are independent.

During the power-down phase, V_{DD} can temporarily become lower than other supplies only if the energy provided to the microcontroller remains below 1 mJ. This allows external decoupling capacitors to be discharged with different time constants during the power-down transient phase.



1. V_{DDx} refers to any power supply among V_{DDA} , $V_{DD33USB}$, $V_{DD50USB}$.

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3.7.2 Power supply supervisor

The devices have an integrated power-on reset (POR)/ power-down reset (PDR) circuitry coupled with a Brownout reset (BOR) circuitry:

Power-on reset (POR)

The POR supervisor monitors V_{DD} power supply and compares it to a fixed threshold. The devices remain in Reset mode when V_{DD} is below this threshold,

Power-down reset (PDR)

The PDR supervisor monitors V_{DD} power supply. A reset is generated when V_{DD} drops below a fixed threshold.

The PDR supervisor can be enabled/disabled through PDR_ON pin.

Brownout reset (BOR)

The BOR supervisor monitors V_{DD} power supply. Three BOR thresholds (from 2.1 to 2.7 V) can be configured through option bytes. A reset is generated when V_{DD} drops below this threshold.

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3.7.3 Voltage regulator

The same voltage regulator supplies the 3 power domains (D1, D2 and D3). D1 and D2 can be independently switched off.

Voltage regulator output can be adjusted according to application needs through 6 power supply levels:

- Run mode (VOS0 to VOS3)
 - Scale 0: boosted performance
 - Scale 1: high performance
 - Scale 2: medium performance and consumption
 - Scale 3: optimized performance and low-power consumption
- Stop mode (SVOS3 to SVOS5)
 - Scale 3: peripheral with wakeup from Stop mode capabilities (UART, SPI, I2C, LPTIM) are operational
 - Scale 4 and 5 where the peripheral with wakeup from Stop mode is disabled. The
 peripheral functionality is disabled but wakeup from Stop mode is possible through
 GPIO or asynchronous interrupt.

3.8 Low-power strategy

There are several ways to reduce power consumption on STM32H725xE/G:

- Decrease the dynamic power consumption by slowing down the system clocks even in Run mode and by individually clock gating the peripherals that are not used.
- Save power when the CPU is idle, by selecting among the available low-power modes
 according to the user application needs. This allows the best compromise between
 short startup time and low power consumption to be achieved, according to the
 available wakeup sources.

The devices feature several low-power modes:

- CSleep (CPU clock stopped)
- CStop (CPU sub-system clock stopped)
- DStop (Domain bus matrix clock stopped)
- Stop (System clock stopped)
- DStandby (Domain powered down)
- Standby (System powered down)

CSleep and CStop low-power modes are entered by the MCU when executing the WFI (Wait for Interrupt) or WFE (Wait for Event) instructions, or when the SLEEPONEXIT bit of the Cortex[®]-Mx core is set after returning from an interrupt service routine.

A domain can enter low-power mode (DStop or DStandby) when the processor, its subsystem and the peripherals allocated in the domain enter low-power mode.

If part of the domain is not in low-power mode, the domain remains in the current mode.

Finally the system can enter Stop or Standby when all EXTI wakeup sources are cleared and the power domains are in DStop or DStandby mode.

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System power mode	D1 domain power mode	D2 domain power mode	D3 domain power mode								
Run	DRun/DStop/DStandby	DRun/DStop/DStandby	DRun								
Stop	DStop/DStandby	DStop/DStandby	DStop								
Standby	DStandby	DStandby	DStandby								

Table 3. System versus domain low-power mode

3.9 Reset and clock controller (RCC)

The clock and reset controller is located in D3 domain. The RCC manages the generation of all the clocks, as well as the clock gating and the control of the system and peripheral resets. It provides a high flexibility in the choice of clock sources and allows to apply clock ratios to improve the power consumption. In addition, on some communication peripherals that are capable to work with two different clock domains (either a bus interface clock or a kernel peripheral clock), thus the system frequency can be changed without modifying the baudrate.

3.9.1 Clock management

The devices embed four internal oscillators, two oscillators with external crystal or resonator, two internal oscillators with fast startup time and three PLLs.

The RCC receives the following clock source inputs:

- Internal oscillators:
 - 64 MHz HSI clock
 - 48 MHz RC oscillator
 - 4 MHz CSI clock
 - 32 kHz LSI clock
- External oscillators:
 - HSE clock: 4-50 MHz (generated from an external source) or 4-48 MHz(generated from a crystal/ceramic resonator)
 - LSE clock: 32.768 kHz

The RCC provides three PLLs: one for system clock, two for kernel clocks.

The system starts on the HSI clock. The user application can then select the clock configuration.

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3.9.2 System reset sources

Power-on reset initializes all registers while system reset reinitializes the system except for the debug, part of the RCC and power controller status registers, as well as the backup power domain.

A system reset is generated in the following cases:

- Power-on reset (pwr por rst)
- Brownout reset
- Low level on NRST pin (external reset)
- Window watchdog
- Independent watchdog
- Software reset
- Low-power mode security reset
- Exit from Standby

3.10 General-purpose input/outputs (GPIOs)

Each of the GPIO pins can be configured by software as output (push-pull or open-drain, with or without pull-up or pull-down), as input (floating, with or without pull-up or pull-down) or as peripheral alternate function. Most of the GPIO pins are shared with digital or analog alternate functions. All GPIOs are high-current-capable and have speed selection to better manage internal noise, power consumption and electromagnetic emission.

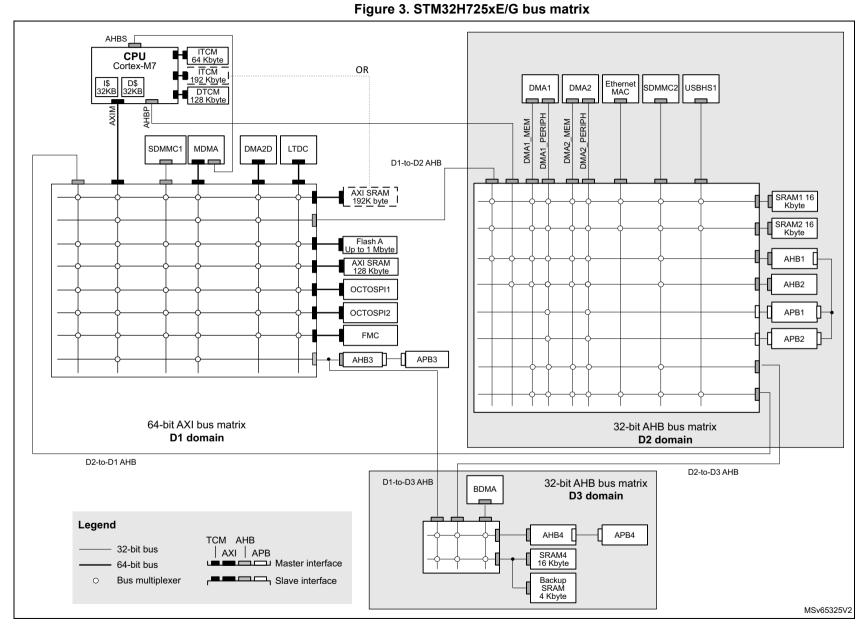
After reset, all GPIOs (except debug pins) are in Analog mode to reduce power consumption (refer to GPIOs register reset values in the device reference manual).

The I/O configuration can be locked if needed by following a specific sequence in order to avoid spurious writing to the I/Os registers.

3.11 Bus-interconnect matrix

The devices feature an AXI bus matrix, two AHB bus matrices and bus bridges that allow the interconnection of bus masters with bus slaves (see *Figure 3*).





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3.12 DMA controllers

The devices feature four DMA instances and a DMA request router to unload CPU activity:

A master direct memory access (MDMA)

The MDMA is a high-speed DMA controller, which is in charge of all types of memory transfers (peripheral to memory, memory to memory, memory to peripheral), without any CPU action. It features a master AXI interface and a dedicated AHB interface to access Cortex[®]-M7 TCM memories.

The MDMA is located in D1 domain. It is able to interface with the other DMA controllers located in D2 domain to extend the standard DMA capabilities, or can manage peripheral DMA requests directly.

Each of the 16 channels can perform single block transfers, repeated block transfers and linked list transfers.

- Two dual-port DMAs (DMA1, DMA2) located in D2 domain, with FIFO and request router capabilities.
- One basic DMA (BDMA) located in D3 domain, with request router capabilities.
- A DMA request multiplexer (DMAMUX)

The DMA request router could be considered as an extension of the DMA controller. It routes the DMA peripheral requests to the DMA controller itself. This allowing managing the DMA requests with a high flexibility, maximizing the number of DMA requests that run concurrently, as well as generating DMA requests from peripheral output trigger or DMA event.

3.13 Chrom-ART Accelerator (DMA2D)

The Chrom-Art Accelerator (DMA2D) is a specialized DMA dedicated to image manipulation. It can perform the following operations:

- Filling a part or the whole of a destination image with a specific color
- Copying a part or the whole of a source image into a part or the whole of a destination
- image
- Copying a part or the whole of a source image into a part or the whole of a destination
- image with a pixel format conversion
- Blending a part and/or two complete source images with different pixel format and copy
- the result into a part or the whole of a destination image with a different color format.
- All the classical color coding schemes are supported from 4-bit up to 32-bit per pixel with indexed or direct color mode, including block based YCbCr to handle JPEG decoder output.
- The DMA2D has its own dedicated memories for CLUTs (color look-up tables).

An interrupt can be generated when an operation is complete or at a programmed watermark.

All the operations are fully automated and are running independently from the CPU or the DMAs.

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3.14 Nested vectored interrupt controller (NVIC)

The devices embed a nested vectored interrupt controller which is able to manage 16 priority levels, and handle up to 140 maskable interrupt channels plus the 16 interrupt lines of the Cortex[®]-M7 with FPU core.

- Closely coupled NVIC gives low-latency interrupt processing
- Interrupt entry vector table address passed directly to the core
- Allows early processing of interrupts
- Processing of late arriving, higher-priority interrupts
- Support tail chaining
- Processor context automatically saved on interrupt entry, and restored on interrupt exit with no instruction overhead

This hardware block provides flexible interrupt management features with minimum interrupt latency.

3.15 Extended interrupt and event controller (EXTI)

The EXTI controller performs interrupt and event management. In addition, it can wake up the processor, power domains and/or D3 domain from Stop mode.

The EXTI handles up to 80 independent event/interrupt lines split as 26 configurable events and 54 direct events.

Configurable events have dedicated pending flags, active edge selection, and software trigger capable.

Direct events provide interrupts or events from peripherals having a status flag.

3.16 Cyclic redundancy check calculation unit (CRC)

The CRC (cyclic redundancy check) calculation unit is used to get a CRC code using a programmable polynomial.

Among other applications, CRC-based techniques are used to verify data transmission or storage integrity. In the scope of the EN/IEC 60335-1 standard, they offer a means of verifying the Flash memory integrity. The CRC calculation unit helps compute a signature of the software during runtime, to be compared with a reference signature generated at link-time and stored at a given memory location.

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3.17 Flexible memory controller (FMC)

The FMC controller main features are the following:

- Interface with static-memory mapped devices including:
 - Static random access memory (SRAM)
 - NOR Flash memory/OneNAND Flash memory
 - PSRAM (4 memory banks)
 - NAND Flash memory with ECC hardware to check up to 8 Kbytes of data
- Interface with synchronous DRAM (SDRAM/Mobile LPSDR SDRAM) memories
- 8-,16-, 24-bit data bus width
- Independent Chip Select control for each memory bank
- Independent configuration for each memory bank
- Write FIFO
- Read FIFO for SDRAM controller
- The maximum FMC_CLK/FMC_SDCLK frequency for synchronous accesses is the FMC kernel clock divided by 2.

3.18 Octo-SPI memory interface (OCTOSPI)

The OCTOSPI is a specialized communication interface targeting single, dual, quad or octal SPI memories. The STM32H725xE/G embeds two separate Octo-SPI interfaces.

Each OCTOSPI instance supports single/dual/quad/octal SPI formats. multiplexing of single/dual/quad/octal SPI over the same bus can be achieved using the integrated Octo-SPI I/O manager (OCTOSPIM).

The OCTOSPI can operate in any of the three following modes:

- Indirect mode: all the operations are performed using the OCTOSPI registers
- Status-polling mode: the external memory status register is periodically read and an interrupt can be generated in case of flag setting
- Memory-mapped mode: the external memory is memory mapped and it is seen by the system as if it was an internal memory supporting both read and write operations.

The OCTOSPI supports two frame formats supported by most external serial memories such as serial PSRAMs, serial NAND and serial NOR Flash memories, Hyper RAMs and Hyper Flash memories.

Multi chip package (MCP) combining any of the above mentioned memory types can also be supported.

- The classical frame format with the command, address, alternate byte, dummy cycles and data phase
- The HyperBus™ frame format.

3.19 Analog-to-digital converters (ADCs)

STM32H725xE/G devices embed three analog-to-digital converters, two of 16-bit resolution, and the third of 12-bit resolution. The 16-bit resolution ADCs can be configured as 16, 14, 12, 10 or 8 bits. The 12-bit resolution ADC can be configured to 12, 10 or 8 bits.

Each ADC shares up to 20 external channels, performing conversions in Single-shot or Scan mode. In Scan mode, automatic conversion is performed on a selected group of analog inputs.

Additional logic functions embedded in the ADC interface allow:

- simultaneous sample and hold
- Interleaved sample and hold

The ADC can be served by the DMA controller, thus allowing automatic transfer of ADC converted values to a destination location without any software action.

In addition, an analog watchdog feature can accurately monitor the converted voltage of one, some, or all selected channels. An interrupt is generated when the converted voltage is outside the programmed thresholds.

To synchronize A/D conversion and timers, the ADCs can be triggered by any of the TIM1, TIM2, TIM3, TIM4, TIM6, TIM8, TIM15, TIM23, TIM24, and LPTIM1 timers.

3.20 Temperature sensor

STM32H725xE/G devices embed a temperature sensor that generates a voltage (V_{TS}) that varies linearly with the temperature. This temperature sensor is internally connected to ADC3_IN17. The conversion range is between 1.7 V and 3.6 V. It can measure the device junction temperature ranging from -40 to +125°C.

The temperature sensor have a good linearity, but it has to be calibrated to obtain a good overall accuracy of the temperature measurement. As the temperature sensor offset varies from chip to chip due to process variation, the uncalibrated internal temperature sensor is suitable for applications that detect temperature changes only. To improve the accuracy of the temperature sensor measurement, each device is individually factory-calibrated by ST. The temperature sensor factory calibration data are stored by ST in the System memory area, which is accessible in Read-only mode.

3.21 Digital temperature sensor (DTS)

STM32H725xE/G devices embed a sensor that converts the temperature into a square wave the frequency of which is proportional to the temperature. The PCLK or the LSE clock can be used as the reference clock for the measurements. A formula given in the product reference manual allows calculation of the temperature according to the measured frequency stored in the DTS DR register.

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3.22 V_{BAT} operation

The V_{BAT} power domain contains the RTC, the backup registers and the backup SRAM.

To optimize battery duration, this power domain is supplied by V_{DD} when available or by the voltage applied on VBAT pin (when V_{DD} supply is not present). V_{BAT} power is switched when the PDR detects that V_{DD} dropped below the PDR level.

The voltage on the VBAT pin could be provided by an external battery, a supercapacitor or directly by V_{DD} , in which case, the V_{BAT} mode is not functional.

 V_{BAT} operation is activated when V_{DD} is not present.

The V_{BAT} pin supplies the RTC, the backup registers and the backup SRAM.

Note: When the microcontroller is supplied from V_{BAT} , external interrupts and RTC alarm/events do not exit it from V_{BAT} operation.

When PDR_ON pin is connected to V_{SS} (Internal Reset OFF), the V_{BAT} functionality is no more available and V_{BAT} pin should be connected to V_{DD} .

3.23 Digital-to-analog converters (DAC)

The two 12-bit buffered DAC channels can be used to convert two digital signals into two analog voltage signal outputs.

This dual digital Interface supports the following features:

- two DAC converters: one for each output channel
- 8-bit or 12-bit monotonic output
- left or right data alignment in 12-bit mode
- · synchronized update capability
- noise-wave generation
- triangular-wave generation
- dual DAC channel independent or simultaneous conversions
- DMA capability for each channel including DMA underrun error detection
- external triggers for conversion
- input voltage reference V_{REF+} or internal VREFBUF reference.

The DAC channels are triggered through the timer update outputs that are also connected to different DMA streams.

3.24 Ultra-low-power comparators (COMP)

STM32H725xE/G devices embed two rail-to-rail comparators (COMP1 and COMP2). They feature programmable reference voltage (internal or external), hysteresis and speed (low speed for low-power) as well as selectable output polarity.

The reference voltage can be one of the following:

- An external I/O
- A DAC output channel
- An internal reference voltage or submultiple (1/4, 1/2, 3/4).

All comparators can wake up from Stop mode, generate interrupts and breaks for the timers, and be combined into a window comparator.

3.25 Operational amplifiers (OPAMP)

STM32H725xE/G devices embed two rail-to-rail operational amplifiers (OPAMP1 and OPAMP2) with external or internal follower routing and PGA capability.

The operational amplifier main features are:

- PGA with a non-inverting gain ranging of 2, 4, 8 or 16 or inverting gain ranging of -1, -3,
 -7 or -15
- One positive input connected to DAC
- Output connected to internal ADC
- Low input bias current down to 1 nA
- Low input offset voltage down to 1.5 mV
- Gain bandwidth up to 7.3 MHz

The devices embeds two operational amplifiers (OPAMP1 and OPAMP2) with two inputs and one output each. These three I/Os can be connected to the external pins, thus enabling any type of external interconnections. The operational amplifiers can be configured internally as a follower, as an amplifier with a non-inverting gain ranging from 2 to 16 or with inverting gain ranging from -1 to -15.

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3.26 Digital filter for sigma-delta modulators (DFSDM)

The devices embed one DFSDM with 4 digital filters modules and 8 external input serial channels (transceivers) or alternately 8 internal parallel inputs support.

The DFSDM peripheral is dedicated to interface the external $\Sigma\Delta$ modulators to microcontroller and then to perform digital filtering of the received data streams (which represent analog value on $\Sigma\Delta$ modulators inputs). DFSDM can also interface PDM (Pulse Density Modulation) microphones and perform PDM to PCM conversion and filtering in hardware. DFSDM features optional parallel data stream inputs from internal ADC peripherals or microcontroller memory (through DMA/CPU transfers into DFSDM).

DFSDM transceivers support several serial interface formats (to support various $\Sigma\Delta$ modulators). DFSDM digital filter modules perform digital processing according user selected filter parameters with up to 24-bit final ADC resolution.

The DFSDM peripheral supports:

- 8 multiplexed input digital serial channels:
 - configurable SPI interface to connect various SD modulator(s)
 - configurable Manchester coded 1 wire interface support
 - PDM (Pulse Density Modulation) microphone input support
 - maximum input clock frequency up to 20 MHz (10 MHz for Manchester coding)
 - clock output for SD modulator(s): 0..20 MHz
- alternative inputs from 8 internal digital parallel channels (up to 16 bit input resolution):
 - internal sources: ADC data or memory data streams (DMA)
- 4 digital filter modules with adjustable digital signal processing:
 - Sinc^x filter: filter order/type (1..5), oversampling ratio (up to 1..1024)
 - integrator: oversampling ratio (1..256)
- up to 24-bit output data resolution, signed output data format
- automatic data offset correction (offset stored in register by user)
- continuous or single conversion
- start-of-conversion triggered by:
 - software trigger
 - internal timers
 - external events
 - start-of-conversion synchronously with first digital filter module (DFSDM0)
- analog watchdog feature:
 - low value and high value data threshold registers
 - dedicated configurable Sincx digital filter (order = 1..3, oversampling ratio = 1..32)
 - input from final output data or from selected input digital serial channels
 - continuous monitoring independently from standard conversion
- short circuit detector to detect saturated analog input values (bottom and top range):
 - up to 8-bit counter to detect 1..256 consecutive 0's or 1's on serial data stream
 - monitoring continuously each input serial channel
- break signal generation on analog watchdog event or on short circuit detector event



- extremes detector:
 - storage of minimum and maximum values of final conversion data
 - refreshed by software
- DMA capability to read the final conversion data
- interrupts: end of conversion, overrun, analog watchdog, short circuit, input serial channel clock absence
- "regular" or "injected" conversions:
 - "regular" conversions can be requested at any time or even in Continuous mode without having any impact on the timing of "injected" conversions
 - "injected" conversions for precise timing and with high conversion priority
- Pulse skipper feature to support beamforming applications (delay-line like behavior).

Table 4. DFSDM implementation

DFSDM features	DFSDM1
Number of filters	4
Number of input transceivers/channels	8
Internal ADC parallel input	X
Number of external triggers	16
Regular channel information in identification register	X

3.27 Digital camera interface (DCMI)

The devices embed a camera interface that can connect with camera modules and CMOS sensors through an 8-bit to 14-bit parallel interface, to receive video data. The camera interface can achieve a data transfer rate up to 140 Mbyte/s using a 80 MHz pixel clock. It features:

- Programmable polarity for the input pixel clock and synchronization signals
- Parallel data communication can be 8-, 10-, 12- or 14-bit
- Supports 8-bit progressive video monochrome or raw bayer format, YCbCr 4:2:2 progressive video, RGB 565 progressive video or compressed data (like JPEG)
- Supports Continuous mode or Snapshot (a single frame) mode
- Capability to automatically crop the image

3.28 **PSSI**

The PSSI is a generic synchronous 8-/16-bit parallel data input/output slave interface. It allows the transmitter to send a data valid signal to indicate when the data is valid, and the receiver to output a flow control signal to indicate when it is ready to sample the data.

The main PSSI features are:

- Slave mode operation
- 8- or 16-bit parallel data input or output
- 8-word (32-byte) FIFO
- Data enable (DE) alternate function input and Ready (RDY) alternate function output.

When enabled, these signals can either allow the transmitter to indicate when the data is valid or, the receiver to indicate when it is ready to sample the data, or both.

The PSSI shares most of its circuitry with the digital camera interface (DCMI). It therefore cannot be used simultaneously with the DCMI.

3.29 LCD-TFT controller

The LCD-TFT display controller provides a 24-bit parallel digital RGB (Red, Green, Blue) and delivers all signals to interface directly to a broad range of LCD and TFT panels up to XGA (1024 x 768) resolution with the following features:

- 2 display layers with dedicated FIFO (64x64-bit)
- Color Look-Up table (CLUT) up to 256 colors (256x24-bit) per layer
- Up to 8 input color formats selectable per layer
- Flexible blending between two layers using alpha value (per pixel or constant)
- Flexible programmable parameters for each layer
- Color keying (transparency color)
- Up to 4 programmable interrupt events
- AXI master interface with burst of 16 words

3.30 True random number generator (RNG)

The RNG is a true random number generator that provides full entropy outputs to the application as 32-bit samples. It is composed of a live entropy source (analog) and an internal conditioning component.

The RNG can be used to construct a Non-deterministic Random Bit Generator (NDRBG), as a NIST SP 800-90B compliant entropy source.

The RNG true random number generator has been tested using German BSI statistical tests of AIS-31 (T0 to T8), and NIST SP800-90B statistical test suite.

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3.31 Timers and watchdogs

The devices include two advanced-control timers, twelve general-purpose timers, two basic timers, five low-power timers, two watchdogs and a SysTick timer.

All timer counters can be frozen in Debug mode.

Table 5 compares the features of the advanced-control, general-purpose and basic timers.

Table 5. Timer feature comparison

Timer type	Timer	Counter resolution	Counter type	Prescaler factor	DMA request generation	Capture/ compare channels	Comple- mentary output	Max interface clock (MHz)	Max timer clock (MHz)
Advanced -control	TIM1, TIM8	16-bit	Up, Down, Up/down	Any integer between 1 and 65536	Yes	4	Yes	137.5	275
	TIM2, TIM5, TIM23, TIM24	32-bit	Up, Down, Up/down	Any integer between 1 and 65536	Yes	4	No	137.5	275
	TIM3, TIM4	16-bit	Up, Down, Up/down	Any integer between 1 and 65536	Yes	4	No	137.5	275
General	TIM12	16-bit	Up	Any integer between 1 and 65536	No	2	No	137.5	275
purpose	TIM13, TIM14	16-bit	Up	Any integer between 1 and 65536	No	1	No	137.5	275
	TIM15	16-bit	Up	Any integer between 1 and 65536	Yes	2	1	137.5	275
	TIM16, TIM17	16-bit	Up	Any integer between 1 and 65536	Yes	1	1	137.5	275

Table 5. Timer feature comparison (continued)

Timer type	Timer	Counter resolution	Counter type	Prescaler factor	DMA request generation	Capture/ compare channels	Comple- mentary output	Max interface clock (MHz)	Max timer clock (MHz)
Basic	TIM6, TIM7	16-bit	Up	Any integer between 1 and 65536	Yes	0	No	137.5	275
Low- power timer	LPTIM1, LPTIM2, LPTIM3, LPTIM4, LPTIM5	16-bit	Up	1, 2, 4, 8, 16, 32, 64, 128	No	0	No	137.5	275

^{1.} The maximum timer clock is up to 550 MHz depending on the TIMPRE bit in the RCC_CFGR register and D2PRE1/2 bits in RCC_D2CFGR register.

3.31.1 Advanced-control timers (TIM1, TIM8)

The advanced-control timers (TIM1, TIM8) can be seen as three-phase PWM generators multiplexed on 6 channels. They have complementary PWM outputs with programmable inserted dead times. They can also be considered as complete general-purpose timers. Their 4 independent channels can be used for:

- Input capture
- Output compare
- PWM generation (Edge- or Center-aligned modes)
- One-pulse mode output

If configured as standard 16-bit timers, they have the same features as the general-purpose TIMx timers. If configured as 16-bit PWM generators, they have full modulation capability (0-100%).

The advanced-control timer can work together with the TIMx timers via the Timer Link feature for synchronization or event chaining.

TIM1 and TIM8 support independent DMA request generation.

3.31.2 General-purpose timers (TIMx)

There are ten synchronizable general-purpose timers embedded in the STM32H725xE/G devices (see *Table 5: Timer feature comparison* for differences).

TIM2, TIM3, TIM4, TIM5, TIM23, TIM24

The devices include 4 full-featured general-purpose timers: TIM2, TIM3, TIM4, TIM5, TIM23 and TIM24. TIM5, TIM5, TIM23 and TIM24 are based on a 32-bit auto-reload up/downcounter and a 16-bit prescaler while TIM3 and TIM4 are based on a 16-bit auto-reload up/downcounter and a 16-bit prescaler. All timers feature 4 independent channels for input capture/output compare, PWM or One-pulse mode output. This gives up to 24 input capture/output compare/PWMs on the largest packages.

TIM2, TIM3, TIM4, TIM5, TIM23 and TIM24 general-purpose timers can work together, or with the other general-purpose timers and the advanced-control timers TIM1 and TIM8 via the Timer Link feature for synchronization or event chaining.

Any of these general-purpose timers can be used to generate PWM outputs. TIM2, TIM3, TIM4, TIM5, TIM23, and TIM24 all have independent DMA request generation. They are capable of handling quadrature (incremental) encoder signals and the digital outputs from 1 to 4 hall-effect sensors.

TIM12, TIM13, TIM14, TIM15, TIM16, TIM17

These timers are based on a 16-bit auto-reload upcounter and a 16-bit prescaler. TIM13, TIM14, TIM16 and TIM17 feature one independent channel, whereas TIM12 and TIM15 have two independent channels for input capture/output compare, PWM or One-pulse mode output. They can be synchronized with the TIM2, TIM3, TIM4, TIM5, TIM23, and TIM24 full-featured general-purpose timers or used as simple time bases.

3.31.3 Basic timers TIM6 and TIM7

These timers are mainly used for DAC trigger and waveform generation. They can also be used as a generic 16-bit time base.

TIM6 and TIM7 support independent DMA request generation.

3.31.4 Low-power timers (LPTIM1, LPTIM2, LPTIM3, LPTIM4, LPTIM5)

The low-power timers have an independent clock and is running also in Stop mode if it is clocked by LSE, LSI or an external clock. It is able to wakeup the devices from Stop mode.

This low-power timer supports the following features:

- 16-bit up counter with 16-bit autoreload register
- 16-bit compare register
- Configurable output: pulse, PWM
- Continuous / One-shot mode
- Selectable software / hardware input trigger
- Selectable clock source:
- Internal clock source: LSE, LSI, HSI or APB clock
- External clock source over LPTIM input (working even with no internal clock source running, used by the Pulse Counter Application)
- Programmable digital glitch filter
- Encoder mode

3.31.5 Independent watchdog

The independent watchdog is based on a 12-bit downcounter and 8-bit prescaler. It is clocked from an independent 32 kHz internal RC and as it operates independently from the main clock, it can operate in Stop and Standby modes. It can be used either as a watchdog to reset the device when a problem occurs, or as a free-running timer for application timeout management. It is hardware- or software-configurable through the option bytes.

A window option allows the device to be reset when a reload operation is made too early after the previous reload.

3.31.6 Window watchdog

The window watchdog is based on a 7-bit downcounter that can be set as free-running. It can be used as a watchdog to reset the device when a problem occurs. It is clocked from the main clock. It has an early warning interrupt capability and the counter can be frozen in Debug mode.

3.31.7 SysTick timer

This timer is dedicated to real-time operating systems, but could also be used as a standard down counter. It features:

- A 24-bit down counter
- Autoreload capability
- Maskable system interrupt generation when the counter reaches 0
- Programmable clock source.



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3.32 Real-time clock (RTC), backup SRAM and backup registers

The RTC is an independent BCD timer/counter. It supports the following features:

- Calendar with subsecond, seconds, minutes, hours (12 or 24 format), week day, date, month, year, in BCD (binary-coded decimal) format.
- Automatic correction for 28, 29 (leap year), 30, and 31 days of the month.
- Two programmable alarms.
- On-the-fly correction from 1 to 32767 RTC clock pulses. This can be used to synchronize it with a master clock.
- Reference clock detection: a more precise second source clock (50 or 60 Hz) can be used to enhance the calendar precision.
- Digital calibration circuit with 0.95 ppm resolution, to compensate for quartz crystal inaccuracy.
- Three anti-tamper detection pins with programmable filter.
- Timestamp feature which can be used to save the calendar content. This function can be triggered by an event on the timestamp pin, or by a tamper event, or by a switch to V_{BAT} mode.
- 17-bit auto-reload wakeup timer (WUT) for periodic events with programmable resolution and period.

The RTC and the 32 backup registers are supplied through a switch that takes power either from the V_{DD} supply when present or from the V_{BAT} pin.

The backup registers are 32-bit registers used to store 128 bytes of user application data when VDD power is not present. They are not reset by a system or power reset, or when the device wakes up from Standby mode.

The RTC clock sources can be:

- A 32.768 kHz external crystal (LSE)
- An external resonator or oscillator (LSE)
- The internal low-power RC oscillator (LSI, with typical frequency of 32 kHz)
- The high-speed external clock (HSE) divided by 32.

The RTC is functional in V_{BAT} mode and in all low-power modes when it is clocked by the LSE. When clocked by the LSI, the RTC is not functional in V_{BAT} mode, but is functional in all low-power modes.

All RTC events (Alarm, Wakeup Timer, Timestamp or Tamper) can generate an interrupt and wakeup the device from the low-power modes.

3.33 Inter-integrated circuit interface (I2C)

STM32H725xE/G devices embed five I²C interfaces.

The I²C bus interface handles communications between the microcontroller and the serial I²C bus. It controls all I²C bus-specific sequencing, protocol, arbitration and timing.

The I2C peripheral supports:

- I²C-bus specification and user manual rev. 5 compatibility:
 - Slave and Master modes, multimaster capability
 - Standard-mode (Sm), with a bitrate up to 100 kbit/s
 - Fast-mode (Fm), with a bitrate up to 400 kbit/s
 - Fast-mode Plus (Fm+), with a bitrate up to 1 Mbit/s and 20 mA output drive I/Os
 - 7-bit and 10-bit addressing mode, multiple 7-bit slave addresses
 - Programmable setup and hold times
 - Optional clock stretching
- System Management Bus (SMBus) specification rev 2.0 compatibility:
 - Hardware PEC (Packet Error Checking) generation and verification with ACK control
 - Address resolution protocol (ARP) support
 - SMBus alert
- Power System Management Protocol (PMBusTM) specification rev 1.1 compatibility
- Independent clock: a choice of independent clock sources allowing the I2C communication speed to be independent from the PCLK reprogramming.
- Wakeup from Stop mode on address match
- Programmable analog and digital noise filters
- 1-byte buffer with DMA capability

3.34 Universal synchronous/asynchronous receiver transmitter (USART)

STM32H725xE/G devices have five embedded universal synchronous receiver transmitters (USART1, USART2, USART3, USART6, and USART10) and five universal asynchronous receiver transmitters (UART4, UART5, UART7, UART8, and UART9). Refer to *Table 6: USART features* for a summary of USARTx and UARTx features.

These interfaces provide asynchronous communication, IrDA SIR ENDEC support, multiprocessor communication mode, single-wire Half-duplex communication mode and have LIN Master/Slave capability. They provide hardware management of the CTS and RTS signals, and RS485 Driver Enable. They are able to communicate at speeds of up to 12.5 Mbit/s.

USART1, USART2, USART3, USART6, and USART10 also provide Smartcard mode (ISO 7816 compliant) and SPI-like communication capability.

The USARTs embed a Transmit FIFO (TXFIFO) and a Receive FIFO (RXFIFO). FIFO mode is enabled by software and is disabled by default.

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All USART have a clock domain independent from the CPU clock, allowing the USARTx to wake up the MCU from Stop mode. The wakeup from Stop mode is programmable and can be done on:

- Start bit detection
- Any received data frame
- A specific programmed data frame
- Specific TXFIFO/RXFIFO status when FIFO mode is enabled.

All USART interfaces can be served by the DMA controller.

Table 6. USART features

USART modes/features ⁽¹⁾	USART1/2/3/6/10	UART4/5/7/8/9
Hardware flow control for modem	Х	Х
Continuous communication using DMA	Х	Х
Multiprocessor communication	Х	Х
Synchronous mode (Master/Slave)	Х	-
Smartcard mode	Х	-
Single-wire Half-duplex communication	Х	Х
IrDA SIR ENDEC block	Х	Х
LIN mode	Х	Х
Dual clock domain and wakeup from low power mode	Х	Х
Receiver timeout interrupt	Х	Х
Modbus communication	Х	Х
Auto baud rate detection	Х	Х
Driver Enable	Х	Х
USART data length	7, 8 and	d 9 bits
Tx/Rx FIFO	Х	Х
Tx/Rx FIFO size	1	6

^{1.} X = supported.

3.35 Low-power universal asynchronous receiver transmitter (LPUART)

The device embeds one Low-Power UART (LPUART1). The LPUART supports asynchronous serial communication with minimum power consumption. It supports half duplex single wire communication and modem operations (CTS/RTS). It allows multiprocessor communication.

The LPUARTs embed a Transmit FIFO (TXFIFO) and a Receive FIFO (RXFIFO). FIFO mode is enabled by software and is disabled by default.

The LPUART has a clock domain independent from the CPU clock, and can wakeup the system from Stop mode. The wakeup from Stop mode are programmable and can be done on:

- Start bit detection
- Any received data frame
- A specific programmed data frame
- Specific TXFIFO/RXFIFO status when FIFO mode is enabled.

Only a 32.768 kHz clock (LSE) is needed to allow LPUART communication up to 9600 baud. Therefore, even in Stop mode, the LPUART can wait for an incoming frame while having an extremely low energy consumption. Higher speed clock can be used to reach higher baudrates.

LPUART interface can be served by the DMA controller.

3.36 Serial peripheral interface (SPI)/inter- integrated sound interfaces (I2S)

The devices feature up to six SPIs (SPI2S1, SPI2S2, SPI2S3, SPI4, SPI5 and SPI2S6) that allow communicating up to 150 Mbits/s in Master and Slave modes, in Half-duplex, Full-duplex and Simplex modes. The 3-bit prescaler gives 8 master mode frequencies and the frame is configurable from 4 to 16 bits. All SPI interfaces support NSS pulse mode, TI mode, Hardware CRC calculation and 8x 8-bit embedded Rx and Tx FIFOs with DMA capability.

Four standard I^2S interfaces (multiplexed with SPI1, SPI2, SPI3 and SPI6) are available. They can be operated in Master or Slave mode, in Simplex communication modes, and can be configured to operate as a 16-/32-bit resolution input or output channel (except SPI2S6 which is limited to 16 bits). Audio sampling frequencies from 8 kHz up to 192 kHz are supported. When either or both of the I^2S interfaces is/are configured in Master mode, the master clock can be output to the external DAC/CODEC at 256 times the sampling frequency. All I^2S interfaces support 16x 8-bit embedded Rx and Tx FIFOs with DMA capability.

3.37 Serial audio interfaces (SAI)

The devices embed 2 SAIs (SAI1, and SAI4) that allow designing many stereo or mono audio protocols such as I2S, LSB or MSB-justified, PCM/DSP, TDM or AC'97. An SPDIF output is available when the audio block is configured as a transmitter. To bring this level of flexibility and reconfigurability, the SAI contains two independent audio sub-blocks. Each block has it own clock generator and I/O line controller.

Audio sampling frequencies up to 192 kHz are supported.

In addition, up to 8 microphones can be supported thanks to an embedded PDM interface. The SAI can work in master or slave configuration. The audio sub-blocks can be either receiver or transmitter and can work synchronously or asynchronously (with respect to the other one). The SAI can be connected with other SAIs to work synchronously.



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3.38 SPDIFRX Receiver Interface (SPDIFRX)

The SPDIFRX peripheral is designed to receive an S/PDIF flow compliant with IEC-60958 and IEC-61937. These standards support simple stereo streams up to high sample rate, and compressed multi-channel surround sound, such as those defined by Dolby or DTS (up to 5.1).

The main SPDIFRX features are the following:

- Up to 4 inputs available
- Automatic symbol rate detection
- Maximum symbol rate: 12.288 MHz
- Stereo stream from 32 to 192 kHz supported
- Supports Audio IEC-60958 and IEC-61937, consumer applications
- Parity bit management
- Communication using DMA for audio samples
- Communication using DMA for control and user channel information
- Interrupt capabilities

The SPDIFRX receiver provides all the necessary features to detect the symbol rate, and decode the incoming data stream. The user can select the wanted SPDIF input, and when a valid signal will be available, the SPDIFRX will re-sample the incoming signal, decode the Manchester stream, recognize frames, sub-frames and blocks elements. It delivers to the CPU decoded data, and associated status flags.

The SPDIFRX also offers a signal named spdif_frame_sync, which toggles at the S/PDIF sub-frame rate that will be used to compute the exact sample rate for clock drift algorithms.

3.39 Single wire protocol master interface (SWPMI)

The Single wire protocol master interface (SWPMI) is the master interface corresponding to the Contactless Frontend (CLF) defined in the ETSI TS 102 613 technical specification. The main features are:

- Full-duplex communication mode
- automatic SWP bus state management (active, suspend, resume)
- configurable bitrate up to 2 Mbit/s
- automatic SOF, EOF and CRC handling

SWPMI can be served by the DMA controller.

3.40 Management data input/output (MDIO) slaves

The devices embed an MDIO slave interface it includes the following features:

- 32 MDIO Registers addresses, each of which is managed using separate input and output data registers:
 - 32 x 16-bit firmware read/write, MDIO read-only output data registers
 - 32 x 16-bit firmware read-only, MDIO write-only input data registers
- Configurable slave (port) address
- Independently maskable interrupts/events:
 - MDIO Register write
 - MDIO Register read
 - MDIO protocol error
- Able to operate in and wake up from Stop mode

3.41 SD/SDIO/MMC card host interfaces (SDMMC)

Two SDMMC host interfaces are available. They support *MultiMediaCard System*Specification Version 4.51 in three different databus modes: 1 bit (default), 4 bits and 8 bits.

Both interfaces support the *SD memory card specifications version 4.1.* and the *SDIO card specification version 4.0.* in two different databus modes: 1 bit (default) and 4 bits.

Each SDMMC host interface supports only one SD/SDIO/MMC card at any one time and a stack of MMC Version 4.51 or previous.

The SDMMC host interface embeds a dedicated DMA controller allowing high-speed transfers between the interface and the SRAM.

3.42 Controller area network (FDCAN1, FDCAN2, FDCAN3)

The controller area network (CAN) subsystem consists of two CAN modules, a shared message RAM memory and a clock calibration unit.

All CAN modules (FDCAN1, FDCAN2, and FDCAN3) are compliant with ISO 11898-1 (CAN protocol specification version 2.0 part A, B) and CAN FD protocol specification version 1.0.

FDCAN1 supports time triggered CAN (TT-FDCAN) specified in ISO 11898-4, including event synchronized time-triggered communication, global system time, and clock drift compensation. The FDCAN1 contains additional registers, specific to the time triggered feature. The CAN FD option can be used together with event-triggered and time-triggered CAN communication.

A 10-Kbyte message RAM memory implements filters, receive FIFOs, receive buffers, transmit event FIFOs, transmit buffers (and triggers for TT-FDCAN). This message RAM is shared between the three modules - FDCAN1 FDCAN2 and FDCAN3.

The common clock calibration unit is optional. It can be used to generate a calibrated clock for FDCAN1, FDCAN2 and FDCAN3 from the HSI internal RC oscillator and the PLL, by evaluating CAN messages received by the FDCAN1.

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3.43 Universal serial bus on-the-go high-speed (OTG_HS)

The devices embed an USB OTG high-speed (up to 480 Mbit/s) device/host/OTG peripheral that supports both full-speed and high-speed operations. It integrates the transceivers for full-speed operation (12 Mbit/s) and a UTMI low-pin interface (ULPI) for high-speed operation (480 Mbit/s). When using the USB OTG_HS interface in HS mode, an external PHY device connected to the ULPI is required.

The USB OTG_HS peripheral is compliant with the USB 2.0 specification and with the OTG 2.0 specification. It features software-configurable endpoint setting and supports suspend/resume. The USB OTG_HS controller requires a dedicated 48 MHz clock that is generated by a PLL connected to the HSE oscillator.

The main features are:

- Combined Rx and Tx FIFO size of 4 Kbytes with dynamic FIFO sizing
- Supports the session request protocol (SRP) and host negotiation protocol (HNP)
- 8 bidirectional endpoints
- 16 host channels with periodic OUT support
- Software configurable to OTG1.3 and OTG2.0 modes of operation
- USB 2.0 LPM (Link Power Management) support
- Battery Charging Specification Revision 1.2 support
- Internal FS OTG PHY support
- External HS or HS OTG operation supporting ULPI in SDR mode The OTG PHY is connected to the microcontroller ULPI port through 12 signals. It can be clocked using the 60 MHz output.
- Internal USB DMA
- HNP/SNP/IP inside (no need for any external resistor)
- For OTG/Host modes, a power switch is needed in case bus-powered devices are connected

3.44 Ethernet MAC interface with dedicated DMA controller (ETH)

The devices provide an IEEE-802.3-2002-compliant media access controller (MAC) for ethernet LAN communications through an industry-standard medium-independent interface (MII) or a reduced medium-independent interface (RMII). The microcontroller requires an external physical interface device (PHY) to connect to the physical LAN bus (twisted-pair, fiber, etc.). The PHY is connected to the device MII port using 17 signals for MII or 9 signals for RMII, and can be clocked using the 25 MHz (MII) from the microcontroller.

The devices include the following features:

- Supports 10 and 100 Mbit/s rates
- Dedicated DMA controller allowing high-speed transfers between the dedicated SRAM and the descriptors
- Tagged MAC frame support (VLAN support)
- Half-duplex (CSMA/CD) and full-duplex operation
- MAC control sublayer (control frames) support
- 32-bit CRC generation and removal
- Several address filtering modes for physical and multicast address (multicast and group addresses)
- 32-bit status code for each transmitted or received frame
- Internal FIFOs to buffer transmit and receive frames. The transmit FIFO and the receive FIFO are both 2 Kbytes.
- Supports hardware PTP (precision time protocol) in accordance with IEEE 1588 2008 (PTP V2) with the time stamp comparator connected to the TIM2 input
- Triggers interrupt when system time becomes greater than target time

3.45 High-definition multimedia interface (HDMI) - consumer electronics control (CEC)

The devices embed a HDMI-CEC controller that provides hardware support for the Consumer Electronics Control (CEC) protocol (Supplement 1 to the HDMI standard).

This protocol provides high-level control functions between all audiovisual products in an environment. It is specified to operate at low speeds with minimum processing and memory overhead. It has a clock domain independent from the CPU clock, allowing the HDMI-CEC controller to wakeup the MCU from Stop mode on data reception.

3.46 Debug infrastructure

The devices offer a comprehensive set of debug and trace features to support software development and system integration.

- Breakpoint debugging
- Code execution tracing
- Software instrumentation
- JTAG debug port
- Serial-wire debug port
- Trigger input and output
- Serial-wire trace port
- Trace port
- Arm[®] CoreSight[™] debug and trace components

The debug can be controlled via a JTAG/Serial-wire debug access port, using industry standard debugging tools. The trace port performs data capture for logging and analysis.

Memory mapping STM32H725xE/G

4 Memory mapping

Refer to the product line reference manual for details on the memory mapping as well as the boundary addresses for all peripherals.

5 Pinouts, pin descriptions and alternate functions

VBAT 🔲 1 51 🗖 VDD PC14-OSC32_IN 2 50 🗆 VSS PC15-OSC32_OUT 3 49 VCAP VSSSMPS ☐ 4 48 🗖 PA13 VLXSMPS ☐ 5 47 🗖 PA12 VDDSMPS ☐ 6 46 🗀 PA11 VFBSMPS ☐ 7 45 PA10 VSS 8 44 | PA9 VFQFPN68 VDD 🔲 9 43 🔲 PA8 PH0-OSC_IN ☐ 10 42 PC9 PH1-OSC_OUT [11 41 PC7 NRST 🗌 12 40 PC6 PC0 🗆 13 39 🗖 PB15 PC1 🔲 14 38 🔲 PB14 VSSA 🗆 15 37 PB13 VDDA ☐ 16 36 🗖 PB12 PA0 🗆 17 35 VDD 18 19 20 21 22 22 23 23 24 25 26 27 27 28 28 30 30 31 33 33 33 33 33 34 PA1 | PA2 | PA2 | PA3 | VSS | VSS | PA4 | PA5 | PA6 | PA6 | PC4 | PC4 | PC4 | PC4 | PC4 | PC5 | PC4 | PC5 | PC5 | PC6 |

Figure 4. VFQFPN68 pinout

1. The above figure shows the package top view.

Figure 5. TFBGA100 pinout 10 PE6 PE5 PE2 PB8 воото PB5 PD6 PD3 PD2 PC12 PC15-OSC32_OUT PE3 PE0 PB7 PB3 PD4 PD1 PC11 PC10 VSS VBAT PE4 PE1 PB4 PD7 PD0 PA15 PA14 PA13 VSSSMPS VLXSMPS PDR ON PB6 vss VDD PD5 VCAP PA12 PA11 VDDSMPS VFBSMPS PC13 VDD VDDLDO VSS VDD33USE PA10 NRST PC2_C vss VDD PA8 PH1-OSC_OUT PH0-OSC II PC3 C PA3 VCAP PD15 PC8 VDDA VSSA PA2 PC4 PE7 PE10 PD11 PD12 PD13 VREF+

The above figure shows the package top view.

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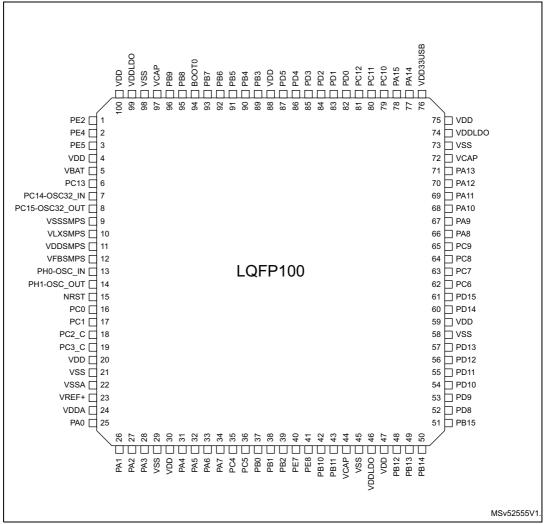


Figure 6. LQFP100 pinout

A7/

VDDLDO PC14-OSC32_IN PA14 PD5 PC12 PA15 VSSSMPS VDD33USB PA9 PE0 VLXSMPS PD0 VBAT PC7 PA10 PB6 PDR_ON VDD PD13 PC9 PB7 PC0 vss PD15 PD9 PE7 PA0 VDD vss PD10 PB13 PA3 PC1 PD11 PB14 PA7 PA1 NRST PA6 PD12 PD8 PB10 VSSA PH1-OSC_OUT vss PB12 PB0 PA5 vss VDD PB15 PE8 vss PA2 VDD VDDLDO PB11 VCAP vss VDD PA4 VDDA VDD PB2 PC5 vss VDD VDD MSv52557V1

Figure 7. WLCSP115 ballout



Figure 8. LQFP144 pinout

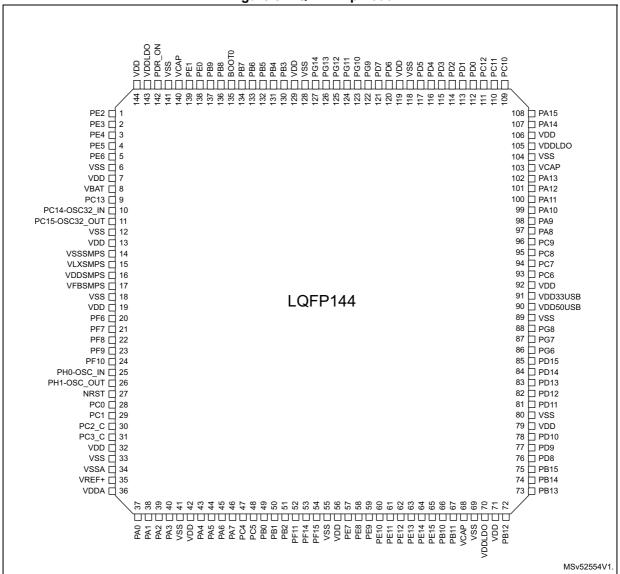
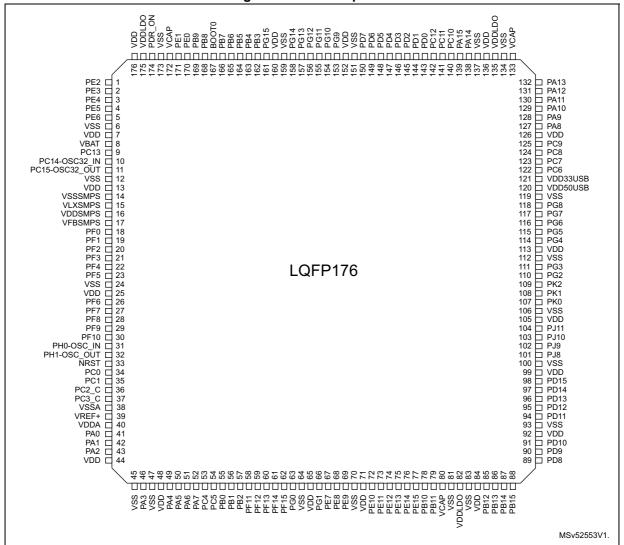


Figure 9. LQFP176 pinout



1. The above figure shows the package top view.



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Figure 10. UFBGA169 ballout

1	2	3	4	5	6	7	8	9	10	11		
						•	٠	3	10	11	12	13
PE4	PE2	VDD	VCAP	PB6	VDD	VDD	PG10	PD5	VDD	PC12	PC10	PH14
PC15- OSC32_OUT	PE3	vss	VDDLDO	PB8	PB4	vss	PG11	PD6	vss	PC11	PA14	PH13
PC14- OSC32_IN	PE6	PE5	PDR_ON	PB9	PB5	PG14	PG9	PD4	PD1	PA15	vss	VDD
VDD	vss	PC13	PE1	PE0	PB7	PG13	PD7	PD3	PD0	PA13	VDDLDO	VCAP
VLXSMPS	VSSSMPS	VBAT	PF1	PF3	воото	PG15	PG12	PD2	PA10	PA9	PA8	PA12
VDDSMPS	VFBSMPS	PF0	PF2	PF5	PF7	PB3	PG4	PC6	PC7	PC9	PC8	PA11
VDD	vss	PF4	PF6	PF9	NRST	PF13	PE7	PG6	PG7	PG8	VDD50USB	VDD33USB
PH0-OSC_IN	PH1- OSC_OUT	PF10	PF8	PC2	PA4	PF14	PE8	PG2	PG3	PG5	vss	VDD
PC0	PC1	VSSA	PC3	PA0	PA7	PF15	PE9	PE14	PD11	PD13	PD15	PD14
PC3_C	PC2_C	PA0_C	PA1	PA6	PC4	PG0	PE13	PH10	PH12	PD9	PD10	PD12
VDDA	VREF+	PA1_C	PA5	PB1	PB2	PG1	PE12	PB10	PH11	PB13	vss	VDD
VDD	vss	PH3	vss	PB0	PF11	vss	PE10	PB11	VDDLDO	vss	PD8	PB15
PA2	PH2	PA3	VDD	PC5	PF12	VDD	PE11	PE15	VCAP	VDD	PB12	PB14
v	PC14-NSC32_IN VDD //LXSMPS //DDSMPS VDD H0-OSC_IN PC0 PC3_C VDDA VDD	PE3	PC14- PC14- PC32- PC32- VDD	PC14_ PC14_ PC3_ VSS	PE3	PE3	PE3	No.	PE3	PE3	PE3	PE3

Figure 11. UFBGA176+25 ballout

						9									
	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15
Α	vss	PB8	VDDLDO	VCAP	PB6	PB3	PG11	PG9	PD3	PD1	PA15	PA14	VDDLDO	VCAP	vss
В	PE4	PE3	PB9	PE0	PB7	PB4	PG13	PD7	PD5	PD2	PC12	PH14	PA13	PA8	PA12
С	PC13	vss	PE2	PE1	воото	PB5	PG14	PG10	PD4	PD0	PC11	PC10	PH13	PA10	PA11
D	PC15- OSC32_OUT	PC14- OSC32_IN	PE5	PDR_ON	VDD	vss	PG15	PG12	PD6	vss	VDD	PH15	PA9	PC8	PC7
E	vss	VBAT	PE6	VDD			•		•	•		VDD	PC9	PC6	VDD50USB
F	VLXSMPS	VSSSMPS	PF1	PF0		vss	vss	vss	vss	vss		vss	VDD33USB	PG6	PG5
G	VDDSMPS	VFBSMPS	PF2	VDD		vss	vss	vss	vss	vss		PG8	PG7	PG4	PG2
н	PF6	PF4	PF5	PF3		vss	vss	vss	vss	vss		VDD	PG3	PD14	PD13
J	PH0-OSC_IN	PF8	PF7	PF9		vss	vss	vss	vss	vss		PD15	PD11	vss	PD12
к	PH1- OSC_OUT	vss	PF10	VDD		vss	vss	vss	vss	vss		vss	PD9	PB15	PB14
L	NRST	PC0	PC1	VREF-			•	•		•	•	VDD	PD10	PD8	PB13
м	PC2	PC3	VREF+	VDDA	VDD	vss	PC5	PB1	VDD	vss	PH7	PE14	PH11	PH9	PB12
N	PC2_C	PC3_C	VSSA	PH2	PA3	PA7	PF11	PE8	PG1	PF15	PF13	PB10	PH8	PH10	PH12
P	PA0	PA1	PA1_C	PH4	PA4	PA5	PB2	PG0	PE7	PB11	PF12	PE12	PE13	PE15	PH6
R	vss	PA2	PA0_C	PH3	PH5	PC4	PA6	PB0	PE10	PF14	PE9	PE11	VCAP	VDDLDO	vss
														M	Sv52552V

1. The above figure shows the package top view.



Table 7. Legend/abbreviations used in the pinout table

Nar	ne	Abbreviation	Definition						
Pin na	ame		ecified in brackets below the pin name, the pin function during same as the actual pin name						
		S	Supply pin						
Din t	VIDO	I	Input only pin						
Pin t	ype	I/O	Input / output pin						
		ANA	Analog-only Input						
		FT	5 V tolerant I/O						
		TT	3.3 V tolerant I/O						
		В	Dedicated BOOT0 pin						
		RST	Bidirectional reset pin with embedded weak pull-up resistor						
I/O stru	ıcture	Option for TT and FT I/Os							
		_f	I2C FM+ option						
		_a	analog option (supplied by V _{DDA})						
		_u	USB option (supplied by V _{DD33USB})						
		_h	High-speed low-voltage I/O						
Not	es	Unless otherwise speafter reset.	ecified by a note, all I/Os are set as floating inputs during and						
Pin functions	Alternate functions	Functions selected the	nrough GPIOx_AFR registers						
THITIUNCUOTIS	Additional functions	Functions directly selected/enabled through peripheral registers							



Table 8. STM32H725 pin and ball descriptions

			Pin n	umber	140		<u> </u>	32H725 pi		buil u			
VFQFPN68 SMPS	LQFP100 SMPS	TFBGA100 SMPS	LQFP144 SMPS	WLCSP115 SMPS	UFBGA169 SMPS	UFBGA176+25 SMPS	LQFP176 SMPS	Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
-	1	А3	1	B11	A2	C3	1	PE2	I/O	FT_h	-	TRACECLK, SAI1_CK1, USART10_RX, SPI4_SCK, SAI1_MCLK_A, SAI4_MCLK_A, OCTOSPIM_P1_IO2, SAI4_CK1, ETH_MII_TXD3, FMC_A23, EVENTOUT	-
-	1	В3	2	-	B2	B2	2	PE3	I/O	FT_h	-	TRACED0, TIM15_BKIN, SAI1_SD_B, SAI4_SD_B, USART10_TX, FMC_A19, EVENTOUT	-
-	2	C3	3	F9	A1	B1	3	PE4	I/O	FT_h	-	TRACED1, SAI1_D2, DFSDM1_DATIN3, TIM15_CH1N, SPI4_NSS, SAI1_FS_A, SAI4_FS_A, SAI4_D2, FMC_A20, DCMI_D4/PSSI_D4, LCD_B0, EVENTOUT	-
-	3	A2	4	-	С3	D3	4	PE5	I/O	FT_h	-	TRACED2, SAI1_CK2, DFSDM1_CKIN3, TIM15_CH1, SPI4_MISO, SAI1_SCK_A, SAI4_SCK_A, SAI4_CK2, FMC_A21, DCMI_D6/PSSI_D6, LCD_G0, EVENTOUT	-

Table 8. STM32H725 pin and ball descriptions (continued)

			Pin n	umber				-				, (continuou)	
VFQFPN68 SMPS	LQFP100 SMPS	TFBGA100 SMPS	LQFP144 SMPS	WLCSP115 SMPS	UFBGA169 SMPS	UFBGA176+25 SMPS	LQFP176 SMPS	Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
-	-	A1	5	-	C2	E3	5	PE6	I/O	FT_h	-	TRACED3, TIM1_BKIN2, SAI1_D1,TIM15_CH2, SPI4_MOSI, SAI1_SD_A, SAI4_SD_A, SAI4_D1, SAI4_MCLK_B, TIM1_BKIN2_COMP1 2, FMC_A22, DCMI_D7/PSSI_D7, LCD_G1, EVENTOUT	-
-	-	-	6	-	-	-	6	VSS	S	-	-	-	-
-	4	-	7	-	-	-	7	VDD	S	-	-	-	-
1	5	C2	8	K9	E3	E2	8	VBAT	S	-	-	-	-
-	6	E4	9	H9	D3	C1	9	PC13	I/O	FT	1	EVENTOUT	RTC_TAMP1/ RTC_TS, WKUP4
-	1	-	-	F11	-	-	-	VSS	S	-	-	-	-
2	7	B1	10	D11	C1	D2	10	PC14- OSC32_IN	I/O	FT	1	EVENTOUT	OSC32_IN
3	8	B2	11	E10	B1	D1	11	PC15- OSC32_ OUT	I/O	FT	-	EVENTOUT	OSC32_OUT
-	-	-	12	F11	-	-	12	VSS	S	-	-	-	-
-	1	-	13	G10	-	1	13	VDD	S	-	-	-	-
4	9	D1	14	H11	E2	F2	14	VSSSMPS	S	-	-	-	-
5	10	D2	15	J10	E1	F1	15	VLXSMPS	S	-	-	-	-
6	11	E1	16	K11	F1	G1	16	VDDSMPS	S	-	1	-	-
7	12	E2	17	L10	F2	G2	17	VFBSMPS	S	-	-	-	-
-	-	-	-	-	F3	F4	18	PF0	I/O	FT_fh	-	I2C2_SDA(boot), I2C5_SDA, OCTOSPIM_P2_IO0, FMC_A0, TIM23_CH1, EVENTOUT	-



Table 8. STM32H725 pin and ball descriptions (continued)

			Pin n	umber	0.0	711110		o pin ana		1000116		(continued)	
VFQFPN68 SMPS	LQFP100 SMPS	TFBGA100 SMPS	LQFP144 SMPS	WLCSP115 SMPS	UFBGA169 SMPS	UFBGA176+25 SMPS	LQFP176 SMPS	Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
-	1	-	-	-	E4	F3	19	PF1	I/O	FT_fh	-	I2C2_SCL(boot), I2C5_SCL, OCTOSPIM_P2_IO1, FMC_A1, TIM23_CH2, EVENTOUT	-
-	1	-	-	-	F4	G3	20	PF2	I/O	FT_h	-	I2C2_SMBA, I2C5_SMBA, OCTOSPIM_P2_IO2, FMC_A2, TIM23_CH3, EVENTOUT	-
-	1	-	-	-	E5	H4	21	PF3	I/O	FT_ha	-	OCTOSPIM_P2_IO3, FMC_A3, TIM23_CH4, EVENTOUT	ADC3_INP5
-	1	-	-	-	G3	H2	22	PF4	I/O	FT_ha	-	OCTOSPIM_P2_CLK, FMC_A4, EVENTOUT	ADC3_INN5, ADC3_INP9
-	1	-	-	-	F5	НЗ	23	PF5	I/O	FT_ha	-	OCTOSPIM_P2_NCL K, FMC_A5, EVENTOUT	ADC3_INP4
8	-	-	18	M11	-	-	24	VSS	S	-	-	-	-
9	-	-	19	N10	-	-	25	VDD	S	-	-	-	-
-	-	-	20	-	G4	Н1	26	PF6	I/O	FT_ha	-	TIM16_CH1, FDCAN3_RX, SPI5_NSS, SAI1_SD_B, UART7_RX, SAI4_SD_B, OCTOSPIM_P1_IO3, TIM23_CH1, EVENTOUT	ADC3_INN4, ADC3_INP8
-	-	-	21	-	F6	J3	27	PF7	I/O	FT_ha	-	TIM17_CH1, FDCAN3_TX, SPI5_SCK, SAI1_MCLK_B, UART7_TX, SAI4_MCLK_B, OCTOSPIM_P1_IO2, TIM23_CH2, EVENTOUT	ADC3_INP3

Table 8. STM32H725 pin and ball descriptions (continued)

			Pin n	umber				p aa				(continued)	
VFQFPN68 SMPS	LQFP100 SMPS	TFBGA100 SMPS	LQFP144 SMPS	WLCSP115 SMPS	UFBGA169 SMPS	UFBGA176+25 SMPS	LQFP176 SMPS	Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
-		-	22	-	H4	J2	28	PF8	I/O	FT_ha	-	TIM16_CH1N, SPI5_MISO, SAI1_SCK_B, UART7_RTS/UART7_ DE, SAI4_SCK_B, TIM13_CH1, OCTOSPIM_P1_IO0, TIM23_CH3, EVENTOUT	ADC3_INN3, ADC3_INP7
-	-	-	23	-	G5	J4	29	PF9	I/O	FT_ha	-	TIM17_CH1N, SPI5_MOSI, SAI1_FS_B, UART7_CTS, SAI4_FS_B, TIM14_CH1, OCTOSPIM_P1_IO1, TIM23_CH4, EVENTOUT	ADC3_INP2
-	1	-	24	-	Н3	K3	30	PF10	I/O	FT_ha	1	TIM16_BKIN, SAI1_D3, PSSI_D15, OCTOSPIM_P1_CLK, SAI4_D3, DCMI_D11/PSSI_D11, LCD_DE, EVENTOUT	ADC3_INN2, ADC3_INP6
10	13	G1	25	P11	H1	J1	31	PH0- OSC_IN	I/O	FT	-	EVENTOUT	OSC_IN
11	14	G2	26	T11	H2	K1	32	PH1- OSC_OUT	I/O	FT	-	EVENTOUT	OSC_OUT
12	15	F2	27	R10	G6	L1	33	NRST	I/O	RST	1	-	-
13	16	F3	28	М9	J1	L2	34	PC0	I/O	FT_ha	-	FMC_D12/FMC_AD12 , DFSDM1_CKIN0, DFSDM1_DATIN4, SAI4_FS_B, FMC_A25, OTG_HS_ULPI_STP, LCD_G2, FMC_SDNWE, LCD_R5, EVENTOUT	ADC123_INP10



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Table 8. STM32H725 pin and ball descriptions (continued)

			Pin n	umber				- piii uiiu		1000116		(continuea)	
VFQFPN68 SMPS	LQFP100 SMPS	TFBGA100 SMPS	LQFP144 SMPS	WLCSP115 SMPS	UFBGA169 SMPS	UFBGA176+25 SMPS	LQFP176 SMPS	Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
14	17	F1	29	P9	J2	L3	35	PC1	I/O	FT_ha	-	TRACEDO, SAI4_D1, SAI1_D1, DFSDM1_DATINO, DFSDM1_CKIN4, SPI2_MOSI/I2S2_SD O, SAI1_SD_A, SAI4_SD_A, SDMMC2_CK, OCTOSPIM_P1_IO4, ETH_MDC, MDIOS_MDC, LCD_G5, EVENTOUT	ADC123_INN10 , ADC123_INP11 , RTC_TAMP3, WKUP6
-	-	-	-	-	H5	M1	-	PC2	I/O	FT_a	-	PWR_DEEPSLEEP, DFSDM1_CKIN1, OCTOSPIM_P1_IO5, SPI2_MISO/I2S2_SDI, DFSDM1_CKOUT, OCTOSPIM_P1_IO2, OTG_HS_ULPI_DIR, ETH_MII_TXD2, FMC_SDNE0, EVENTOUT	ADC123_INN11 , ADC123_INP12
-	18	F4	30	-	K2	N1	36	PC2_C	ANA	TT_a	-	-	ADC3_INN1, ADC3_INP0
-	-	-	-	-	J4	M2	-	PC3	I/O	FT_a	-	PWR_SLEEP, DFSDM1_DATIN1, OCTOSPIM_P1_IO6, SPI2_MOSI/ I2S2_SDO, OCTOSPIM_P1_IO0, OTG_HS_ULPI_NXT, ETH_MII_TX_CLK, FMC_SDCKE0, EVENTOUT	ADC12_INN12, ADC12_INP13
-	19	G4	31	-	K1	N2	37	PC3_C	ANA	TT_a	-	-	ADC3_INP1
-	20	1	32	V11	-	-	-	VDD	S	-	-	-	-
-	21	-	33	U10	-	-	-	VSS	S	-	-	-	-
15	22	H2	34	Т9	J3	N3	38	VSSA	S	-	-	-	-

Table 8. STM32H725 pin and ball descriptions (continued)

			Pin n	umber				-				(continued)	
VFQFPN68 SMPS	LQFP100 SMPS	TFBGA100 SMPS	LQFP144 SMPS	WLCSP115 SMPS	UFBGA169 SMPS	UFBGA176+25 SMPS	LQFP176 SMPS	Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
-	-	-	-	-	-	L4	-	VREF-	S	-	1	-	-
-	23	J1	35	W10	L2	МЗ	39	VREF+	S	-	ı	-	-
16	24	H1	36	Y11	L1	M4	40	VDDA	S	-	-	-	-
17	25	G3	37	N8	J5	P1	41	PA0	I/O	FT_ha	-	TIM2_CH1/TIM2_ETR, TIM5_CH1, TIM8_ETR, TIM15_BKIN, SPI6_NSS/I2S6_WS, USART2_CTS/USART 2_NSS, UART4_TX, SDMMC2_CMD, SAI4_SD_B, ETH_MII_CRS, FMC_A19, EVENTOUT	ADC1_INP16, WKUP1
-	-	-	-	-	K3	R3	-	PA0_C	ANA	TT_a	-	-	ADC12_INN1, ADC12_INP0
18	26	J2	38	R8	K4	P2	42	PA1	I/O	FT_ha	-	TIM2_CH2, TIM5_CH2, LPTIM3_OUT, TIM15_CH1N, USART2_RTS/USART 2_DE, UART4_RX, OCTOSPIM_P1_IO3, SAI4_MCLK_B, ETH_MII_RX_CLK/ET H_RMII_REF_CLK, OCTOSPIM_P1_DQS, LCD_R2, EVENTOUT	ADC1_INN16, ADC1_INP17
-	-	-	-	-	L3	P3	-	PA1_C	ANA	TT_a	-	-	ADC12_INP1



Table 8. STM32H725 pin and ball descriptions (continued)

			Pin n	umber				pin unu				(continued)	
VFQFPN68 SMPS	LQFP100 SMPS	TFBGA100 SMPS	LQFP144 SMPS	WLCSP115 SMPS	UFBGA169 SMPS	UFBGA176+25 SMPS	LQFP176 SMPS	Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
19	27	Н3	39	V9	N1	R2	43	PA2	I/O	FT_ha	-	TIM2_CH3, TIM5_CH3, LPTIM4_OUT, TIM15_CH1, OCTOSPIM_P1_IO0, USART2_TX(boot), SAI4_SCK_B, ETH_MDIO, MDIOS_MDIO, LCD_R1, EVENTOUT	ADC12_INP14, WKUP2
-	-	-	-	-	N2	N4	-	PH2	I/O	FT_ha	-	LPTIM1_IN2, OCTOSPIM_P1_IO4, SAI4_SCK_B, ETH_MII_CRS, FMC_SDCKE0, LCD_R0, EVENTOUT	ADC3_INP13
-	-	-	-	AA10	-	-	44	VDD	S	-	-	-	-
-	-	-	-	-	-	-	45	VSS	S	-	-	-	-
-	1	1	-	-	М3	R4	-	PH3	I/O	FT_ha	-	OCTOSPIM_P1_IO5, SAI4_MCLK_B, ETH_MII_COL, FMC_SDNE0, LCD_R1, EVENTOUT	ADC3_INN13, ADC3_INP14
-	-	-	-	-	-	P4	-	PH4	I/O	FT_fa	-	I2C2_SCL, LCD_G5, OTG_HS_ULPI_NXT, PSSI_D14, LCD_G4, EVENTOUT	ADC3_INN14, ADC3_INP15
-	-	-	-	-	-	R5	-	PH5	I/O	FT_fh a	-	I2C2_SDA, SPI5_NSS, FMC_SDNWE, EVENTOUT	ADC3_INN15, ADC3_INP16

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Table 8. STM32H725 pin and ball descriptions (continued)

			Pin n	umber				•				(continued)	
VFQFPN68 SMPS	LQFP100 SMPS	TFBGA100 SMPS	LQFP144 SMPS	WLCSP115 SMPS	UFBGA169 SMPS	UFBGA176+25 SMPS	LQFP176 SMPS	Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
20	28	G5	40	P7	N3	N5	46	PA3	I/O	FT_ha	-	TIM2_CH4, TIM5_CH4, LPTIM5_OUT, TIM15_CH2, I2S6_MCK, OCTOSPIM_P1_IO2, USART2_RX(boot), LCD_B2, OTG_HS_ULPI_D0, ETH_MII_COL, OCTOSPIM_P1_CLK, LCD_B5, EVENTOUT	ADC12_INP15
21	29	-	41	-	-	-	47	VSS	S	-	-	-	-
22	30	-	42	-	-	-	48	VDD	S	-	-	-	-
23	31	K1	43	Y9	Н6	P5	49	PA4	I/O	TT_ha	-	D1PWREN, TIM5_ETR, SPI1_NSS(boot)/I2S1 _WS, SPI3_NSS/I2S3_WS, USART2_CK, SPI6_NSS/I2S6_WS, FMC_D8/FMC_AD8, DCMI_HSYNC/PSSI_ DE, LCD_VSYNC, EVENTOUT	ADC12_INP18, DAC1_OUT1
24	32	K2	44	U8	L4	P6	50	PA5	I/O	TT_ha	-	D2PWREN, TIM2_CH1/TIM2_ETR, TIM8_CH1N, SPI1_SCK(boot)/I2S1CK, SPI6_SCK/I2S6_CK, OTG_HS_ULPI_CK, FMC_D9/FMC_AD9, PSSI_D14, LCD_R4, EVENTOUT	ADC12_INN18, ADC12_INP19, DAC1_OUT2



Table 8. STM32H725 pin and ball descriptions (continued)

			Pin n	umber				pin unu				(continued)	
VFQFPN68 SMPS	LQFP100 SMPS	TFBGA100 SMPS	LQFP144 SMPS	WLCSP115 SMPS	UFBGA169 SMPS	UFBGA176+25 SMPS	LQFP176 SMPS	Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
25	33	J3	45	Т7	K5	R7	51	PA6	I/O	FT_ha	-	TIM1_BKIN, TIM3_CH1, TIM8_BKIN, SPI1_MISO(boot)/I2S1 _SDI, OCTOSPIM_P1_IO3, SPI6_MISO/I2S6_SDI, TIM13_CH1, TIM8_BKIN_COMP12, MDIOS_MDC, TIM1_BKIN_COMP12, DCMI_PIXCLK/PSSI_ PDCK, LCD_G2, EVENTOUT	ADC12_INP3
26	34	К3	46	R6	J6	N6	52	PA7	I/O	TT_ha	-	TIM1_CH1N, TIM3_CH2, TIM8_CH1N, SPI1_MOSI(boot)/I2S1 _SDO, SPI6_MOSI/I2S6_SD O, TIM14_CH1, OCTOSPIM_P1_IO2, ETH_MII_RX_DV/ETH _RMII_CRS_DV, FMC_SDNWE, LCD_VSYNC, EVENTOUT	ADC12_INN3, ADC12_INP7, OPAMP1_VINM
27	35	H4	47	W8	K6	R6	53	PC4	I/O	TT_ha	-	PWR_DEEPSLEEP, FMC_A22, DFSDM1_CKIN2, I2S1_MCK, SPDIFRX1_IN3, SDMMC2_CKIN, ETH_MII_RXD0/ETH_ RMII_RXD0, FMC_SDNE0, LCD_R7, EVENTOUT	ADC12_INP4, OPAMP1_ VOUT, COMP1_INM



Table 8. STM32H725 pin and ball descriptions (continued)

			Pin n	umber				-				(continued)	
VFQFPN68 SMPS	LQFP100 SMPS	TFBGA100 SMPS	LQFP144 SMPS	WLCSP115 SMPS	UFBGA169 SMPS	UFBGA176+25 SMPS	LQFP176 SMPS	Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
28	36	J4	48	AA8	N5	M7	54	PC5	I/O	TT_ha	-	PWR_SLEEP, SAI4_D3, SAI1_D3, DFSDM1_DATIN2, PSSI_D15, SPDIFRX1_IN4, OCTOSPIM_P1_DQS, ETH_MII_RXD1/ETH_ RMII_RXD1, FMC_SDCKE0, COMP1_OUT, LCD_DE, EVENTOUT	ADC12_INN4, ADC12_INP8, OPAMP1_VINM
-	-	-	-	V7	-	-	-	VSS	S	-	-	-	-
-	ı	ı	-	Y7	-	-	1	VDD	S	-	ı	-	-
29	37	K4	49	U6	M5	R8	55	PB0	I/O	TT_ha	-	TIM1_CH2N, TIM3_CH3, TIM8_CH2N, OCTOSPIM_P1_IO1, DFSDM1_CKOUT, UART4_CTS, LCD_R3, OTG_HS_ULPI_D1, ETH_MII_RXD2, LCD_G1, EVENTOUT	ADC12_INN5, ADC12_INP9, OPAMP1_VINP, COMP1_INP
30	38	K5	50	W6	L5	M8	56	PB1	I/O	FT_ha	-	TIM1_CH3N, TIM3_CH4, TIM8_CH3N, OCTOSPIM_P1_IO0, DFSDM1_DATIN1, LCD_R6, OTG_HS_ULPI_D2, ETH_MII_RXD3, LCD_G0, EVENTOUT	ADC12_INP5, COMP1_INM



Table 8. STM32H725 pin and ball descriptions (continued)

			Pin n	umber	0. 0	7111102		o pin ana		1000116		(continuea)	
VFQFPN68 SMPS	LQFP100 SMPS	TFBGA100 SMPS	LQFP144 SMPS	WLCSP115 SMPS	UFBGA169 SMPS	UFBGA176+25 SMPS	LQFP176 SMPS	Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
31	39	J5	51	AA6	L6	P7	57	PB2	I/O	FT_ha	-	RTC_OUT, SAI4_D1, SAI1_D1, DFSDM1_CKIN1, SAI1_SD_A, SPI3_MOSI/I2S3_SD O, SAI4_SD_A, OCTOSPIM_P1_CLK, OCTOSPIM_P1_DQS, ETH_TX_ER, TIM23_ETR, EVENTOUT	COMP1_INP
-	-	1	52	,	M6	N7	58	PF11	I/O	FT_ha	1	SPI5_MOSI, OCTOSPIM_P1_NCL K, SAI4_SD_B, FMC_NRAS, DCMI_D12/PSSI_D12, TIM24_CH1, EVENTOUT	ADC1_INP2
-	-	-	-	-	N6	P11	59	PF12	I/O	FT_ha	-	OCTOSPIM_P2_DQS, FMC_A6, TIM24_CH2, EVENTOUT	ADC1_INN2, ADC1_INP6
-	-	-	-	-	G7	N11	60	PF13	I/O	FT_ha	-	DFSDM1_DATIN6, I2C4_SMBA, FMC_A7, TIM24_CH3, EVENTOUT	ADC2_INP2
-	-	-	53	-	H7	R10	61	PF14	I/O	FT_fh a	-	DFSDM1_CKIN6, I2C4_SCL, FMC_A8, TIM24_CH4, EVENTOUT	ADC2_INN2, ADC2_INP6
-	-	-	54	-	J7	N10	62	PF15	I/O	FT_fh	-	I2C4_SDA, FMC_A9, EVENTOUT	-
-	-	-	-	-	K7	P8	63	PG0	I/O	FT_h	-	OCTOSPIM_P2_IO4, UART9_RX, FMC_A10, EVENTOUT	-
-	-	-	55	-	-	-	64	VSS	S	-	-	-	-
-	-	-	56	-	-	-	65	VDD	S	-	-	-	-

Table 8. STM32H725 pin and ball descriptions (continued)

			Pin n	umber				•				(continued)	
VFQFPN68 SMPS	LQFP100 SMPS	TFBGA100 SMPS	LQFP144 SMPS	WLCSP115 SMPS	UFBGA169 SMPS	UFBGA176+25 SMPS	LQFP176 SMPS	Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
-	1	-	-	-	L7	N9	66	PG1	I/O	TT_h	-	OCTOSPIM_P2_IO5, UART9_TX, FMC_A11, EVENTOUT	OPAMP2_VINM
-	40	H5	57	N6	G8	P9	67	PE7	I/O	TT_ha	-	TIM1_ETR, DFSDM1_DATIN2, UART7_RX, OCTOSPIM_P1_IO4, FMC_D4/FMC_AD4, EVENTOUT	OPAMP2_ VOUT, COMP2_INM
-	41	J6	58	V5	Н8	N8	68	PE8	I/O	TT_ha	-	TIM1_CH1N, DFSDM1_CKIN2, UART7_TX, OCTOSPIM_P1_IO5, FMC_D5/FMC_AD5, COMP2_OUT, EVENTOUT	OPAMP2_VINM
-	1	K6	59	-	J8	R11	69	PE9	I/O	TT_ha	-	TIM1_CH1, DFSDM1_CKOUT, UART7_RTS/UART7_ DE, OCTOSPIM_P1_IO6, FMC_D6/FMC_AD6, EVENTOUT	OPAMP2_VINP, COMP2_INP
-	1	-	-	Y5	-	-	70	VSS	S	-	-	-	-
-	-	-	-	AA4	-	-	71	VDD	S	-	-	-	-
-	-	H6	60	1	M8	R9	72	PE10	I/O	FT_ha	-	TIM1_CH2N, DFSDM1_DATIN4, UART7_CTS, OCTOSPIM_P1_IO7, FMC_D7/FMC_AD7, EVENTOUT	COMP2_INM
-	-	-	61	-	N8	R12	73	PE11	I/O	FT_ha	-	TIM1_CH2, DFSDM1_CKIN4, SPI4_NSS(boot), SAI4_SD_B, OCTOSPIM_P1_NCS, FMC_D8/FMC_AD8, LCD_G3, EVENTOUT	COMP2_INP



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Table 8. STM32H725 pin and ball descriptions (continued)

			Pin n	umber				pin unu				(continued)	
VFQFPN68 SMPS	LQFP100 SMPS	TFBGA100 SMPS	LQFP144 SMPS	WLCSP115 SMPS	UFBGA169 SMPS	UFBGA176+25 SMPS	LQFP176 SMPS	Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
-	1	-	62	-	L8	P12	74	PE12	I/O	FT_h	-	TIM1_CH3N, DFSDM1_DATIN5, SPI4_SCK(boot), SAI4_SCK_B, FMC_D9/FMC_AD9, COMP1_OUT, LCD_B4, EVENTOUT	-
-	1	1	63	1	K8	P13	75	PE13	I/O	FT_h	-	TIM1_CH3, DFSDM1_CKIN5, SPI4_MISO(boot), SAI4_FS_B, FMC_D10/FMC_AD10 , COMP2_OUT, LCD_DE, EVENTOUT	-
-	-	-	64	-	J9	M12	76	PE14	I/O	FT_h	-	TIM1_CH4, SPI4_MOSI(boot), SAI4_MCLK_B, FMC_D11/FMC_AD11, LCD_CLK, EVENTOUT	-
-	-	-	65	-	N9	P14	77	PE15	I/O	FT_h	-	TIM1_BKIN, USART10_CK, FMC_D12/FMC_AD12 , TIM1_BKIN_COMP12, LCD_R7, EVENTOUT	-
32	42	K7	66	T5	L9	N12	78	PB10	I/O	FT_fh	-	TIM2_CH3, LPTIM2_IN1, I2C2_SCL, SPI2_SCK/I2S2_CK, DFSDM1_DATIN7, USART3_TX(boot), OCTOSPIM_P1_NCS, OTG_HS_ULPI_D3, ETH_MII_RX_ER, LCD_G4, EVENTOUT	-

Table 8. STM32H725 pin and ball descriptions (continued)

			Pin n	umber				pin and				(continued)	
VFQFPN68 SMPS	LQFP100 SMPS	TFBGA100 SMPS	LQFP144 SMPS	WLCSP115 SMPS	UFBGA169 SMPS	UFBGA176+25 SMPS	LQFP176 SMPS	Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
-	43	J7	67	W4	М9	P10	79	PB11	I/O	FT_f	,	TIM2_CH4, LPTIM2_ETR, I2C2_SDA, DFSDM1_CKIN7, USART3_RX(boot), OTG_HS_ULPI_D4, ETH_MII_TX_EN/ETH _RMII_TX_EN, LCD_G5, EVENTOUT	-
33	44	G6	68	Y3	N10	R13	80	VCAP	S	-	-	-	-
34	45	-	69	AA2	-	-	81	VSS	S	-	-	-	-
-	46	F7	70	W2	M10	R14	82	VDDLDO	S	-	-	-	-
35	47	-	71	Y1	-	-	-	VDD	S	-	-	-	-
-	-	-	-	-	-	P15	-	PH6	I/O	FT_h	-	TIM12_CH1, I2C2_SMBA, SPI5_SCK, ETH_MII_RXD2, FMC_SDNE1, DCMI_D8/PSSI_D8, EVENTOUT	-
1	1	-	-	-	-	M11	-	PH7	I/O	FT_fh	-	I2C3_SCL, SPI5_MISO, ETH_MII_RXD3, FMC_SDCKE1, DCMI_D9/PSSI_D9, EVENTOUT	-
-	-	-	-	-	-	N13	-	PH8	I/O	FT_fh	-	TIM5_ETR, I2C3_SDA, FMC_D16, DCMI_HSYNC/PSSI_ DE, LCD_R2, EVENTOUT	-
-	-	-	-	-	-	M14	-	PH9	I/O	FT_h	-	TIM12_CH2, I2C3_SMBA, FMC_D17, DCMI_D0/PSSI_D0, LCD_R3, EVENTOUT	-



Table 8. STM32H725 pin and ball descriptions (continued)

			Pin n	umber				-					
VFQFPN68 SMPS	LQFP100 SMPS	TFBGA100 SMPS	LQFP144 SMPS	WLCSP115 SMPS	UFBGA169 SMPS	UFBGA176+25 SMPS	LQFP176 SMPS	Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
-	-	-	-	-	K9	N14	-	PH10	I/O	FT_h	-	TIM5_CH1, I2C4_SMBA, FMC_D18, DCMI_D1/PSSI_D1, LCD_R4, EVENTOUT	-
-	1	-	-	-	L10	M13	-	PH11	I/O	FT_fh	-	TIM5_CH2,I2C4_SCL, FMC_D19, DCMI_D2/PSSI_D2, LCD_R5, EVENTOUT	-
-	-	-	-	-	-	-	83	VSS	S	-	-	-	-
-	-	-	-	Y1	-	-	84	VDD	S	-	-	-	-
-	-	-	-	-	K10	N15	-	PH12	I/O	FT_fh	-	TIM5_CH3, I2C4_SDA, FMC_D20, DCMI_D3/PSSI_D3, LCD_R6, EVENTOUT	-
36	48	K8	72	U4	N12	M15	85	PB12	I/O	FT_h	-	TIM1_BKIN, OCTOSPIM_P1_NCL K, I2C2_SMBA, SPI2_NSS/I2S2_WS, DFSDM1_DATIN1, USART3_CK, FDCAN2_RX, OTG_HS_ULPI_D5, ETH_MII_TXD0/ETH_ RMII_TXD0, OCTOSPIM_P1_IO0, TIM1_BKIN_COMP12, UART5_RX, EVENTOUT	-

Table 8. STM32H725 pin and ball descriptions (continued)

			Pin n	umber				, , , , , , , , , , , , , , , , , , ,				(continued)	
VFQFPN68 SMPS	LQFP100 SMPS	TFBGA100 SMPS	LQFP144 SMPS	WLCSP115 SMPS	UFBGA169 SMPS	UFBGA176+25 SMPS	LQFP176 SMPS	Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
37	49	J8	73	P5	L11	L15	86	PB13	I/O	FT_h	-	TIM1_CH1N, LPTIM2_OUT, OCTOSPIM_P1_IO2, SPI2_SCK/I2S2_CK, DFSDM1_CKIN1, USART3_CTS/USART 3_NSS, FDCAN2_TX, OTG_HS_ULPI_D6, ETH_MII_TXD1/ETH_ RMII_TXD1, SDMMC1_D0, DCMI_D2/PSSI_D2, UART5_TX, EVENTOUT	-
38	50	K9	74	R4	N13	K15	87	PB14	I/O	FT_h	-	TIM1_CH2N, TIM12_CH1, TIM8_CH2N, USART1_TX, SPI2_MISO/I2S2_SDI, DFSDM1_DATIN2, USART3_RTS/USART 3_DE, UART4_RTS/UART4_ DE, SDMMC2_D0, FMC_D10/FMC_AD10 , LCD_CLK, EVENTOUT	-
39	51	K10	75	V3	M13	K14	88	PB15	I/O	FT_h	,	RTC_REFIN, TIM1_CH3N, TIM12_CH2, TIM8_CH3N, USART1_RX, SPI2_MOSI/I2S2_SD O, DFSDM1_CKIN2, UART4_CTS, SDMMC2_D1, FMC_D11/FMC_AD11, LCD_G7, EVENTOUT	-



Table 8. STM32H725 pin and ball descriptions (continued)

			Pin n	umber	0.0	7111102		o pin ana			7610113	(continued)	
VFQFPN68 SMPS	LQFP100 SMPS	TFBGA100 SMPS	LQFP144 SMPS	WLCSP115 SMPS	UFBGA169 SMPS	UFBGA176+25 SMPS	LQFP176 SMPS	Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
-	52	J9	76	Т3	M12	L14	89	PD8	I/O	FT_h	-	DFSDM1_CKIN3, USART3_TX(boot), SPDIFRX1_IN2, FMC_D13/FMC_AD13 , EVENTOUT	-
-	53	Н8	77	N4	K11	K13	90	PD9	I/O	FT_h	-	DFSDM1_DATIN3, USART3_RX(boot), FMC_D14/FMC_AD14 , EVENTOUT	-
-	54	J10	78	P3	K12	L13	91	PD10	I/O	FT_h	1	DFSDM1_CKOUT, USART3_CK, FMC_D15/FMC_AD15 , LCD_B3, EVENTOUT	-
-	ı	ı	79	V1	-	ı	92	VDD	S	-	ı	-	-
-	ı	ı	80	U2	-	ı	93	VSS	S	-	ı	1	1
-	55	Н7	81	R2	J10	J13	94	PD11	I/O	FT_h	-	LPTIM2_IN2, I2C4_SMBA, USART3_CTS/USART 3_NSS, OCTOSPIM_P1_IO0, SAI4_SD_A, FMC_A16/FMC_CLE, EVENTOUT	-
-	56	Н9	82	T1	K13	J15	95	PD12	I/O	FT_fh	-	LPTIM1_IN1, TIM4_CH1, LPTIM2_IN1, I2C4_SCL, FDCAN3_RX, USART3_RTS/USART 3_DE, OCTOSPIM_P1_IO1, SAI4_FS_A, FMC_A17/FMC_ALE, DCMI_D12/PSSI_D12, EVENTOUT	-

Table 8. STM32H725 pin and ball descriptions (continued)

			Pin n	umber				pin and				(continued)	
VFQFPN68 SMPS	LQFP100 SMPS	TFBGA100 SMPS	LQFP144 SMPS	WLCSP115 SMPS	UFBGA169 SMPS	UFBGA176+25 SMPS	LQFP176 SMPS	Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
-	57	H10	83	МЗ	J11	H15	96	PD13	I/O	FT_fh	,	LPTIM1_OUT, TIM4_CH2, I2C4_SDA, FDCAN3_TX, OCTOSPIM_P1_IO3, SAI4_SCK_A, UART9_RTS/UART9_ DE, FMC_A18, DCMI_D13/PSSI_D13, EVENTOUT	-
-	58	-	-	-	-	-	-	VSS	S	-	-	-	-
-	59	-	-	-	-	-	-	VDD	S	-	-	-	-
-	60	G7	84	L2	J13	H14	97	PD14	I/O	FT_h	1	TIM4_CH3, UART8_CTS, UART9_RX, FMC_D0/FMC_AD0, EVENTOUT	
-	61	G8	85	N2	J12	J12	98	PD15	I/O	FT_h	-	TIM4_CH4, UART8_RTS/UART8_ DE, UART9_TX, FMC_D1/FMC_AD1, EVENTOUT	-
-	-	-	-	-	-	-	99	VDD	S	-	-	-	-
_	-	-	-	P1	-	-	100	VSS	S	-	-	-	-
-	-	-	-	-	-	-	101	PJ8	I/O	FT	-	TIM1_CH3N, TIM8_CH1, UART8_TX, LCD_G1, EVENTOUT	-
-	-	-	-	-	-	-	102	PJ9	I/O	FT	-	TIM1_CH3, TIM8_CH1N, UART8_RX, LCD_G2, EVENTOUT	-
-	-	-	-	-	-	-	103	PJ10	I/O	FT	-	TIM1_CH2N, TIM8_CH2, SPI5_MOSI, LCD_G3, EVENTOUT	-



Table 8. STM32H725 pin and ball descriptions (continued)

			Pin n	umber						-		(continued)	
VFQFPN68 SMPS	LQFP100 SMPS	TFBGA100 SMPS	LQFP144 SMPS	WLCSP115 SMPS	UFBGA169 SMPS	UFBGA176+25 SMPS	LQFP176 SMPS	Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
-	ı	1	-	1	-	ı	104	PJ11	I/O	FT	-	TIM1_CH2, TIM8_CH2N, SPI5_MISO, LCD_G4, EVENTOUT	-
-	1	-	-	M1	-	-	105	VDD	S	-	-	-	-
-	1	-	-	-	-	-	106	VSS	S	-	-	-	-
-	1	1	-	-	-	1	107	PK0	I/O	FT	-	TIM1_CH1N, TIM8_CH3, SPI5_SCK, LCD_G5, EVENTOUT	-
-	1	1	-	-	-	1	108	PK1	I/O	FT	-	TIM1_CH1, TIM8_CH3N, SPI5_NSS, LCD_G6, EVENTOUT	-
-	1	-	-	-	-	-	109	PK2	I/O	FT	-	TIM1_BKIN, TIM8_BKIN, TIM8_BKIN_COMP12, TIM1_BKIN_COMP12, LCD_G7, EVENTOUT	-
1	1	-	-	-	Н9	G15	110	PG2	I/O	FT_h	-	TIM8_BKIN, TIM8_BKIN_COMP12, FMC_A12, TIM24_ETR, EVENTOUT	-
-	-	-	-	-	H10	H13	111	PG3	I/O	FT_h	-	TIM8_BKIN2, TIM8_BKIN2_COMP1 2, FMC_A13, TIM23_ETR, EVENTOUT	-
-	1	-	-	-	-	-	112	VSS	S	-	-	-	-
-	-	-	-	M1	-	-	113	VDD	S	-	-	-	-
-	1	-	-	-	F8	G14	114	PG4	I/O	FT_h	-	TIM1_BKIN2, TIM1_BKIN2_COMP1 2, FMC_A14/FMC_BA0, EVENTOUT	-

Table 8. STM32H725 pin and ball descriptions (continued)

			Pin n	umber				-				(continued)	
VFQFPN68 SMPS	LQFP100 SMPS	TFBGA100 SMPS	LQFP144 SMPS	WLCSP115 SMPS	UFBGA169 SMPS	UFBGA176+25 SMPS	LQFP176 SMPS	Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
-	-	-	-	-	H11	F15	115	PG5	I/O	FT_h	-	TIM1_ETR, FMC_A15/FMC_BA1, EVENTOUT	-
-	ı	-	86	-	G9	F14	116	PG6	I/O	FT_h	-	TIM17_BKIN, OCTOSPIM_P1_NCS, FMC_NE3, DCMI_D12/PSSI_D12, LCD_R7, EVENTOUT	-
1	1	-	87	-	G10	G13	117	PG7	I/O	FT_h	-	SAI1_MCLK_A, USART6_CK, OCTOSPIM_P2_DQS, FMC_INT, DCMI_D13/PSSI_D13, LCD_CLK, EVENTOUT	-
-	-	-	88	-	G11	G12	118	PG8	I/O	FT_h	-	TIM8_ETR, SPI6_NSS/I2S6_WS, USART6_RTS/USART 6_DE, SPDIFRX1_IN3, ETH_PPS_OUT, FMC_SDCLK, LCD_G7, EVENTOUT	-
-	1	-	89	P1	-	-	119	VSS	S	-	-	-	-
-	-	-	90	K1	G12	E15	120	VDD50US B	S	-	-	-	-
-	-	E8	91	J2	G13	F13	121	VDD33US B	S	-	-	-	-
-	1	-	92	-	-	-	-	VDD	S	-	1	-	-



Table 8. STM32H725 pin and ball descriptions (continued)

			Pin n	umber	-			р ии				(continued)	
VFQFPN68 SMPS	LQFP100 SMPS	TFBGA100 SMPS	LQFP144 SMPS	WLCSP115 SMPS	UFBGA169 SMPS	UFBGA176+25 SMPS	LQFP176 SMPS	Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
40	62	F8	93	H1	F9	E14	122	PC6	I/O	FT_h	-	TIM3_CH1, TIM8_CH1, DFSDM1_CKIN3, I2S2_MCK, USART6_TX, SDMMC1_DODIR, FMC_NWAIT, SDMMC2_D6, SDMMC1_D6, DCMI_D0/PSSI_D0, LCD_HSYNC, EVENTOUT	SWPMI_IO
41	63	G9	94	К3	F10	D15	123	PC7	I/O	FT_h	-	DBTRGIO, TIM3_CH2, TIM8_CH2, DFSDM1_DATIN3, I2S3_MCK, USART6_RX, SDMMC1_D123DIR, FMC_NE1, SDMMC2_D7, SWPMI_TX, SDMMC1_D7, DCMI_D1/PSSI_D1, LCD_G6, EVENTOUT	-
-	64	G10	95	L4	F12	D14	124	PC8	I/O	FT_h	-	TRACED1, TIM3_CH3, TIM8_CH3, USART6_CK, UART5_RTS/UART5_ DE, FMC_NE2/FMC_NCE, FMC_INT, SWPMI_RX, SDMMC1_D0, DCMI_D2/PSSI_D2, EVENTOUT	-

Table 8. STM32H725 pin and ball descriptions (continued)

			Pin n	umber				pin unu				(continued)	
VFQFPN68 SMPS	LQFP100 SMPS	TFBGA100 SMPS	LQFP144 SMPS	WLCSP115 SMPS	UFBGA169 SMPS	UFBGA176+25 SMPS	LQFP176 SMPS	Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
42	65	F9	96	M5	F11	E13	125	PC9	I/O	FT_fh	-	MCO2, TIM3_CH4, TIM8_CH4, I2C3_SDA(boot), I2S_CKIN, I2C5_SDA, UART5_CTS, OCTOSPIM_P1_IO0, LCD_G3, SWPMI_SUSPEND, SDMMC1_D1, DCMI_D3/PSSI_D3, LCD_B2, EVENTOUT	-
-	-	-	-	G2	-	-	-	VSS	S	-	-	-	-
-	ı	-	-	F1	-	-	126	VDD	S	-	ı	-	-
43	66	F10	97	Н3	E12	B14	127	PA8	I/O	FT_fh	-	MCO1, TIM1_CH1, TIM8_BKIN2, I2C3_SCL(boot), I2C5_SCL, USART1_CK, OTG_HS_SOF, UART7_RX, TIM8_BKIN2_COMP1 2, LCD_B3, LCD_R6, EVENTOUT	-
44	67	E9	98	J4	E11	D13	128	PA9	I/O	FT_u	-	TIM1_CH2, LPUART1_TX, I2C3_SMBA, SPI2_SCK/I2S2_CK, I2C5_SMBA, USART1_TX(boot), ETH_TX_ER, DCMI_D0/PSSI_D0, LCD_R5, EVENTOUT	OTG_HS_ VBUS
45	68	E10	99	K5	E10	C14	129	PA10	I/O	FT_u	-	TIM1_CH3, LPUART1_RX, USART1_RX(boot), OTG_HS_ID, MDIOS_MDIO, LCD_B4, DCMI_D1/PSSI_D1, LCD_B1, EVENTOUT	-



Table 8. STM32H725 pin and ball descriptions (continued)

			Pin n	umber				P				(continued)	
VFQFPN68 SMPS	LQFP100 SMPS	TFBGA100 SMPS	LQFP144 SMPS	WLCSP115 SMPS	UFBGA169 SMPS	UFBGA176+25 SMPS	LQFP176 SMPS	Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
46	69	D10	100	E2	F13	C15	130	PA11	I/O	FT_u	-	TIM1_CH4, LPUART1_CTS, SPI2_NSS/I2S2_WS, UART4_RX, USART1_CTS/USART 1_NSS, FDCAN1_RX, LCD_R4, EVENTOUT	OTG_HS_DM (boot)
47	70	D9	101	F3	E13	B15	131	PA12	I/O	FT_u	-	TIM1_ETR, LPUART1_RTS/LPUA RT1_DE, SPI2_SCK/I2S2_CK, UART4_TX, USART1_RTS/USART 1_DE, SAI4_FS_B, FDCAN1_TX, TIM1_BKIN2, LCD_R5, EVENTOUT	OTG_HS_DP (boot)
48	71	C10	102	G4	D11	B13	132	PA13(JTM S/ SWDIO)	I/O	FT	-	JTMS/SWDIO, EVENTOUT	-
49	72	D8	103	D1	D13	A14	133	VCAP	S	-	-	-	-
50	73	-	104	B1	-	-	134	VSS	S	-	-	-	-
-	74	E6	105	C2	D12	A13	135	VDDLDO	S	-	-	-	-
51	75	-	106	A2	-	-	136	VDD	S	-	-	-	-
-	76	-	-	-	-	-	-	VDD33US B	S	-	-	-	-
-	-	-	-	-	B13	C13	-	PH13	I/O	FT_h	-	TIM8_CH1N, UART4_TX, FDCAN1_TX(boot), FMC_D21, LCD_G2, EVENTOUT	-
-	-	-	-	-	A13	B12	-	PH14	I/O	FT_h	-	TIM8_CH2N, UART4_RX, FDCAN1_RX(boot), FMC_D22, DCMI_D4/PSSI_D4, LCD_G3, EVENTOUT	-

Table 8. STM32H725 pin and ball descriptions (continued)

			Pin n	umber				pin unu				(continued)	
VFQFPN68 SMPS	LQFP100 SMPS	TFBGA100 SMPS	LQFP144 SMPS	WLCSP115 SMPS	UFBGA169 SMPS	UFBGA176+25 SMPS	LQFP176 SMPS	Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
-	-	-	-	-	-	D12	-	PH15	I/O	FT_h	-	TIM8_CH3N, FMC_D23, DCMI_D11/PSSI_D11, LCD_G4, EVENTOUT	-
-	ı	1	-	-	-	-	137	VSS	S	-	-	-	-
-	•	•	-	A2	-	-	-	VDD	S	-	-	-	-
52	77	C9	107	D3	B12	A12	138	PA14(JTC K/SWCLK)	I/O	FT	1	JTCK/SWCLK, EVENTOUT	-
53	78	C8	108	Н5	C11	A11	139	PA15(JTDI)	I/O	FT	-	JTDI, TIM2_CH1/TIM2_ETR, CEC, SPI1_NSS/I2S1_WS, SPI3_NSS/I2S3_WS, SPI6_NSS/I2S6_WS, UART4_RTS/UART4_ DE, LCD_R3, UART7_TX, LCD_B6, EVENTOUT	-
54	79	B10	109	E4	A12	C12	140	PC10	I/O	FT_fh	-	DFSDM1_CKIN5, I2C5_SDA, SPI3_SCK(boot)/I2S3 _CK, USART3_TX, UART4_TX, OCTOSPIM_P1_IO1, LCD_B1, SWPMI_RX, SDMMC1_D2, DCMI_D8/PSSI_D8, LCD_R2, EVENTOUT	-
55	80	B9	110	L6	B11	C11	141	PC11	I/O	FT_fh	-	DFSDM1_DATIN5, I2C5_SCL, SPI3_MISO(boot)/I2S3 _SDI, USART3_RX, UART4_RX, OCTOSPIM_P1_NCS, SDMMC1_D3, DCMI_D4/PSSI_D4, LCD_B4, EVENTOUT	-



Table 8. STM32H725 pin and ball descriptions (continued)

			Pin n	umber				•		•		(continued)	
VFQFPN68 SMPS	LQFP100 SMPS	TFBGA100 SMPS	LQFP144 SMPS	WLCSP115 SMPS	UFBGA169 SMPS	UFBGA176+25 SMPS	LQFP176 SMPS	Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
56	81	A10	111	F5	A11	B11	142	PC12	I/O	FT_h	-	TRACED3, FMC_D6/FMC_AD6, TIM15_CH1, I2C5_SMBA, SPI6_SCK/I2S6_CK, SPI3_MOSI(boot)/I2S3 _SDO, USART3_CK, UART5_TX, SDMMC1_CK, DCMI_D9/PSSI_D9, LCD_R6, EVENTOUT	-
-	-	-	-	В3	-	-	-	VDD	S	-	-	-	-
-	-	-	-	C4	-	-	-	VSS	S	-	-	-	-
-	82	C7	112	J6	D10	C10	143	PD0	I/O	FT_h	-	DFSDM1_CKIN6, UART4_RX, FDCAN1_RX(boot), UART9_CTS, FMC_D2/FMC_AD2, LCD_B1, EVENTOUT	-
-	83	В8	113	D5	C10	A10	144	PD1	I/O	FT_h	-	DFSDM1_DATIN6, UART4_TX, FDCAN1_TX(boot), FMC_D3/FMC_AD3, EVENTOUT	-
57	84	A9	114	A4	E9	B10	145	PD2	I/O	FT_h	-	TRACED2, FMC_D7/FMC_AD7, TIM3_ETR, TIM15_BKIN, UART5_RX, LCD_B7, SDMMC1_CMD, DCMI_D11/PSSI_D11, LCD_B2, EVENTOUT	-
-	85	A8	115	B5	D9	A9	146	PD3	I/O	FT_h	-	DFSDM1_CKOUT, SPI2_SCK/I2S2_CK, USART2_CTS/USART 2_NSS, FMC_CLK, DCMI_D5/PSSI_D5, LCD_G7, EVENTOUT	-

Table 8. STM32H725 pin and ball descriptions (continued)

			Pin n	umber				•		-		(continued)	
VFQFPN68 SMPS	LQFP100 SMPS	TFBGA100 SMPS	LQFP144 SMPS	WLCSP115 SMPS	UFBGA169 SMPS	UFBGA176+25 SMPS	LQFP176 SMPS	Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
,	86	В7	116	G6	С9	С9	147	PD4	I/O	FT_h	-	USART2_RTS/USART 2_DE, OCTOSPIM_P1_IO4, FMC_NOE, EVENTOUT	-
-	87	D7	117	E6	A9	В9	148	PD5	I/O	FT_h	-	USART2_TX, OCTOSPIM_P1_IO5, FMC_NWE, EVENTOUT	-
-	-	-	118	-	-	-	-	VSS	S	-	-	-	-
-	88	-	119	-	-	-	-	VDD	S	-	ı	-	-
-	1	A7	120	-	B9	D9	149	PD6	I/O	FT_h	-	SAI4_D1, SAI1_D1, DFSDM1_CKIN4, DFSDM1_DATIN1, SPI3_MOSI/I2S3_SD O, SAI1_SD_A, USART2_RX, SAI4_SD_A, OCTOSPIM_P1_IO6, SDMMC2_CK, FMC_NWAIT, DCMI_D10/PSSI_D10, LCD_B2, EVENTOUT	-
-	-	C6	121	-	D8	B8	150	PD7	I/O	FT_h	-	DFSDM1_DATIN4, SPI1_MOSI/I2S1_SD O, DFSDM1_CKIN1, USART2_CK, SPDIFRX1_IN1, OCTOSPIM_P1_IO7, SDMMC2_CMD, FMC_NE1, EVENTOUT	-
-	ı	ı	-	C6	-	ı	151	VSS	S	-	ı	-	-
-	-	1	-	A6	-	-	152	VDD	S	-	1	-	-



Table 8. STM32H725 pin and ball descriptions (continued)

			Pin n	umber								(continued)	
VFQFPN68 SMPS	LQFP100 SMPS	TFBGA100 SMPS	LQFP144 SMPS	WLCSP115 SMPS	UFBGA169 SMPS	UFBGA176+25 SMPS	LQFP176 SMPS	Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
-	-	-	122	-	C8	A8	153	PG9	I/O	FT_h	-	FDCAN3_TX, SPI1_MISO/I2S1_SDI, USART6_RX, SPDIFRX1_IN4, OCTOSPIM_P1_IO6, SAI4_FS_B, SDMMC2_D0, FMC_NE2/FMC_NCE, DCMI_VSYNC/PSSI_ RDY, EVENTOUT	-
-	-	-	123	-	A8	C8	154	PG10	I/O	FT_h	-	FDCAN3_RX, OCTOSPIM_P2_IO6, SPI1_NSS/I2S1_WS, LCD_G3, SAI4_SD_B, SDMMC2_D1, FMC_NE3, DCMI_D2/PSSI_D2, LCD_B2, EVENTOUT	-
-	-	-	124	-	B8	A7	155	PG11	I/O	FT_h	-	LPTIM1_IN2, USART10_RX, SPI1_SCK/I2S1_CK, SPDIFRX1_IN1, OCTOSPIM_P2_IO7, SDMMC2_D2, ETH_MII_TX_EN/ETH _RMII_TX_EN, DCMI_D3/PSSI_D3, LCD_B3, EVENTOUT	-

Table 8. STM32H725 pin and ball descriptions (continued)

			Pin n	umber				o pin ana				(continuea)	
VFQFPN68 SMPS	LQFP100 SMPS	TFBGA100 SMPS	LQFP144 SMPS	WLCSP115 SMPS	UFBGA169 SMPS	UFBGA176+25 SMPS	LQFP176 SMPS	Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
-	-	-	125	-	E8	D8	156	PG12	I/O	FT_h		LPTIM1_IN1, OCTOSPIM_P2_NCS, USART10_TX, SPI6_MISO/I2S6_SDI, USART6_RTS/USART 6_DE, SPDIFRX1_IN2, LCD_B4, SDMMC2_D3, ETH_MII_TXD1/ETH_ RMII_TXD1, FMC_NE4, TIM23_CH1, LCD_B1, EVENTOUT	-
-	-	-	126	,	D7	В7	157	PG13	I/O	FT_h	1	TRACEDO, LPTIM1_OUT, USART10_CTS/USAR T10_NSS, SPI6_SCK/I2S6_CK, USART6_CTS/USART 6_NSS, SDMMC2_D6, ETH_MII_TXD0/ETH_ RMII_TXD0, FMC_A24, TIM23_CH2, LCD_R0, EVENTOUT	-
-	-	-	127	-	C7	C7	158	PG14	I/O	FT_h	-	TRACED1, LPTIM1_ETR, USART10_RTS/USAR T10_DE, SPI6_MOSI/I2S6_SD O, USART6_TX, OCTOSPIM_P1_IO7, SDMMC2_D7, ETH_MII_TXD1/ETH_ RMII_TXD1, FMC_A25, TIM23_CH3, LCD_B0, EVENTOUT	-
-	-	-	128	-	-	-	159	VSS	S	-	-	-	-
-	-	-	129	A6	-	-	160	VDD	S	1	-	-	-



Table 8. STM32H725 pin and ball descriptions (continued)

			Pin n	umber								(continued)	
VFQFPN68 SMPS	LQFP100 SMPS	TFBGA100 SMPS	LQFP144 SMPS	WLCSP115 SMPS	UFBGA169 SMPS	UFBGA176+25 SMPS	LQFP176 SMPS	Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
-	-	-	-	-	E7	D7	161	PG15	I/O	FT_h	-	USART6_CTS/USART 6_NSS, OCTOSPIM_P2_DQS, USART10_CK, FMC_NCAS, DCMI_D13/PSSI_D13, EVENTOUT	-
58	89	B6	130	Н7	F7	A6	162	PB3(JTDO/ TRACES WO)	I/O	FT_h	-	JTDO/TRACESWO, TIM2_CH2, SPI1_SCK/I2S1_CK, SPI3_SCK/I2S3_CK, SPI6_SCK/I2S6_CK, SDMMC2_D2, CRS_SYNC, UART7_RX, TIM24_ETR, EVENTOUT	-
59	90	C5	131	F7	B6	В6	163	PB4(NJTR ST)	I/O	FT_h	-	NJTRST, TIM16_BKIN, TIM3_CH1, SPI1_MISO/I2S1_SDI, SPI3_MISO/I2S3_SDI, SPI2_NSS/I2S2_WS, SPI6_MISO/I2S6_SDI, SDMMC2_D3, UART7_TX, EVENTOUT	-
60	91	A6	132	D7	C6	C6	164	PB5	I/O	FT_h	-	TIM17_BKIN, TIM3_CH2, LCD_B5, I2C1_SMBA, SPI1_MOSI/I2S1_SD O, I2C4_SMBA, SPI3_MOSI/I2S3_SD O, SPI6_MOSI/I2S6_SD O, FDCAN2_RX, OTG_HS_ULPI_D7, ETH_PPS_OUT, FMC_SDCKE1, DCMI_D10/PSSI_D10, UART5_RX, EVENTOUT	-

Table 8. STM32H725 pin and ball descriptions (continued)

			Pin n	umber				P				(continued)	
VFQFPN68 SMPS	LQFP100 SMPS	TFBGA100 SMPS	LQFP144 SMPS	WLCSP115 SMPS	UFBGA169 SMPS	UFBGA176+25 SMPS	LQFP176 SMPS	Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
61	92	D4	133	K 7	A5	A5	165	PB6	I/O	FT_fh	-	TIM16_CH1N, TIM4_CH1, I2C1_SCL(boot), CEC, I2C4_SCL, USART1_TX, LPUART1_TX, FDCAN2_TX, OCTOSPIM_P1_NCS, DFSDM1_DATIN5, FMC_SDNE1, DCMI_D5/PSSI_D5, UART5_TX, EVENTOUT	-
-	-	-	-	В7	-	-	-	VSS	S	-	-	-	-
-	-	-	-	A8	-	-	-	VDD	S	-	-	-	-
62	93	B5	134	M7	D6	B5	166	PB7	I/O	FT_fa	-	TIM17_CH1N, TIM4_CH2, I2C1_SDA, I2C4_SDA, USART1_RX, LPUART1_RX, DFSDM1_CKIN5, FMC_NL, DCMI_VSYNC/PSSI_ RDY, EVENTOUT	PVD_IN
63	94	A5	135	C8	E6	C5	167	воото	I	В	-	-	VPP
64	95	A4	136	E8	B5	A2	168	PB8	I/O	FT_fh	-	TIM16_CH1, TIM4_CH3, DFSDM1_CKIN7, I2C1_SCL, I2C4_SCL, SDMMC1_CKIN, UART4_RX, FDCAN1_RX, SDMMC2_D4, ETH_MII_TXD3, SDMMC1_D4, DCMI_D6/PSSI_D6, LCD_B6, EVENTOUT	-



Table 8. STM32H725 pin and ball descriptions (continued)

			Pin n	umber								(continued)	
VFQFPN68 SMPS	LQFP100 SMPS	TFBGA100 SMPS	LQFP144 SMPS	WLCSP115 SMPS	UFBGA169 SMPS	UFBGA176+25 SMPS	LQFP176 SMPS	Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
65	96	E3	137	G8	C5	В3	169	PB9	I/O	FT_fh	-	TIM17_CH1, TIM4_CH4, DFSDM1_DATIN7, I2C1_SDA(boot), SPI2_NSS/I2S2_WS, I2C4_SDA, SDMMC1_CDIR, UART4_TX, FDCAN1_TX, SDMMC2_D5, I2C4_SMBA, SDMMC1_D5, DCMI_D7/PSSI_D7, LCD_B7, EVENTOUT	-
-	ı	B4	138	J8	D5	B4	170	PE0	I/O	FT_h	1	LPTIM1_ETR, TIM4_ETR, LPTIM2_ETR, UART8_RX, SAI4_MCLK_A, FMC_NBL0, DCMI_D2/PSSI_D2, LCD_R0, EVENTOUT	-
-	•	C4	139	1	D4	C4	171	PE1	I/O	FT_h	1	LPTIM1_IN2, UART8_TX, FMC_NBL1, DCMI_D3/PSSI_D3, LCD_R6, EVENTOUT	-
66	97	D8	140	B9	A4	A4	172	VCAP	S	-	-	-	-
67	98	-	141	A10	-	-	173	VSS	S	-	-	-	-
-	-	D3	142	L8	C4	D4	174	PDR_ON	S	-	-	-	-
-	99	E6	143	D9	B4	A3	175	VDDLDO	S	-	-	-	-
68	100	-	-	C10	-	-	- 176	VDD	S	-	-	-	-
-	-	- C1	144	C10	- B3	- A1	176	VDD	S S	-	-	-	-
_	-	D5	-	-	В3 В7	A15	-	VSS	S	-	-	-	-
-	_	E7	-	_	B10	C2	_	VSS	S	_	_	-	_
		_'		-	510	J2		***************************************			-		·

Table 8. STM32H725 pin and ball descriptions (continued)

F5 C12 D10 - VSS S	
D2 D6 - VSS S	Additional functions
	-
H12 F10 - VSS S	-
L12 F12 - VSS S	-
M2 F6 - VSS S	-
M4 F7 - VSS S	-
M7 F8 - VSS S	-
M11 F9 - VSS S	-
G10 - VSS S	-
	-
G7 - VSS S	-
	-
	-
H10 - VSS S	-
H6 - VSS S	-
H7 - VSS S	-
H8 - VSS S H9 - VSS S	-
H9 - VSS S	-
	-
140 1/00 0	-
- - - - - J10 - VSS S - - -	-
J14 - VSS S	-
J6 - VSS S	-
J7 - VSS S	-
J8 - VSS S	-
J9 - VSS S	-
K10 - VSS S	-
K12 - VSS S	-



Table 8. STM32H725 pin and ball descriptions (continued)

			Pin n	umber				P aa.				(continued)	
VFQFPN68 SMPS	LQFP100 SMPS	TFBGA100 SMPS	LQFP144 SMPS	WLCSP115 SMPS	UFBGA169 SMPS	UFBGA176+25 SMPS	LQFP176 SMPS	Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
-	1	1	-	-	-	K2	-	VSS	S	1	-	-	-
-	ı	ı	-	-	-	K6	1	VSS	S	ı	ı	-	-
-	ı	ı	-	-	-	K7	1	VSS	S	ı	ı	1	-
-	1	ı	-	-	-	K8	1	VSS	S	ı	ı	-	-
-	ı	1	-	-	-	K9	1	VSS	S	ı	ı	-	-
-	ı	ı	-	-	-	M10	1	VSS	S	ı	ı	1	-
-	1	-	-	-	1	M6	-	VSS	S	-	-	-	-
-	1	-	-	-	-	R1	-	VSS	S	-	-	-	-
-	-	-	-	-	1	R15	-	VSS	S	-	-	-	-
-	1	D6	-	-	А3	D5	-	VDD	S	-	-	-	-
-	-	E5	-	-	A6	D11	-	VDD	S	-	-	-	-
-	1	F6	-	-	A7	E4	-	VDD	S	-	-	-	-
-	-	-	-	-	A10	E12	-	VDD	S	-	-	-	-
-	-	-	-	-	C13	G4	-	VDD	S	-	-	-	-
-	ı	-	-	-	D1	H12	-	VDD	S	-	-	-	-
-	-	-	-	-	G1	K4	-	VDD	S	-	-	-	-
-	1	-	-	-	H13	L12	-	VDD	S	-	-	-	-
-	1	-	-	-	L13	M5	-	VDD	S	-	-	-	-
-	-	-	-	-	M1	М9	-	VDD	S	-	-	-	-
-	1	-	-	-	N4	-	-	VDD	S	-	-	-	-
-	1	-	-	-	N7	-	-	VDD	S	-	-	-	-
-	1	1	-	-	N11	1	1	VDD	S	-	1	-	-

Table 9. STM32H725 pin alternate functions

		AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7	AF8	AF9	AF10	AF11	AF12	AF13	AF14	AF15
Po	ort	sys	FMC/LP TIM1/SA I4/TIM16 /17/TIM1 x/TIM2x	FDCAN3 /PDM_S AI1/TIM3 /4/5/12/1 5	DFSDM1 /LCD/LP TIM2/3/4 /5/LPUA RT1/OC TOSPIM _P1/2/TI M8	CEC/DC MI/PSSI/ DFSDM1 /I2C1/2/3 /4/5/LPTI M2/OCT OSPIM_ P1/TIM1 5/USAR T1/10	CEC/FD CAN3/S P11/12S1/ SP12/12S 2/SP13/12 S3/SP14/ 5/6	DFSDM1 /I2C4/5/ OCTOS PIM_P1/ SAI1/SPI 3/I2S3/U ART4	SDMMC 1/SPI2/I2 S2/SPI3/ I2S3/SPI 6/UART 7/USAR T1/2/3/6	LPUART 1/SAI4/S DMMC1/ SPDIFR X1/SPI6/ UART4/ 5/8	FDCAN1 /2/FMC/ LCD/OC TOSPIM _P1/2/S AI4/SDM MC2/SP DIFRX1/ TIM13/1 4	CRS/FM C/LCD/O CTOSPI M_P1/O TG1_FS/ OTG1_H S/SAI4/S DMMC2/ TIM8	DFSDM1 /ETH/I2C 4/LCD/M DIOS/O CTOSPI M_P1/S DMMC2/ SWPMI1 /TIM1x/T IM8/UAR T7/9/US ART10	FMC/LC D/MDIO S/OCTO SPIM_P 1/SDMM C1/TIM1 x/TIM8	COMP/D CMI/PSS I/LCD/TI M1x/TIM 23	LCD/TIM 24/UAR T5	sys
	PA0	-	TIM2_C H1/TIM2 _ETR	TIM5_C H1	TIM8_ET R	TIM15_B KIN	SPI6_NS S/I2S6_ WS	-	USART2 _CTS/U SART2_ NSS	UART4_ TX	SDMMC 2_CMD	SAI4_SD _B	ETH_MII _CRS	FMC_A1	-	-	EVENTO UT
	PA1	-	TIM2_C H2	TIM5_C H2	LPTIM3_ OUT	TIM15_C H1N	-	-	USART2 _RTS/U SART2_ DE	UART4_ RX	OCTOS PIM_P1_ IO3	SAI4_M CLK_B	ETH_MII _RX_CL K/ETH_ RMII_RE F_CLK	OCTOS PIM_P1_ DQS	-	LCD_R2	EVENTO UT
	PA2	-	TIM2_C H3	TIM5_C H3	LPTIM4_ OUT	TIM15_C H1	-	OCTOS PIM_P1_ IO0	USART2 _TX	SAI4_SC K_B	-	-	ETH_MD IO	MDIOS_ MDIO	-	LCD_R1	EVENTO UT
Port A	PA3	-	TIM2_C H4	TIM5_C H4	LPTIM5_ OUT	TIM15_C H2	I2S6_M CK	OCTOS PIM_P1_ IO2	USART2 _RX	-	LCD_B2	OTG_HS _ULPI_D 0	ETH_MII _COL	OCTOS PIM_P1_ CLK	-	LCD_B5	EVENTO UT
	PA4	D1PWREN	-	TIM5_ET R	-	-	SPI1_NS S/I2S1_ WS	SPI3_NS S/I2S3_ WS	USART2 _CK	SPI6_NS S/I2S6_ WS	-	-	-	FMC_D8 /FMC_A D8	DCMI_H SYNC/P SSI_DE	LCD_VS YNC	EVENTO UT
	PA5	D2PWREN	TIM2_C H1/TIM2 _ETR	-	TIM8_C H1N	-	SPI1_SC K/I2S1_ CK	-	-	SPI6_SC K/I2S6_ CK	-	OTG_HS _ULPI_C K	-	FMC_D9 /FMC_A D9	PSSI_D1 4	LCD_R4	EVENTO UT
	PA6	-	TIM1_B KIN	TIM3_C H1	TIM8_B KIN	-	SPI1_MI SO/I2S1 _SDI	OCTOS PIM_P1_ IO3	-	SPI6_MI SO/I2S6 _SDI	TIM13_C H1	TIM8_B KIN_CO MP12	MDIOS_ MDC	TIM1_B KIN_CO MP12	DCMI_PI XCLK/P SSI_PD CK	LCD_G2	EVENTO UT

					Table	9. STM	32H725	pin alte	ernate fo	unction	s (conti	nued)					
		AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7	AF8	AF9	AF10	AF11	AF12	AF13	AF14	AF15
Po	ort	sys	FMC/LP TIM1/SA I4/TIM16 /17/TIM1 x/TIM2x	FDCAN3 /PDM_S AI1/TIM3 /4/5/12/1 5	DFSDM1 /LCD/LP TIM2/3/4 /5/LPUA RT1/OC TOSPIM _P1/2/TI M8	CEC/DC MI/PSSI/ DFSDM1 /I2C1/2/3 /4/5/LPTI M2/OCT OSPIM_ P1/TIM1 5/USAR T1/10	CEC/FD CAN3/S P11/12S1/ SP12/12S 2/SP13/12 S3/SP14/ 5/6	DFSDM1 /I2C4/5/ OCTOS PIM_P1/ SAI1/SPI 3/I2S3/U ART4	SDMMC 1/SPI2/I2 S2/SPI3/ I2S3/SPI 6/UART 7/USAR T1/2/3/6	LPUART 1/SAI4/S DMMC1/ SPDIFR X1/SPI6/ UART4/ 5/8	FDCAN1 /2/FMC/ LCD/OC TOSPIM _P1/2/S AI4/SDM MC2/SP DIFRX1/ TIM13/1 4	CRS/FM C/LCD/O CTOSPI M_P1/O TG1_FS/ OTG1_H S/SAI4/S DMMC2/ TIM8	DFSDM1 /ETH/I2C 4/LCD/M DIOS/O CTOSPI M_P1/S DMMC2/ SWPMI1 /TIM1x/T IM8/UAR T7/9/US ART10	FMC/LC D/MDIO S/OCTO SPIM_P 1/SDMM C1/TIM1 x/TIM8	COMP/D CMI/PSS I/LCD/TI M1x/TIM 23	LCD/TIM 24/UAR T5	sys
	PA7	-	TIM1_C H1N	TIM3_C H2	TIM8_C H1N	-	SPI1_M OSI/I2S1 _SDO	-	-	SPI6_M OSI/I2S6 _SDO	TIM14_C H1	OCTOS PIM_P1_ IO2	ETH_MII _RX_DV /ETH_R MII_CRS _DV	FMC_SD NWE	-	LCD_VS YNC	EVENTO UT
	PA8	MCO1	TIM1_C H1	-	TIM8_B KIN2	I2C3_SC L	-	12C5_SC L	USART1 _CK	-	-	OTG_HS _SOF	UART7_ RX	TIM8_B KIN2_C OMP12	LCD_B3	LCD_R6	EVENTO UT
	PA9	-	TIM1_C H2	_	LPUART 1_TX	I2C3_S MBA	SPI2_SC K/I2S2_ CK	I2C5_S MBA	USART1 _TX	-	-	-	ETH_TX _ER	-	DCMI_D 0/PSSI_ D0	LCD_R5	EVENTO UT
	PA10	-	TIM1_C H3	_	LPUART 1_RX	-	-	-	USART1 _RX	-	-	OTG_HS _ID	MDIOS_ MDIO	LCD_B4	DCMI_D 1/PSSI_ D1	LCD_B1	EVENTO UT
Port A	PA11	_	TIM1_C H4		LPUART 1_CTS	-	SPI2_NS S/I2S2_ WS	UART4_ RX	USART1 _CTS/U SART1_ NSS	-	FDCAN1 _RX	-	-	-	-	LCD_R4	EVENTO UT
	PA12	-	TIM1_ET R	-	LPUART 1_RTS/L PUART1 _DE	-	SPI2_SC K/I2S2_ CK	UART4_ TX	USART1 _RTS/U SART1_ DE	SAI4_FS _B	FDCAN1 _TX	-	-	TIM1_B KIN2	-	LCD_R5	EVENTO UT
	PA13	JTMS/SWDIO	-	-	-	-	-	-	-	-	-	-	-	-	-	-	EVENTO UT
	PA14	JTCK/SWCLK	-	_	-	-	-	-	-	-	-	-	-	-	-	-	EVENTO UT
	PA15	JTDI	TIM2_C H1/TIM2 _ETR	_	-	CEC	SPI1_NS S/I2S1_ WS	SPI3_NS S/I2S3_ WS	SPI6_NS S/I2S6_ WS	UART4_ RTS/UA RT4_DE	LCD_R3	-	UART7_ TX	-	-	LCD_B6	EVENTO UT



Table 9. STM32H725 pin alternate functions (continued)

		AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7	AF8	AF9	AF10	AF11	AF12	AF13	AF14	AF15
Po	ort	sys	FMC/LP TIM1/SA I4/TIM16 /17/TIM1 x/TIM2x	FDCAN3 /PDM_S AI1/TIM3 /4/5/12/1 5	DFSDM1 /LCD/LP TIM2/3/4 /5/LPUA RT1/OC TOSPIM _P1/2/TI M8	CEC/DC MI/PSSI/ DFSDM1 /I2C1/2/3 /4/5/LPTI M2/OCT OSPIM_ P1/TIM1 5/USAR T1/10	CEC/FD CAN3/S P11/12S1/ SP12/12S 2/SP13/12 S3/SP14/ 5/6	DFSDM1 /I2C4/5/ OCTOS PIM_P1/ SAI1/SPI 3/I2S3/U ART4	SDMMC 1/SPI2/I2 S2/SPI3/ I2S3/SPI 6/UART 7/USAR T1/2/3/6	LPUART 1/SAI4/S DMMC1/ SPDIFR X1/SPI6/ UART4/ 5/8	FDCAN1 /2/FMC/ LCD/OC TOSPIM _P1/2/S AI4/SDM MC2/SP DIFRX1/ TIM13/1 4	CRS/FM C/LCD/O CTOSPI M_P1/O TG1_FS/ OTG1_H S/SAI4/S DMMC2/ TIM8	DFSDM1 /ETH/I2C 4/LCD/M DIOS/O CTOSPI M_P1/S DMMC2/ SWPMI1 /TIM1x/T IM8/UAR T7/9/US ART10	FMC/LC D/MDIO S/OCTO SPIM_P 1/SDMM C1/TIM1 x/TIM8	COMP/D CMI/PSS I/LCD/TI M1x/TIM 23	LCD/TIM 24/UAR T5	SYS
	PB0	-	TIM1_C H2N	TIM3_C H3	TIM8_C H2N	OCTOS PIM_P1_ IO1	-	DFSDM1 _CKOUT	-	UART4_ CTS	LCD_R3	OTG_HS _ULPI_D 1	ETH_MII _RXD2	-	-	LCD_G1	EVENTO UT
	PB1	-	TIM1_C H3N	TIM3_C H4	TIM8_C H3N	OCTOS PIM_P1_ IO0	-	DFSDM1 _DATIN1	-	-	LCD_R6	OTG_HS _ULPI_D 2	ETH_MII _RXD3	-	-	LCD_G0	EVENTO UT
	PB2	RTC_OUT	SAI4_D1	SAI1_D1	-	DFSDM1 _CKIN1	-	SAI1_SD _A	SPI3_M OSI/I2S3 _SDO	SAI4_SD _A	OCTOS PIM_P1_ CLK	OCTOS PIM_P1_ DQS	ETH_TX _ER	-	TIM23_E TR	-	EVENTO UT
	PB3	JTDO/TRACE SWO	TIM2_C H2	-	-	-	SPI1_SC K/I2S1_ CK	SPI3_SC K/I2S3_ CK	-	SPI6_SC K/I2S6_ CK	SDMMC 2_D2	CRS_SY NC	UART7_ RX	-	-	TIM24_E TR	EVENTO UT
	PB4	NJTRST	TIM16_B KIN	TIM3_C H1	-	-	SPI1_MI SO/I2S1 _SDI	SPI3_MI SO/I2S3 _SDI	SPI2_NS S/I2S2_ WS	SPI6_MI SO/I2S6 _SDI	SDMMC 2_D3	-	UART7_ TX	-	-	-	EVENTO UT
Port B	PB5	-	TIM17_B KIN	TIM3_C H2	LCD_B5	I2C1_S MBA	SPI1_M OSI/I2S1 _SDO	I2C4_S MBA	SPI3_M OSI/I2S3 _SDO	SPI6_M OSI/I2S6 _SDO	FDCAN2 _RX	OTG_HS _ULPI_D 7	ETH_PP S_OUT	FMC_SD CKE1	DCMI_D 10/PSSI _D10	UART5_ RX	EVENTO UT
	PB6	-	TIM16_C H1N	TIM4_C H1	-	I2C1_SC L	CEC	I2C4_SC L	USART1 _TX	LPUART 1_TX	FDCAN2 _TX	OCTOS PIM_P1_ NCS	DFSDM1 _DATIN5	FMC_SD NE1	DCMI_D 5/PSSI_ D5	UART5_ TX	EVENTO UT
	PB7	-	TIM17_C H1N	TIM4_C H2	-	I2C1_SD A	-	I2C4_SD A	USART1 _RX	LPUART 1_RX	-	-	DFSDM1 _CKIN5	FMC_NL	DCMI_V SYNC/P SSI_RD Y	-	EVENTO UT
	PB8	-	TIM16_C H1	TIM4_C H3	DFSDM1 _CKIN7	I2C1_SC L	-	I2C4_SC L	SDMMC 1_CKIN	UART4_ RX	FDCAN1 _RX	SDMMC 2_D4	ETH_MII _TXD3	SDMMC 1_D4	DCMI_D 6/PSSI_ D6	LCD_B6	EVENTO UT
	PB9	-	TIM17_C H1	TIM4_C H4	DFSDM1 _DATIN7	I2C1_SD A	SPI2_NS S/I2S2_ WS	I2C4_SD A	SDMMC 1_CDIR	UART4_ TX	FDCAN1 _TX	SDMMC 2_D5	I2C4_S MBA	SDMMC 1_D5	DCMI_D 7/PSSI_ D7	LCD_B7	EVENTO UT

					Table	9. STM	32H725	pin alte	ernate f	unction	s (conti	nued)					
		AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7	AF8	AF9	AF10	AF11	AF12	AF13	AF14	AF15
P	ort	sys	FMC/LP TIM1/SA I4/TIM16 /17/TIM1 x/TIM2x	FDCAN3 /PDM_S AI1/TIM3 /4/5/12/1 5	DFSDM1 /LCD/LP TIM2/3/4 /5/LPUA RT1/OC TOSPIM _P1/2/TI M8	CEC/DC MI/PSSI/ DFSDM1 /I2C1/2/3 /4/5/LPTI M2/OCT OSPIM_ P1/TIM1 5/USAR T1/10	CEC/FD CAN3/S P11/12S1/ SP12/12S 2/SP13/12 S3/SP14/ 5/6	DFSDM1 /I2C4/5/ OCTOS PIM_P1/ SAI1/SPI 3/I2S3/U ART4	SDMMC 1/SPI2/I2 S2/SPI3/ I2S3/SPI 6/UART 7/USAR T1/2/3/6	LPUART 1/SAI4/S DMMC1/ SPDIFR X1/SPI6/ UART4/ 5/8	FDCAN1 /2/FMC/ LCD/OC TOSPIM _P1/2/S AI4/SDM MC2/SP DIFRX1/ TIM13/1 4	CRS/FM C/LCD/O CTOSPI M_P1/O TG1_FS/ OTG1_H S/SAI4/S DMMC2/ TIM8	DFSDM1 /ETH/I2C 4/LCD/M DIOS/O CTOSPI M_P1/S DMMC2/ SWPMI1 /TIM1x/T IM8/UAR T7/9/US ART10	FMC/LC D/MDIO S/OCTO SPIM_P 1/SDMM C1/TIM1 x/TIM8	COMP/D CMI/PSS I/LCD/TI M1x/TIM 23	LCD/TIM 24/UAR T5	SYS
	PB10	-	TIM2_C H3	-	LPTIM2_ IN1	I2C2_SC L	SPI2_SC K/I2S2_ CK	DFSDM1 _DATIN7	USART3 _TX	-	OCTOS PIM_P1_ NCS	OTG_HS _ULPI_D 3	ETH_MII _RX_ER	-	-	LCD_G4	EVENTO UT
	PB11	-	TIM2_C H4	-	LPTIM2_ ETR	I2C2_SD A	-	DFSDM1 _CKIN7	USART3 _RX	-	-	OTG_HS _ULPI_D 4	ETH_MII _TX_EN/ ETH_RM II_TX_E N	-	-	LCD_G5	EVENTO UT
Port B	PB12	-	TIM1_B KIN	-	OCTOS PIM_P1_ NCLK	I2C2_S MBA	SPI2_NS S/I2S2_ WS	DFSDM1 _DATIN1	USART3 _CK	-	FDCAN2 _RX	OTG_HS _ULPI_D 5	ETH_MII _TXD0/E TH_RMII _TXD0	OCTOS PIM_P1_ IO0	TIM1_B KIN_CO MP12	UART5_ RX	EVENTO UT
	PB13	-	TIM1_C H1N	-	LPTIM2_ OUT	OCTOS PIM_P1_ IO2	SPI2_SC K/I2S2_ CK	DFSDM1 _CKIN1	USART3 _CTS/U SART3_ NSS	-	FDCAN2 _TX	OTG_HS _ULPI_D 6	ETH_MII _TXD1/E TH_RMII _TXD1	SDMMC 1_D0	DCMI_D 2/PSSI_ D2	UART5_ TX	EVENTO UT
	PB14	-	TIM1_C H2N	TIM12_C H1	TIM8_C H2N	USART1 _TX	SPI2_MI SO/I2S2 _SDI	DFSDM1 _DATIN2	USART3 _RTS/U SART3_ DE	UART4_ RTS/UA RT4_DE	SDMMC 2_D0	-	-	FMC_D1 0/FMC_ AD10	-	LCD_CL K	EVENTO UT
	PB15	RTC_REFIN	TIM1_C H3N	TIM12_C H2	TIM8_C H3N	USART1 _RX	SPI2_M OSI/I2S2 _SDO	DFSDM1 _CKIN2	-	UART4_ CTS	SDMMC 2_D1	-	-	FMC_D1 1/FMC_ AD11	-	LCD_G7	EVENTO UT



Table 9. STM32H725 pin alternate functions (continued)

		AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7	AF8	AF9	AF10	AF11	AF12	AF13	AF14	AF15
Po	ort	sys	FMC/LP TIM1/SA I4/TIM16 /17/TIM1 x/TIM2x	FDCAN3 /PDM_S AI1/TIM3 /4/5/12/1 5	DFSDM1 /LCD/LP TIM2/3/4 /5/LPUA RT1/OC TOSPIM _P1/2/TI M8	CEC/DC MI/PSSI/ DFSDM1 /I2C1/2/3 /4/5/LPTI M2/OCT OSPIM P1/TIM1 5/USAR T1/10	CEC/FD CAN3/S P11/12S1/ SP12/12S 2/SP13/12 S3/SP14/ 5/6	DFSDM1 //2C4/5/ OCTOS PIM_P1/ SAI1/SPI 3//2S3/U ART4	SDMMC 1/SPI2/I2 S2/SPI3/ I2S3/SPI 6/UART 7/USAR T1/2/3/6	LPUART 1/SAI4/S DMMC1/ SPDIFR X1/SPI6/ UART4/ 5/8	FDCAN1 /2/FMC/ LCD/OC TOSPIM _P1/2/S AI4/SDM MC2/SP DIFRX1/ TIM13/1 4	CRS/FM C/LCD/O CTOSPI M_P1/O TG1_FS/ OTG1_H S/SAI4/S DMMC2/ TIM8	DFSDM1 /ETH/I2C 4/LCD/M DIOS/O CTOSPI M_P1/S DMMC2/ SWPMI1 /TIM1x/T IM8/UAR T7/9/US ART10	FMC/LC D/MDIO S/OCTO SPIM_P 1/SDMM C1/TIM1 x/TIM8	COMP/D CMI/PSS I/LCD/TI M1x/TIM 23	LCD/TIM 24/UAR T5	sys
	PC0	-	FMC_D1 2/FMC_ AD12	-	DFSDM1 _CKIN0	-	-	DFSDM1 _DATIN4	-	SAI4_FS _B	FMC_A2 5	OTG_HS _ULPI_S _TP	LCD_G2	FMC_SD NWE	-	LCD_R5	EVENTO UT
	PC1	TRACED0	SAI4_D1	SAI1_D1	DFSDM1 _DATIN0	DFSDM1 _CKIN4	SPI2_M OSI/I2S2 _SDO	SAI1_SD _A	-	SAI4_SD _A	SDMMC 2_CK	OCTOS PIM_P1_ IO4	ETH_MD C	MDIOS_ MDC	-	LCD_G5	EVENTO UT
	PC2	PWR_DEEPS LEEP	-	-	DFSDM1 _CKIN1	OCTOS PIM_P1_ IO5	SPI2_MI SO/I2S2 _SDI	DFSDM1 _CKOUT	-	-	OCTOS PIM_P1_ IO2	OTG_HS _ULPI_D IR	ETH_MII _TXD2	FMC_SD NE0	-	-	EVENTO UT
	PC3	PWR_SLEEP	-	-	DFSDM1 _DATIN1	OCTOS PIM_P1_ IO6	SPI2_M OSI/I2S2 _SDO	-	-	-	OCTOS PIM_P1_ IO0	OTG_HS _ULPI_N XT	ETH_MII _TX_CL K	FMC_SD CKE0	-	-	EVENTO UT
Port C	PC4	PWR_DEEPS LEEP	FMC_A2 2	-	DFSDM1 _CKIN2	-	I2S1_M CK	-	-	-	SPDIFR X1_IN3	SDMMC 2_CKIN	ETH_MII _RXD0/ ETH_RM II_RXD0	FMC_SD NE0	-	LCD_R7	EVENTO UT
	PC5	PWR_SLEEP	SAI4_D3	SAI1_D3	DFSDM1 _DATIN2	PSSI_D1 5	-	-	-	-	SPDIFR X1_IN4	OCTOS PIM_P1_ DQS	ETH_MII _RXD1/ ETH_RM II_RXD1	FMC_SD CKE0	COMP1_ OUT	LCD_DE	EVENTO UT
	PC6	-	-	TIM3_C H1	TIM8_C H1	DFSDM1 _CKIN3	12S2_M CK	-	USART6 _TX	SDMMC 1_D0DIR	FMC_N WAIT	SDMMC 2_D6	-	SDMMC 1_D6	DCMI_D 0/PSSI_ D0	LCD_HS YNC	EVENTO UT
	PC7	DBTRGIO	-	TIM3_C H2	TIM8_C H2	DFSDM1 _DATIN3	-	I2S3_M CK	USART6 _RX	SDMMC 1_D123 DIR	FMC_NE	SDMMC 2_D7	SWPMI_ TX	SDMMC 1_D7	DCMI_D 1/PSSI_ D1	LCD_G6	EVENTO UT
	PC8	TRACED1	-	TIM3_C H3	TIM8_C H3	-	-	-	USART6 _CK	UART5_ RTS/UA RT5_DE	FMC_NE 2/FMC_ NCE	FMC_IN T	SWPMI_ RX	SDMMC 1_D0	DCMI_D 2/PSSI_ D2	-	EVENTO UT

		AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7	AF8	AF9	AF10	AF11	AF12	AF13	AF14	AF15
P	ort	sys	FMC/LP TIM1/SA I4/TIM16 /17/TIM1 x/TIM2x	FDCAN3 /PDM_S AI1/TIM3 /4/5/12/1 5	DFSDM1 /LCD/LP TIM2/3/4 /5/LPUA RT1/OC TOSPIM _P1/2/TI M8	CEC/DC MI/PSSI/ DFSDM1 /I2C1/2/3 /4/5/LPTI M2/OCT OSPIM_ P1/TIM1 5/USAR T1/10	CEC/FD CAN3/S P11/12S1/ SP12/12S 2/SP13/12 S3/SP14/ 5/6	DFSDM1 //2C4/5/ OCTOS PIM_P1/ SAI1/SPI 3//2S3/U ART4	SDMMC 1/SPI2/I2 S2/SPI3/ I2S3/SPI 6/UART 7/USAR T1/2/3/6	LPUART 1/SAI4/S DMMC1/ SPDIFR X1/SPI6/ UART4/ 5/8	FDCAN1 /2/FMC/ LCD/OC TOSPIM _P1/2/S AI4/SDM MC2/SP DIFRX1/ TIM13/1 4	CRS/FM C/LCD/O CTOSPI M_P1/O TG1_FS/ OTG1_H S/SAI4/S DMMC2/ TIM8	DFSDM1 /ETH/I2C 4/LCD/M DIOS/O CTOSPI M_P1/S DMMC2/ SWPMI1 /TIM1x/T IM8/UAR T7/9/US ART10	FMC/LC D/MDIO S/OCTO SPIM_P 1/SDMM C1/TIM1 x/TIM8	COMP/D CMI/PSS I/LCD/TI M1x/TIM 23	LCD/TIM 24/UAR T5	sys
	PC9	MCO2	-	TIM3_C H4	TIM8_C H4	I2C3_SD A	I2S_CKI N	I2C5_SD A	-	UART5_ CTS	OCTOS PIM_P1_ IO0	LCD_G3	SWPMI_ SUSPEN D	SDMMC 1_D1	DCMI_D 3/PSSI_ D3	LCD_B2	EVENTO UT
	PC10	-	-	-	DFSDM1 _CKIN5	I2C5_SD A	-	SPI3_SC K/I2S3_ CK	USART3 _TX	UART4_ TX	OCTOS PIM_P1_ IO1	LCD_B1	SWPMI_ RX	SDMMC 1_D2	DCMI_D 8/PSSI_ D8	LCD_R2	EVENTO UT
	PC11	-	-	-	DFSDM1 _DATIN5	I2C5_SC L	-	SPI3_MI SO/I2S3 _SDI	USART3 _RX	UART4_ RX	OCTOS PIM_P1_ NCS	-	-	SDMMC 1_D3	DCMI_D 4/PSSI_ D4	LCD_B4	EVENTO UT
Port C	PC12	TRACED3	FMC_D6 /FMC_A D6	TIM15_C H1	-	I2C5_S MBA	SPI6_SC K/I2S6_ CK	SPI3_M OSI/I2S3 _SDO	USART3 _CK	UART5_ TX	-	-	-	SDMMC 1_CK	DCMI_D 9/PSSI_ D9	LCD_R6	EVENTO UT
	PC13	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	EVENTO UT
	PC14	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	EVENTO UT
	PC15	-	-	-	=	-	-	=	-	-	-	-	-	-	-	-	EVENTO UT

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		AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7	AF8	AF9	AF10	AF11	AF12	AF13	AF14	AF15
P¢	ort	sys	FMC/LP TIM1/SA I4/TIM16 /17/TIM1 x/TIM2x	FDCAN3 /PDM_S AI1/TIM3 /4/5/12/1 5	DFSDM1 /LCD/LP TIM2/3/4 /5/LPUA RT1/OC TOSPIM _P1/2/TI M8	CEC/DC MI/PSSI/ DFSDM1 /I2C1/2/3 /4/5/LPTI M2/OCT OSPIM_ P1/TIM1 5/USAR T1/10	CEC/FD CAN3/S P11/12S1/ SP12/12S 2/SP13/12 S3/SP14/ 5/6	DFSDM1 /I2C4/5/ OCTOS PIM_P1/ SAI1/SPI 3/I2S3/U ART4	SDMMC 1/SPI2/I2 S2/SPI3/ I2S3/SPI 6/UART 7/USAR T1/2/3/6	LPUART 1/SAI4/S DMMC1/ SPDIFR X1/SPI6/ UART4/ 5/8	FDCAN1 /2/FMC/ LCD/OC TOSPIM _P1/2/S AI4/SDM MC2/SP DIFRX1/ TIM13/1 4	CRS/FM C/LCD/O CTOSPI M_P1/O TG1_FS/ OTG1_H S/SAI4/S DMMC2/ TIM8	DFSDM1 /ETH/I2C 4/LCD/M DIOS/O CTOSPI M_P1/S DMMC2/ SWPMI1 /TIM1x/T IM8/UAR T7/9/US ART10	FMC/LC D/MDIO S/OCTO SPIM_P 1/SDMM C1/TIM1 x/TIM8	COMP/D CMI/PSS I/LCD/TI M1x/TIM 23	LCD/TIM 24/UAR T5	sys
	PD0	-	-	-	DFSDM1 _CKIN6	-	-	-	1	UART4_ RX	FDCAN1 _RX	-	UART9_ CTS	FMC_D2 /FMC_A D2	-	LCD_B1	EVENTO UT
	PD1	-	-	-	DFSDM1 _DATIN6	-	-	-	-	UART4_ TX	FDCAN1 _TX	-	-	FMC_D3 /FMC_A D3	-	-	EVENTO UT
	PD2	TRACED2	FMC_D7 /FMC_A D7	TIM3_ET R	-	TIM15_B KIN	-	-	ı	UART5_ RX	LCD_B7	-	-	SDMMC 1_CMD	DCMI_D 11/PSSI_ D11	LCD_B2	EVENTO UT
	PD3	-	-	-	DFSDM1 _CKOUT	-	SPI2_SC K/I2S2_ CK	-	USART2 _CTS/U SART2_ NSS	-	-	-	-	FMC_CL K	DCMI_D 5/PSSI_ D5	LCD_G7	EVENTO UT
Port D	PD4	-	-	-	-	-	-	-	USART2 _RTS/U SART2_ DE	-	-	OCTOS PIM_P1_ IO4	-	FMC_N OE	-	-	EVENTO UT
	PD5	-	-	-	-	-	-	-	USART2 _TX	-	-	OCTOS PIM_P1_ IO5	-	FMC_N WE	-	-	EVENTO UT
	PD6	-	SAI4_D1	SAI1_D1	DFSDM1 _CKIN4	DFSDM1 _DATIN1	SPI3_M OSI/I2S3 _SDO	SAI1_SD _A	USART2 _RX	SAI4_SD _A	-	OCTOS PIM_P1_ IO6	SDMMC 2_CK	FMC_N WAIT	DCMI_D 10/PSSI _D10	LCD_B2	EVENTO UT
	PD7	-	-	-	DFSDM1 _DATIN4	-	SPI1_M OSI/I2S1 _SDO	DFSDM1 _CKIN1	USART2 _CK	-	SPDIFR X1_IN1	OCTOS PIM_P1_ IO7	SDMMC 2_CMD	FMC_NE 1	-	-	EVENTO UT
	PD8	-	-	-	DFSDM1 _CKIN3	-	-	-	USART3 _TX	-	SPDIFR X1_IN2	-	-	FMC_D1 3/FMC_ AD13	-	-	EVENTO UT

		AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7	AF8	AF9	AF10	AF11	AF12	AF13	AF14	AF15
Pc	ort	sys	FMC/LP TIM1/SA I4/TIM16 /17/TIM1 x/TIM2x	FDCAN3 /PDM_S AI1/TIM3 /4/5/12/1 5	DFSDM1 /LCD/LP TIM2/3/4 /5/LPUA RT1/OC TOSPIM _P1/2/TI M8	CEC/DC MI/PSSI/ DFSDM1 /I2C1/2/3 /4/5/LPTI M2/OCT OSPIM_ P1/TIM1 5/USAR T1/10	CEC/FD CAN3/S P11/12S1/ SP12/12S 2/SP13/12 S3/SP14/ 5/6	DFSDM1 /I2C4/5/ OCTOS PIM_P1/ SAI1/SPI 3/I2S3/U ART4	SDMMC 1/SPI2/I2 S2/SPI3/ I2S3/SPI 6/UART 7/USAR T1/2/3/6	LPUART 1/SAI4/S DMMC1/ SPDIFR X1/SPI6/ UART4/ 5/8	FDCAN1 /2/FMC/ LCD/OC TOSPIM _P1/2/S AI4/SDM MC2/SP DIFRX1/ TIM13/1 4	CRS/FM C/LCD/O CTOSPI M_P1/O TG1_FS/ OTG1_H S/SAI4/S DMMC2/ TIM8	DFSDM1 /ETH/I2C 4/LCD/M DIOS/O CTOSPI M_P1/S DMMC2/ SWPMI1 /TIM1x/T IM8/UAR T7/9/US ART10	FMC/LC D/MDIO S/OCTO SPIM_P 1/SDMM C1/TIM1 x/TIM8	COMP/D CMI/PSS I/LCD/TI M1x/TIM 23	LCD/TIM 24/UAR T5	SYS
	PD9	-	-	-	DFSDM1 _DATIN3	-	-	-	USART3 _RX	ı	-	-	-	FMC_D1 4/FMC_ AD14	-	ı	EVENTO UT
	PD10	ı	-	-	DFSDM1 _CKOUT	-	-	-	USART3 _CK	ı	-	-	-	FMC_D1 5/FMC_ AD15	-	LCD_B3	EVENTO UT
	PD11	-	-	-	LPTIM2_ IN2	I2C4_S MBA	-	-	USART3 _CTS/U SART3_ NSS	-	OCTOS PIM_P1_ IO0	SAI4_SD _A	-	FMC_A1 6/FMC_ CLE	-	-	EVENTO UT
Port D	PD12	-	LPTIM1_ IN1	TIM4_C H1	LPTIM2_ IN1	12C4_SC L	FDCAN3 _RX	-	USART3 _RTS/U SART3_ DE	-	OCTOS PIM_P1_ IO1	SAI4_FS _A	-	FMC_A1 7/FMC_ ALE	DCMI_D 12/PSSI _D12	-	EVENTO UT
	PD13	-	LPTIM1_ OUT	TIM4_C H2	-	I2C4_SD A	FDCAN3 _TX	-	-	-	OCTOS PIM_P1_ IO3	SAI4_SC K_A	UART9_ RTS/UA RT9_DE	FMC_A1	DCMI_D 13/PSSI _D13	-	EVENTO UT
	PD14	-	-	TIM4_C H3	-	-	-	-	-	UART8_ CTS	-	-	UART9_ RX	FMC_D0 /FMC_A D0	-	1	EVENTO UT
	PD15	-	-	TIM4_C H4	-	-	-	-	-	UART8_ RTS/UA RT8_DE	-	-	UART9_ TX	FMC_D1 /FMC_A D1	-	-	EVENTO UT

Table 9. STM32H725 pin alternate functions (continued)

		AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7	AF8	AF9	AF10	AF11	AF12	AF13	AF14	AF15
Po	ort	sys	FMC/LP TIM1/SA I4/TIM16 /17/TIM1 x/TIM2x	FDCAN3 /PDM_S AI1/TIM3 /4/5/12/1 5	DFSDM1 /LCD/LP TIM2/3/4 /5/LPUA RT1/OC TOSPIM _P1/2/TI M8	CEC/DC MI/PSSI/ DFSDM1 /I2C1/2/3 /4/5/LPTI M2/OCT OSPIM_ P1/TIM1 5/USAR T1/10	CEC/FD CAN3/S P11/12S1/ SP12/12S 2/SP13/12 S3/SP14/ 5/6	DFSDM1 /I2C4/5/ OCTOS PIM_P1/ SAI1/SPI 3/I2S3/U ART4	SDMMC 1/SPI2/I2 S2/SPI3/ I2S3/SPI 6/UART 7/USAR T1/2/3/6	LPUART 1/SAI4/S DMMC1/ SPDIFR X1/SPI6/ UART4/ 5/8	FDCAN1 /2/FMC/ LCD/OC TOSPIM _P1/2/S AI4/SDM MC2/SP DIFRX1/ TIM13/1 4	CRS/FM C/LCD/O CTOSPI M_P1/O TG1_FS/ OTG1_H S/SAI4/S DMMC2/ TIM8	DFSDM1 /ETH/I2C 4/LCD/M DIOS/O CTOSPI M_P1/S DMMC2/ SWPMI1 /TIM1x/T IM8/UAR T7/9/US ART10	FMC/LC D/MDIO S/OCTO SPIM_P 1/SDMM C1/TIM1 x/TIM8	COMP/D CMI/PSS I/LCD/TI M1x/TIM 23	LCD/TIM 24/UAR T5	sys
	PE0	-	LPTIM1_ ETR	TIM4_ET R	-	LPTIM2_ ETR	-	-	-	UART8_ RX	-	SAI4_M CLK_A	-	FMC_NB L0	DCMI_D 2/PSSI_ D2	LCD_R0	EVENTO UT
	PE1	-	LPTIM1_ IN2	-	-	-	-	-	-	UART8_ TX	-	-	-	FMC_NB L1	DCMI_D 3/PSSI_ D3	LCD_R6	EVENTO UT
	PE2	TRACECLK	-	SAI1_CK 1	-	USART1 0_RX	SPI4_SC K	SAI1_M CLK_A	-	SAI4_M CLK_A	OCTOS PIM_P1_ IO2	SAI4_CK 1	ETH_MII _TXD3	FMC_A2	-	-	EVENTO UT
	PE3	TRACED0	-	-	-	TIM15_B KIN	-	SAI1_SD _B	-	SAI4_SD _B	-	-	USART1 0_TX	FMC_A1	-	-	EVENTO UT
	PE4	TRACED1	-	SAI1_D2	DFSDM1 _DATIN3	TIM15_C H1N	SPI4_NS S	SAI1_FS _A	-	SAI4_FS _A	-	SAI4_D2	-	FMC_A2	DCMI_D 4/PSSI_ D4	LCD_B0	EVENTO UT
Port E	PE5	TRACED2	-	SAI1_CK 2	DFSDM1 _CKIN3	TIM15_C H1	SPI4_MI SO	SAI1_SC K_A	1	SAI4_SC K_A	-	SAI4_CK 2	ı	FMC_A2 1	DCMI_D 6/PSSI_ D6	LCD_G0	EVENTO UT
	PE6	TRACED3	TIM1_B KIN2	SAI1_D1	ı	TIM15_C H2	SPI4_M OSI	SAI1_SD _A	ı	SAI4_SD _A	SAI4_D1	SAI4_M CLK_B	TIM1_B KIN2_C OMP12	FMC_A2 2	DCMI_D 7/PSSI_ D7	LCD_G1	EVENTO UT
	PE7	1	TIM1_ET R	-	DFSDM1 _DATIN2	-	-	-	UART7_ RX	-	-	OCTOS PIM_P1_ IO4	1	FMC_D4 /FMC_A D4	ı	ı	EVENTO UT
	PE8	-	TIM1_C H1N	-	DFSDM1 _CKIN2	-	-	-	UART7_ TX	-	-	OCTOS PIM_P1_ IO5	-	FMC_D5 /FMC_A D5	COMP2_ OUT	-	EVENTO UT
	PE9	-	TIM1_C H1	-	DFSDM1 _CKOUT	-	-	-	UART7_ RTS/UA RT7_DE	-	-	OCTOS PIM_P1_ IO6	-	FMC_D6 /FMC_A D6	-	-	EVENTO UT

		AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7	AF8	AF9	AF10	AF11	AF12	AF13	AF14	AF15
Port		sys	FMC/LP TIM1/SA I4/TIM16 /17/TIM1 x/TIM2x	FDCAN3 /PDM_S AI1/TIM3 /4/5/12/1 5	DFSDM1 /LCD/LP TIM2/3/4 /5/LPUA RT1/OC TOSPIM _P1/2/TI M8	CEC/DC MI/PSSI/ DFSDM1 /I2C1/2/3 /4/5/LPTI M2/OCT OSPIM P1/TIM1 5/USAR T1/10	CEC/FD CAN3/S P11/12S1/ SP12/12S 2/SP13/12 S3/SP14/ 5/6	DFSDM1 /I2C4/5/ OCTOS PIM_P1/ SAI1/SPI 3/I2S3/U ART4	SDMMC 1/SPI2/I2 S2/SPI3/ I2S3/SPI 6/UART 7/USAR T1/2/3/6	LPUART 1/SAI4/S DMMC1/ SPDIFR X1/SPI6/ UART4/ 5/8	FDCAN1 /2/FMC/ LCD/OC TOSPIM _P1/2/S AI4/SDM MC2/SP DIFRX1/ TIM13/1 4	CRS/FM C/LCD/O CTOSPI M_P1/O TG1_FS/ OTG1_H S/SAI4/S DMMC2/ TIM8	DFSDM1 /ETH/I2C 4/LCD/M DIOS/O CTOSPI M_P1/S DMMC2/ SWPMI1 /TIM1x/T IM8/UAR T7/9/US ART10	FMC/LC D/MDIO S/OCTO SPIM_P 1/SDMM C1/TIM1 x/TIM8	COMP/D CMI/PSS I/LCD/TI M1x/TIM 23	LCD/TIM 24/UAR T5	SYS
	PE10	-	TIM1_C H2N	-	DFSDM1 _DATIN4	-	-	-	UART7_ CTS	-	-	OCTOS PIM_P1_ IO7	-	FMC_D7 /FMC_A D7	-	-	EVENTO UT
	PE11	-	TIM1_C H2	-	DFSDM1 _CKIN4	-	SPI4_NS S	-	-	-	-	SAI4_SD _B	OCTOS PIM_P1_ NCS	FMC_D8 /FMC_A D8	-	LCD_G3	EVENTO UT
Dort C	PE12	-	TIM1_C H3N	-	DFSDM1 _DATIN5	-	SPI4_SC K	-	-	-	-	SAI4_SC K_B	-	FMC_D9 /FMC_A D9	COMP1_ OUT	LCD_B4	EVENTO UT
Port E	PE13	-	TIM1_C H3	-	DFSDM1 _CKIN5	-	SPI4_MI SO	-	-	-	-	SAI4_FS _B	-	FMC_D1 0/FMC_ AD10	COMP2_ OUT	LCD_DE	EVENTO UT
	PE14	-	TIM1_C H4	-		-	SPI4_M OSI	-	-	-	-	SAI4_M CLK_B	-	FMC_D1 1/FMC_ AD11	-	LCD_CL K	EVENTO UT
	PE15	-	TIM1_B KIN	-	-	-	-	-	-	-	-	-	USART1 0_CK	FMC_D1 2/FMC_ AD12	TIM1_B KIN_CO MP12	LCD_R7	EVENTO UT



Table 9. STM32H725 pin alternate functions (continued)

		AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7	AF8	AF9	AF10	AF11	AF12	AF13	AF14	AF15
Port		sys	FMC/LP TIM1/SA I4/TIM16 /17/TIM1 x/TIM2x	FDCAN3 /PDM_S AI1/TIM3 /4/5/12/1 5	DFSDM1 /LCD/LP TIM2/3/4 /5/LPUA RT1/OC TOSPIM _P1/2/TI M8	CEC/DC MI/PSSI/ DFSDM1 /I2C1/2/3 /4/5/LPTI M2/OCT OSPIM_ P1/TIM1 5/USAR T1/10	CEC/FD CAN3/S P11/12S1/ SP12/12S 2/SP13/12 S3/SP14/ 5/6	DFSDM1 /I2C4/5/ OCTOS PIM_P1/ SAI1/SPI 3/I2S3/U ART4	SDMMC 1/SPI2/I2 S2/SPI3/ I2S3/SPI 6/UART 7/USAR T1/2/3/6	LPUART 1/SAI4/S DMMC1/ SPDIFR X1/SPI6/ UART4/ 5/8	FDCAN1 /2/FMC/ LCD/OC TOSPIM _P1/2/S A14/SDM MC2/SP DIFRX1/ TIM13/1 4	CRS/FM C/LCD/O CTOSPI M_P1/O TG1_FS/ OTG1_H S/SAI4/S DMMC2/ TIM8	DFSDM1 /ETH/I2C 4/LCD/M DIOS/O CTOSPI M_P1/S DMMC2/ SWPMI1 /TIM1x/T IM8/UAR T7/9/US ART10	FMC/LC D/MDIO S/OCTO SPIM_P 1/SDMM C1/TIM1 x/TIM8	COMP/D CMI/PSS I/LCD/TI M1x/TIM 23	LCD/TIM 24/UAR T5	SYS
	PF0	-	-	-	1	I2C2_SD A	1	I2C5_SD A	1	1	OCTOS PIM_P2_ IO0	1	1	FMC_A0	TIM23_C H1	1	EVENTO UT
	PF1	-	-	-	-	I2C2_SC L	-	I2C5_SC L	-	-	OCTOS PIM_P2_ IO1	-	-	FMC_A1	TIM23_C H2	-	EVENTO UT
	PF2	-	-	-	-	I2C2_S MBA	-	I2C5_S MBA	-	-	OCTOS PIM_P2_ IO2	-	-	FMC_A2	TIM23_C H3	-	EVENTO UT
	PF3	-	-	-	-	-	-	-	-	-	OCTOS PIM_P2_ IO3	-	-	FMC_A3	TIM23_C H4	-	EVENTO UT
Do # E	PF4	-	-	-	-	-	-	-	-	-	OCTOS PIM_P2_ CLK	-	-	FMC_A4	-	-	EVENTO UT
Port F	PF5	-	-	-	-	-	-	-	-	-	OCTOS PIM_P2_ NCLK	-	-	FMC_A5	-	-	EVENTO UT
	PF6	-	TIM16_C H1	FDCAN3 _RX	-	-	SPI5_NS S	SAI1_SD _B	UART7_ RX	SAI4_SD _B	-	OCTOS PIM_P1_ IO3	-	-	TIM23_C H1	-	EVENTO UT
	PF7	-	TIM17_C H1	FDCAN3 _TX	-	-	SPI5_SC K	SAI1_M CLK_B	UART7_ TX	SAI4_M CLK_B	-	OCTOS PIM_P1_ IO2	-	-	TIM23_C H2	-	EVENTO UT
	PF8	-	TIM16_C H1N	-	-	-	SPI5_MI SO	SAI1_SC K_B	UART7_ RTS/UA RT7_DE	SAI4_SC K_B	TIM13_C H1	OCTOS PIM_P1_ IO0	-	-	TIM23_C H3	-	EVENTO UT
	PF9	-	TIM17_C H1N	-	-	-	SPI5_M OSI	SAI1_FS _B	UART7_ CTS	SAI4_FS _B	TIM14_C H1	OCTOS PIM_P1_ IO1	-	-	TIM23_C H4	-	EVENTO UT

Table 9. STM32H725 pin alternate functions (continued)

		AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7	AF8	AF9	AF10	AF11	AF12	AF13	AF14	AF15
Port		sys	FMC/LP TIM1/SA I4/TIM16 /17/TIM1 x/TIM2x	FDCAN3 /PDM_S AI1/TIM3 /4/5/12/1 5	DFSDM1 /LCD/LP TIM2/3/4 /5/LPUA RT1/OC TOSPIM _P1/2/TI M8	CEC/DC MI/PSSI/ DFSDM1 /I2C1/2/3 /4/5/LPTI M2/OCT OSPIM_ P1/TIM1 5/USAR T1/10	CEC/FD CAN3/S P11/12S1/ SP12/12S 2/SP13/12 S3/SP14/ 5/6	DFSDM1 /I2C4/5/ OCTOS PIM_P1/ SAI1/SPI 3/I2S3/U ART4	SDMMC 1/SPI2/I2 S2/SPI3/ I2S3/SPI 6/UART 7/USAR T1/2/3/6	LPUART 1/SAI4/S DMMC1/ SPDIFR X1/SPI6/ UART4/ 5/8	FDCAN1 /2/FMC/ LCD/OC TOSPIM _P1/2/S AI4/SDM MC2/SP DIFRX1/ TIM13/1 4	CRS/FM C/LCD/O CTOSPI M_P1/O TG1_FS/ OTG1_H S/SAI4/S DMMC2/ TIM8	DFSDM1 /ETH/I2C 4/LCD/M DIOS/O CTOSPI M_P1/S DMMC2/ SWPMI1 /TIM1x/T IM8/UAR T7/9/US ART10	FMC/LC D/MDIO S/OCTO SPIM_P 1/SDMM C1/TIM1 x/TIM8	COMP/D CMI/PSS I/LCD/TI M1x/TIM 23	LCD/TIM 24/UAR T5	SYS
	PF10	-	TIM16_B KIN	SAI1_D3	-	PSSI_D1 5	-	-	-	-	OCTOS PIM_P1_ CLK	SAI4_D3	-	-	DCMI_D 11/PSSI_ D11	LCD_DE	EVENTO UT
	PF11	-	-	-	-	-	SPI5_M OSI	-	-	-	OCTOS PIM_P1_ NCLK	SAI4_SD _B	-	FMC_N RAS	DCMI_D 12/PSSI _D12	TIM24_C H1	EVENTO UT
Port F	PF12	-	-	-	-	-	-	-	-	-	OCTOS PIM_P2_ DQS	-	-	FMC_A6	-	TIM24_C H2	EVENTO UT
	PF13	-	-	-	DFSDM1 _DATIN6	I2C4_S MBA	-	-	-	-	-	-	-	FMC_A7	-	TIM24_C H3	EVENTO UT
	PF14	-	-	-	DFSDM1 _CKIN6	I2C4_SC L	-	-	-	-	-	-	-	FMC_A8	-	TIM24_C H4	EVENTO UT
	PF15	-	-	-	-	I2C4_SD A	-	-	-	-	-	-	-	FMC_A9	-	-	EVENTO UT



Table 9. STM32H725 pin alternate functions (continued)

		AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7	AF8	AF9	AF10	AF11	AF12	AF13	AF14	AF15
Po	ort	sys	FMC/LP TIM1/SA I4/TIM16 /17/TIM1 x/TIM2x	FDCAN3 /PDM_S AI1/TIM3 /4/5/12/1 5	DFSDM1 /LCD/LP TIM2/3/4 /5/LPUA RT1/OC TOSPIM _P1/2/TI M8	CEC/DC MI/PSSI/ DFSDM1 /I2C1/2/3 /4/5/LPTI M2/OCT OSPIM P1/TIM1 5/USAR T1/10	CEC/FD CAN3/S P11/12S1/ SP12/12S 2/SP13/12 S3/SP14/ 5/6	DFSDM1 //2C4/5/ OCTOS PIM_P1/ SAI1/SPI 3//2S3/U ART4	SDMMC 1/SPI2/I2 S2/SPI3/ I2S3/SPI 6/UART 7/USAR T1/2/3/6	LPUART 1/SAI4/S DMMC1/ SPDIFR X1/SPI6/ UART4/ 5/8	FDCAN1 /2/FMC/ LCD/OC TOSPIM _P1/2/S AI4/SDM MC2/SP DIFRX1/ TIM13/1 4	CRS/FM C/LCD/O CTOSPI M_P1/O TG1_FS/ OTG1_H S/SAI4/S DMMC2/ TIM8	DFSDM1 /ETH/I2C 4/LCD/M DIOS/O CTOSPI M_P1/S DMMC2/ SWPMI1 /TIM1x/T IM8/UAR T7/9/US ART10	FMC/LC D/MDIO S/OCTO SPIM_P 1/SDMM C1/TIM1 x/TIM8	COMP/D CMI/PSS I/LCD/TI M1x/TIM 23	LCD/TIM 24/UAR T5	SYS
	PG0	-	-	-	-	-	-	-	-	-	OCTOS PIM_P2_ IO4	-	UART9_ RX	FMC_A1	-	-	EVENTO UT
	PG1	-	-	-	-	-	-	-	-	-	OCTOS PIM_P2_ IO5	-	UART9_ TX	FMC_A1	-	=	EVENTO UT
	PG2	-	-	-	TIM8_B KIN	-	-	-	-	-	-	-	TIM8_B KIN_CO MP12	FMC_A1	-	TIM24_E TR	EVENTO UT
	PG3	-	-	-	TIM8_B KIN2	-	-	-	-	-	-	-	TIM8_B KIN2_C OMP12	FMC_A1	TIM23_E TR	-	EVENTO UT
Port G	PG4	-	TIM1_B KIN2	-	-	-	-	-	-	-	-	-	TIM1_B KIN2_C OMP12	FMC_A1 4/FMC_ BA0	-	-	EVENTO UT
	PG5	-	TIM1_ET R	-	-	-	-	-	1	ı	-	-	ı	FMC_A1 5/FMC_ BA1	-	-	EVENTO UT
	PG6	-	TIM17_B KIN	-	1	ı	-	1	ı	ı	-	OCTOS PIM_P1_ NCS	ı	FMC_NE 3	DCMI_D 12/PSSI _D12	LCD_R7	EVENTO UT
	PG7	-	-	-	-	-	-	SAI1_M CLK_A	USART6 _CK	-	OCTOS PIM_P2_ DQS	-	-	FMC_IN T	DCMI_D 13/PSSI _D13	LCD_CL K	EVENTO UT
	PG8	-	-	-	TIM8_ET R	-	SPI6_NS S/I2S6_ WS	-	USART6 _RTS/U SART6_ DE	SPDIFR X1_IN3	-	-	ETH_PP S_OUT	FMC_SD CLK	-	LCD_G7	EVENTO UT

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Pinouts, pin descriptions and alternate functions

Table	9. STM	32H725	pin alte	ernate fu	unction	s (conti	nued)
AF3	AF4	AF5	AF6	AF7	AF8	AF9	AF10

		AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7	AF8	AF9	AF10	AF11	AF12	AF13	AF14	AF15
Pí	ort	sys	FMC/LP TIM1/SA I4/TIM16 /17/TIM1 x/TIM2x	FDCAN3 /PDM_S AI1/TIM3 /4/5/12/1 5	DFSDM1 /LCD/LP TIM2/3/4 /5/LPUA RT1/OC TOSPIM _P1/2/TI M8	CEC/DC MI/PSSI/ DFSDM1 /I2C1/2/3 /4/5/LPTI M2/OCT OSPIM_ P1/TIM1 5/USAR T1/10	CEC/FD CAN3/S P11/12S1/ SP12/12S 2/SP13/12 S3/SP14/ 5/6	DFSDM1 /I2C4/5/ OCTOS PIM_P1/ SAI1/SPI 3/I2S3/U ART4	SDMMC 1/SPI2/I2 S2/SPI3/ I2S3/SPI 6/UART 7/USAR T1/2/3/6	LPUART 1/SAI4/S DMMC1/ SPDIFR X1/SPI6/ UART4/ 5/8	FDCAN1 /2/FMC/ LCD/OC TOSPIM _P1/2/S AI4/SDM MC2/SP DIFRX1/ TIM13/1 4	CRS/FM C/LCD/O CTOSPI M_P1/O TG1_FS/ OTG1_H S/SAI4/S DMMC2/ TIM8	DFSDM1 /ETH/I2C 4/LCD/M DIOS/O CTOSPI M_P1/S DMMC2/ SWPMI1 /TIM1x/T IM8/UAR T7/9/US ART10	FMC/LC D/MDIO S/OCTO SPIM_P 1/SDMM C1/TIM1 x/TIM8	COMP/D CMI/PSS I/LCD/TI M1x/TIM 23	LCD/TIM 24/UAR T5	sys
	PG9	-	-	FDCAN3 _TX	-	-	SPI1_MI SO/I2S1 _SDI	-	USART6 _RX	SPDIFR X1_IN4	OCTOS PIM_P1_ IO6	SAI4_FS _B	SDMMC 2_D0	FMC_NE 2/FMC_ NCE	DCMI_V SYNC/P SSI_RD Y	-	EVENTO UT
	PG10	-	-	FDCAN3 _RX	OCTOS PIM_P2_ IO6	-	SPI1_NS S/I2S1_ WS	-	-	-	LCD_G3	SAI4_SD _B	SDMMC 2_D1	FMC_NE	DCMI_D 2/PSSI_ D2	LCD_B2	EVENTO UT
	PG11	-	LPTIM1_ IN2	-	-	USART1 0_RX	SPI1_SC K/I2S1_ CK	-	-	SPDIFR X1_IN1	OCTOS PIM_P2_ IO7	SDMMC 2_D2	ETH_MII _TX_EN/ ETH_RM II_TX_E N	-	DCMI_D 3/PSSI_ D3	LCD_B3	EVENTO UT
Port G	PG12	-	LPTIM1_ IN1	-	OCTOS PIM_P2_ NCS	USART1 0_TX	SPI6_MI SO/I2S6 _SDI	-	USART6 _RTS/U SART6_ DE	SPDIFR X1_IN2	LCD_B4	SDMMC 2_D3	ETH_MII _TXD1/E TH_RMII _TXD1	FMC_NE	TIM23_C H1	LCD_B1	EVENTO UT
	PG13	TRACED0	LPTIM1_ OUT	-	-	USART1 0_CTS/U SART10 _NSS	SPI6_SC K/I2S6_ CK	-	USART6 _CTS/U SART6_ NSS	-	-	SDMMC 2_D6	ETH_MII _TXD0/E TH_RMII _TXD0	FMC_A2	TIM23_C H2	LCD_R0	EVENTO UT
	PG14	TRACED1	LPTIM1_ ETR	-	-	USART1 0_RTS/U SART10 _DE	SPI6_M OSI/I2S6 _SDO	-	USART6 _TX	-	OCTOS PIM_P1_ IO7	SDMMC 2_D7	ETH_MII _TXD1/E TH_RMII _TXD1	FMC_A2 5	TIM23_C H3	LCD_B0	EVENTO UT
	PG15	-	-	-	-	-	-	-	USART6 _CTS/U SART6_ NSS	-	OCTOS PIM_P2_ DQS	-	USART1 0_CK	FMC_N CAS	DCMI_D 13/PSSI _D13	-	EVENTO UT

Table 9. STM32H725 pin alternate functions (continued)

		AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7	AF8	AF9	AF10	AF11	AF12	AF13	AF14	AF15
Pe	ort	sys	FMC/LP TIM1/SA I4/TIM16 /17/TIM1 x/TIM2x	FDCAN3 /PDM_S AI1/TIM3 /4/5/12/1 5	DFSDM1 /LCD/LP TIM2/3/4 /5/LPUA RT1/OC TOSPIM _P1/2/TI M8	CEC/DC MI/PSSI/ DFSDM1 /I2C1/2/3 /4/5/LPTI M2/OCT OSPIM_ P1/TIM1 5/USAR T1/10	CEC/FD CAN3/S P11/12S1/ SP12/12S 2/SP13/12 S3/SP14/ 5/6	DFSDM1 /I2C4/5/ OCTOS PIM_P1/ SAI1/SPI 3/I2S3/U ART4	SDMMC 1/SPI2/I2 S2/SPI3/ I2S3/SPI 6/UART 7/USAR T1/2/3/6	LPUART 1/SAI4/S DMMC1/ SPDIFR X1/SPI6/ UART4/ 5/8	FDCAN1 /2/FMC/ LCD/OC TOSPIM _P1/2/S AI4/SDM MC2/SP DIFRX1/ TIM13/1 4	CRS/FM C/LCD/O CTOSPI M_P1/O TG1_FS/ OTG1_H S/SAI4/S DMMC2/ TIM8	DFSDM1 /ETH/I2C 4/LCD/M DIOS/O CTOSPI M_P1/S DMMC2/ SWPMI1 /TIM1x/T IM8/UAR T7/9/US ART10	FMC/LC D/MDIO S/OCTO SPIM_P 1/SDMM C1/TIM1 x/TIM8	COMP/D CMI/PSS I/LCD/TI M1x/TIM 23	LCD/TIM 24/UAR T5	sys
	PH0	-	-	-	ı	-	ı	-	-	-	-	-	ı	-	-	ı	EVENTO UT
	PH1	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	EVENTO UT
	PH2	-	LPTIM1_ IN2	-	-	-	-	-	-	-	OCTOS PIM_P1_ IO4	SAI4_SC K_B	ETH_MII _CRS	FMC_SD CKE0	-	LCD_R0	EVENTO UT
	PH3	-	-	-	-	-	-	-	-	-	OCTOS PIM_P1_ IO5	SAI4_M CLK_B	ETH_MII _COL	FMC_SD NE0	-	LCD_R1	EVENTO UT
	PH4	-	-	-	-	I2C2_SC L	-	-	-	-	LCD_G5	OTG_HS _ULPI_N _XT	-	-	PSSI_D1 4	LCD_G4	EVENTO UT
Port H	PH5	-	-	-	-	I2C2_SD A	SPI5_NS S	-	-	-	-	-	-	FMC_SD NWE	-	-	EVENTO UT
	PH6	-	-	TIM12_C H1	-	I2C2_S MBA	SPI5_SC K	-	-	-	-	-	ETH_MII _RXD2	FMC_SD NE1	DCMI_D 8/PSSI_ D8	-	EVENTO UT
	PH7	-	-	-	-	I2C3_SC L	SPI5_MI SO	-	-	-	-	-	ETH_MII _RXD3	FMC_SD CKE1	DCMI_D 9/PSSI_ D9	-	EVENTO UT
	PH8	-	-	TIM5_ET R	1	I2C3_SD A	-	-	-	-	-	-	1	FMC_D1	DCMI_H SYNC/P SSI_DE	LCD_R2	EVENTO UT
	PH9	-	-	TIM12_C H2	-	I2C3_S MBA	-	-	-	-	-	-	-	FMC_D1	DCMI_D 0/PSSI_ D0	LCD_R3	EVENTO UT
	PH10	-	-	TIM5_C H1	-	I2C4_S MBA	-	-	-	-	-	-	-	FMC_D1 8	DCMI_D 1/PSSI_ D1	LCD_R4	EVENTO UT

Pinouts, pin descriptions and alternate functions

Table 9. STM32H725 pin alternate functions (continued))
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		AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7	AF8	AF9	AF10	AF11	AF12	AF13	AF14	AF15
Po	ort	sys	FMC/LP TIM1/SA I4/TIM16 /17/TIM1 x/TIM2x	FDCAN3 /PDM_S AI1/TIM3 /4/5/12/1 5	DFSDM1 /LCD/LP TIM2/3/4 /5/LPUA RT1/OC TOSPIM _P1/2/TI M8	CEC/DC MI/PSSI/ DFSDM1 /I2C1/2/3 /4/5/LPTI M2/OCT OSPIM_ P1/TIM1 5/USAR T1/10	CEC/FD CAN3/S P11/12S1/ SP12/12S 2/SP13/12 S3/SP14/ 5/6	DFSDM1 /I2C4/5/ OCTOS PIM_P1/ SAI1/SPI 3/I2S3/U ART4	SDMMC 1/SPI2/I2 S2/SPI3/ I2S3/SPI 6/UART 7/USAR T1/2/3/6	LPUART 1/SAI4/S DMMC1/ SPDIFR X1/SPI6/ UART4/ 5/8	FDCAN1 /2/FMC/ LCD/OC TOSPIM _P1/2/S AI4/SDM MC2/SP DIFRX1/ TIM13/1 4	CRS/FM C/LCD/O CTOSPI M_P1/O TG1_FS/ OTG1_H S/SAI4/S DMMC2/ TIM8	DFSDM1 /ETH/I2C 4/LCD/M DIOS/O CTOSPI M_P1/S DMMC2/ SWPMI1 /TIM1x/T IM8/UAR T7/9/US ART10	FMC/LC D/MDIO S/OCTO SPIM_P 1/SDMM C1/TIM1 x/TIM8	COMP/D CMI/PSS I/LCD/TI M1x/TIM 23	LCD/TIM 24/UAR T5	sys
	PH11	-	-	TIM5_C H2	-	I2C4_SC L	-	-	-	-	-	-	-	FMC_D1	DCMI_D 2/PSSI_ D2	LCD_R5	EVENTO UT
	PH12	-	-	TIM5_C H3	-	I2C4_SD A	-	-	-	-	-	-	-	FMC_D2	DCMI_D 3/PSSI_ D3	LCD_R6	EVENTO UT
Port H	PH13	-	-	-	TIM8_C H1N	-	-	-	-	UART4_ TX	FDCAN1 _TX	-	-	FMC_D2 1	-	LCD_G2	EVENTO UT
	PH14	-	-	-	TIM8_C H2N	-	-	-	-	UART4_ RX	FDCAN1 _RX	-	-	FMC_D2	DCMI_D 4/PSSI_ D4	LCD_G3	EVENTO UT
	PH15	-	-	-	TIM8_C H3N	-	-	-	-	-	-	-	-	FMC_D2	DCMI_D 11/PSSI_ D11	LCD_G4	EVENTO UT
	PJ8	-	TIM1_C H3N	-	TIM8_C H1	-	-	-	-	UART8_ TX	-	-	-	-	-	LCD_G1	EVENTO UT
Dort !	PJ9	-	TIM1_C H3	-	TIM8_C H1N	-	-	-	-	UART8_ RX	-	-	-	-	-	LCD_G2	EVENTO UT
Port J	PJ10	-	TIM1_C H2N	-	TIM8_C H2	-	SPI5_M OSI	-	-	-	-	-	-	-	-	LCD_G3	EVENTO UT
	PJ11	-	TIM1_C H2	-	TIM8_C H2N	-	SPI5_MI SO	-	-	-	-	-	-	-	-	LCD_G4	EVENTO UT



Table 9. STM32H725 pin alternate functions (continued)

											- (
		AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7	AF8	AF9	AF10	AF11	AF12	AF13	AF14	AF15
P	ort	sys	FMC/LP TIM1/SA I4/TIM16 /17/TIM1 x/TIM2x	FDCAN3 /PDM_S AI1/TIM3 /4/5/12/1 5	DFSDM1 /LCD/LP TIM2/3/4 /5/LPUA RT1/OC TOSPIM _P1/2/TI M8	CEC/DC MI/PSSI/ DFSDM1 /I2C1/2/3 /4/5/LPTI M2/OCT OSPIM_ P1/TIM1 5/USAR T1/10	CEC/FD CAN3/S P11/12S1/ SP12/12S 2/SP13/12 S3/SP14/ 5/6	DFSDM1 /I2C4/5/ OCTOS PIM_P1/ SAI1/SPI 3/I2S3/U ART4	SDMMC 1/SPI2/I2 S2/SPI3/ I2S3/SPI 6/UART 7/USAR T1/2/3/6		FDCAN1 /2/FMC/ LCD/OC TOSPIM _P1/2/S AI4/SDM MC2/SP DIFRX1/ TIM13/1 4	CRS/FM C/LCD/O CTOSPI M_P1/O TG1_FS/ OTG1_H S/SAI4/S DMMC2/ TIM8	DFSDM1 /ETH/I2C 4/LCD/M DIOS/O CTOSPI M_P1/S DMMC2/ SWPMI1 /TIM1x/T IM8/UAR T7/9/US ART10	FMC/LC D/MDIO S/OCTO SPIM_P 1/SDMM C1/TIM1 x/TIM8	COMP/D CMI/PSS I/LCD/TI M1x/TIM 23	LCD/TIM 24/UAR T5	sys
	PK0	-	TIM1_C H1N	-	TIM8_C H3	-	SPI5_SC K	-	-	-	-	-	-	-	-	LCD_G5	EVENTO UT
Port K	PK1	-	TIM1_C H1	-	TIM8_C H3N	-	SPI5_NS S	-	-	-	-	-	-	-	-	LCD_G6	EVENTO UT
	PK2	-	TIM1_B KIN	-	TIM8_B KIN	-	-	-	-	-	-	TIM8_B KIN_CO MP12	TIM1_B KIN_CO MP12	-	-	LCD_G7	EVENTO UT

6 Electrical characteristics

6.1 Parameter conditions

Unless otherwise specified, all voltages are referenced to V_{SS}.

6.1.1 Minimum and maximum values

Unless otherwise specified the minimum and maximum values are guaranteed in the worst conditions of junction temperature, supply voltage and frequencies by tests in production on 100% of the devices with an junction temperature at T_J = 25 °C and T_J = T_{Jmax} (given by the selected temperature range).

Data based on characterization results, design simulation and/or technology characteristics are indicated in the table footnotes. Based on characterization, the minimum and maximum values refer to sample tests and represent the mean value plus or minus three times the standard deviation (mean $\pm 3\sigma$).

6.1.2 Typical values

Unless otherwise specified, typical data are based on T_J = 25 °C, V_{DD} = 3.3 V (for the 1.7 V \leq V_{DD} \leq 3.6 V voltage range). They are given only as design guidelines and are not tested.

Typical ADC accuracy values are determined by characterization of a batch of samples from a standard diffusion lot over the full temperature range, where 95% of the devices have an error less than or equal to the value indicated (mean $\pm 2\sigma$).

6.1.3 Typical curves

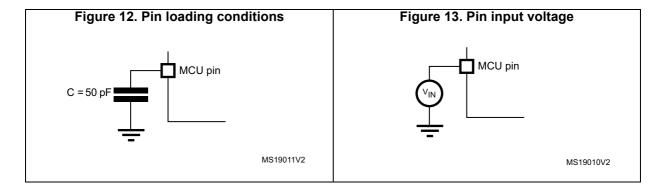
Unless otherwise specified, all typical curves are given only as design guidelines and are not tested.

6.1.4 Loading capacitor

The loading conditions used for pin parameter measurement are shown in *Figure 12*.

6.1.5 Pin input voltage

The input voltage measurement on a pin of the device is described in Figure 13.



6.1.6 Power supply scheme

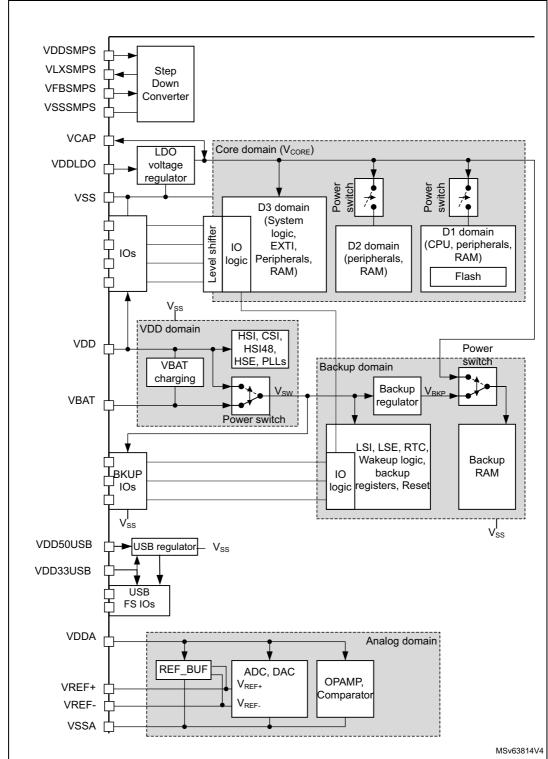


Figure 14. Power supply scheme

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Refer to application note AN5419 "Getting started with STM32H723/733, STM32H725/735 and STM32H730 Value Line hardware development" for the possible power scheme and connected capacitors.

6.1.7 Current consumption measurement

Figure 15. Current consumption measurement scheme

6.2 Absolute maximum ratings

Stresses above the absolute maximum ratings listed in *Table 10: Voltage characteristics*, *Table 11: Current characteristics*, and *Table 12: Thermal characteristics* may cause permanent damage to the device. These are stress ratings only and the functional operation of the device at these conditions is not implied. Exposure to maximum rating conditions for extended periods may affect device reliability. Device mission profile (application conditions) is compliant with JEDEC JESD47 Qualification Standard, extended mission profiles are available on demand.

Symbols	Ratings	Min	Max	Unit
V _{DDX} - V _{SS} ⁽¹⁾	External main supply voltage (including V_{DD} , V_{DDLDO} , V_{DDSMPS} , V_{DDA} , $V_{DD33USB}$, V_{BAT})	-0.3	4.0	V
	Input voltage on FT_xxx pins	V _{SS} -0.3	Min(V _{DD} , V _{DDA} , V _{DD33USB} , V _{BAT}) +4.0 ⁽³⁾⁽⁴⁾	٧
V _{IN} ⁽²⁾	Input voltage on TT_xx pins	V _{SS} -0.3	4.0	٧
	Input voltage on BOOT0 pin	V _{SS}	9.0	V
	Input voltage on any other pins	V _{SS} -0.3	4.0	V
$ \Delta V_{DDX} $	Variations between different V _{DDX} power pins of the same domain	-	50	mV
V _{SSx} -V _{SS}	Variations between all the different ground pins	-	50	mV
		•	•	

Table 10. Voltage characteristics

^{1.} All main power (V_{DD} , V_{DDA} , $V_{DD33USB}$, V_{DDSMPS} , V_{BAT}) and ground (V_{SS} , V_{SSA}) pins must always be connected to the external power supply, in the permitted range.

^{2.} V_{IN} maximum must always be respected.

This formula has to be applied on power supplies related to the IO structure described by the pin definition table.

4. To sustain a voltage higher than 4V the internal pull-up/pull-down resistors must be disabled.

Table 11. Current characteristics

Symbols	Ratings	Max	Unit
ΣIV_{DD}	Total current into sum of all V _{DD} power lines (source) ⁽¹⁾	620	
ΣIV _{SS}	Total current out of sum of all V _{SS} ground lines (sink) ⁽¹⁾	620	
IV _{DD}	Maximum current into each V _{DD} power pin (source) ⁽¹⁾	100	
IV _{SS}	Maximum current out of each V _{SS} ground pin (sink) ⁽¹⁾	100	
	Output current sunk by any I/O and control pin, except Px_C	20	
I _{IO}	Output current sunk by Px_C pins	1	mA
71	Total output current sunk by sum of all I/Os and control pins ⁽²⁾	140	
ΣI _(PIN)	Total output current sourced by sum of all I/Os and control pins ⁽²⁾	140	
I _{INJ(PIN)} (3)(4)	Injected current on FT_xxx, TT_xx, RST and B pins except PA4, PA5	-5/+0	
,	Injected current on PA4, PA5	-0/0	
ΣΙ _{ΙΝJ(PIN)}	Total injected current (sum of all I/Os and control pins) ⁽⁵⁾	±25	

- 1. All main power $(V_{DD}, V_{DDA}, V_{DD33USB})$ and ground (V_{SS}, V_{SSA}) pins must always be connected to the external power supplies, in the permitted range.
- This current consumption must be correctly distributed over all I/Os and control pins. The total output current must not be sunk/sourced between two consecutive power supply pins referring to high pin count QFP packages.
- 3. Positive injection is not possible on these I/Os and does not occur for input voltages lower than the specified maximum value.
- A positive injection is induced by V_{IN}>V_{DD} while a negative injection is induced by V_{IN}<V_{SS}. I_{INJ(PIN)} must never be exceeded. Refer also to *Table 10: Voltage characteristics* for the maximum allowed input voltage values.
- When several inputs are submitted to a current injection, the maximum ∑I_{INJ(PIN)} is the absolute sum of the
 positive and negative injected currents (instantaneous values).

Table 12. Thermal characteristics

5	Symbol	Ra	atings	Value	Unit
	T _{STG}	Storage temperature range		- 65 to +150	
		Maximum junation	Industrial temperature range 6	125	°C
	TJ	Maximum junction temperature	Extended Industrial temperature range 3	140	



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6.3 Operating conditions

6.3.1 General operating conditions

Table 13. General operating conditions

Symbol	Parameter	Operating conditions	Min	Тур	Max	Unit
V_{DD}	Standard operating voltage	-	1.62 ⁽¹⁾	-	3.6	
V _{DDLDO}	Supply voltage for the internal regulator	V _{DDLDO} ≤ V _{DD}	1.62 ⁽¹⁾	-	3.6	
V _{DDSMPS}	Supply voltage for the internal SMPS Step-down converter	V _{DDSMPS} = V _{DD}	1.62 ⁽¹⁾	-	3.6	
V		USB regulator ON	4	5	5.5	
V _{DD50USB}	-	USB regulator OFF	-	V _{DD33USB}	-	
V	Standard operating voltage, USB	USB used	3.0	-	3.6	
V _{DD33USB}	domain	USB not used	0	-	3.6	
		ADC or COMP used	1.62	-		
		DAC used	1.8	-		V
		OPAMP used	2.0	-		
V_{DDA}	Analog operating voltage	VREFBUF used	1.8	-	3.6	
		ADC, DAC, OPAMP, COMP, VREFBUF not used	0	-		
		TT_xx I/O	-0.3	-	V _{DD} +0.3	
		воото	0	-	9	
V _{IN}	I/O Input voltage	All I/O except BOOT0 and TT_xx	-0.3	-	$\begin{array}{c} {\rm Min(V_{DD},} \\ {\rm V_{DDA},} \\ {\rm V_{DD33USB})} \\ +3.6{\rm V} < \\ 5.5{\rm V}^{(2)} \end{array}$	
		VOS3	0.95	1.0	1.05	
	Internal regulator ON (LDO or	VOS2	1.05	1.10	1.15	
	SMPS) ⁽³⁾	VOS1	1.15	1.21	1.26	
Vaans		VOS0	1.30	1.36	1.40	V
V _{CORE}		VOS3	0.98	1.03	1.08	_ v
	Regulator OFF: external V _{CORE} voltage must be supplied from	VOS2	1.08	1.13	1.18	
	external regulator on VCAP pins	VOS1	1.18	1.23	1.28	
		VOS0	1.33	1.38	1.40	

Table 13. General operating conditions (continued)

Symbol	Parameter	Operating conditions	Min	Тур	Max	Unit
		VOS3	-	-	170	
		VOS2	-	-	300	
f _{CPU}	Arm [®] Cortex [®] -M7 clock frequency	VOS1	-	-	400	
CPU	7 min Cortex wir Glock hequeincy	VOS0	-	-	520	
		VOS0 and CPU_FREQ_BOOST	-	-	550	
		VOS3	-	-	85	
£	AVI alask fra svensv	VOS2	-	-	150	
f _{ACLK}	AXI clock frequency	VOS1	-	-	200	
		VOS0	-	-	275	MHz
		VOS3	-	-	85	
£	ALID aloak fraguency	VOS2	-	-	150	
f _{HCLK}	AHB clock frequency	VOS1	-	-	200	
		VOS0	-	-	275	
		VOS3	-	-	42.5 ⁽⁴⁾	
£	ADD aloge fraguency	VOS2	-	-	75	
f _{PCLK}	APB clock frequency	VOS1	-	-	100	
		VOS0	-	-	137.5	
	Ambient temperature for temperature range 3	Maximum power dissipation	-40		125	
T _A ⁽⁵⁾	Ambient temperature for	Maximum power dissipation	-40		85	°C
	temperature range 6	Low-power dissipation ⁽⁶⁾	-40		105	

When RESET is released, the functionality is guaranteed down to V_{PDRmax} or down to the specified V_{DDmin} when the PDR is OFF. The PDR can only be switched OFF though the PDR_ON pin that not available in all packages.

^{2.} This formula has to be applied on power supplies related to the I/O structure described by the pin definition table.

^{3.} At startup, the external V_{CORE} voltage must remain higher or equal to 1.10 V before disabling the internal regulator (LDO).

^{4.} This value corresponds to the maximum APB clock frequency when at least one peripheral is enabled.

The device junction temperature must be kept below maximum T_J indicated in *Table 14: Supply voltage and maximum temperature configuration* and the maximum temperature.

In low-power dissipation state, T_A can be extended to this range as long as T_J does not exceed T_{Jmax} (see Section 7.9: Thermal characteristics).

Table 14. Supply voltage and maximum temperature configuration

Power scale	V _{CORE} source	Max. T _J (°C) ⁽¹⁾	Min. V _{DD} (V)	Min. V _{DDLDO} (V)
	SMPS		2.2	-
VOS0	LDO	105	1.7	1.7
VO30	SMPS supplies LDO	105	3 ⁽²⁾	1.7
	External (Bypass)		1.62	1.62
	SMPS	140	2.2	-
	SIVIPS		1.62	-
VOS1	LDO	125	1.62	1.62
	SMPS supplies LDO	125	2.3	-
	External (Bypass)		1.62	-
	SMPS	140	1.62	-
VOS2	LDO		1.62	1.62
VUS2	SMPS supplies LDO	125	2.3	-
	External (Bypass)		1.62	-
	SMPS	140	1.62	-
VOS3	LDO		1.62	1.62
VO33	SMPS supplies LDO	125	2.3	-
	external (Bypass)E		1.62	-
	SMPS	140	1.62	-
	LDO	125	2	2
SVOS4/SVOS5	LDO	105	1.62	1.62
37034/37035	SMPS supplies LDO	125	3 ⁽²⁾	2
	Siving supplies LDO	105	2.3	-
	External (Bypass)	125	1.62	-

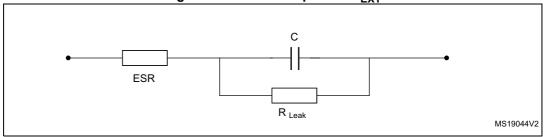
^{1.} $140~^{\circ}$ C can be reached only for part numbers in temperature range 3. For part numbers in temperature range 6, this value must be decreased to 125 $^{\circ}$ C.

^{2.} The SMPS must be configured to output 2,5 V.

6.3.2 VCAP external capacitor

Stabilization for the main regulator is achieved by connecting an external capacitor C_{EXT} to the VCAP pin. C_{EXT} is specified in *Table 15*. Two external capacitors can be connected to VCAP pins.

Figure 16. External capacitor C_{EXT}



1. Legend: ESR is the equivalent series resistance.

Table 15. VCAP operating conditions⁽¹⁾

Symbol	Parameter	Conditions
CEXT	Capacitance of external capacitor	2.2 µF ⁽²⁾⁽³⁾
ESR	ESR of external capacitor	< 100 mΩ

- 1. When bypassing the voltage regulator, the two 2.2 μ F V_{CAP} capacitors are not required and should be replaced by two 100 nF decoupling capacitors.
- 2. This value corresponds to CEXT typical value. A variation of +/-20% is tolerated.
- 3. If a third VCAP pin is available on the package, it must be connected to the other VCAP pins but no additional capacitor is required.

6.3.3 SMPS step-down converter

The devices embed a high power efficiency SMPS step-down converter. SMPS characteristics for external usage are given in *Table 17*. The SMPS step-down converter requires external components that are specified in *Figure 17* and *Table 16*.

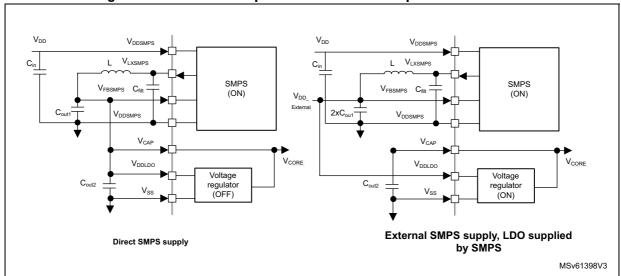


Figure 17. External components for SMPS step-down converter

Table 16. Characteristics of SMPS step-down converter external components

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Symbol	Parameter	Conditions				
C	Capacitance of external capacitor on V _{DDSMPS}	4.7 µF				
C _{in}	ESR of external capacitor	100 mΩ				
C _{filt}	Capacitance of external capacitor on V _{LXSMPS} pin	220 pF				
C	Capacitance of external capacitor on V _{FBSMPS} pin	10 μF				
C _{OUT}	ESR of external capacitor	20 mΩ				
L	Inductance of external Inductor on V _{LXSMPS} pin	2.2 µH				
-	Serial DC resistor	150 mΩ				
I _{SAT}	DC current at which the inductance drops 30% from its value without current.	1.7 A				
I _{RMS}	Average current for a 40 °C rise: rated current for which the temperature of the inductor is raised 40°C by DC current	1.4 A				

Table 17. SMPS step-down converter characteristics for external usage

Parameters	Conditions	Min	Тур	Max	Unit
V _{DDSMPS} ⁽¹⁾	V _{OUT} = 1.8 V	2.3	-	3.6	V
VDDSMPS` /	V _{OUT} = 2.5 V	3	-	3.6	V
V _{OUT} ⁽²⁾	lout=600 mA	2.25	2.5	2.75	V
VOUT` ′		1.62	1.8	1.98	V
	internal and external usage	-	-	600	mA
lout	External usage only ⁽³⁾	-	-	600	IIIA
RDS _{ON}	-	-	100	120	mΩ

Table 17. SMPS step-down converter characteristics for external usage (continued)

Parameters	Conditions	Min	Тур	Max	Unit
I _{DDSMPS_Q}	Quiescent current	-	220	-	μΑ
т	V _{OUT} = 1.8 V	-	270	405	116
ISMPS_START	V _{OUT} = 2.5 V	-	360	540	μs

- 1. The switching frequency is 2.4 MHz±10%
- 2. Including line transient and load transient.
- 3. These characteristics are given for SDEXTHP bit is set in the PWR_CR3 register.

Table 18. Inrush current and inrush electric charge characteristics for LDO and ${\rm SMPS}^{(1)(2)}$

Symbol	Parameter	Conditions	-	Min	Тур	Max	Unit
	Inrush current on voltage regulator power-on (POR or wakeup from Standby)	on V _{DDLDO} ⁽³⁾	-	-	55	96 ⁽⁴⁾	
		on V _{DDSMPS} ⁽⁵⁾	SMPS supplies the V _{DDCORE}	-	100	420 ⁽⁶⁾	
			SMPS supplies internal LDO, V _{OUT} = 1.8 V ⁽⁷⁾	ı	130	400 ⁽⁶⁾	
	Inrush current on voltage	on V _{DDSMPS} ⁽⁵⁾	SMPS supplies internal LDO, V _{OUT} = 2.5 V ⁽⁷⁾	-	-	300 ⁽⁶⁾	
I _{RUSH}	regulator power-on (POR)		SMPS supplies external circuit, $V_{OUT} = 1.8 V^{(7)}$	-	100	320 ⁽⁶⁾	mA
			SMPS supplies external circuit, $V_{OUT} = 2.5 V^{(7)}$	-	-	240 ⁽⁶⁾	
	Inrush current on voltage regulator power-on (wakeup from Standby)	on V _{DDSMPS} ⁽⁵⁾	SMPS supplies internal LDO, V _{OUT} = 1.8 V	-	170	530 ⁽⁶⁾	
			SMPS supplies internal LDO, V _{OUT} = 2.5 V	-	240	550 ⁽⁶⁾	

Table 18. Inrush current and inrush electric charge characteristics for LDO and SMPS⁽¹⁾⁽²⁾ (continued)

Symbol	Parameter	Conditions	-	Min	Тур	Max	Unit
	Inrush current on voltage	on V _{DDLDO} ⁽³⁾	-	-	4.4	5.3 ⁽⁴⁾	
	regulator power-on (POR or wakeup from Standby)	on V _{DDSMPS} ⁽⁵⁾	SMPS supplies the V _{DDCORE}	-	7.3	18 ⁽⁶⁾	
Q _{RUSH} r			SMPS supplies internal LDO, V _{OUT} = 1.8 V ⁽⁷⁾	-	8.8	17 ⁽⁶⁾	
	Inrush current on voltage regulator power-on (POR)	on V _{DDSMPS} ⁽⁵⁾	SMPS supplies internal LDO, V _{OUT} = 2.5 V ⁽⁷⁾	-	0.0	13 ⁽⁶⁾	
			SMPS supplies external circuit, $V_{OUT} = 1.8 V^{(7)}$	-	7.3	13.7 ⁽⁶⁾	μC
			SMPS supplies external circuit, $V_{OUT} = 2.5 V^{(7)}$	-	7.5	10.5 ⁽⁶⁾	
	Inrush current on voltage regulator power-on (wakeup from Standby)	on V _{DDSMPS} ⁽⁵⁾	SMPS supplies internal LDO, V _{OUT} = 1.8 V	-	15.0	28 ⁽⁶⁾	
			SMPS supplies internal LDO, V _{OUT} = 2.5 V	-	28.0	39 ⁽⁶⁾	

The typical values are given for V_{DDLDO} = V_{DDSMPS} = 3.3 V and for typical decoupling capacitor values of C_{EVT} and C_{OUT}.

^{2.} The product consumption (on VDDCORE) is not taken into account in the inrush current and inrush electric charges.

^{3.} The inrush current and inrush electric charge on VDDLDO are not present in Bypass mode or when the SMPS supplies the VDDCORE.

^{4.} The maximum value is given for the maximum decoupling capacitor C_{EXT} .

^{5.} The inrush current and inrush electric charges on VDDSMPS are not present if the external component (L or C_{OUT}) is not present that is if the SMPS is not used.

The maximum value is given for the maximum decoupling capacitor C_{OUT} and the minimum V_{DDSMPS} voltage.

The inrush current due to transition from 1.2 V to the final V_{OUT} Value (1.8 V or 2.5 V) is not taken into account.

6.3.4 Operating conditions at power-up / power-down

Subject to general operating conditions for T_A .

Table 19. Operating conditions at power-up / power-down (regulator ON)

Symbol	Parameter	Min	Max	Unit
t _{VDD}	V _{DD} rise time rate	0	∞	
	V _{DD} fall time rate	10	œ	
+	V _{DDA} rise time rate	0	œ	μs/V
t_{VDDA}	V _{DDA} fall time rate	10	∞	μ5/ ν
t _{VDDUSB}	V _{DDUSB} rise time rate	0	∞	
	V _{DDUSB} fall time rate	10	∞	

6.3.5 Embedded reset and power control block characteristics

The parameters given in *Table 20* are derived from tests performed under ambient temperature and V_{DD} supply voltage conditions summarized in *Table 13: General operating conditions*.

Table 20. Reset and power control block characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
t _{RSTTEMPO} ⁽¹⁾	Reset temporization after BOR0 released	-	-	377	550	μs
	Power-on/power-down reset	Rising edge ⁽¹⁾	1.62	1.67	1.71	
V _{POR/PDR}	threshold	Falling edge	1.58	1.62	1.68	
V	Brown-out reset threshold 1	Rising edge	2.04	2.10	2.15	
V _{BOR1}	Brown-out reset threshold 1	Falling edge	1.95	2.00	2.06	
V	Brown-out reset threshold 2	Rising edge	2.34	2.41	2.47	
V_{BOR2}	Brown-out reset threshold 2	Falling edge	2.25	2.31	2.37	
V	Brown-out reset threshold 3	Rising edge	2.63	2.70	2.78	
V _{BOR3}		Falling edge	2.54	2.61	2.68	
V	Programmable Voltage Detector threshold 0	Rising edge	1.90	1.96	2.01	
V _{PVD0}		Falling edge	1.81	1.86	1.91	
	Programmable Voltage Detector threshold 1	Rising edge	2.05	2.10	2.16	.,
V _{PVD1}		Falling edge	1.96	2.01	2.06	V
	Programmable Voltage	Rising edge	2.19	2.26	2.32	
V _{PVD2}	Detector threshold 2	Falling edge	2.10	2.15	2.21	
	Programmable Voltage	Rising edge	2.35	2.41	2.47	
V _{PVD3}	Detector threshold 3	Falling edge	2.25	2.31	2.37	
	Programmable Voltage	Rising edge	2.49	2.56	2.62	
V_{PVD4}	Detector threshold 4	Falling edge	2.39	2.45	2.51	
	Programmable Voltage	Rising edge	2.64	2.71	2.78	
V _{PVD5}	Detector threshold 5	Falling edge	2.55	2.61	2.68	
	Programmable Voltage	Rising edge	2.78	2.86	2.94	
V _{PVD6}	Detector threshold 6	Falling edge in Run mode	2.69	2.76	2.83	
V _{POR/PDR}	Hysteresis voltage for Power-on/power-down reset	Hysteresis in Run mode	-	43.00	-	mV
V _{hyst_BOR_PVD}	Hysteresis voltage for BOR	Hysteresis in Run mode	-	100	-	
I _{DD_BOR_PVD} ⁽¹⁾	BOR and PVD consumption from V _{DD}	-			0.630	μA
I _{DD_POR_PVD}	POR and PVD consumption from V _{DD}	-	0.8	-	1.200	μΛ

Unit **Symbol Parameter Conditions** Min Тур Max Rising edge 1.66 1.71 1.76 Analog voltage detector for V_{AVM_0} V_{DDA} threshold 0 1.61 Falling edge 1.56 1.66 Rising edge 2.06 2.12 2.19 Analog voltage detector for V_{AVM_1} V_{DDA} threshold 1 Falling edge 1.96 2.02 2.08 ٧ Rising edge 2.42 2.50 2.58 Analog voltage detector for V_{AVM_2} V_{DDA} threshold 2 Falling edge 2.35 2.42 2.49 Rising edge 2.74 2.83 2.91 Analog voltage detector for $V_{AVM 3}$ V_{DDA} threshold 3 Falling edge 2.64 2.72 2.80 Hysteresis of V_{DDA} voltage 100 mV V_{hyst_VDDA} detector PVM consumption from 0.25 μΑ I_{DD PVM} $V_{DD(1)}$ Voltage detector Resistor bridge 2.5 μΑ I_{DD_VDDA} consumption on $V_{DDA}^{(1)}$

Table 20. Reset and power control block characteristics (continued)

6.3.6 Embedded reference voltage characteristics

The parameters given in *Table 21* are derived from tests performed under ambient temperature and V_{DD} supply voltage conditions summarized in *Table 13: General operating conditions*.

Table 21. Embedded reference voltage

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V _{REFINT}	Internal reference voltages	-40°C < T _J < T _{Jmax}	1.180	1.216	1.255	V
t _{S_vrefint} (1)(2)	ADC sampling time when reading the internal reference voltage	-	4.3	-	-	
t _{S_vbat} ⁽²⁾	VBAT sampling time when reading the internal VBAT reference voltage	-	9	-	-	μs
t _{start_vrefint} (2)	Start time of reference voltage buffer when ADC is enable	-	-	-	4.4	
I _{refbuf} ⁽²⁾	Reference Buffer consumption for ADC	V _{DD} = 3.3 V	9	13.5	23	μΑ
ΔV _{REFINT} ⁽²⁾	Internal reference voltage spread over the temperature range	-40°C < T _J < T _{Jmax}	-	5	15	mV
T _{coeff} ⁽²⁾	Average temperature coefficient	Average temperature coefficient	-	20	70	ppm/°C
V _{DDcoeff} ⁽²⁾	Average Voltage coefficient	3.0 V < V _{DD} < 3.6 V	-	10	1370	ppm/V



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^{1.} Guaranteed by design.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V _{REFINT_DIV1}	1/4 reference voltage	-	-	25	-	2,4
V _{REFINT_DIV2}	1/2 reference voltage	-	-	50	-	% V _{REFINT}
V _{REFINT DIV3}	3/4 reference voltage	-	-	75	-	IXLI IINI

- 1. The shortest sampling time for the application can be determined by multiple iterations.
- 2. Guaranteed by design.
- 3. Guaranteed by design. and tested in production at 3.3 V.

Table 22. Internal reference voltage calibration values

Symbol	Parameter	Memory address
V _{REFIN_CAL}	Raw data acquired at temperature of 30 °C, V _{DDA} = 3.3 V	1FF1 E860 - 1FF1 E861

6.3.7 Embedded USB regulator characteristics

The parameters given in *Table 23* are derived from tests performed under ambient temperature and V_{DD} supply voltage conditions summarized in *Table 13: General operating conditions*.

Table 23. USB regulator characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V _{DD50USB}	Supply voltage	-	4	5	5.5	V
I _{DD50USB}	Current consumption	-	-	14	-	μA
V _{REGOUTV33V}	Regulated output voltage	-	3	-	3.6	V
I _{OUT}	Output current load sinked by USB block	-	-	-	20	mA
T _{WKUP}	Wakeup time	-	-	120	170	us

6.3.8 Supply current characteristics

The current consumption is a function of several parameters and factors such as the operating voltage, ambient temperature, I/O pin loading, device software configuration, operating frequencies, I/O pin switching rate, program location in memory and executed binary code.

The current consumption is measured as described in *Figure 15: Current consumption measurement scheme*.

All the run-mode current consumption measurements given in this section are performed with a CoreMark code.

Typical and maximum current consumption

The MCU is placed under the following conditions:

- All I/O pins are in analog input mode.
- All peripherals are disabled except when explicitly mentioned.
- The Flash memory access time is adjusted with the minimum wait states number, depending on the f_{ACLK} frequency (refer to the table "Number of wait states according to CPU clock (f_{rcc c ck}) frequency and V_{CORE} range" available in the reference manual).
- When the peripherals are enabled, the AHB clock frequency is the CPU frequency divided by 2 and the APB clock frequency is AHB clock frequency divided by 2.

The parameters given in the below tables are derived from tests performed under ambient temperature and supply voltage conditions summarized in *Table 13: General operating conditions*.



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Table 24. Typical and maximum current consumption in Run mode, code with data processing running from $ITCM^{(1)}$

Symbol	Parameter	Conditi		f _{rcc c ck}	Typ LDO	Typ SMPS			egulator (ON ⁽²⁾	Max SMPS ON ⁽³⁾	Unit							
,				(MHz)	regulator ON	ON	T _J = 25 °C	T _J = 85 °C	T _J = 105 °C	T _J = 125 °C	T _J = 140 °C								
			VOS0	550	145	81	170	260	330	-	-								
			(4)	520	135	76	160	260	320	-	-								
				520	135	76	160	260	320	-	-								
			VOS0	480	125	72.5	150	250	310	-	-								
			VUS0	450	115	67.5	150	240	300	-	-								
				400	105	60	130	230	290	-	-								
			VOC4	400	90.5	47	110	170	220	280	160								
			VOS1	300	69.5	36.5	84	150	200	260	150								
				300	63	31.5	74	130	170	220	110								
			VOS2	280	58	29	69	120	160	210	110								
					VUS2	216	45.5	22.5	56	110	150	200	110						
	Supply			200	42	21	53	110	140	200	110								
				170	32.5	15	40	80	110	160	74	4							
I _{DD}	current in Run mode				ı	Ì	168	32	15	40	79	110	160	74	mA				
			VOS3	144	28	13.5	36	75	110	150	74								
				60	13.5	6.7	21	61	90	140	67								
				25	6.9	3.6	14	54	83	130	67								
					VOS0	550	215	125	250	360	430	-	-						
												,	(4)	520	205	120	240	350	420
			1/000	520	205	120	240	350	420	-	-								
		A II	VOS0	400	160	92.5	190	300	370	-	-								
		All peripherals	1/00 /	400	135	72	160	230	290	360	200								
		enabled	VOS1	300	105	54.5	130	200	250	330	180								
				300	95	46.5	110	170	210	280	140								
			VOS	V		VOS2	280	88	43	100	160	210	270	140					
			VOS3	170	49	22.5	58	110	140	190	93								

^{1.} Data are in DTCM for best computation performance, the cache has no influence on consumption in this case.

^{2.} Guaranteed by characterization results, unless otherwise specified. Refer to Section 6.3.3: SMPS step-down converter for the SMPS maximum consumption.

The parameter values given in the above table for the SMPS regulator are extrapolated from the LDO consumption and typical SMPS efficiency factors.

^{4.} CPU_FREQ_BOOST is enabled.

Table 25. Typical and maximum current consumption in Run mode, code with data processing running from Flash memory, cache $\mathrm{ON}^{(1)}$

Symbol	Parameter	Conditi		f _{rcc_c_ck}	Typ LDO regulator	Typ SMPS			gulator (ON ⁽²⁾	Max SMPS ON ⁽³⁾	Unit				
				(IVILIZ)	ON	ON	T _J = 25 °C	T _J = 85 °C	T _J = 105 °C	T _J = 125 °C	T _J = 140 °C					
			VOS0	550	145	83.5	170	270	330	-	-					
			(4)	520	140	78.5	170	260	320	ı	ı					
			VOS0	520	140	78.5	170	260	320	-	-					
			VO30	400	110	62	140	230	290	-	-					
			VOS1	400	92	48.5	110	180	220	290	160					
			V001	300	71	37.5	86	150	200	260	150					
		All peripherals disabled		300	64	32	75	130	170	220	110					
	Supply current in			280	59	29.5	70	120	160	210	110					
				216	46.5	23	-	-	-	-	-					
				200	42.5	21.5	53	110	140	200	110					
				180	36	17	43	83	120	160	85					
				170	33.5	15.5	41	81	110	160	74					
I _{DD}				168	33	15.5	-	-	-	-	-	mA				
	Run mode		VOS3	144	29	13.5	-	-	-	-	-					
				60	14	6.85	-	-	-	1	1					
				25	6.85	3.7	-	-	-	ı	ı					
		_					VOS0	550	220	130	250	360	430	ı	ı	
			(4)	520	210	120	240	350	420	ı	ı					
			VOS0	520	210	120	240	350	420	1	ı					
		All	V000	400	160	94.5	190	300	370	-	-					
		peripherals	VOS1	400	140	73	160	240	290	360	200					
		enabled	VOO1	300	105	55.5	130	200	250	330	180					
			VOS2	300	96	47	110	170	210	280	140					
		VOS2	VOS2	VC		280	89	43.5	110	160	210	270	140			
			VOS3	170	50	23	59	110	140	190	93					

^{1.} Data are in DTCM for best computation performance, the cache has no influence on consumption in this case.

4. CPU_FREQ_BOOST is enabled.



^{2.} Guaranteed by characterization results, unless otherwise specified. Refer to Section 6.3.3: SMPS step-down converter for the SMPS maximum consumption.

^{3.} The parameter values given in the above table for the SMPS regulator are extrapolated from the LDO consumption and typical SMPS efficiency factors.

Table 26. Typical and maximum current consumption in Run mode, code with data processing running from Flash memory, cache $\mathsf{OFF}^{(1)}$

Symbol	Parameter	Conditio	ons	f _{rcc_c_ck} (MHz)	Typ LDO regulator ON	Typ SMPS ON	Unit										
			VOS0 ⁽²⁾	550	99	59.5											
			VO30.7	520	95	56											
			VOS0	520	95	56											
			VO30	400	76.5	47											
		All peripherals disabled	VOS1	400	66.5	38											
			0.000.00				0.000.00	disabled	0.00.0.00				VUS1	300	51.5	30	
			VOS2	300	47.5	26											
					VU32	280	43.5	24									
	Supply current		VOS3	170	24.5	13	mA										
I _{DD}	in Run mode		VOS0 ⁽²⁾	550	170	100	IIIA										
			VO30(/	520	165	95.5											
									VOS0	520	165	95.5					
			VO30	400	130	77.5											
		All peripherals enabled	VOS1	400	115	62											
			VU31	300	87	47.5											
			VOS2	300	79	41.5											
			VU32	280	73.5	38											
			VOS3	170	41	20.5											

^{1.} Data are in DTCM for best computation performance, the cache has no influence on consumption in this case

^{2.} CPU_FREQ_BOOST is enabled.

Table 27. Typical consumption in Run mode and corresponding performance versus code position

		Condit	ions			Typ LDO	Тур		LDO I _{DD} /	SMPS	
Symbol	Parameter	Peripheral	Code	f _{rcc_c_ck} (MHz)	Coremark	regulator ON	SMPS ON	Unit	Coremark	I _{DD} / Coremark	Unit
			ITCM	550	2777	145	81		52.2	29.2	
	Supply		FLASH	550	2777	145	83.5		52.2	30.1	
			AXI SRAM	550	2777	145	83.5		52.2	30.1	
			SRAM 1	550	2777	150	86		54.0	31.0	μΑ/
I _{DD}	current in		SRAM 4	550	2777	145	83.5	mA	52.2	30.1	Core-
	Run mode		FLASH	550	923	99	59.5		107.3	64.5	mark
		disabled —	AXI SRAM	550	1271	105	60.5		82.6	47.6	
			SRAM 1	550	790	96.5	54.5		122.2	69.0	
			SRAM 4	550	723	89.5	50.5		123.8	69.8	

Table 28. Typical current consumption in Autonomous mode

Symbol	Parameter	Conditio	ns	f _{rcc_c_c k} (MHz)	Typ LDO regulator ON	Typ SMPS ON	Unit
	, Supply current in		VOS3	64	3.6	2.2	
I _{DD}	Autonous mode	Run, D1Standby, D2Standby	VOS3	64	2.6	1.6	mA

Table 29. Typical current consumption in Sleep mode

Ob. al	B	arameter Conditio	tions f _{rcc_c_ck}		Typ LDO	Тур		LDO reg	N ⁽¹⁾⁽²⁾	Max SMPS ON ⁽³⁾	Unit	
Symbol	1 didiliotoi	Conditions		(MHz)	regulator ON	SMPS ON	T _J = 25 °C	T _J = 85 °C	T _J = 105 °C	T _J = 125 °C	T _J = 140 °C	Oilit
			VOS0	550	36	20.5	-	-	-	-	-	
	Supply	olv All	(4)	520	33.5	19.5	60	170	240	-	-	
			VOS0	520	33.5	19.5	60	170	240	-	-	
				400	27	16	52	160	230	-	-	
I _{DD(Sleep)}	current in	peripherals	VOS1	400	22.5	12.5	39	110	170	240	140	mA
	Sleep mode	disabled	VU31	300	18.5	10.5	34	110	160	240	140	
			VOS2	300	16.5	8.75	28	85	130	190	110	
		VO	VOS2	170	9.7	5.2	21	78	120	190	110	
			VOS3	170	8.5	4.35	17	61	96	150	74	



- 1. Guaranteed by characterization results.
- 2. Refer to Section 6.3.3: SMPS step-down converter for the SMPS maximum consumption.
- 3. The parameter values given in the above table for the SMPS regulator are extrapolated from the LDO consumption and typical SMPS efficiency factors.
- 4. CPU_FREQ_BOOST is enabled.

Table 30. Typical current consumption in System Stop mode

Symbol	Parameter	Parameter Conditions		Typ LDO regulator	Typ SMPS ON	Max	_DO reg	ulator O	N ⁽¹⁾⁽²⁾	Max SMPS ON ⁽³⁾	Unit
			ON	ON	T _J = 25 °C	T _J = 85 °C	T _J = 105 °C	T _J = 125 °C	T _J = 140 °C		
			SVOS5	0.52	0.2	3.7	26	44	72	50	
	Supply	Supply current in Stop and DStop modes Flash memory in low power mode Flash memory in normal mode	SVOS4	0.81	0.35	6.1	39	64	110	70	
l.			SVOS3	1.15	0.515	8.6	51	82	130	100	A
I _{DD(Stop)}			SVOS5	0.535	0.205	3.7	26	44	72	50	mA
	modes		SVOS4	0.96	0.475	6.2	39	64	110	75	
			SVOS3	1.45	0.645	8.8	51	83	130	100	

- 1. Guaranteed by characterization results.
- 2. Refer to Section 6.3.3: SMPS step-down converter for the SMPS maximum consumption.
- The parameter values given in the above table for the SMPS regulator are extrapolated from the LDO consumption and typical SMPS efficiency factors.

Table 31. Typical current consumption in Standby mode

Symbol	Parameter	Condit	ions		Typ ⁽¹⁾ Max at 3.6 V with LDO regulator ON ⁽²⁾			Max at 3.6 V with SMPS ON ⁽³⁾	Unit				
		Backup SRAM	RTC and LSE ⁽⁴⁾	1.65 V	2.4 V	3 V	3.3 V	T _J = 25 °	T _J = 85 ° C	T _J = 105 ° C	T _J = 125 ° C	T _J = 140 °C	
	Supply	OFF	OFF	2.2	2.35	2.5	2.8	-	-	-	-	-	
I _{DD}	current in Standby	ON	OFF	3.5	3.7	4	4.3	-	-	-	-	-	μA
(Standby)	mode,	OFF	ON	2.2	2.4	2.85	3.25	4.5	15	30	64	96	μΑ
	IWDG OFF	ON	ON	3.5	3.8	4.35	4.75	8.3	39	75	140	180	

These values are given for PDR OFF. When the PDR is ON, the typical current consumption is increased (refer to Table 20: Reset and power control block characteristics.

4. The LSE is in Low-drive mode.

^{2.} Guaranteed by characterization results.

^{3.} The parameter values given in the above table for the SMPS regulator are extrapolated from the LDO consumption and typical SMPS efficiency factors.

Max at 3.6 V Max at 3.6 V with LDO **Conditions** Тур with regulator ON⁽¹⁾⁽²⁾ **SMPS** Sym-Para- $ON^{(1)(2)}$ Unit bol meter Back-RTC $T_J =$ $T_J =$ $T_J =$ $T_J =$ $T_J =$ up and 1.2 V 2 V 3 V 3.3 V 85° 105 125 25°C 140 °C LSE(3) **SRAM** C °C °C OFF 0.008 **OFF** 0.01 0.025 0.05 0.3 3.1 7.4 18 34 Supply ON **OFF** 110 1.5 1.7 1.9 1.9 4 28 53 current I_{DD} μΑ in VBAT **OFF** (VBAT) ON 0.4 0.5 0.75 8.0 mode ON ON 1.8 2.1 2.8 3.2

Table 32. Typical and maximum current consumption in V_{BAT} mode

Typical SMPS efficiency versus load current and temperature

Figure 18. Typical SMPS efficiency (%) vs load current (A) in Run mode at T_J = 30 °C 100 90 60 VDDSMPS = 1.8V, VOS1 VDDSMPS = 3.3V,VOS1 VDDSMPS = 1.8V, VOS2 VDDSMPS = 3.3V, VOS2 40 VDDSMPS = 1.8V, VOS3 30 20 0.001 0.01 0.1

^{1.} Guaranteed by characterization results.

^{2.} The LDO regulator is used before switching to V_{BAT} mode.

^{3.} The LSE is in Low-drive mode.

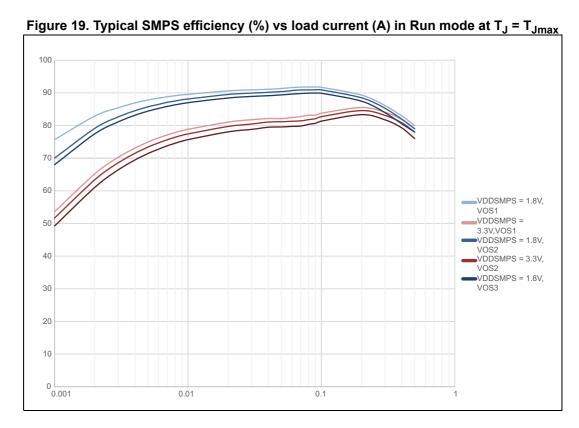
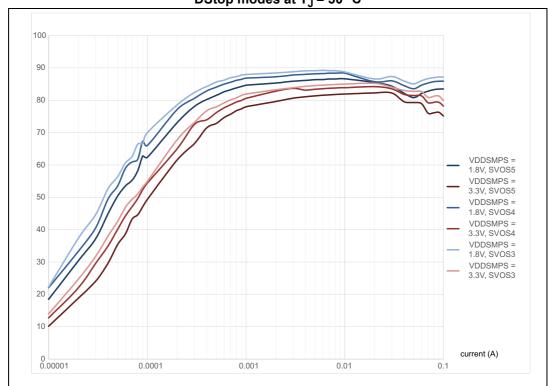


Figure 20. Typical SMPS efficiency (%) vs load current (A) in Stop and DStop modes at $T_J = 30 \, ^{\circ}\text{C}$



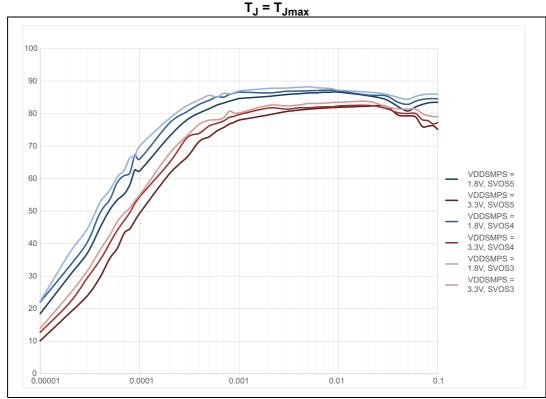


Figure 21. Typical SMPS efficiency (%) vs load current (A) in low-power mode at

I/O system current consumption

The current consumption of the I/O system has two components: static and dynamic.

I/O static current consumption

All the I/Os used as inputs with pull-up generate a current consumption when the pin is externally held low. The value of this current consumption can be simply computed by using the pull-up/pull-down resistors values given in *Table 54: I/O static characteristics*.

For the output pins, any external pull-down or external load must also be considered to estimate the current consumption.

An additional I/O current consumption is due to I/Os configured as inputs if an intermediate voltage level is externally applied. This current consumption is caused by the input Schmitt trigger circuits used to discriminate the input value. Unless this specific configuration is required by the application, this supply current consumption can be avoided by configuring these I/Os in analog mode. This is notably the case of ADC input pins which should be configured as analog inputs.

Caution:

Any floating input pin can also settle to an intermediate voltage level or switch inadvertently, as a result of external electromagnetic noise. To avoid a current consumption related to floating pins, they must either be configured in analog mode, or forced internally to a definite digital value. This can be done either by using pull-up/down resistors or by configuring the pins in output mode.

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I/O dynamic current consumption

In addition to the internal peripheral current consumption, the I/Os used by an application also contribute to the current consumption. When an I/O pin switches, it uses the current from the MCU supply voltage to supply the I/O pin circuitry and to charge/discharge the capacitive load (internal or external) connected to the pin:

$$I_{SW} = V_{DDx} \times f_{SW} \times C_{L}$$

where

 $\rm I_{SW}$ is the current sunk by a switching I/O to charge/discharge the capacitive load

 V_{DDx} is the MCU supply voltage

 f_{SW} is the I/O switching frequency

 C_L is the total capacitance seen by the I/O pin: $C = C_{INT} + C_{EXT}$

The test pin is configured in push-pull output mode and is toggled by software at a fixed frequency.

6.3.9 Wakeup time from low-power modes

The wakeup times given in *Table 33* are measured starting from the wakeup event trigger up to the first instruction executed by the CPU:

- For Stop or Sleep modes: the wakeup event is WFE.
- WKUP (PC1) pin is used to wakeup from Standby, Stop and Sleep modes.

All timings are derived from tests performed under ambient temperature and V_{DD} =3.3 V.

Table 33. Low-power mode wakeup timings

Symbol	Parameter	Conditions	Typ ⁽¹⁾	Max ⁽¹⁾	Unit
t _{WUSLEEP} (3)	Wakeup from Sleep	-	14.00	15.00	CPU clock cycles
		SVOS3, HSI, Flash memory in Normal mode	4.6	6.2	
		SVOS3, HSI, Flash memory in low-power mode	12.4	17.4	
		SVOS4, HSI, Flash memory in Normal mode	15.5	21.1	
		SVOS4, HSI, Flash memory in low-power mode	23.3	31.8	
		SVOS5, HSI, Flash memory in Normal mode	39.1	52.6	
4 (3)	Wakeup from Stop	SVOS5, HSI, Flash memory in low-power mode	39.1	52.7	
t _{WUSTOP} (3)	mode	SVOS3, CSI, Flash memory in Normal mode	30.0	41.6	
		SVOS3, CSI, Flash memory in low power mode	40.6	55.0	μs
		SVOS4, CSI, Flash memory in Normal mode	41.0	55.4	
		SVOS4, CSI, Flash memory in low-power mode	51.5	68.8	
		SVOS5, CSI, Flash memory in Normal mode	67.3	89.5	
		SVOS5, CSI, Flash memory in low-power mode	67.2	89.5	
t _{WUSTDBY} (3)	Wakeup from Standby mode	-	400.0	504.3	

- 1. Guaranteed by characterization results.
- 2. The maximum values have been measured at -40 °C, in worst conditions.
- 3. The wakeup times are measured from the wakeup event to the point in which the application code reads the first

6.3.10 External clock source characteristics

High-speed external user clock generated from an external source

In bypass mode the HSE oscillator is switched off and the input pin is a standard I/O.

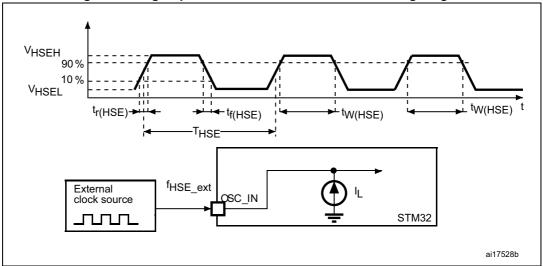
The external clock signal has to respect the *Table 54: I/O static characteristics*. However, the recommended clock input waveform is shown in *Figure 22*.

Table 34. High-speed external user clock characteristics⁽¹⁾

Symbol	Parameter	Min	Тур	Max	Unit
f _{HSE_ext}	User external clock source frequency	4	25	50	MHz
V _{SW} (V _{HSEH} -V _{HSEL)}	OSC_IN amplitude	0.7V _{DD}	-	V_{DD}	V
V_{DC}	OSC_IN input voltage	V_{SS}	-	0.3V _{SS}	
t _{W(HSE)}	OSC_IN high or low time	7	-	-	ns

^{1.} Guaranteed by design.

Figure 22. High-speed external clock source AC timing diagram



Low-speed external user clock generated from an external source

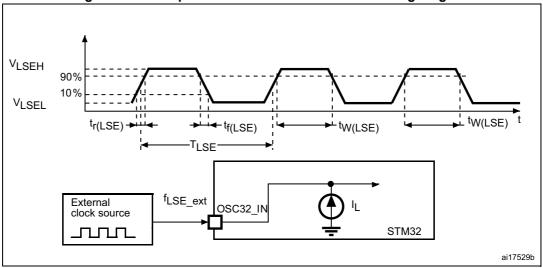
In bypass mode the LSE oscillator is switched off and the input pin is a standard I/O. The external clock signal has to respect the *Table 54: I/O static characteristics*. However, the recommended clock input waveform is shown in *Figure 23*.

Table 35. Low-speed external user clock characteristics⁽¹⁾

Symbol	Parameter	Conditions	Min	Тур	Max	Unit	
f _{LSE_ext}	User external clock source frequency	-	-	32.768	1000	kHz	
V _{LSEH}	OSC32_IN input pin high level voltage	-	0.7 V _{DD}	-	V _{DD}	V	
V _{LSEL}	OSC32_IN input pin low level voltage	-	V _{SS}	-	0.3 V _{DD}	V	
t _{w(LSEH)}	OSC32_IN high or low time	-	250	-	-	ns	

^{1.} Guaranteed by design.

Figure 23. Low-speed external clock source AC timing diagram



High-speed external clock generated from a crystal/ceramic resonator

The high-speed external (HSE) clock can be supplied with a 4 to 50 MHz crystal/ceramic resonator oscillator. All the information given in this paragraph are based on characterization results obtained with typical external components specified in *Table 36*. In the application, the resonator and the load capacitors have to be placed as close as possible to the oscillator pins in order to minimize output distortion and startup stabilization time. Refer to the crystal resonator manufacturer for more details on the resonator characteristics (frequency, package, accuracy).

Symbol	Parameter	Operating conditions ⁽²⁾	Min	Тур	Max	Unit
F	Oscillator frequency	-	4	-	50	MHz
R _F	Feedback resistor	-	-	200	-	kΩ
	HSE current consumption	During startup ⁽³⁾	-	-	4	
I _{DD(HSE)}		V_{DD} =3 V, Rm=30 Ω C_L =10 pF at 4 MHz	-	0.35	-	
		V_{DD} =3 V, Rm=30 Ω C_L =10 pF at 8 MHz	-	0.40	-	
		V_{DD} =3 V, Rm=30 Ω C_L =10 pF at 16 MHz	-	0.45	-	mA
		V_{DD} =3 V, Rm=30 Ω C_L =10 pF at 32 MHz	-	0.65	-	
		V_{DD} =3 V, Rm=30 Ω C_L =10 pF at 48 MHz	-	0.95 -		
Gm _{critmax}	Maximum critical crystal gm	Startup	-	-	1.5	mA/V
t _{SU} ⁽⁴⁾	Start-up time	V _{DD} is stabilized	-	2	-	ms

Table 36. 4-50 MHz HSE oscillator characteristics⁽¹⁾

- 1. Guaranteed by design.
- 2. Resonator characteristics given by the crystal/ceramic resonator manufacturer.
- 3. This consumption level occurs during the first 2/3 of the $t_{SU(HSE)}$ startup time.
- 4. t_{SU(HSE)} is the startup time measured from the moment it is enabled (by software) to a stabilized 8 MHz oscillation is reached. This value is measured for a standard crystal resonator and it can vary significantly with the crystal manufacturer.

For C_{L1} and C_{L2} , it is recommended to use high-quality external ceramic capacitors in the 5 pF to 25 pF range (typical), designed for high-frequency applications, and selected to match the requirements of the crystal or resonator (see *Figure 24*). C_{L1} and C_{L2} are usually the same size. The crystal manufacturer typically specifies a load capacitance which is the series combination of C_{L1} and C_{L2} . The PCB and MCU pin capacitance must be included (10 pF can be used as a rough estimate of the combined pin and board capacitance) when sizing C_{L1} and C_{L2} .

Note: For information on selecting the crystal, refer to application note AN2867 "Oscillator design guide for ST microcontrollers" available from the ST website www.st.com.



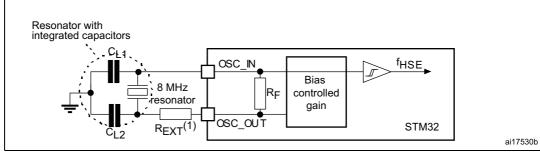


Figure 24. Typical application with an 8 MHz crystal

R_{EXT} value depends on the crystal characteristics.

Low-speed external clock generated from a crystal/ceramic resonator

The low-speed external (LSE) clock can be supplied with a 32.768 kHz crystal/ceramic resonator oscillator. All the information given in this paragraph are based on characterization results obtained with typical external components specified in *Table 37*. In the application, the resonator and the load capacitors have to be placed as close as possible to the oscillator pins in order to minimize output distortion and startup stabilization time. Refer to the crystal resonator manufacturer for more details on the resonator characteristics (frequency, package, accuracy).

lable 37. Low-speed external user clock characteristics						
rameter	Operating conditions ⁽²⁾	Min	Tvi			

Symbol	Parameter	Operating conditions ⁽²⁾	Min	Тур	Max	Unit	
F	Oscillator frequency	-	-	32.768	-	kHz	
I _{DD}	LSE current consumption	LSEDRV[1:0] = 00, Low drive capability	-	290	-	nA	
		LSEDRV[1:0] = 01, Medium Low drive capability	-	390	-		
		LSEDRV[1:0] = 10, Medium high drive capability	-	550	-		
		LSEDRV[1:0] = 11, High drive capability	-	900	-		
Gm _{critmax}	Maximum critical crystal gm	LSEDRV[1:0] = 00, Low drive capability	-	-	0.5		
		LSEDRV[1:0] = 01, Medium Low drive capability	-	-	0.75		
		LSEDRV[1:0] = 10, Medium high drive capability	-	-	1.7	μΑ/V	
		LSEDRV[1:0] = 11, High drive capability	-	-	2.7		
t _{SU} ⁽³⁾	Startup time	VDD is stabilized	-	2	-	s	

Guaranteed by design.

^{3.} t_{SU} is the startup time measured from the moment it is enabled (by software) to a stabilized 32.768k Hz oscillation is reached. This value is measured for a standard crystal resonator and it can vary significantly with the crystal manufacturer.



Refer to the note and caution paragraphs below the table, and to the application note AN2867 "Oscillator design guide for ST microcontrollers".

Note:

For information on selecting the crystal, refer to the application note AN2867 "Oscillator design guide for ST microcontrollers" available from the ST website www.st.com.

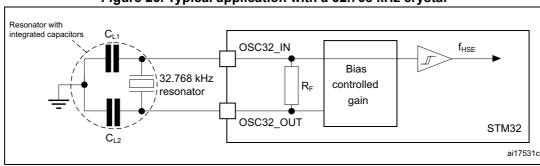


Figure 25. Typical application with a 32.768 kHz crystal

1. An external resistor is not required between OSC32_IN and OSC32_OUT and it is forbidden to add one.

6.3.11 Internal clock source characteristics

The parameters given in *Table 38* to *Table 40* are derived from tests performed under ambient temperature and V_{DD} supply voltage conditions summarized in *Table 13: General operating conditions*.

48 MHz high-speed internal RC oscillator (HSI48)

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
f _{HSI48}	HSI48 frequency	V _{DD} =3.3 V, TJ=30 °C	47.5 ⁽¹⁾	48	48.5 ⁽¹⁾	MHz
TRIM ⁽²⁾	USER trimming step	-	-	0.175	0.250	%
USER TRIM COVERAGE ⁽³⁾	USER TRIMMING coverage	± 32 steps	±4.70	±5.6	-	%
DuCy(HSI48) ⁽²⁾	Duty Cycle	-	45	-	55	%
ACCHSI48_REL ⁽³⁾	Accuracy of the HSI48 oscillator over temperature (factory calibrated)	T _J =-40 to 125 °C	-4.5	-	3.5	%
ACCHSI46_REL		T _J =-40 to 140 °C	-4.5	-	4	
$\Delta_{VDD}(HSI48)^{(2)(4)}$	HSI48 oscillator frequency drift with V _{DD} ⁽⁵⁾ (the reference is 3.3 V)	V _{DD} =3 to 3.6 V	-	0.025	0.05	%
Δ _{VDD} (H3146). // /		V _{DD} =1.62 V to 3.6 V	-	0.05	0.1	
t _{su(HSI48)} ⁽²⁾	HSI48 oscillator start-up time	-	-	2.1	4.0	μs
I _{DD(HSI48)} (2)	HSI48 oscillator power consumption	-	-	350	400	μA
N _T jitter ⁽²⁾	Next transition jitter Accumulated jitter on 28 cycles ⁽⁶⁾	-	-	± 0.15	-	ns
P _T jitter ⁽²⁾	Paired transition jitter Accumulated jitter on 56 cycles ⁽⁶⁾	-	-	± 0.25	-	ns

Table 38. HSI48 oscillator characteristics

Ty/

^{1.} Guaranteed by test in production.

^{2.} Guaranteed by design.

^{3.} Guaranteed by characterization results.

^{4.} $\Delta f_{HSI} = ACCHSI48_REL + \Delta_{VDD}$.

- 5. These values are obtained by using the formula: (Freq(3.6 V) Freq(3.0 V)) / Freq(3.0 V) or (Freq(3.6 V) Freq(1.62 V)) / Freq(1.62 V).
- 6. Jitter measurements are performed without clock source activated in parallel.

64 MHz high-speed internal RC oscillator (HSI)

Table 39. HSI oscillator characteristics⁽¹⁾

Symbol	Parameter	Conditions	Min	Тур	Max	Unit	
f _{HSI}	HSI frequency	V _{DD} =3.3 V, T _J =30 °C	63.7 ⁽²⁾	64	64.3 ⁽²⁾	MHz	
	HSI user trimming step	Trimming is not a multiple of 32	-	0.24	0.32		
TRIM		Trimming is 128, 256 and 384	-5.2	-1.8	-		
		Trimming is 64, 192, 320 and 448	-1.4	-0.8	-	%	
		Other trimming are a multiple of 32 (not including multiple of 64 and 128)	-0.6	-0.25	-		
DuCy(HSI)	Duty cycle	-	45	-	55	%	
Δ _{VDD (HSI)}	HSI oscillator frequency drift over V _{DD} (the reference is 3.3 V)	V _{DD} =1.62 to 3.6 V	-0.12	-	0.03	%	
	HSI oscillator frequency drift over	T _J =-20 to 105 °C	-1 ⁽³⁾	-	1 ⁽³⁾	21	
$\Delta_{TEMP(HSI)}$	temperature (the reference is 64 MHz)	T _J =-40 to T _J max °C	-2 ⁽³⁾	-	1 ⁽³⁾	%	
t _{su} (HSI)	HSI oscillator start-up time	-	-	1.4	2		
+ (HQI)	HSI oscillator stabilization time	at 1% of target frequency	-	4	8	μs	
t _{stab} (HSI)	noi osciliator stabilization time	at 5% of target frequency	-	-	4		
I _{DD} (HSI)	HSI oscillator power consumption -		-	300	400	μA	

^{1.} Guaranteed by design unless otherwise specified.

^{2.} Guaranteed by test in production.

^{3.} Guaranteed by characterization results.

4 MHz low-power internal RC oscillator (CSI)

Table 40. CSI oscillator characteristics⁽¹⁾

Symbol	Parameter	Conditions	Min	Тур	Max	Unit	
f _{CSI}	CSI frequency	V _{DD} =3.3 V, T _J =30 °C	3.96 ⁽²⁾	4	4.04 ⁽²⁾	MHz	
TRIM	CSI trimming step	Trimming is not a multiple of 16	-	0.40	0.75		
		Trimming is a multiple of 32	-4.75	-2.75	0.75	%	
	G I	Other trimming values not multiple of 16 (excluding multiple of 32)	-0.43	0.00	0.75	0.75	
DuCy(CSI)	Duty cycle	-	45	-	55	%	
A (CCI)	CSI oscillator frequency drift over	T _J = 0 to 85 °C	-3.7 ⁽³⁾	-	4.5 ⁽³⁾	%	
Δ _{TEMP} (CSI)	temperature	$T_J = -40 \text{ to } 125 ^{\circ}\text{C}$	-11 ⁽³⁾	-	7.5 ⁽³⁾	70	
Δ _{VDD} (CSI)	CSI oscillator frequency drift over V_{DD}	V _{DD} = 1.62 to 3.6 V	-0.06	-	0.06	%	
t _{su(CSI)}	CSI oscillator startup time	-	-	1	2	μs	
t _{stab(CSI)}	CSI oscillator stabilization time (to reach ± 3% of f _{CSI})	-	-	-	4	cycle	
I _{DD(CSI)}	CSI oscillator power consumption	-	-	23	30	μA	

^{1.} Guaranteed by design, unless otherwise specified.

Low-speed internal (LSI) RC oscillator

Table 41. LSI oscillator characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
	f _{LSI} LSI frequency	V _{DD} = 3.3 V, T _J = 25 °C	31.4 ⁽¹⁾	32	32.6 ⁽¹⁾	
f _{LSI}		$T_J = -40 \text{ to } 110 ^{\circ}\text{C},$ $V_{DD} = 1.62 \text{ to } 3.6 \text{ V}$	29.76 ⁽²⁾	-	33.6 ⁽²⁾	kHz
		$T_J = -40 \text{ to } 125 \text{ °C},$ $V_{DD} = 1.62 \text{ to } 3.6 \text{ V}$	29.4 ⁽²⁾	-	33.6 ⁽²⁾	
t _{su(LSI)} ⁽³⁾	LSI oscillator startup time	-	-	80	130	
t _{stab(LSI)} ⁽³⁾	LSI oscillator stabilization time (5% of final value)	-	-	120	170	μs
I _{DD(LSI)} ⁽³⁾	LSI oscillator power consumption -		-	130	280	nA

^{1.} Guaranteed by test in production.

^{2.} Guaranteed by test in production.

^{3.} Guaranteed by characterization results.

^{2.} Guaranteed by characterization results.

^{3.} Guaranteed by design.

6.3.12 PLL characteristics

The parameters given in *Table 42*, *Table 45* are derived from tests performed under temperature and V_{DD} supply voltage conditions summarized in *Table 13: General operating conditions*.

Table 42. PLL1 characteristics (wide VCO frequency range)⁽¹⁾

Symbol	Parameter	Condition	ons	Min	Тур	Max	Unit	
f	PLL input clock	-		2	-	16	MHz	
f _{PLL_IN}	PLL input clock duty cycle	-		10	-	90	%	
		VOS0		1.5	-	550 ⁽²⁾		
f _{PLL_P_OUT}	PLL multiplier output clock P	VOS	1	1.5	-	400 ⁽²⁾		
'PLL_P_001	LE manipher output Glock i	VOS2	2	1.5	-	300 ⁽²⁾	MHz	
		VOS	3	1.5	-	170 ⁽²⁾		
f _{VCO_OUT}	PLL VCO output	-		192	-	836 ⁽³⁾		
		Normal mode		15	50	150 ⁽³⁾		
t _{LOCK}	PLL lock time	Sigma-delta mod 8 MHz)	e (CKIN ≥	25	65	170	μs	
			f _{VCO_OUT} = 192 MHz	-	51	-		
		(4)		f _{VCO_OUT} = 400 MHz	-	19	ı	
		yde-to-cyde jitter	f _{VCO_OUT} = 560 MHz	-	10	-		
		f _{PLL_OUT} = f _{VCO_OUT} /100	f _{VCO_OUT} = 800 MHz	-	9	-		
			f _{VCO_OUT} = 192 MHz	-	38	-		
	Period jitter		f _{VCO_OUT} = 560 MHz	-	8	ı		
Jitter			f _{VCO_OUT} = 800 MHz	-	7	i	ps	
			f _{VCO_OUT} = 192 MHz	-	0.15	ı		
		Normal mode (CKIN = 2 MHz)	f _{VCO_OUT} = 400 MHz	-	0.14	ı		
	Long term jitter		f _{VCO_OUT} = 832 MHz	-	0.16	ı		
		Sigma-delta mode (CKIN = 16 MHz)		f _{VCO_OUT} = 192 MHz	-	0.17	-	
			f _{VCO_OUT} = 500 MHz	-	0.08	-		
		,	f _{VCO_OUT} = 836 MHz	-	0.06	-		

Table 42. PLL1 characteristics (wide VCO frequency range)⁽¹⁾ (continued)

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
	f _{VCO_OUT} = 560 MHz	V_{DDA}	530	557	670		
I		560 MHz	V _{CORE}	1190	1285	6300	μA
IDD(PLL)	PLL power consumption	f _{VCO OUT} =	V_{DDA}	260	286	513	μΛ
		192 MHz	V _{CORE}	309	377	5700	

- 1. Guaranteed by design unless otherwise specified.
- 2. This value must be limited to the maximum frequency due to the product limitation.
- 3. Guaranteed by characterization results.
- 4. Integer mode only.

Table 43. PLL1 characteristics (medium VCO frequency range)⁽¹⁾

Symbol	Parameter	Cond	itions	Min	Тур	Max	Unit
£	PLL input clock		-	1	-	2	MHz
f _{PLL_IN}	PLL input clock duty cycle		-	10	-	90	%
		VC)S0	1.17	-	210	
£	Did modification assistants along D.O.D.	VC)S1	1.17	-	210	
f _{PLL_OUT}	PLL multiplier output clock P, Q, R	VC)S2	1.17	-	210	MHz
		VC)S3	1.17	-	200	
f _{VCO_OUT}	PLL VCO output	-		150	-	420	
4	DL Look time	Norma	l mode	-	60 ⁽²⁾	100 ⁽²⁾	
t _{LOCK}	PLL lock time	Sigma-delta mode		fo	forbidden		μs
	Cycle-to-cycle jitter ⁽³⁾		f _{VCO_OUT} = 150 MHz	-	145	-	
			f _{VCO_OUT} = 300 MHz	-	91	-	±20
			f _{VCO_OUT} = 400 MHz	-	64	-	±ps
Jitter			f _{VCO_OUT} = 420 MHz	-	63	-	
	David iittar	f _{PLL_OUT} =	f _{VCO_OUT} = 150 MHz	-	55	-	
	Period jitter	50 MHz	f _{VCO_OUT} = 400 MHz	-	30	-	±-ps
	Long term jitter	Normal mode	f _{VCO_OUT} = 400 MHz	-	±0.3	-	%
		f _{VCO_OUT} =	VDD	-	440	1150	
I/DLL)	DLL newer consumption on V	420 MHz	VCORE	-	530	-	μA
I(PLL)	PLL power consumption on V _{DD}	f _{VCO_OUT} = 150 MHz	VDD	-	180	500	
			VCORE	-	200	-	

- 1. Guaranteed by design unless otherwise specified.
- 2. Guaranteed by characterization results.
- 3. Integer mode only.

Table 44. PLL2 and PLL3 characteristics (wide VCO frequency range)⁽¹⁾

Symbol	Parameter	Cond	itions	Min	Тур	Max	Unit
f	PLL input clock	-	-	2	-	16	MHz
f _{PLL_IN}	PLL input clock duty cycle	-	-	10	-	90	%
		VO)S0	1.5	-	550 ⁽²⁾	
£	PLL multiplier output clock P,	VO)S1	1.5	-	400 ⁽²⁾	
f _{PLL_OUT}	Q, R	VO)S2	1.5	-	300 ⁽²⁾	MHz
		VOS3		1.5	-	170 ⁽²⁾	
f _{VCO_OUT}	PLL VCO output	-	-	192	-	960 ⁽³⁾	
		Norma	I mode	-	50	150 ⁽³⁾	
t _{LOCK}	PLL lock time		Sigma-delta mode (f _{PLL_IN} ≥ 8 MHz)		58	166 ⁽³⁾	μs
		f _{VCO_OUT} =	= 192 MHz	-	134	-	
	Cycle to evelo iitter(4)	f _{VCO_OUT} =	= 200 MHz	-	134	-	Lang
	Cycle-to-cycle jitter ⁽⁴⁾	f _{VCO_OUT} = 400 MHz		-	76	-	±ps
		f _{VCO_OUT} = 800 MHz		-	39	-	
		Normal mode (f _{PLL_IN} = 2 MHz)	f _{VCO_OUT} = 560 MHz	-	±0.2	-	
Jitter	Long torm litter	Normal mode (f _{PLL_IN} = 16 MHz)	f _{VCO_OUT} = 560 MHz	-	±0.8	-	%
	Long term jitter	Sigma-delta mode (f _{PLL_IN} = 2 MHz)	f _{VCO_OUT} = 560 MHz	-	±0.2	-	76
		Sigma-delta mode (f _{PLL_IN} = 16 MHz)	f _{VCO_OUT} = 560 MHz	-	±0.8	-	
		f _{VCO_OUT} =	V_{DD}	-	590	1500	
(3)	PLL power consumption	836 MHz	V _{CORE}	-	720	-	^
I _{DD(PLL)} ⁽³⁾	fvco ou	f _{VCO_OUT} =	V_{DD}	-	180	600	μA
		192 MHz	V _{CORE}	ı	280	-	

^{1.} Guaranteed by design unless otherwise specified.

^{2.} This value must be limited to the maximum frequency due to the product limitation.

- 3. Guaranteed by characterization results.
- 4. Integer mode only.

Table 45. PLL2 and PLL3 characteristics (medium VCO frequency range)⁽¹⁾

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
f	PLL input clock		-	1	-	2	MHz
f _{PLL_IN}	PLL input clock duty cycle		-		-	90	%
		V	OS0	1.17	-	210	MHz
£	PLL multiplier output clock	V	OS1	1.17	-	210	-
f _{PLL_OUT}	P, Q, R	V	OS2	1.17	-	210	-
		V	OS3	1.17	-	200	-
f _{VCO_OUT}	PLL VCO output		-	150	-	420	-
t. a au	PLL lock time	Norma	al mode	-	60	100 ⁽²⁾	
t _{LOCK}	PLL lock time	Sigma-d	elta mode		forbidden		μs
	Cycle-to-cycle jitter ⁽³⁾	f _{VCO_OUT} = 150 MHz		-	145	-	
		f _{VCO_OUT} = 200 MHz		-	91	-	±ps
	Cycle-to-cycle jitter	f _{VCO_OUT} = 400 MHz		-	64	-	±μs
		f _{VCO_OUT} = 420 MHz		-	63	-	
Jitter	Period jitter	f _{PLL_OUT} = 50 MHz	f _{VCO_OUT} = 150 MHz	-	55	-	±ps
	-	f _{VCO_OUT}	= 400 MHz	-	30	-	-
	Long term jitter	Normal mode	f _{VCO_OUT} = 400 MHz	-	±0.3	-	%
		f _{VCO OUT} =	V _{DD}	-	440	1150	
	PLL power consumption on	420 MHz	V _{CORE}	-	530	-	^
I _{DD(PLL)}	V_{DD}	f _{VCO_OUT} =	V_{DD}	-	180	500	μA
		150 MHz	V _{CORE}	-	200	-	

^{1.} Guaranteed by design unless otherwise specified.

^{2.} Guaranteed by characterization results.

^{3.} Integer mode only.

6.3.13 Memory characteristics

Flash memory

The characteristics are given at T_J = -40 to 125 $^{\circ}$ C unless otherwise specified.

The devices are shipped to customers with the Flash memory erased.

Table 46. Flash memory characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
	0 1	Write / Erase 8-bit mode	-	6.5	-	
		Write / Erase 16-bit mode	-	11.5	-	mA
IDD	Supply current	Write / Erase 32-bit mode	-	20	-	IIIA
		Write / Erase 64-bit mode	-	35	-	

Table 47. Flash memory programming

Symbol	Parameter	Conditions	Min ⁽¹⁾	Тур	Max ⁽¹⁾	Unit
	Word (266 bits) programming	Program/erase parallelism x 8	-	290	580 ⁽²⁾	
+		Program/erase parallelism x 16	-	180	360	116
t _{prog}	time	Program/erase parallelism x 32	-	130	260	μs
		Program/erase parallelism x 64	-	100	200	
		Program/erase parallelism x 8	-	2	4	
t _{ERASE}		Program/erase parallelism x 16	-	1.8	3.6	
		Program/erase parallelism x 32	ı			
		Program/erase parallelism x 8	-	3	26	s
+	Mass erase time (1 Mbyte)	Program/erase parallelism x 16	-	8	16	
t _{ME}	wass erase time (1 wbyte)	Program/erase parallelism x 32	-	6	12	
		Program/erase parallelism x 64	-	5	10	
		Program parallelism x 8				
V_{prog}	Programming voltage	Program parallelism x 16	1.62	-	3.6	V
		Program parallelism x 32				V
		Program parallelism x 64	1.8	-	3.6	

^{1.} Guaranteed by characterization results.

Table 48. Flash memory endurance and data retention

Symbol	Parameter	Conditions	Min ⁽¹⁾	Unit
N_{END}	Endurance	$T_{\rm J}$ = -40 to +125 °C	10	kcycles
+	Data retention	1 kcycle at T _A = 85 °C	30	Years
^I RET		10 kcycles at T _A = 55 °C	20	leais



^{2.} The maximum programming time is measured after 10K erase operations.

1. Guaranteed by characterization results.

6.3.14 EMC characteristics

Susceptibility tests are performed on a sample basis during device characterization.

Functional EMS (electromagnetic susceptibility)

While a simple application is executed on the device (toggling 2 LEDs through I/O ports). the device is stressed by two electromagnetic events until a failure occurs. The failure is indicated by the LEDs:

- Electrostatic discharge (ESD) (positive and negative) is applied to all device pins until a functional disturbance occurs. This test is compliant with the IEC 61000-4-2 standard.
- FTB: A burst of fast transient voltage (positive and negative) is applied to V_{DD} and V_{SS} through a 100 pF capacitor, until a functional disturbance occurs. This test is compliant with the IEC 61000-4-4 standard.

A device reset allows normal operations to be resumed.

The test results are given in *Table 49*. They are based on the EMS levels and classes defined in application note AN1709 "*EMC design guide for STM8, STM32 and Legacy MCUs*".

Symbol	Parameter	Conditions	Level/ Class
V _{FESD}	Voltage limits to be applied on any I/O pin to induce a functional disturbance	V_{DD} = 3.3 V, T_{A} = 25 °C, LQFP176, conforming to IEC 61000-4-2	3B
V _{FTB}	Fast transient voltage burst limits to be applied through 100 pF on $V_{\rm DD}$ and $V_{\rm SS}$ pins to induce a functional disturbance	V_{DD} = 3.3 V, T_{A} = 25 °C, LQFP176, conforming to IEC 61000-4-4	5A

Table 49. EMS characteristics

As a consequence, it is recommended to add a serial resistor (1 $k\Omega$) located as close as possible to the MCU to the pins exposed to noise (connected to tracks longer than 50 mm on PCB).

Designing hardened software to avoid noise problems

EMC characterization and optimization are performed at component level with a typical application environment and simplified MCU software. It should be noted that good EMC performance is highly dependent on the user application and the software in particular.

Therefore it is recommended that the user applies EMC software optimization and prequalification tests in relation with the EMC level requested for his application.

Software recommendations

The software flowchart must include the management of runaway conditions such as:

- Corrupted program counter
- Unexpected reset
- Critical Data corruption (control registers...)

Prequalification trials

Most of the common failures (unexpected reset and program counter corruption) can be reproduced by manually forcing a low state on the NRST pin or the Oscillator pins for 1 second.

To complete these trials, ESD stress can be applied directly on the device, over the range of specification values. When unexpected behavior is detected, the software can be hardened to prevent unrecoverable errors occurring (see application note AN1015 "Software techniques for improving microcontrollers EMC performance").

Electromagnetic Interference (EMI)

The electromagnetic field emitted by the device are monitored while a simple application, executing EEMBC code, is running. This emission test is compliant with SAE IEC61967-2 standard which specifies the test board and the pin loading.

Max vs. Monitored [f_{HSE}/f_{CPU}] Symbol **Parameter** Conditions Unit frequency band 8/550 MHz 0.1 to 30 MHz 14 30 to 130 MHz 20 $dB\mu V$ V_{DD} = 3.6 V, T_A = 25 °C, LQFP176 package, $\mathsf{S}_{\mathsf{EMI}}$ Peak level 130 MHz to 1 GHz 27 conforming to IEC61967-2 1 GHz to 2 GHz 17 EMI Level 4

Table 50. EMI characteristics

6.3.15 Absolute maximum ratings (electrical sensitivity)

Based on three different tests (ESD, LU) using specific measurement methods, the device is stressed in order to determine its performance in terms of electrical sensitivity.

Electrostatic discharge (ESD)

Electrostatic discharges (a positive then a negative pulse) are applied to the pins of each sample according to each pin combination. This test conforms to the ANSI/ESDA/JEDEC JS-001 and ANSI/ESDA/JEDEC JS-002 standards.

Table 31. LOD absolute maximum ratings						
Symbol	Ratings	Conditions	Packages	Class	Maximum value ⁽¹⁾	Unit
V _{ESD(HBM)}	Electrostatic discharge voltage (human body model)	T _A = 25 °C conforming to ANSI/ESDA/JEDEC JS-001	All packages	1C	1000 ⁽²⁾	
V	Electrostatic discharge voltage (charge device	T _A = +25 °C conforming to	All LQFP packages	C1	250	٧
V _{ESD(CDM)}	model)	ANSI/ESDA/JEDEC JS-002	All BGA and WLCSP packages	C2a	500	

Table 51, ESD absolute maximum ratings

1. Guaranteed by characterization results.



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2. Excluding V_{FBSMPS}, the maximum value is 2000 V.

Static latchup

Two complementary static tests are required on six parts to assess the latchup performance:

- A supply overvoltage is applied to each power supply pin
- A current injection is applied to each input, output and configurable I/O pin

These tests are compliant with JESD78 IC latchup standard.

Table 52. Electrical sensitivities

Symbol	Parameter	Conditions	Class	
LU	Static latchup class	Conforming to JESD78, $T_J = T_{JMax}$	II level A	

6.3.16 I/O current injection characteristics

As a general rule, a current injection to the I/O pins, due to external voltage below V_{SS} or above V_{DD} (for standard, 3.3 V-capable I/O pins) should be avoided during the normal product operation. However, in order to give an indication of the robustness of the microcontroller in cases when an abnormal injection accidentally happens, susceptibility tests are performed on a sample basis during the device characterization.

Functional susceptibility to I/O current injection

While a simple application is executed on the device, the device is stressed by injecting current into the I/O pins programmed in floating input mode. While current is injected into the I/O pin, one at a time, the device is checked for functional failures.

The failure is indicated by an out of range parameter: ADC error above a certain limit (higher than 5 LSB TUE), out of conventional limits of induced leakage current on adjacent pins (out of $-5 \mu A/+0 \mu A$ range), or other functional failure (for example reset, oscillator frequency deviation).

The following tables are the compilation of the SIC1/SIC2 and functional ESD results.

Negative induced A negative induced leakage current is caused by negative injection and positive induced leakage current by positive injection.

Table 53. I/O current injection susceptibility⁽¹⁾

		Functional s		
Symbol	Description	Negative injection	Positive injection	Unit
	PA12, PE8	5	0	
	PC4, PE12, PF15, PH0	0	NA	
I _{INJ}	PA0, PA0_C, PA1, PA1_C, PC2, PC2_C, PC3, PC3_C, PA4, PA5, PE7, PG1, PH4, PH5, BOOT0	0	0	mA
	All other I/Os	5	NA	

1. Guaranteed by characterization results.

6.3.17 I/O port characteristics

General input/output characteristics

Unless otherwise specified, the parameters given in *Table 54: I/O static characteristics* are derived from tests performed under the conditions summarized in *Table 13: General operating conditions*. All I/Os are CMOS and TTL compliant (except for BOOT0).

Note:

For information on GPIO configuration, refer to application note AN4899 "STM32 GPIO configuration for hardware settings and low-power consumption" available from the ST website www.st.com.

Table 54. I/O static characteristics

Symbol	Parameter	Condition	Min	Тур	Max	Unit
	I/O input low level voltage except BOOT0		-	-	0.3V _{DD} ⁽¹⁾	
V_{IL}	I/O input low level voltage except BOOT0	1.62 V <v<sub>DD<3.6 V</v<sub>	-	-	0.4V _{DD} =0.1	٧
	BOOT0 I/O input low level voltage		-	-	0.19V _{DD} +0.1	
	I/O input high level voltage except BOOT0		0.7V _{DD} ⁽¹⁾	-	-	
V_{IH}	I/O input high level voltage except BOOT0	1.62 V <v<sub>DD<3.6 V</v<sub>	0.47V _{DD} + 0.25 ⁽²⁾	-	-	٧
	BOOT0 I/O input high level voltage	·	0.17V _{DD} + 0.6 ⁽²⁾	-	-	
V _{HYS} ⁽²⁾	TT_xx, FT_xxx and NRST I/O input hysteresis	1.62 V< V _{DD} <3.6 V	-	250	-	mV
	BOOT0 I/O input hysteresis]	-	200	-	
		$0 < V_{IN} \le Max(V_{DDXXX})^{(8)}$	-	-	+/-250	
	FT_xx Input leakage current ⁽²⁾	$Max(V_{DDXXX}) < V_{IN} \le 5.5 \text{ V}$	-	-	1500	
		$0 < V_{IN} \le Max(V_{DDXXX})^{(8)}$	-	-	+/- 350	
I _{leak} ⁽³⁾	FT_u IO	$Max(V_{DDXXX}) < V_{IN} \le 5.5 \text{ V}$	-	-	5000 ⁽⁶⁾	nA
	TT_xx Input leakage current	$0 < V_{IN} \le Max(V_{DDXXX})^{(8)}$	-	-	+/-250	
	VPP (BOOT0 alternate	0< V _{IN} ≤ V _{DD}	-	-	15	
	function)	V _{DD} < V _{IN} ≤ 9 V			35	
R _{PU}	Weak pull-up equivalent resistor ⁽⁷⁾	V _{IN} =V _{SS}	30	40	50	kΩ
R _{PD}	Weak pull-down equivalent resistor ⁽⁷⁾	V _{IN} =V _{DD} ⁽⁸⁾	30	40	50	, v77
C _{IO}	I/O pin capacitance	-	-	5	-	pF



- 1. Compliant with CMOS requirements.
- 2. Guaranteed by design.
- 3. This parameter represents the pad leakage of the I/O itself. The total product pad leakage is provided by the following formula: $I_{Total_leak_max} = 10 \ \mu A + [number of I/Os where V_{IN}]$ is applied on the pad] $_x \ I_{lkg(Max)}$.
- 4. All FT_xx IO except FT_lu, FT_u and PC3.
- 5. V_{IN} must be less than Max(VDDXXX) + 3.6 V.
- To sustain a voltage higher than MIN(V_{DD}, V_{DDA}, V_{DD33USB}) +0.3 V, the internal pull-up and pull-down resistors must be disabled.
- The pull-up and pull-down resistors are designed with a true resistance in series with a switchable PMOS/NMOS. This PMOS/NMOS contribution to the series resistance is minimal (~10% order).
- 8. Max(VDDXXX) is the maximum value of all the I/O supplies.

All I/Os are CMOS and TTL compliant (no software configuration required). Their characteristics cover more than the strict CMOS-technology or TTL parameters. The coverage of these requirements for FT I/Os is shown in *Figure 26*.

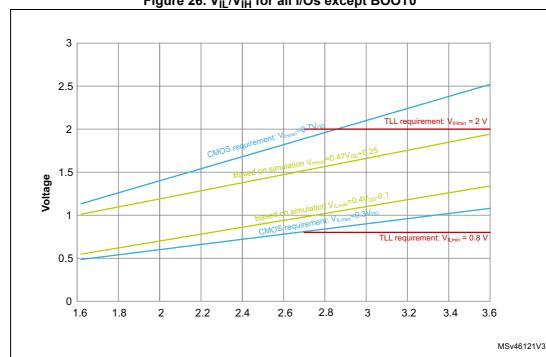


Figure 26. V_{IL}/V_{IH} for all I/Os except BOOT0

Output driving current

The GPIOs (general purpose input/outputs) can sink or source up to ± 8 mA, and sink or source up to ± 20 mA (with a relaxed V_{OL}/V_{OH}).

In the user application, the number of I/O pins which can drive current must be limited to respect the absolute maximum rating specified in *Section 6.2*. In particular:

- The sum of the currents sourced by all the I/Os on V_{DD} , plus the maximum Run consumption of the MCU sourced on V_{DD} , cannot exceed the absolute maximum rating ΣI_{VDD} (see *Table 11*).
- The sum of the currents sunk by all the I/Os on V_{SS} plus the maximum Run consumption of the MCU sunk on V_{SS} cannot exceed the absolute maximum rating ΣI_{VSS} (see *Table 11*).



Output voltage levels

Unless otherwise specified, the parameters given in *Table 55: Output voltage characteristics* for all I/Os except PC13, PC14 and PC15 and *Table 56: Output voltage characteristics* for PC13, PC14 and PC15 are derived from tests performed under ambient temperature and V_{DD} supply voltage conditions summarized in *Table 13: General operating conditions*. All I/Os are CMOS and TTL compliant.

Table 55. Output voltage characteristics for all I/Os except PC13, PC14 and PC15⁽¹⁾

Symbol	Parameter	Conditions ⁽³⁾	Min	Max	Unit
V _{OL}	Output low level voltage	CMOS port ⁽²⁾ $I_{IO} = 8 \text{ mA}$ $2.7 \text{ V} \leq V_{DD} \leq 3.6 \text{ V}$	-	0.4	
V _{OH}	Output high level voltage	CMOS port ⁽²⁾ $I_{IO} = -8 \text{ mA}$ $2.7 \text{ V} \leq V_{DD} \leq 3.6 \text{ V}$	V _{DD} -0.4	-	
V _{OL} ⁽³⁾	Output low level voltage	TTL port ⁽²⁾ $I_{IO} = 8 \text{ mA}$ $2.7 \text{ V} \leq V_{DD} \leq 3.6 \text{ V}$	-	0.4	
V _{OH} ⁽³⁾	Output high level voltage	TTL port ⁽²⁾ $I_{IO} = -8 \text{ mA}$ $2.7 \text{ V} \leq \text{V}_{DD} \leq 3.6 \text{ V}$	2.4	-	
V _{OL} ⁽³⁾	Output low level voltage	I _{IO} = 20 mA 2.7 V≤ V _{DD} ≤3.6 V	-	1.3	V
V _{OH} ⁽³⁾	Output high level voltage	I _{IO} = -20 mA 2.7 V≤ V _{DD} ≤3.6 V	V _{DD} -1.3	-	
V _{OL} ⁽³⁾	Output low level voltage	I _{IO} = 4 mA 1.62 V≤ V _{DD} ≤3.6 V	-	0.4	
V _{OH} ⁽³⁾	Output high level voltage	I _{IO} = -4 mA 1.62 V≤V _{DD} <3.6 V	V _{DD} 0.4	-	
V _{OLFM+} ⁽³⁾	Output low level voltage for an FTf	I _{IO} = 20 mA 2.3 V≤ V _{DD} ≤3.6 V	-	0.4	
VOLFM+`°′	I/O pin in FM+ mode	I _{IO} = 10 mA 1.62 V≤ V _{DD} ≤3.6 V	-	0.4	

The IIO current sourced or sunk by the device must always respect the absolute maximum rating specified in Table 10:
 Voltage characteristics, and the sum of the currents sourced or sunk by all the I/Os (I/O ports and control pins) must always respect the absolute maximum ratings ΣIIO.

^{2.} TTL and CMOS outputs are compatible with JEDEC standards JESD36 and JESD52.

^{3.} Guaranteed by design.

Table 56. Output voltage characteristics for PC13, PC14 and PC15⁽¹⁾

Symbol	Parameter	Conditions ⁽³⁾	Min	Max	Unit
V _{OL}	Output low level voltage	CMOS port ⁽²⁾ $I_{IO} = 3 \text{ mA}$ $2.7 \text{ V} \leq V_{DD} \leq 3.6 \text{ V}$	-	0.4	
V _{OH}	Output high level voltage	CMOS port ⁽²⁾ $I_{IO} = -3 \text{ mA}$ $2.7 \text{ V} \leq \text{V}_{DD} \leq 3.6 \text{ V}$	V _{DD} -0.4	-	
V _{OL} ⁽³⁾	Output low level voltage	TTL port ⁽²⁾ $I_{IO} = 3 \text{ mA}$ $2.7 \text{ V} \leq V_{DD} \leq 3.6 \text{ V}$	-	0.4	V
V _{OH} ⁽²⁾	Output high level voltage	TTL port ⁽²⁾ $I_{IO} = -3 \text{ mA}$ $2.7 \text{ V} \leq \text{V}_{DD} \leq 3.6 \text{ V}$	2.4	-	
V _{OL} ⁽²⁾	Output low level voltage	I _{IO} = 1.5 mA 1.62 V≤ V _{DD} ≤3.6 V	-	0.4	
V _{OH} ⁽²⁾	Output high level voltage	$I_{IO} = -1.5 \text{ mA}$ 1.62 V≤ V _{DD} ≤3.6 V	V _{DD} -0.4	-	

The IIO current sourced or sunk by the device must always respect the absolute maximum rating specified in Table 10:
 Voltage characteristics, and the sum of the currents sourced or sunk by all the I/Os (I/O ports and control pins) must always respect the absolute maximum ratings ΣIIO.

^{2.} TTL and CMOS outputs are compatible with JEDEC standards JESD36 and JESD52.

^{3.} Guaranteed by design.

Output buffer timing characteristics (HSLV option disabled)

The HSLV bit of SYSCFG_CCCSR register can be used to optimize the I/O speed when the product voltage is below 2.7 V.

Table 57. Output timing characteristics (HSLV OFF)⁽¹⁾

Speed	Symbol	Parameter	conditions	Min	Max	Unit
			C=50 pF, 2.7 V≤ V _{DD} ≤3.6 V	-	12	
			C=50 pF, 1.62 V≤V _{DD} ≤2.7 V	-	3	
	F _{max} ⁽²⁾	Maximum fraguanay	C=30 pF, 2.7 V≤V _{DD} ≤3.6 V	-	12	MHz
	「max`′	Maximum frequency	C=30 pF, 1.62 V≤V _{DD} ≤2.7 V	-	3	IVITZ
			C=10 pF, 2.7 V≤V _{DD} ≤3.6 V	-	16	
00			C=10 pF, 1.62 V≤V _{DD} ≤2.7 V	-	4	
00			C=50 pF, 2.7 V≤ V _{DD} ≤3.6 V	-	16.6	
			C=50 pF, 1.62 V≤V _{DD} ≤2.7 V	-	33.3	
	$t_r/t_f^{(3)}$	Output high to low level fall time and output low	C=30 pF, 2.7 V≤V _{DD} ≤3.6 V	-	13.3	ne
	لر/ للأ ^ر ٢	to high level rise time	C=30 pF, 1.62 V≤V _{DD} ≤2.7 V	-	25	ns
			C=10 pF, 2.7 V≤V _{DD} ≤3.6 V	-	10	
			C=10 pF, 1.62 V≤V _{DD} ≤2.7 V	-	20	
			C=50 pF, 2.7 V≤ V _{DD} ≤3.6 V	-	60	
			C=50 pF, 1.62 V≤V _{DD} ≤2.7 V	-	15	
	(2) Navisso	Maximum frequency	C=30 pF, 2.7 V≤V _{DD} ≤3.6 V	-	80	MHz
	F _{max} ⁽²⁾	waximum frequency	C=30 pF, 1.62 V≤V _{DD} ≤2.7 V	-	15	IVITZ
			C=10 pF, 2.7 V≤V _{DD} ≤3.6 V	-	110	
01			C=10 pF, 1.62 V≤V _{DD} ≤2.7 V	-	20	
01			C=50 pF, 2.7 V≤ V _{DD} ≤3.6 V	-	5.2	
			C=50 pF, 1.62 V≤V _{DD} ≤2.7 V	-	10	
	t _r /t _f (3)	Output high to low level	C=30 pF, 2.7 V≤V _{DD} ≤3.6 V	-	4.2	no
	ا لرالخ''	fall time and output low to high level rise time	C=30 pF, 1.62 V≤V _{DD} ≤2.7 V	-	7.5	ns
			C=10 pF, 2.7 V≤V _{DD} ≤3.6 V	-	2.8	
			C=10 pF, 1.62 V≤V _{DD} ≤2.7 V	-	5.2	

Table 57. Output timing characteristics (HSLV OFF)⁽¹⁾ (continued)

Speed	Symbol	Parameter	conditions	Min	Max	Unit
			C=50 pF, 2.7 V≤V _{DD} ≤3.6 V ⁽⁴⁾	-	85	
			C=50 pF, 1.62 V≤V _{DD} ≤2.7 V ⁽⁴⁾	-	35	
	F (2)	Maximum fra accorde	C=30 pF, 2.7 V≤V _{DD} ≤3.6 V ⁽⁴⁾	-	110	
	F _{max} ⁽²⁾	Maximum frequency	C=30 pF, 1.62 V≤V _{DD} ≤2.7 V ⁽⁴⁾	-	40	MHz
			C=10 pF, 2.7 V≤V _{DD} ≤3.6 V ⁽⁴⁾	-	166	
10			C=10 pF, 1.62 V≤V _{DD} ≤2.7 V ⁽⁴⁾	-	100	
10			C=50 pF, 2.7 V≤V _{DD} ≤3.6 V ⁽⁴⁾	-	3.8	
			C=50 pF, 1.62 V≤V _{DD} ≤2.7 V ⁽⁴⁾	-	6.9	
	t _r /t _f (3)	Output high to low level fall time and output low	C=30 pF, 2.7 V≤V _{DD} ≤3.6 V ⁽⁴⁾	-	2.8	ne
	l _r /lf` ′	to high level rise time	C=30 pF, 1.62 V≤V _{DD} ≤2.7 V ⁽⁴⁾	-	5.2	ns
			C=10 pF, 2.7 V≤V _{DD} ≤3.6 V ⁽⁴⁾	-	1.8	
			C=10 pF, 1.62 V≤V _{DD} ≤2.7 V ^v	-	3.3	
			C=50 pF, 2.7 V≤V _{DD} ≤3.6 V ^V	-	100	
			C=50 pF, 1.62 V≤V _{DD} ≤2.7 V ⁽⁴⁾	-	50	
	F _{max} ⁽²⁾	Maximum frequency	C=30 pF, 2.7 V≤V _{DD} ≤3.6 V ^V	-	133	MHz
	「max`	Maximum frequency	C=30 pF, 1.62 V≤V _{DD} ≤2.7 V ⁽⁴⁾	-	66	IVII IZ
			C=10 pF, 2.7 V≤V _{DD} ≤3.6 V ⁽⁴⁾	-	220	
11			C=10 pF, 1.62 V≤V _{DD} ≤2.7 V ⁽⁴⁾	-	85	
''			C=50 pF, 2.7 V≤V _{DD} ≤3.6 V ⁽⁴⁾	-	3.3	
			C=50 pF, 1.62 V≤V _{DD} ≤2.7 V ⁽⁴⁾	-	6.6	
	t _r /t _f (3)	Output high to low level fall time and output low	C=30 pF, 2.7 V≤V _{DD} ≤3.6 V ⁽⁴⁾	-	2.4	1
	\r'\f` '	to high level rise time	C=30 pF, 1.62 V≤V _{DD} ≤2.7 V ⁽⁴⁾	-	4.5	ns
			C=10 pF, 2.7 V≤V _{DD} ≤3.6 V ⁽⁴⁾	-	1.5	=
			C=10 pF, 1.62 V≤V _{DD} ≤2.7 V ⁽⁴⁾	-	2.7	

^{1.} Guaranteed by design.

- 3. The fall and rise times are defined between 90% and 10% and between 10% and 90% of the output waveform, respectively.
- 4. Compensation system enabled.

^{2.} The maximum frequency is defined with the following conditions: $(t_r+t_f) \le 2/3$ T Skew $\le 1/20$ T 45%<Duty cycle<55%

Output buffer timing characteristics (HSLV option enabled)

Table 58. Output timing characteristics (HSLV ON)⁽¹⁾

Speed	Symbol	Parameter	conditions	Min	Max	Unit
			C=50 pF, 1.62 V≤V _{DD} ≤2.7 V	-	10	
	F _{max} ⁽²⁾	F _{max} ⁽²⁾ Maximum frequency	C=30 pF, 1.62 V≤V _{DD} ≤2.7 V	-	10	MHz
00			C=10 pF, 1.62 V≤V _{DD} ≤2.7 V	-	10	
00		Output high to low level	C=50 pF, 1.62 V≤V _{DD} ≤2.7 V	-	11	
	$t_r/t_f^{(3)}$	fall time and output low	C=30 pF, 1.62 V≤V _{DD} ≤2.7 V	-	9	ns
		to high level rise time	C=10 pF, 1.62 V≤V _{DD} ≤2.7 V	-	6.6	
			C=50 pF, 1.62 V≤V _{DD} ≤2.7 V	-	50	
	F _{max} ⁽²⁾	Maximum frequency	C=30 pF, 1.62 V≤V _{DD} ≤2.7 V	-	58	MHz
01		C=10 pF, 1.62 V≤V _{DD} ≤2.7 V	-	66		
01		Output high to low level	C=50 pF, 1.62 V≤V _{DD} ≤2.7 V	-	6.6	
	$t_r/t_f^{(3)}$	$t_r/t_f^{(3)}$ fall time and output low to high level rise time	C=30 pF, 1.62 V≤V _{DD} ≤2.7 V	-	4.8	ns
			C=10 pF, 1.62 V≤V _{DD} ≤2.7 V	-	3	
		F _{max} ⁽²⁾ Maximum frequency	C=50 pF, 1.62 V≤V _{DD} ≤2.7 V ⁽⁴⁾	-	55	
	F _{max} ⁽²⁾		C=30 pF, 1.62 V≤V _{DD} ≤2.7 V ⁽⁴⁾	-	80	MHz
10			C=10 pF, 1.62 V≤V _{DD} ≤2.7 V ⁽⁴⁾	-	133	
10		Output high to low level	C=30 pF, 1.62 V≤V _{DD} ≤2.7 V ⁽⁴⁾	-	5.8	
	$t_r/t_f^{(3)}$	fall time and output low	C=30 pF, 1.62 V≤V _{DD} ≤2.7 V ⁽⁴⁾	-	4	ns
		to high level rise time	C=30 pF, 1.62 V≤V _{DD} ≤2.7 V ⁽⁴⁾	-	2.4	
			C=30 pF, 1.62 V≤V _{DD} ≤2.7 V ⁽⁴⁾	-	60	
	F _{max} ⁽²⁾ Maxi	Maximum frequency	C=30 pF, 1.62 V≤V _{DD} ≤2.7 V ⁽⁴⁾	-	90	MHz
44			C=30 pF, 1.62 V≤V _{DD} ≤2.7 V ⁽⁴⁾	-	175	
11		Output high to low level	C=30 pF, 1.62 V≤V _{DD} ≤2.7 V ⁽⁴⁾	-	5.3	
	$t_r/t_f^{(3)}$	fall time and output low	C=30 pF, 1.62 V≤V _{DD} ≤2.7 V ⁽⁴⁾	-	3.6	ns
		to high level rise time	C=30 pF, 1.62 V≤V _{DD} ≤2.7 V ⁽⁴⁾	-	1.9	

^{1.} Guaranteed by design.

3. The fall and rise times are defined between 90% and 10% and between 10% and 90% of the output waveform, respectively.

4. Compensation system enabled.

^{2.} The maximum frequency is defined with the following conditions: $(t_r+t_f) \le 2/3$ T Skew $\le 1/20$ T 45%-Duty cycle<55%

Analog switch between ports Pxy_C and Pxy

PA0_C, PA1_C, PC2_C and PC3_C can be connected internally to PA0, PA1, PC2 and PC3, respectively (refer to SYSCFG_PMCR register in RM0468 reference manual). The switch is controlled by $V_{\mbox{\scriptsize DDSWITCH}}$ voltage level. It is defined through BOOSTVDDSEL bit of SYSCFG_PMCR. If the switch is closed the switch characteristics are given in the table below.

Parameter Conditions Min Max Unit Тур Switch control boosted 315 V_{DDSWITCH} > 2.7 V 315 V_{DDSWITCH} > 2.4 V 335 Switch Ω Switch control impedance V_{DDSWITCH} > 2.0 V 390 not boosted V_{DDSWITCH} > 1.8 V 445 V_{DDSWITCH} > 1.62 V 550

Table 59. Pxy_C and Pxy analog switch characteristics

6.3.18 NRST pin characteristics

The NRST pin input driver uses CMOS technology. It is connected to a permanent pull-up resistor, R_{PU} (see *Table 54: I/O static characteristics*).

Unless otherwise specified, the parameters given in *Table 60* are derived from tests performed under the ambient temperature and V_{DD} supply voltage conditions summarized in *Table 13: General operating conditions*.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R _{PU} ⁽²⁾	Weak pull-up equivalent resistor ⁽¹⁾	$V_{IN} = V_{SS}$	30	40	50	kΩ
V _{F(NRST)} ⁽²⁾	NRST Input filtered pulse	1.71 V < V _{DD} < 3.6 V	-	-	50	
V _{NF(NRST)} ⁽²⁾	NDCT Innut not filtered nulse	1.71 V < V _{DD} < 3.6 V	350	-	-	ns
	NRST Input not filtered pulse	1.62 V < V _{DD} < 3.6 V	1000	-	-	

Table 60. NRST pin characteristics

2. Guaranteed by design.

The pull-up is designed with a true resistance in series with a switchable PMOS. This PMOS contribution
to the series resistance must be minimum (~10% order).

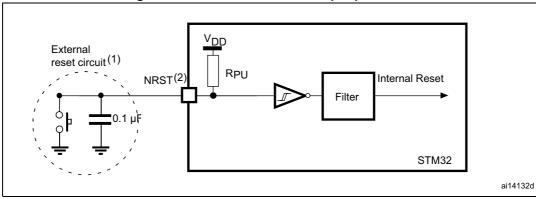


Figure 27. Recommended NRST pin protection

- 1. The reset network protects the device against parasitic resets.
- The user must ensure that the level on the NRST pin can go below the V_{IL(NRST)} max level specified in Table 54. Otherwise the reset is not taken into account by the device.

6.3.19 FMC characteristics

Unless otherwise specified, the parameters given in *Table 61* to *Table 74* for the FMC interface are derived from tests performed under the ambient temperature, f_{HCLK} frequency and V_{DD} supply voltage conditions summarized in *Table 13: General operating conditions*, with the following configuration:

- Output speed is set to OSPEEDRy[1:0] = 11
- Measurement points are done at CMOS levels: 0.5V_{DD}
- IO Compensation cell activated.
- HSLV activated when V_{DD} ≤ 2.7 V
- VOS level set to VOS0.

Refer to Section 6.3.17: I/O port characteristics for more details on the input/output alternate function characteristics.

Asynchronous waveforms and timings

Figure 28 through Figure 30 represent asynchronous waveforms and Table 61 through Table 68 provide the corresponding timings. The results shown in these tables are obtained with the following FMC configuration:

- AddressSetupTime = 0x1
- AddressHoldTime = 0x1
- DataSetupTime = 0x1 (except for asynchronous NWAIT mode, DataSetupTime = 0x5)
- BusTurnAroundDuration = 0x0
- Capacitive load C_L = 30 pF

In all timing tables, the $T_{\mbox{\scriptsize KERCK}}$ is the $f_{\mbox{\scriptsize mc_ker_ck}}$ clock period.

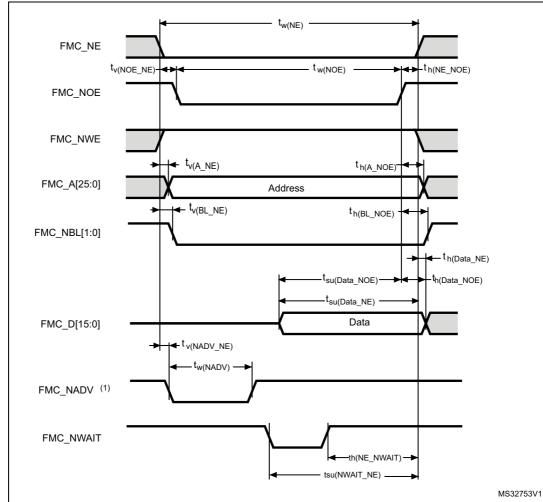


Figure 28. Asynchronous non-multiplexed SRAM/PSRAM/NOR read waveforms

1. Mode 2/B, C and D only. In Mode 1, FMC_NADV is not used.

Table 61. Asynchronous non-multiplexed SRAM/PSRAM/NOR read timings⁽¹⁾

Symbol	Parameter	Min	Max	Unit
t _{w(NE)}	FMC_NE low time	3T _{fmc_ker_ck} -1	3T _{fmc_ker_ck} +1	
t _{v(NOE_NE)}	FMC_NEx low to FMC_NOE low	0	0.5	
t _{w(NOE)}	FMC_NOE low time	2T _{fmc_ker_ck} -1	2T _{fmc_ker_ck} +1	
t _{h(NE_NOE)}	FMC_NOE high to FMC_NE high hold time	T _{fmc_ker_ck}	-	
t _{v(A_NE)}	FMC_NEx low to FMC_A valid	-	0.5	
t _{h(A_NOE)}	Address hold time after FMC_NOE high	2T _{fmc_ker_ck}	-	
t _{su(Data_NE)}	Data to FMC_NEx high setup time	T _{fmc_ker_ck} +14	-	ns
t _{su(Data_NOE)}	Data to FMC_NOEx high setup time	13	-	
t _{h(Data_NOE)}	Data hold time after FMC_NOE high	0	-	
t _{h(Data_NE)}	Data hold time after FMC_NEx high	0	-	
t _{v(NADV_NE)}	FMC_NEx low to FMC_NADV low	-	4	
t _{w(NADV)}	FMC_NADV low time	-	T _{fmc_ker_ck} +1	

^{1.} Guaranteed by characterization results.

Table 62. Asynchronous non-multiplexed SRAM/PSRAM/NOR read-NWAIT timings $^{(1)(2)}$

Symbol	Parameter	Min	Max	Unit
t _{w(NE)}	FMC_NE low time	7T _{fmc_ker_ck} -1	7T _{fmc_ker_ck} +1	
t _{w(NOE)}	FMC_NOE low time	5T _{fmc_ker_ck} -1	5T _{fmc_ker_ck} +1	
t _{w(NWAIT)}	FMC_NWAIT low time	T _{fmc_ker_ck} - 0.5	-	
t _{su(NWAIT_NE)}	FMC_NWAIT valid before FMC_NEx high	4T _{fmc_ker_ck} +9	-	ns
t _{h(NE_NWAIT)}	FMC_NEx hold time after FMC_NWAIT invalid	3T _{fmc_ker_ck} +12	-	

^{1.} Guaranteed by characterization results.

^{2.} N_{WAIT} pulse width is equal to 1 fmc_ker_ck cycle.

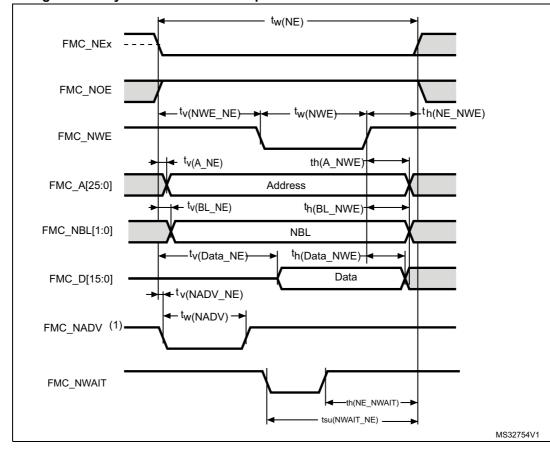


Figure 29. Asynchronous non-multiplexed SRAM/PSRAM/NOR write waveforms

1. Mode 2/B, C and D only. In Mode 1, FMC_NADV is not used.

Table 63. Asynchronous non-multiplexed SRAM/PSRAM/NOR write timings⁽¹⁾

Symbol	Parameter	Min	Max	Unit
t _{w(NE)}	FMC_NE low time	3T _{fmc_ker_ck} -1	3T _{fmc_ker_ck} + 1	
t _{v(NWE_NE)}	FMC_NEx low to FMC_NWE low	T _{fmc_ker_ck} -1	T _{fmc_ker_ck}	
t _{w(NWE)}	FMC_NWE low time	T _{fmc_ker_ck} -0.5	T _{fmc_ker_ck} +0.5	
t _{h(NE_NWE)}	FMC_NWE high to FMC_NE high hold time	T _{fmc_ker_ck}	-	
t _{v(A_NE)}	FMC_NEx low to FMC_A valid	-	1	
t _{h(A_NWE)}	Address hold time after FMC_NWE high	T _{fmc_ker_ck} -0.5	-	ns
t _{v(BL_NE)}	FMC_NEx low to FMC_BL valid	1	0.5	
t _{h(BL_NWE)}	FMC_BL hold time after FMC_NWE high	T _{fmc_ker_ck} -0.5	-	
t _{v(Data_NE)}	Data to FMC_NEx low to Data valid	-	T _{fmc_ker_ck} + 2	
t _{h(Data_NWE)}	Data hold time after FMC_NWE high	T _{fmc_ker_ck}	-	
t _{v(NADV_NE)}	FMC_NEx low to FMC_NADV low	-	5	
t _{w(NADV)}	FMC_NADV low time	-	T _{fmc_ker_ck} + 1	

^{1.} Guaranteed by characterization results.

Table 64. Asynchronous non-multiplexed SRAM/PSRAM/NOR write-NWAIT timings $^{(1)(2)}$

Symbol	Parameter	Min	Max	Unit
t _{w(NE)}	FMC_NE low time	8T _{fmc_ker_ck} –1	8T _{fmc_ker_ck} +1	
t _{w(NWE)}	FMC_NWE low time	6T _{fmc_ker_ck} -1	6T _{fmc_ker_ck} +1	
t _{su(NWAIT_NE)}	FMC_NWAIT valid before FMC_NEx high	5T _{fmc_ker_ck} +13	-	ns
t _{h(NE_NWAIT)}	FMC_NEx hold time after FMC_NWAIT invalid	4T _{fmc_ker_ck} +12	-	

^{1.} Guaranteed by characterization results.

^{2.} N_{WAIT} pulse width is equal to 1 fmc_ker_ck cycle.

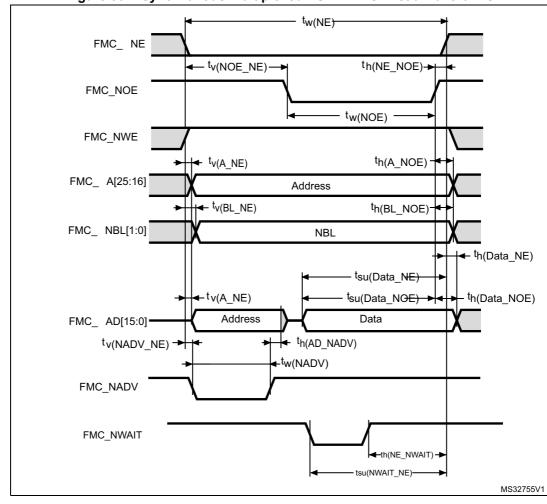


Figure 30. Asynchronous multiplexed PSRAM/NOR read waveforms

Table 65. Asynchronous multiplexed PSRAM/NOR read timings⁽¹⁾

Symbol	Parameter	Min	Max	Unit
t _{w(NE)}	FMC_NE low time	4T _{fmc_ker_ck} -1	4T _{fmc_ker_ck} +1	
t _{v(NOE_NE)}	FMC_NEx low to FMC_NOE low	2T _{fmc_ker_ck}	2T _{fmc_ker_ck} +0.5	
t _{tw(NOE)}	FMC_NOE low time	T _{fmc_ker_ck} -1	T _{fmc_ker_ck} +1	
t _{h(NE_NOE)}	FMC_NOE high to FMC_NE high hold time	T _{fmc_ker_ck}	-	
t _{v(A_NE)}	FMC_NEx low to FMC_A valid	-	0.5	
t _{v(NADV_NE)}	FMC_NEx low to FMC_NADV low	0	4.0	
t _{w(NADV)}	FMC_NADV low time	T _{fmc_ker_ck} -0.5	T _{fmc_ker_ck} +1	ns
t _{h(AD_NADV)}	FMC_AD(address) valid hold time after FMC_NADV high)	T _{fmc_ker_ckk} -4	-	
t _{h(A_NOE)}	Address hold time after FMC_NOE high	T _{fmc_ker_ck} -0.5	-	
t _{su(Data_NE)}	Data to FMC_NEx high setup time	T _{fmc_ker_ck} +14	-	
t _{su(Data_NOE)}	Data to FMC_NOE high setup time	13	-	
t _{h(Data_NE)}	Data hold time after FMC_NEx high	0	-	
t _{h(Data_NOE)}	Data hold time after FMC_NOE high	0	-	

^{1.} Guaranteed by characterization results.

Table 66. Asynchronous multiplexed PSRAM/NOR read-NWAIT timings⁽¹⁾

Symbol	Parameter	Min	Max	Unit
t _{w(NE)}	FMC_NE low time	8T _{fmc_ker_ck} -1	8T _{fmc_ker_ck} +1	
t _{w(NOE)}	FMC_NWE low time	5T _{fmc_ker_ck} –1	5T _{fmc_ker_ck} +1	
t _{su(NWAIT_NE)}	FMC_NWAIT valid before FMC_NEx high	4T _{fmc_ker_ck} +9	-	ns
t _{h(NE_NWAIT)}	FMC_NEx hold time after FMC_NWAIT invalid	3T _{fmc_ker_ck} +12	-	

^{1.} Guaranteed by characterization results.

Table 67. Asynchronous multiplexed PSRAM/NOR write timings⁽¹⁾

Symbol	Parameter	Min	Max	Unit
t _{w(NE)}	FMC_NE low time	4T _{fmc_ker_ck} -1	4T _{fmc_ker_ck}	
t _{v(NWE_NE)}	FMC_NEx low to FMC_NWE low	T _{fmc_ker_ck} -1	T _{fmc_ker_ck} +0.5	
t _{w(NWE)}	FMC_NWE low time	2T _{fmc_ker_ck} -0.5	2T _{fmc_ker_ck} +0.5	
t _{h(NE_NWE)}	FMC_NWE high to FMC_NE high hold time	T _{fmc_ker_ck} –0.5	-	
t _{v(A_NE)}	FMC_NEx low to FMC_A valid	-	1	
t _{v(NADV_NE)}	FMC_NEx low to FMC_NADV low	0	5.0	
t _{w(NADV)}	FMC_NADV low time	T _{fmc_ker_ck} -0.5	T _{fmc_ker_ck} + 1	
t _{h(AD_NADV)}	FMC_AD(adress) valid hold time after FMC_NADV high)	T _{fmc_ker_ck} -4.5	-	ns
t _{h(A_NWE)}	Address hold time after FMC_NWE high	T _{fmc_ker_ck} - 0.5	-	
t _{h(BL_NWE)}	FMC_BL hold time after FMC_NWE high	T _{fmc_ker_ck} – 0.5	-	
t _{v(BL_NE)}	FMC_NEx low to FMC_BL valid	-	0.5	
t _{v(Data_NADV)}	FMC_NADV high to Data valid	-	T _{fmc_ker_ck} +2	
t _{h(Data_NWE)}	Data hold time after FMC_NWE high	T _{fmc_ker_ck}	-	

^{1.} Guaranteed by characterization results.

Table 68. Asynchronous multiplexed PSRAM/NOR write-NWAIT timings⁽¹⁾⁽²⁾

Symbol	Parameter	Min	Max	Unit
t _{w(NE)}	FMC_NE low time	9T _{fmc_ker_ck} –1	9T _{fmc_ker_ck}	
t _{w(NWE)}	FMC_NWE low time	7T _{fmc_ker_ck} –0.5	7T _{fmc_ker_ck} +0.5	
t _{su(NWAIT_NE)}	FMC_NWAIT valid before FMC_NEx high	5T _{fmc_ker_ck} +9	-	ns
t _{h(NE_NWAIT)}	FMC_NEx hold time after FMC_NWAIT invalid	4T _{fmc_ker_ck} +12	-	

^{1.} Guaranteed by characterization results.

^{2.} N_{WAIT} pulse width is equal to 1 fmc_ker_ck cycle.

Synchronous waveforms and timings

Figure 31 through *Figure 34* represent synchronous waveforms and *Table 69* through *Table 72* provide the corresponding timings. The results shown in these tables are obtained with the following FMC configuration:

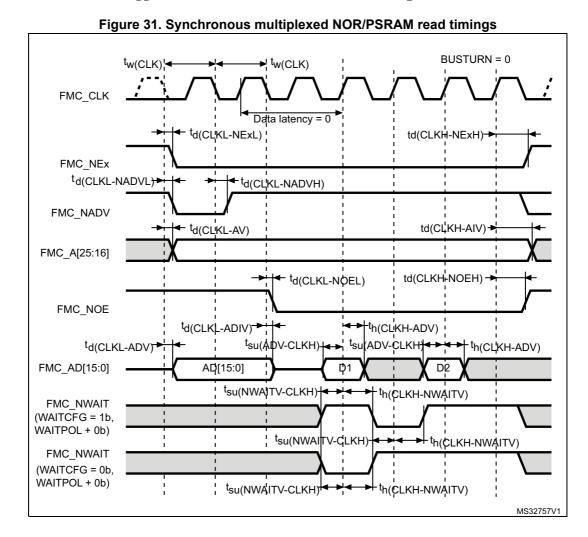
- BurstAccessMode = FMC_BurstAccessMode_Enable
- MemoryType = FMC_MemoryType_CRAM
- WriteBurst = FMC WriteBurst Enable
- CLKDivision = 1

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DataLatency = 1 for NOR Flash, DataLatency = 0 for PSRAM, C_L = 30 pF

In all the timing tables, the $T_{fmc_ker_ck}$ is the $f_{mc_ker_ck}$ clock period, with the following FMC_CLK maximum values:

- For 2.7 V<V_{DD}<3.6 V: maximum FMC_CLK = 137 MHz at C_I = 20 pF
- For 1.8 V<V_{DD}<1.9 V: maximum FMC_CLK = 100 MHz at C_L = 20 pF
- For 1.62 V<V_{DD}<1.8 V: maximumFMC_CLK = 88 MHz at C_L = 15 pF



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Table 69. Synchronous multiplexed NOR/PSRAM read timings⁽¹⁾

Symbol	Parame	eter	Min	Max	Unit
t _{w(CLK)}	FMC_CLK period		2T _{fmc_ker_ck} -0.5	-	
t _{d(CLKL-NExL)}	FMC_CLK low to FMC	_NEx low (x=02)	-	3	
t _{d(CLKH_NExH)}	FMC_CLK high to FMC_	NEx high (x= 02)	T _{fmc_ker_ck} +1.5	-	
+	FMC_CLK low to	1.62 V <v<sub>DD < 3.6 V</v<sub>		5.5	
t _{d(CLKL-NADVL)}	FMC_NADV low	2.7 V <v<sub>DD < 3.6 V</v<sub>	_	2	,
4	FMC_CLK low to	1.62 V <v<sub>DD < 3.6 V</v<sub>	1	-	
t _{d(CLKL-NADVH)}	FMC_NADV high	2.7 V <v<sub>DD < 3.6 V</v<sub>	'	-	,
t _{d(CLKL-AV)}	FMC_CLK low to FMC_	Ax valid (x=1625)	-	3	
t _{d(CLKH-AIV)}	FMC_CLK high to FMC_Ax invalid (x=1625)		T _{fmc_ker_ck}	-	ns
t _{d(CLKL-NOEL)}	FMC_CLK low to FMC_NOE low		-	2.5	
t _{d(CLKH-NOEH)}	FMC_CLK high to FMC_NOE high		T _{fmc_ker_ck} +1	-	
t _{d(CLKL-ADV)}	FMC_CLK low to FMC_AD[15:0] valid		-	3	
t _{d(CLKL-ADIV)}	FMC_CLK low to FMC_AD[15:0] invalid		0	-	
t _{su(ADV-CLKH)}	FMC_A/D[15:0] valid data before FMC_CLK high		3	-	
t _{h(CLKH-ADV)}	FMC_A/D[15:0] valid data after FMC_CLK high		0	-	
t _{su(NWAIT} - CLKH)	FMC_NWAIT valid before FMC_CLK high		3	-	
t _{h(CLKH-NWAIT)}	FMC_NWAIT valid after	er FMC_CLK high	2.5	-	

^{1.} Guaranteed by characterization results.

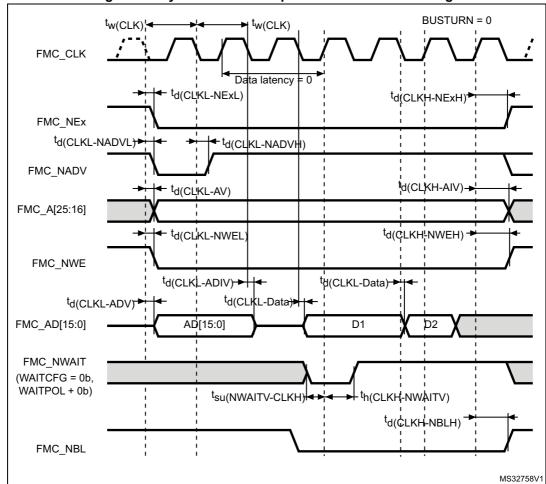


Figure 32. Synchronous multiplexed PSRAM write timings

Table 70. Synchronous multiplexed PSRAM write timings⁽¹⁾

Symbol	Parameter		Min	Max	Unit
t _{w(CLK)}	FMC_CLK period, V _{DD} = 2.7 to 3.6 V		2T _{fmc_ker_ck} -0.5	-	
t _{d(CLKL-NExL)}	FMC_CLK low to FMC	C_NEx low (x =02)	-	3	
t _{d(CLKH-NExH)}	FMC_CLK high to $(x = 0.$		T _{fmc_ker_ck} +1.5	-	
+	FMC_CLK low to	1.62 V <v<sub>DD < 3.6 V</v<sub>		5.5	
t _d (CLKL-NADVL)	FMC_NADV low	2.7 V <v<sub>DD < 3.6 V</v<sub>	-	2.0	
+	FMC_CLK low to	1.62 V <v<sub>DD < 3.6 V</v<sub>	1	-	
t _{d(CLKL-NADVH)}	FMC_NADV high	2.7 V <v<sub>DD < 3.6 V</v<sub>	- 1	-	
t _{d(CLKL-AV)}	FMC_CLK low to FMC_Ax valid (x =1625)		-	3	
t _{d(CLKH-AIV)}	FMC_CLK high to FMC_Ax invalid (x =1625)		T _{fmc_ker_ck}	-	ns
t _{d(CLKL-NWEL)}	FMC_CLK low to FMC_NWE low		-	2.5	
t _(CLKH-NWEH)	FMC_CLK high to FMC_NWE high		T _{fmc_ker_ck} +1	-	
t _{d(CLKL-ADV)}	FMC_CLK low to to FMC_AD[15:0] valid		-	2.5	
t _{d(CLKL-ADIV)}	FMC_CLK low to FM	C_AD[15:0] invalid	0	-	
t _{d(CLKL-DATA)}	FMC_A/D[15:0] valid data after FMC_CLK low		-	3.5	
t _{d(CLKL-NBLL)}	FMC_CLK low to FMC_NBL low		-	2	
t _{d(CLKH-NBLH)}	FMC_CLK high to FMC_NBL high		T _{fmc_ker_ck} +0.5	-	
t _{su(NWAIT-CLKH)}	FMC_NWAIT valid before FMC_CLK high		3	-	
t _{h(CLKH-NWAIT)}	FMC_NWAIT valid after FMC_CLK high		2.5	-	

^{1.} Guaranteed by characterization results.

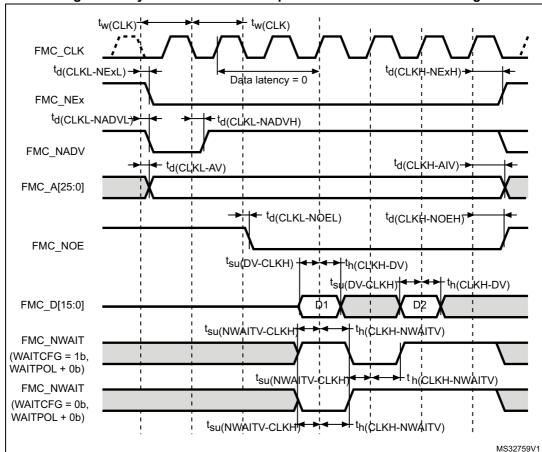


Figure 33. Synchronous non-multiplexed NOR/PSRAM read timings

Table 71. Synchronous non-multiplexed NOR/PSRAM read timings⁽¹⁾

Symbol	Parameter		Min	Max	Unit
t _{w(CLK)}	FMC_CLI	K period	2T _{fmc_ker_ck} -0.5	-	
t _(CLKL-NExL)	FMC_CLK low to FM	C_NEx low (x=02)	-	3	
t _{d(CLKH-NExH)}	FMC_CLK high to FMC	C_NEx high (x= 02)	T _{fmc_ker_ck} +1.5	-	
+	FMC_CLK low to	1.62 V <v<sub>DD < 3.6 V</v<sub>		5.5	
t _{d(CLKL-NADVL)}	FMC_NADV low	2.7 V <v<sub>DD < 3.6 V</v<sub>	-	2.0	
+	FMC_CLK low to	1.62 V <v<sub>DD < 3.6 V</v<sub>	1	-	
t _d (CLKL-NADVH)	FMC_NADV high 2.5	2.7 V <v<sub>DD < 3.6 V</v<sub>		-	
t _{d(CLKL-AV)}	FMC_CLK low to FMC_Ax valid (x=1625)		-	3	ns
t _{d(CLKH-AIV)}	FMC_CLK high to FMC_Ax invalid (x=1625)		T _{fmc_ker_ck}	-	
t _{d(CLKL-NOEL)}	FMC_CLK ow to FMC_NOE low		-	2.5	
t _{d(CLKH-NOEH)}	FMC_CLK high to FMC_NOE high		T _{fmc_ker_ck} +1	-	
t _{su(DV-CLKH)}	FMC_D[15:0] valid data before FMC_CLK high		3	-	
t _{h(CLKH-DV)}	FMC_D[15:0] valid data after FMC_CLK high		0	-	
t _(NWAIT-CLKH)	FMC_NWAIT valid before FMC_CLK high		3	-	
t _{h(CLKH-NWAIT)}	FMC_NWAIT valid after FMC_CLK high		2.5	-	

^{1.} Guaranteed by characterization results.

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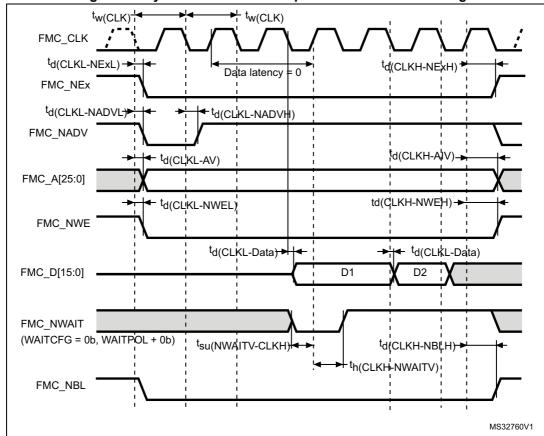


Figure 34. Synchronous non-multiplexed PSRAM write timings

Table 72. Synchronous non-multiplexed PSRAM write timings⁽¹⁾

Symbol	Parameter		Min	Max	Unit
t _(CLK)	FMC_CLK period		2T _{fmc_ker_ck} -0.5	-	
t _{d(CLKL-NExL)}	FMC_CLK low to FMC	C_NEx low (x=02)	-	3	
t _(CLKH-NExH)	FMC_CLK high to FMC	_NEx high (x= 02)	T _{fmc_ker_ck} +1.5	-	
+	FMC_CLK low to	1.62 V <v<sub>DD < 3.6 V</v<sub>		5.5	
t _{d(CLKL-NADVL)}	FMC_NADV low	2.7 V <v<sub>DD < 3.6 V</v<sub>	_	2	
1	FMC_CLK low to	1.62 V <v<sub>DD < 3.6 V</v<sub>	4	1	
t _{d(CLKL-NADVH)}	FMC_NADV high	2.7 V <v<sub>DD < 3.6 V</v<sub>	'	-	
t _{d(CLKL-AV)}	FMC_CLK low to FMC_Ax valid (x=1625)		-	3	
t _{d(CLKH-AIV)}	FMC_CLK high to FMC_Ax invalid (x=1625)		T _{fmc_ker_ck}	Ī	ns
t _{d(CLKL-NWEL)}	FMC_CLK low to FMC_NWE low		-	2.5	
t _{d(CLKH-NWEH)}	FMC_CLK high to FMC_NWE high		T _{fmc_ker_ck} +1	1	
t _{d(CLKL-Data)}	FMC_D[15:0] valid data after FMC_CLK low		-	3.5	
t _{d(CLKL-NBLL)}	FMC_CLK low to FMC_NBL low		-	2	
t _{d(CLKH-NBLH)}	FMC_CLK high to FMC_NBL high		T _{fmc_ker_ck} +0.5	-	
t _{su(NWAIT} - CLKH)	FMC_NWAIT valid before FMC_CLK high		3	-	
t _{h(CLKH-NWAIT)}	FMC_NWAIT valid af	ter FMC_CLK high	2.5	-	

^{1.} Guaranteed by characterization results.

NAND controller waveforms and timings

Figure 35 through Figure 38 represent synchronous waveforms, and Table 73 and Table 74 provide the corresponding timings. The results shown in this table are obtained with the following FMC configuration and a capacitive load ($C_{\rm I}$) of 30 pF:

- COM.FMC_SetupTime = 0x01
- COM.FMC_WaitSetupTime = 0x03
- COM.FMC HoldSetupTime = 0x02
- COM.FMC_HiZSetupTime = 0x01
- ATT.FMC SetupTime = 0x01
- ATT.FMC_WaitSetupTime = 0x03
- ATT.FMC_HoldSetupTime = 0x02
- ATT.FMC_HiZSetupTime = 0x01
- Bank = FMC_Bank_NAND
- MemoryDataWidth = FMC_MemoryDataWidth_16b
- ECC = FMC_ECC_Enable
- ECCPageSize = FMC_ECCPageSize_512Bytes
- TCLRSetupTime = 0
- TARSetupTime = 0

In all timing tables, the $T_{fmc_ker_ck}$ is the fmc_ker_ck clock period.

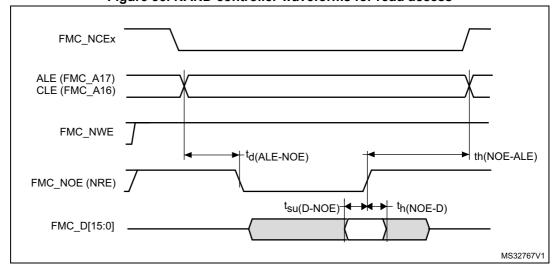


Figure 35. NAND controller waveforms for read access

FMC_NCEX

ALE (FMC_A17)
CLE (FMC_A16)

FMC_NWE

FMC_NOE (NRE)

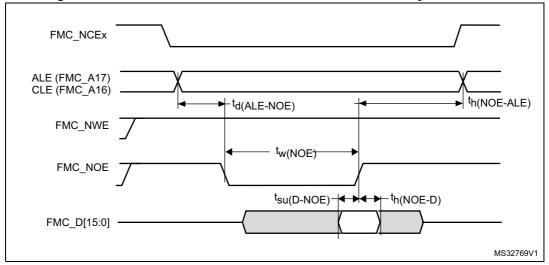
tv(NWE-D)

th(NWE-D)

MS32768V1

Figure 36. NAND controller waveforms for write access





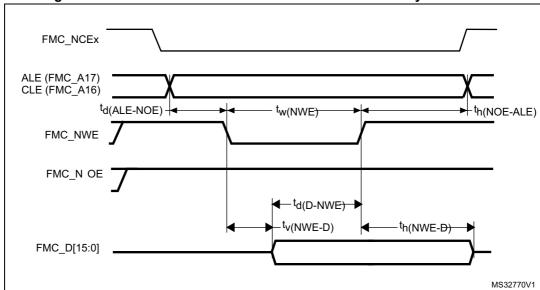


Figure 38. NAND controller waveforms for common memory write access

Table 73. Switching characteristics for NAND Flash read cycles⁽¹⁾

Symbol	Parameter	Min	Max	Unit
t _{w(N0E)}	FMC_NOE low width	4T _{fmc_ker_ck} - 0.5	4T _{fmc_ker_ck} +0.5	
t _{su(D-NOE)}	FMC_D[15-0] valid data before FMC_NOE high	11	-	
t _{h(NOE-D)}	FMC_D[15-0] valid data after FMC_NOE high	0	-	ns
t _{d(ALE-NOE)}	FMC_ALE valid before FMC_NOE low	-	3T _{fmc_ker_ck} +0.5	
t _{h(NOE-ALE)}	FMC_NWE high to FMC_ALE invalid	4T _{fmc_ker_ck} -1	-	

^{1.} Guaranteed by characterization results.

Table 74. Switching characteristics for NAND Flash write cycles⁽¹⁾

Symbol	Parameter	Min	Max	Unit
t _{w(NWE)}	FMC_NWE low width	4T _{fmc_ker_ck} - 0.5	4T _{fmc_ker_ck} +0.5	
t _{v(NWE-D)}	FMC_NWE low to FMC_D[15-0] valid	0	-	
t _{h(NWE-D)}	FMC_NWE high to FMC_D[15-0] invalid	2T _{fmc_ker_ck} +1.5	-	
t _{d(D-NWE)}	FMC_D[15-0] valid before FMC_NWE high	5T _{fmc_ker_ck} – 5	-	ns
t _{d(ALE-NWE)}	FMC_ALE valid before FMC_NWE low	-	3T _{fmc_ker_ck} +0.5	
t _{h(NWE-ALE)}	FMC_NWE high to FMC_ALE invalid	2T _{fmc_ker_ck} - 0.5	-	

^{1.} Guaranteed by characterization results.

SDRAM waveforms and timings

In all timing tables, the TKERCK is the fmc_ker_ck clock period, with the following FMC_SDCLK maximum values:

- For 2.7 V<V_{DD}<3.6 V: maximum FMC_CLK = 95 MHz at 20 pF
- For 1.8 V<V_{DD}<1.9 V: maximum FMC_CLK = 90 MHz at 20 pF
- For 1.62 V<_{DD}<1.8 V: maximum FMC_CLK = 85 MHz at 15 pF

Figure 39. SDRAM read access waveforms (CL = 1)

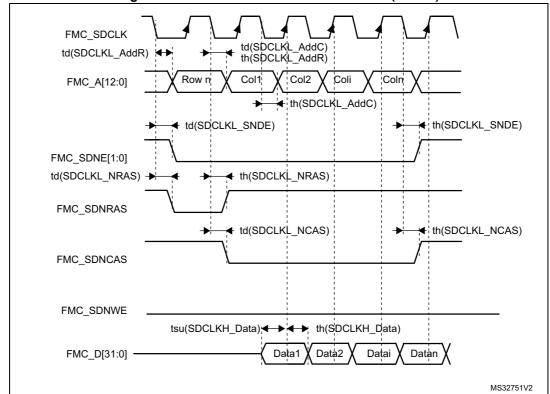


Table 75. SDRAM read timings⁽¹⁾

Symbol	Parameter	Min	Max	Unit
t _{w(SDCLK)}	FMC_SDCLK period	2T _{fmc_ker_ck} – 0.5	2T _{fmc_ker_ck} +0.5	
t _{su(SDCLKH _Data)}	Data input setup time	3	-	
t _{h(SDCLKH_Data)}	Data input hold time	1.5	-	
t _{d(SDCLKL_Add)}	Address valid time	-	2.0	
t _{d(SDCLKL-} SDNE)	Chip select valid time	-	1.5 ⁽²⁾	ns
t _{h(SDCLKL_SDNE)}	Chip select hold time	0	-	
t _d (SDCLKL_SDNRAS)	SDNRAS valid time	-	1	
t _{h(SDCLKL_SDNRAS)}	SDNRAS hold time	0	-	
t _{d(SDCLKL_SDNCAS)}	SDNCAS valid time	-	2.0	
t _{h(SDCLKL_SDNCAS)}	SDNCAS hold time	0.5	-	

- 1. Guaranteed by characterization results.
- 2. Using PC2_C I/O adds 4.5 ns to this timing.

Table 76. LPSDR SDRAM read timings⁽¹⁾

Symbol	Parameter	Min	Max	Unit
tw(sdclk)	FMC_SDCLK period	2T _{fmc_ker_ck} – 0.5	2T _{fmc_ker_ck} +0.5	
t _{su(SDCLKH_Data)}	Data input setup time	3	-	
t _{h(SDCLKH_Data)}	Data input hold time	2.5	-	
t _{d(SDCLKL_Add)}	Address valid time	-	2	
t _{d(SDCLKL_SDNE)}	Chip select valid time	-	1.5 ⁽²⁾⁽³⁾	ns
t _{h(SDCLKL_SDNE)}	Chip select hold time	0	-	
t _{d(SDCLKL_SDNRAS}	SDNRAS valid time	-	1	
th(SDCLKL_SDNRAS)	SDNRAS hold time	0	-	
t _d (SDCLKL_SDNCAS)	SDNCAS valid time	-	2	
t _{h(SDCLKL_SDNCAS)}	SDNCAS hold time	0.5	-	

- 1. Guaranteed by characterization results.
- 2. Using PC2 I/O adds 4 ns to this timing.
- 3. Using PC2_C I/O adds 16.5 ns to this timing.

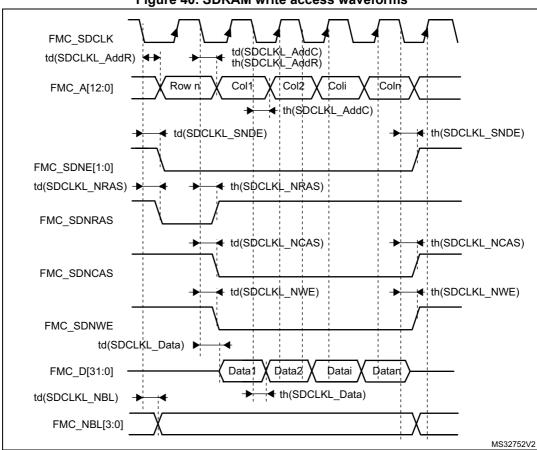


Figure 40. SDRAM write access waveforms

Table 77. SDRAM Write timings⁽¹⁾

Symbol	Parameter	Min	Max	Unit
t _{w(SDCLK)}	FMC_SDCLK period	2T _{fmc_ker_ck} - 0.5	2T _{fmc_ker_ck} +0.5	
t _{d(SDCLKL _Data})	Data output valid time	-	2	
t _{h(SDCLKL_Data)}	Data output hold time	0.5	-	
t _{d(SDCLKL_Add)}	Address valid time	-	2	
t _{d(SDCLKL_SDNWE)}	SDNWE valid time	-	2	
t _{h(SDCLKL_SDNWE)}	SDNWE hold time	0	-	ns
t _{d(SDCLKL_SDNE)}	Chip select valid time	-	1.5 ⁽²⁾	115
t _{h(SDCLKLSDNE)}	Chip select hold time	0	-	
t _d (SDCLKL_SDNRAS)	SDNRAS valid time	-	1	
th(SDCLKL_SDNRAS)	SDNRAS hold time	0	-	
t _d (SDCLKL_SDNCAS)	SDNCAS valid time	-	2	
t _{d(SDCLKL_SDNCAS)}	SDNCAS hold time	0.5	-	

- 1. Guaranteed by characterization results.
- 2. Using PC2_C I/O adds 4.5 ns to this timing.



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Symbol	Parameter	Min	Max	Unit
t _{w(SDCLK)}	FMC_SDCLK period	2T _{fmc_ker_ck} - 0.5	2T _{fmc_ker_ck} +0.5	
t _{d(SDCLKL_Data})	Data output valid time	-	2	
t _{h(SDCLKL_Data)}	Data output hold time	0	-	
t _{d(SDCLKL_Add)}	Address valid time	-	2.5	
t _{d(SDCLKL-SDNWE)}	SDNWE valid time	-	2	
t _{h(SDCLKL-SDNWE)}	SDNWE hold time	0	-	200
t _{d(SDCLKL} - SDNE)	Chip select valid time	-	1.5 ⁽²⁾⁽³⁾	ns
t _{h(SDCLKL-SDNE)}	Chip select hold time	0	-	
t _d (SDCLKL-SDNRAS)	SDNRAS valid time	-	1	
t _{h(SDCLKL-SDNRAS)}	SDNRAS hold time	0	-	
t _d (SDCLKL-SDNCAS)	SDNCAS valid time	-	2	

0.5

Table 78. LPSDR SDRAM Write timings⁽¹⁾

6.3.20 Octo-SPI interface characteristics

 $t_{d(SDCLKL-SDNCAS)}$

Unless otherwise specified, the parameters given in *Table 79* and *Table 81* for OCTOSPI are derived from tests performed under the ambient temperature, f_{HCLK} frequency and V_{DD} supply voltage conditions summarized in *Table 13: General operating conditions*, with the following configuration:

SDNCAS hold time

- Output speed is set to OSPEEDRy[1:0] = 11
- Measurement points are done at CMOS levels: 0.5V_{DD}
- IO Compensation cell activated.
- HSLV activated when V_{DD} ≤ 2.5 V
- VOS level set to VOS0

Refer to Section 6.3.17: I/O port characteristics for more details on the input/output alternate function characteristics.

Table 79. OCTOSPI characteristics in SDR mode⁽¹⁾⁽²⁾

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
F _(CLK)		1.71 V < V _{DD} < 3.6 V, VOS0, C _{LOAD} = 15 pF	-	-	92	
	OCTOSPI clock frequency	1.71 V < V _{DD} < 3.6 V, VOS0, C _{LOAD} =20 pF	-	-	90	MHz
		2.7 V < V _{DD} < 3.6 V, VOS0, C _{LOAD} = 20 pF	-	-	140	



^{1.} Guaranteed by characterization results.

^{2.} Using PC2 I/O adds 4 ns to this timing.

^{3.} Using PC2_C I/O adds 16.5 ns to this timing.

Symbol Conditions Min Unit **Parameter** Тур Max $t_{(CK)}/2$ $t_{(CK)}/2+1$ tw(CKH) OCTOSPI clock high and low PRESCALER[7:0] = ntime, even division = 0,1,3,5 $t_{(CK)}/2-1$ $t_{(CK)}/2$ $t_{w(CKL)}$ (n/2)*t_(CK)/ (n+1) (n/2)*t_(CK)/ (n+1)+1 t_{w(CKH)} OCTOSPI clock high and low PRESCALER[7:0] = ntime, odd division = 2,4,6,8 (n/2+1)*t_(CK)/ (n+1)-1 (n/2+1)*t_(CK) tw(CKL) ns /(n+1) $t_{s(IN)}^{\overline{(3)}}$ Data input setup time -3.0 t_{h(IN)}(3) Data input hold time 1.5 $1^{(4)}$ Data output valid time _ _ 0.5 $t_{v(OUT)}$

Table 79. OCTOSPI characteristics in SDR mode⁽¹⁾⁽²⁾ (continued)

1. All values apply to Octal and Quad-SPI mode.

Data output hold time

- 2. Guaranteed by characterization results.
- 3. Delay block bypassed.

t_{h(OUT)}

4. Using PC2 or PC3 I/O in the data bus adds 4 ns to this timing value.

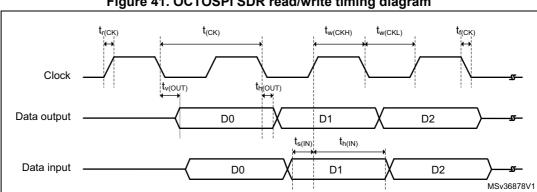


Figure 41. OCTOSPI SDR read/write timing diagram

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Table 80. OCTOSPI characteristics in DTR mode (no DQS)⁽¹⁾⁽²⁾

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
		1.71 V < V _{DD} < 3.6 V, VOS0, C _{LOAD} = 15 pF	-	-	90 ⁽⁴⁾	
F _{CK} ⁽³⁾	OCTOSPI clock frequency	1.71 V < V _{DD} < 3.6 V, VOS0, C _{LOAD} = 20 pF	-	-	87 ⁽⁴⁾	MHz
		2.7 V < V _{DD} < 3.6 V, VOS0, C _{LOAD} = 20 pF	-	-	110	
t _{w(CKH)}	OCTOSPI clock high and	PRESCALER[7:0] = n	t _(CK) /2	-	t _(CK) /2+1	
t _{w(CKL)}	low time, even division	= 0,1,3,5	t _(CK) /2-1	-	t _(CK) /2	
t _{w(CKH)}	OCTOSPI clock high and	PRESCALER[7:0] = n	(n/2)*t _(CK) / (n+1)	-	(n/2)*t _(CK) / (n+1)+1	
t _{w(CKL)}	low time, odd division	= 2,4,6,8	(n/2+1)*t _(CK) /(n+1) – 1	-	(n/2+1)* t _(CK) /(n+1)	
$t_{\rm sr(IN)} \atop t_{\rm sf(IN)}^{(5)}$	Data input setup time	-	3.0	-	-	ns
$t_{\rm hr(IN)} \atop t_{\rm hf(IN)}^{(5)}$	Data input hold time	-	1.50	-	-	113
+		DHQC = 0	-	6	7 ⁽⁶⁾	
t _{vr(OUT)} t _{vf(OUT)}	Data output valid time	DHQC = 1, Prescaler = 1,2	-	t _{pclk} /4+ 1	t _{pclk} /4+1.25	
thr(OLIT)		DHQC = 0	4.5	-	-	
thr(OUT) thf(OUT)	Data output hold time	DHQC = 1, Prescaler = 1,2	t _{pclk} /4	-	-	

- 1. All values apply to Octal and Quad-SPI mode.
- 2. Guaranteed by characterization results.
- 3. DHQC must be set to reach the mentioned frequency.
- 4. Using PC2 or PC3 I/O in the data bus decreases the frequency to 47 MHz.
- 5. Delay block bypassed.
- 6. Using PC2 or PC3 I/O in the data bus adds 4 ns to this timing value.

Figure 42. OCTOSPI DTR mode timing diagram $t_{\text{w}(\text{CKH})}$ $t_{(\mathsf{CK})} \\$ $t_{\text{w}(\text{CKL})}$ $t_{f(CK)}$ Clock t_{hr}(OUT) t_{vr(OUT)} t_{hf(OUT)} Data output D0 D2 D3 D4 D5 $t_{\text{sf(IN)}}\,t_{\text{hf(IN)}}$ $t_{\text{sr(IN)}}t_{\text{hr(IN)}}$ Data input D0 D1 D2 D3 D5 D4 MSv36879V1

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Table 81. OCTOSPI characteristics in DTR mode (with DQS)/Octal and Hyperbus⁽¹⁾

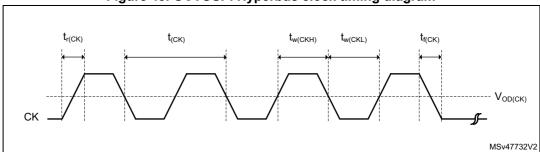
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
F _{CK} ⁽²⁾⁽³⁾	OCTOSPI clock frequency	2,7 V < V _{DD} < 3.6 V, VOS0, C _{LOAD} = 20 pF	-	-	100	MHz
i CK	SO TOOL FOOD MEQUELITY	$1.71 \text{ V} < \text{V}_{DD} < 3.6 \text{ V},$ VOS0, C_{LOAD} = 20 pF	-	1	100 ⁽⁴⁾	1411 12
t _{w(CKH)}	OCTOSPI clock high and	PRESCALER[7:0] = n =	t _(CK) /2	ı	t _(CK) /2+1	ns
t _{w(CKL)}	low time, even division	0,1,3,5	t _(CK) /2-1	1	t _(CK) /2	113
t _{w(CKH)}	OCTOSPI clock high and	PRESCALER[7:0] = n =	(n/2)*t _(CK) / (n+1)	-	(n/2)*t _(CK) / (n+1)+1	
t _{w(CKL)}	low time, odd division	2,4,6,8	(n/2+1)*t _(CK) /(n+1)–1	ı	(n/2+1)*t _(CK) / (n+1)	ns
t _{v(CK)}	Clock valid time	-	-	ı	t _(CK) +1	
t _{h(CK)}	Clock hold time	-	t _(CK) /2	ı	-	
V _{ODr(CK)}	CK, CK crossing level on CK rising edge	VDD = 1.8 V	922	-	1229	mV
V _{ODf(CK)}	CK, CK crossing level on CK falling edge	VDD = 1.8 V	1000	-	1277	IIIV
t _{w(CS)}	Chip select high time	-	3*t _(CK)	-	-	
t _{v(DQ)}	Data input vallid time	-	0	-	-	
t _{v(DS)}	Data strobe input valid time	-	0	-	-	
t _{h(DS)}	Data strobe input hold time	-	0	-	-	
t _{v(RWDS)}	Data strobe output valid time	-	-	-	3 x t _(CK)	
t _{sr(DQ)}	Data input setup time	Rising edge	0	ı	-	
t _{sf(DQ)}	Data input setup time	Falling edge	0	-	-	
t _{hr(DQ)}	Data input hold time	Rising edge	1	ı	-	
t _{hf(DQ)}	Data input noid time	Falling edge	1	ı	-	
	Data output valid time rising	DHQC = 0	-	6	7 ⁽⁵⁾	ns
t _{vr(OUT)}	edge	DHQC = 1, Prescaler = 1,2	-	t _{pclk} /4+ 1	t _{pclk} /4+1.25	
	Data output valid time	DHQC = 0	-	5.5	6 ⁽⁵⁾	
t _{vf(OUT)}	Data output valid time falling edge	DHQC = 1, Prescaler = 1,2	-	t _{pclk} /4+ 0.5	t _{pclk} /4+0.75	
	Data autout hald time vising	DHQC = 0	4.5	-	-	
t _{hr(OUT)}	Data output hold time rising edge	DHQC = 1, Prescaler = 1,2	t _{pclk} /4	-	-	
	Data output hold time falling	DHQC = 0	4.5	-	-	
t _{hf(OUT)}	edge	DHQC = 1, Prescaler = 1,2	t _{pclk} /4	-	-	

^{1.} Guaranteed by characterization results.

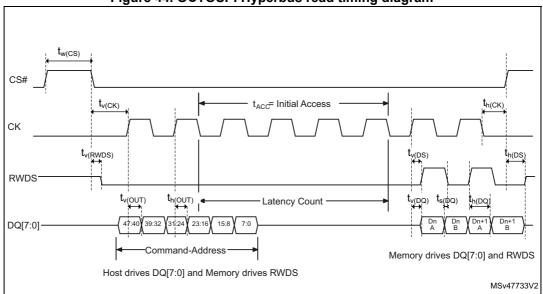


- 2. Maximum frequency values are given for a RWDS to DQ skew of maximum +/-1.0 ns.
- 3. Activating DHQC is mandatory to reach this frequency
- 4. Using PC2 or PC3 I/O on data bus decreases the frequency to 47 MHz.
- 5. Using PC2 or PC3 I/O on the data bus adds 4 ns to this timing value.

Figure 43. OCTOSPI Hyperbus clock timing diagram







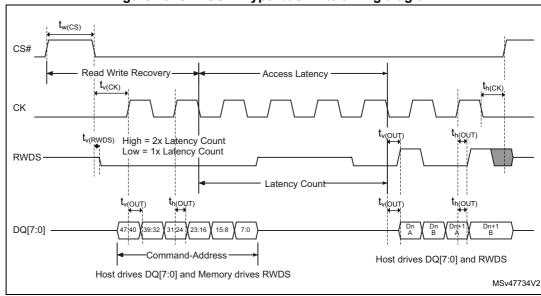


Figure 45. OCTOSPI Hyperbus write timing diagram

6.3.21 Delay block (DLYB) characteristics

Unless otherwise specified, the parameters given in *Table 82* for Delay Block are derived from tests performed under the ambient temperature, f_{rcc_c_ck} frequency and VDD supply voltage summarized in *Table 13: General operating conditions*, with the following configuration:

Symbol Parameter Conditions Unit Min Тур Max Initial delay 900 1300 1900 t_{init} ps 28 33 41 **Unit Delay** t_Δ

Table 82. Delay Block characteristics

6.3.22 16-bit ADC characteristics

Unless otherwise specified, the parameters given in *Table 83*, *Table 84* and *Table 85* are derived from tests performed under the ambient temperature, f_{PCLK2} frequency and V_{DDA} supply voltage conditions summarized in *Table 13: General operating conditions*.

Table 83. 16-bit ADC characteristics⁽¹⁾⁽²⁾

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V_{DDA}	Analog supply voltage for ADC ON	-	1.62	-	3.6	
	Positive	V _{DDA} ≥2 V	1.62	-	V _{DDA}	V
V_{REF+}	reference voltage	V _{DDA} < 2 V		V_{DDA}		V
V _{REF} -	Negative reference voltage	-		V _{SSA}		

Table 83. 16-bit ADC characteristics⁽¹⁾⁽²⁾ (continued)

Symbol	Parameter		Condition	าร		Min	Тур	Max	Unit
					BOOST = 11	0.12	-	50	
	ADC clock	1.62 V ≤ VDDA ≤ 3.6 V			BOOST = 10	0.12	-	25	
f _{ADC}	frequency	1.62 V ≤	VDDA ≤ 3.6 V		BOOST = 01	0.12	-	12.5	MHz
		BOOST = 00					-	6.25	
		Resolution = 16 bits, V _{DDA} >2.5 V	T _J = 90 °C	f _{ADC} = 36 MHz	SMP = 1.5	=	-	3.60	
		Resolution = 16 bits		f _{ADC} = 37 MHz	SMP = 2.5	ı	-	3.35	
		Resolution = 14 bits		f _{ADC} = 50 MHz	SMP = 2.5	ı	-	5.00	
		Resolution = 12 bits	T _J = 125 °C	f _{ADC} = 50 MHz	SMP = 2.5	-	-	5.50	
	Sampling rate for Direct	Resolution = 10 bits	1j - 125 C	f _{ADC} = 50 MHz	SMP = 1.5	-	-	7.10	
	channels	Resolution = 8 bits		f _{ADC} = 50 MHz	SMP = 1.5	-	-	8.30	
		Resolution = 14 bits		f _{ADC} = 49 MHz	SMP = 1.5	-	-	4.90	
		Resolution = 12 bits	T = 140 °C	f _{ADC} = 50 MHz	SMP = 1.5	-	-	5.50	
		Resolution = 10 bits	T _J = 140 °C -	f _{ADC} = 50 MHz	SMP = 1.5	-	-	6.70	
		Resolution = 8 bits		f _{ADC} = 50 MHz	SMP = 1.5	-	-	8.30	
		Resolution = 16 bits, V _{DDA} >2.5 V	T _J = 90 °C	f _{ADC} = 32 MHz	SMP = 2.5	-	-	2.90	
		Resolution = 16 bits		f _{ADC} = 31 MHz	SMP = 2.5	-	-	2.80	0 MSps
f _s ⁽³⁾		Resolution = 14 bits	- T _J = 125 °C	f _{ADC} = 33 MHz	SMP = 2.5	-	-	3.30	
's` ´	Sampling rate	Resolution = 12 bits		f _{ADC} = 39 MHz	SMP = 2.5	-	-	4.30	
	for Fast channels	Resolution = 10 bits		f _{ADC} = 48 MHz	SMP = 2.5	-	-	6.00	
		Resolution = 8 bits		f _{ADC} = 50 MHz	SMP = 2.5	-	-	7.10	7.10
		Resolution = 12 bits		f _{ADC} = 37 MHz	SMP = 2.5	-	-	4.10	
		Resolution = 10 bits	T _J = 140 °C	f _{ADC} = 46 MHz	SMP = 2.5	-	-	5.70	
		Resolution = 8 bits		f _{ADC} = 50 MHz	SMP = 2.5	-	-	7.10	
		Resolution = 16 bits	T _J = 90 °C			-	-		
		resolution = 14 bits				-	-		
	Sampling rate	resolution = 12 bits	T = 405 °C			-	-		
	for Slow	resolution = 10 bits	T _J = 125 °C	f - 10 MH-	CMD = 4.5	-	-	1.00	
	channels, BOOST = 0,	resolution = 8 bits		f _{ADC} = 10 MHz	SMP = 1.5	-	-	1.00	
	f _{ADC} = 10 MHz	resolution = 12 bits				-	-		
		resolution = 10 bits	T _J = 140 °C			-	-		
		resolution = 8 bits				-	-		
t _{TRIG}	External trigger period	Resolution = 16	bits			-	-	10	1/ f _{ADC}
V _{AIN} ⁽⁴⁾	Conversion voltage range	-				0	-	V _{REF+}	V
V_{CMIV}	Common mode input voltage	-				V _{REF} /2 - 10%	V _{REF} /	V _{REF} /2 + 10%	V

Table 83. 16-bit ADC characteristics⁽¹⁾⁽²⁾ (continued)

Symbol	Parameter	Condition	ons		Min	Тур	Max	Unit
		Resolution = 16 bits, T _J = 140 °C			-	-	50	
		Resolution = 16 bits, T _J = 125 °C	-	-	-	-	170	
	Ī	Resolution = 14 bits, T _J = 140 °C			-	-	200	
		Resolution = 14 bits, T _J = 125 °C	-	-	-	-	435	
D (5)	External input	Resolution = 12 bits, T _J = 140 °C			-	-	700	
R _{AIN} ⁽⁵⁾	impedance	Resolution = 12 bits, T _J =125 °C	-	-	-	-	1,150	Ω
		Resolution = 10 bits, T _J = 140 °C			-	-	3,700	
		Resolution = 10 bits, T _J = 125 °C	-	-	-	-	5,650	
		Resolution = 8bits, T _J = 140 °C			-	-	18,000	
	Resolution = 8 bits, T _J = 125 °C	-	-	-	-	26,500		
C _{ADC}	Internal sample and hold capacitor	-			-	4	-	pF
t _{ADCVREG} _STUP	ADC LDO startup time	-			-	5	10	us
t _{STAB}	ADC Power-up time	LDO already started			1	-	-	conver sion cycle
t _{CAL}	Offset and linearity calibration time	-				16,5010		1/f _{ADC}
t _{OFF} _	Offset calibration time	-				1,280		1/f _{ADC}
	Trigger	CKMODE = 00			1.5	2	2.5	
	conversion latency regular	CKMODE = 01			-	-	2.5	1/5
t _{LATR}	and injected channels without	CKMODE = 10			-	-	2.5	1/f _{ADC}
	conversion abort	CKMODE = 11			-	-	2.25	
	Trigger	CKMODE = 00			2.5	3	3.5	
	conversion latency regular	CKMODE = 01			-	-	3.5	
t _{LATRINJ} injected channels	CKMODE = 10			-	-	3.5	1/f _{ADC}	
	aborting a regular conversion	CKMODE = 11			-	-	3.25	
t _S	Sampling time	-			1.5	-	810.5	1/f _{ADC}
t _{CONV}	Total conversion time (including sampling time)	Resolution = N bits			ts + 0.5 + N/2	-	-	1/f _{ADC}

Table 83. 16-bit ADC characteristics⁽¹⁾⁽²⁾ (continued)

Symbol	Parameter	Table 83. 16-bit ADC characteristics		-	Min	Тур	Max	Unit		
	ADC	Resolution = 16 bits, f _{ADC} = 25 MHz	-	-	-	1,440	-			
	consumption on V _{DDA} , BOOST=11,	Resolution = 14 bits, f _{ADC} = 30 MHz	-	-	-	1,350	-			
	BOOST=11, Differential mode	Resolution = 12 bits, f _{ADC} = 40 MHz	-	-	-	990	-			
	ADC	Resolution = 16 bits	-	-	-	1,080	-			
	consumption on V _{DDA} ,	Resolution = 14 bits	-	-	-	810	-			
I _{DDA} _D (ADC)	BOOST=10, Differential mode, f _{ADC} = 25 MHz	Resolution = 12 bits	-	-	-	585	-			
	ADC	Resolution = 16 bits	-	=	-	630	-			
	consumption on V _{DDA} ,	Resolution = 14 bits	-	-	-	432	-			
	BOOST=01, Differential mode, f _{ADC} = 12.5 MHz	Resolution = 12 bits	-	-	-	315	-			
	ADC	Resolution = 16 bits	-	-	-	360	-			
	consumption on V _{DDA,} BOOST=00,	Resolution = 14 bits	-	-	-	270	-			
	BOOST=00, Differential mode, f _{ADC} = 6.25 MHz	Resolution = 12 bits	-	-	-	225	-			
	ADC	Resolution = 16 bits, f _{ADC} =25 MHz	-	-	-	720	-			
	consumption on V _{DDA} ,	Resolution = 14 bits, f _{ADC} =30 MHz	-	-	-	675	-			
	BOOST=11, Single-ended mode	Resolution = 12 bits, f _{ADC} =40 MHz	-	-	-	495		μA		
	ADC consumption on V _{DDA} ,	Resolution = 16 bits	-	-	-	540	-			
		Resolution = 14 bits	-	-	-	405	-			
	BOOST=10, Singl-ended mode, f _{ADC} = 25 MHz	Resolution = 12 bits	-	-	-	292.5	-			
I _{DDA} SE (ADC)	ADC	Resolution = 16 bits	-	=	-	315	-			
	consumption on V _{DDA} , BOOST=01,	Resolution = 14 bits	-	-	-	216	-			
	BOOST=01, Single-ended mode, f _{ADC} = 12.5 MHz	Resolution = 12 bits	-	-	-	157.5	-			
	ADC	Resolution = 16 bits	-	-	-	180	-			
	consumption on V _{DDA}	Resolution = 14 bits	-	-	-	135	-			
	BOOST=00, Single-ended mode f _{ADC} =6.25 MHz	Resolution = 12 bits	-	-	-	112.5	-			
		f _{ADC} =50 MHz	-	=	-	400	-			
	ADC	f _{ADC} =25 MHz	-	-	-	220	-			
I _{DD} (ADC)	consumption on	f _{ADC} =12.5 MHz	-	-	-	180	-			
` -/	V _{DD}	f _{ADC} =6.25 MHz	-	-	-	120	-			
	[f _{ADC} =3.125 MHz	-	=	-	80	-			

^{1.} Guaranteed by design.

^{2.} The voltage booster on ADC switches must be used for V_{DDA} < 2.4 V (embedded I/O switches).

- 3. These values are valid for TFBGA100, UFBGA169 and UFBGA176+25 packages and one ADC. The values for other packages and multiple ADCs may be different.
- 4. Depending on the package, V_{REF^+} can be internally connected to V_{DDA} and V_{REF^-} to V_{SSA} .
- 5. The tolerance is 10 LSBs for 16-bit resolution, 4 LSBs for 14-bit resolution, and 2 LSBs for 12-bit, 10-bit and 8-bit resolutions.

Table 84. Minimum sampling time vs R_{AIN} (16-bit ADC) $^{(1)(2)}$

		Minimum sampling time (s)				
Resolution	RAIN (Ω)	Direct channels ⁽³⁾	Fast channels ⁽⁴⁾	Slow channels ⁽⁵⁾		
16 bits	47	7.37E-08	1.14E-07	1.72E-07		
	47	6.29E-08	9.74E-08	1.55E-07		
	68	6.84E-08	1.02E-07	1.58E-07		
14 bits	100	7.80E-08	1.12E-07	1.62E-07		
	150	9.86E-08	1.32E-07	1.80E-07		
	220	1.32E-07	1.61E-07	2.01E-07		
	47	5.32E-08	8.00E-08	1.29E-07		
	68	5.74E-08	8.50E-08	1.32E-07		
	100	6.58E-08	9.31E-08	1.40E-07		
12 bits	150	8.37E-08	1.10E-07	1.51E-07		
12 bits	220	1.11E-07	1.34E-07	1.73E-07		
	330	1.56E-07	1.78E-07	2.14E-07		
	470	2.16E-07	2.39E-07	2.68E-07		
	680	3.01E-07	3.29E-07	3.54E-07		
	47	4.34E-08	6.51E-08	1.08E-07		
	68	4.68E-08	6.89E-08	1.11E-07		
	100	5.35E-08	7.55E-08	1.16E-07		
	150	6.68E-08	8.77E-08	1.26E-07		
	220	8.80E-08	1.08E-07	1.40E-07		
10 bits	330	1.24E-07	1.43E-07	1.71E-07		
TO DIES	470	1.69E-07	1.89E-07	2.13E-07		
	680	2.38E-07	2.60E-07	2.80E-07		
	1000	3.45E-07	3.66E-07	3.84E-07		
	1500	5.15E-07	5.35E-07	5.48E-07		
	2200	7.42E-07	7.75E-07	7.78E-07		
	3300	1.10E-06	1.14E-06	1.14E-06		

Table 84. Minimum sampling time vs R_{AIN} (16-bit ADC)⁽¹⁾⁽²⁾ (continued)

		Mini	mum sampling tim	ne (s)
Resolution	RAIN (Ω)	Direct channels ⁽³⁾	Fast channels ⁽⁴⁾	Slow channels ⁽⁵⁾
	47	3.32E-08	5.10E-08	8.61E-08
	68	3.59E-08	5.35E-08	8.83E-08
	100	4.10E-08	5.83E-08	9.22E-08
	150	5.06E-08	6.76E-08	9.95E-08
	220	6.61E-08	8.22E-08	1.11E-07
	330	9.17E-08	1.08E-07	1.32E-07
	470	1.24E-07	1.40E-07	1.63E-07
8 bits	680	1.74E-07	1.91E-07	2.12E-07
O Dits	1000	2.53E-07	2.70E-07	2.85E-07
	1500	3.73E-07	3.93E-07	4.05E-07
	2200	5.39E-07	5.67E-07	5.75E-07
	3300	8.02E-07	8.36E-07	8.38E-07
	4700	1.13E-06	1.18E-06	1.18E-06
	6800	1.62E-06	1.69E-06	1.68E-06
	10000	2.36E-06	2.47E-06	2.45E-06
	15000	3.50E-06	3.69E-06	3.65E-06

^{1.} Guaranteed by design.

^{2.} Data valid at up to 130 °C, with a 47 pF PCB capacitor, and V_{DDA} =1.6 V.

^{3.} Direct channels are connected to analog I/Os (PA0_C, PA1_C, PC2_C and PC3_C) to optimize ADC performance.

^{4.} Fast channels correspond to PA6, PB1, PC4, PF11, PF13 for ADCx_INPx, and to PA7, PB0, PC5, PF12, PF14 for ADCx_INNx.

^{5.} Slow channels correspond to all ADC inputs except for the Direct and Fast channels.

Table 85. 16-bit ADC accuracy⁽¹⁾⁽²⁾

Symbol	Parameter	Cor	nditions ⁽³⁾	Min	Тур	Max	Unit
		Direct	Single ended	-	+10/–20	-	
		channel	Differential	-	±15	-	
ET	Total and Protestance	Fast channel	Single ended	-	+10/–20	-	
	Total undadjusted error	rasi channei	Differential	-	±15	-	
		Slow	Single ended	-	±10	-	
		channel	Differential		±10	-	
EO	Offset error		-	-	±10	-	
EG	Gain error		-	-	±15	-	LSB
ED	Differential linearity error	Sin	gle ended	-	+3/–1	-	LOD
ED	Differential linearity error	Di	fferential	-	+4.5/–1	-	
	Integral linearity error	Direct	Single ended	-	±11	-	
		channel	Differential	-	±7	-	
EL		Fast channel	Single ended	-	±13	-	
EL			Differential	-	±7	-	
		Slow	Single ended	-	±10	-	
		channel	Differential	-	±6	-	
ENOB	Effective number of bits	Sin	gle ended	-	12.2	-	Bits
ENOB	Effective number of bits	Di	fferential	-	13.2	-	DILS
CINIAD	Signal-to-noise and	Sin	gle ended	-	75.2	-	
SINAD	distortion ratio	Di	fferential	-	81.2	-	
SNR	Signal to paiga ratio	Sin	gle ended	-	77.0	-	dB
SINK	Signal-to-noise ratio	Di	fferential	-	81.0	-	ub
THD	Total harmonic distortion	Sin	gle ended	-	87	-	
וחט	TOTAL HAITHOUSE CUSTORION	Di	fferential	-	90	-	

^{1.} Guaranteed by characterization results for BGA packages. The values for LQFP packages might differ.

Note:

ADC accuracy vs. negative injection current: injecting a negative current on any analog input pins should be avoided as this significantly reduces the accuracy of the conversion being performed on another analog input. It is recommended to add a Schottky diode (pin to ground) to analog pins which may potentially inject negative currents.

Any positive injection current within the limits specified for $I_{INJ(PIN)}$ and $\Sigma I_{INJ(PIN)}$ does not affect the ADC accuracy.

^{2.} ADC DC accuracy values are measured after internal calibration.

^{3.} ADC clock frequency = 25 MHz, ADC resolution = 16 bits, $V_{DDA}=V_{REF+}=3.3$ V, BOOST=11 and 16-bit mode.

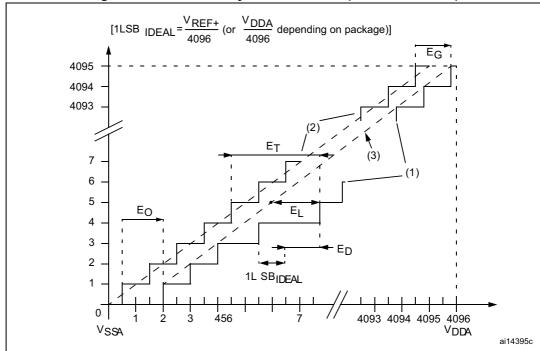


Figure 46. ADC accuracy characteristics (12-bit resolution)

- 1. Example of an actual transfer curve.
- 2. Ideal transfer curve.
- End point correlation line.
- E_T = Total Unadjusted Error: maximum deviation between the actual and the ideal transfer curves. EO = Offset Error: deviation between the first actual transition and the first ideal one. EG = Gain Error: deviation between the last ideal transition and the last actual one.

 - ED = Differential Linearity Error: maximum deviation between actual steps and the ideal one.

EL = Integral Linearity Error: maximum deviation between any actual transition and the end point correlation line.

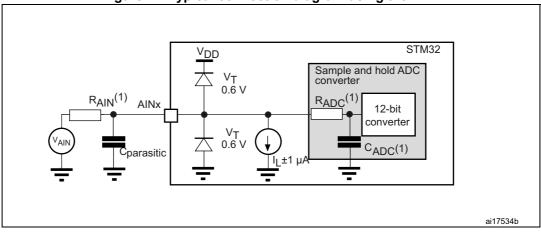


Figure 47. Typical connection diagram using the ADC

- 1. Refer to *Table 83* for the values of R_{AIN}, R_{ADC} and C_{ADC}.
- $C_{parasitic}$ represents the capacitance of the PCB (dependent on soldering and PCB layout quality) plus the pad capacitance (roughly 5 pF). A high $C_{parasitic}$ value downgrades conversion accuracy. To remedy this, f_{ADC} should be reduced.

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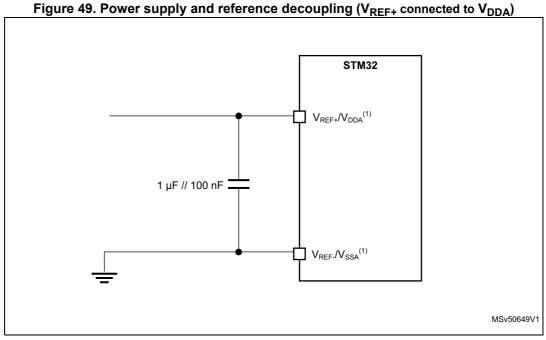
General PCB design guidelines

Power supply decoupling should be performed as shown in Figure 48 or Figure 49, depending on whether V_{RFF+} is connected to V_{DDA} or not. The 100 nF capacitors should be ceramic (good quality). They should be placed them as close as possible to the chip.

STM32 $V_{\mathsf{REF+}}{}^{(1)}$ 1 μF // 100 nF V_{DDA} 1 μF // 100 nF $V_{\text{SSA}}\!/\!V_{\text{REF+}}{}^{(1)}$

Figure 48. Power supply and reference decoupling (V_{REF+} not connected to V_{DDA})

When V_{REF^+} and V_{REF^-} inputs are not available, they are internally connected to V_{DDA} and V_{SSA} , respectively.



When V_{REF^+} and V_{REF^-} inputs are not available, they are internally connected to V_{DDA} and V_{SSA} , respectively.

6.3.23 12-bit ADC characteristics

Unless otherwise specified, the parameters given in *Table 86*, *Table 87* and *Table 88* are derived from tests performed under the ambient temperature and V_{DDA} supply voltage conditions summarized in *Table 13: General operating conditions*. In *Table 86*, *Table 87* and *Table 88*, f_{ADC} refers to $f_{adc_ker_ck}$.

Table 86. 12-bit ADC characteristics⁽¹⁾⁽²⁾

Sym- bol	Parameter		Conditions						Тур	Max	Unit		
V _{DDA}	Analog power supply for ADC ON		-							3.6			
V _{REF+}	Positive reference voltage		V _{DDA} ≥ V _{REF+}							V _{DDA}	V		
V _{REF} -	Negative reference voltage		-						-	1			
f _{ADC}	ADC clock frequency			1,62 V ≤ V _{DDA} :	≤ 3.6 V			1.5	-	75	MHz		
			Continuous and	2.4 V ≤ V _{DDA} ≤ 3.6 V		f _{ADC} = 75 MHz		-	-	5			
				Resolution	Discontinuous mode ⁽⁵⁾	1.6V ≤ V _{DDA} ≤ 3.6 V	40 °C ≤ T _J ≤ 130 °C - , ,	f _{ADC} = 60 MHz	SMP = 2.5	-	-	4	
			= 12 bits		Cia ala mada	2.4 V ≤ V _{DDA} ≤ 3.6 V		f _{ADC} = 50 MHz ⁽⁶⁾		-	-	3.33	
					Single mode	1.6 V ≤ V _{DDA} ≤ 3.6 V		f _{ADC} = 38 MHz ⁽⁶⁾		-	-	2.53	
				Decelution	Continuous and Discontinuous mode ⁽⁵⁾	1.6V ≤ V _{DDA} ≤ 3.6V		f _{ADC} = 75 MHz	SMP	-	-	5.77	
		= 10 bits		Cingle made	2.4 V ≤ V _{DDA} ≤ 3.6 V	–40 °C ≤ T _J ≤ 130 °C	f _{ADC} = 58 MHz ⁽⁶⁾	= 2.5	-	-	4.46		
f _S ⁽⁴⁾	Sampling rate for		Single mode	1.6V ≤ V _{DDA} ≤ 3.6V		f _{ADC} = 42 MHz ⁽⁶⁾		-	-	3.23	MSPS		
J	Direct channels	Resolution	Continuous and Discontinuous mode ⁽⁵⁾	1 1.6V ≤ V _{DDA} ≤ 3.6V	f _{ADC} = 75 MHz		-	-	6.82				
		= 8 bits	Cingle made	2.4 V ≤ V _{DDA} ≤ 3.6 V	–40 °C ≤ T _J ≤ 130 °C	f _{ADC} = 67 MHz ⁽⁶⁾	SMP = 2.5	-	-	6.09			
			Single mode	1.6V ≤ V _{DDA} ≤ 3.6V		f _{ADC} = 48 MHz ⁽⁶⁾		-	-	4.36			
		Pasalution	Continuous and Discontinuous mode ⁽⁵⁾	1.6V ≤ V _{DDA} ≤ 3.6V		f _{ADC} = 75 MHz	SMP	-	-	8.33			
		Resolution - e 6 bits	Single mode	2.4 V ≤ V _{DDA} ≤ 3.6 V	-40 °C ≤ T _J ≤ 130 °C	f _{ADC} = 75 MHz ⁽⁶⁾	= 2.5	-	-	8.33			
			Single mode	1.6V ≤ V _{DDA} ≤ 3.6V		f _{ADC} = 55 MHz ⁽⁶⁾		-	-	6.11			



Table 86. 12-bit ADC characteristics⁽¹⁾⁽²⁾ (continued)

Sym- bol	Parameter			Condition	ıs	•	-	Min	Тур	Max	Unit															
			Continuous and	2.4 V ≤ V _{DDA} ≤ 3.6 V		f _{ADC} = 65 MHz		-	-	4.33																
		Resolution	Discontinuous mode ⁽⁵⁾	1.6V ≤ V _{DDA} ≤ 3.6V	40 %0 < T < 400 %0	f _{ADC} = 58 MHz	SMP	-	-	3.87																
		= 12 bits	Cia ala mada	2.4 V ≤ V _{DDA} ≤ 3.6 V	-40 °C ≤ T _J ≤ 130 °C	f _{ADC} = 32 MHz ⁽⁶⁾	= 2.5	-	-	2.13																
			Single mode	1.6V ≤ V _{DDA} ≤ 3.6V		f _{ADC} = 26 MHz ⁽⁶⁾		-	-	1.73																
		Resolution	Continuous and Discontinuous mode ⁽⁵⁾	1.6V ≤ V _{DDA} ≤ 3.6V		f _{ADC} = 75 MHz	75 z SMP	-	-	5.77																
		= 10 bits		2.4 V ≤ V _{DDA} ≤ 3.6 V	-40 °C ≤ T _J ≤ 130 °C	f _{ADC} = 36 MHz ⁽⁶⁾	= 2.5	-	-	2.77																
	Sampling rate for fast channels (VIN[0:5])	rate for fast		Single mode	1.6V ≤ V _{DDA} ≤ 3.6V		f _{ADC} = 30 MHz ⁽⁶⁾		-	-	2.31															
f _S ⁽⁴⁾		(VIN[0:5])	Decelution	Continuous and Discontinuous mode ⁽⁵⁾	1.6V ≤ V _{DDA} ≤ 3.6V		f _{ADC} = 75 MHz	-	-	6.82																
(conti- nued)		Resolution = 8 bits		2.4 V ≤ V _{DDA} ≤ 3.6 V	-40 °C ≤ T _J ≤ 130 °C	f _{ADC} =44 MHz ⁽⁶⁾	= 2.5	-	-	4.00	MSPS															
			Single mode	1.6V ≤ V _{DDA} ≤ 3.6V		f _{ADC} = 35 MHz ⁽⁶⁾		-	-	3.18																
		Resolution	Resolution = 6 bits Continuous and Discontinuous mode ⁽⁵⁾ Single mode	Pasalution	a Discor mo	and Discontinuous	1.6V ≤ V _{DDA} ≤ 3.6V		f _{ADC} = 75 MHz	SMP	-	-	8.33													
				2.4 V ≤ V _{DDA} ≤ 3.6 V	–40 °C ≤ T _J ≤ 130 °C	f _{ADC} = 56 MHz ⁽⁶⁾	= 2.5	-	-	6.22																
																				Single mode	1.6V ≤ V _{DDA} ≤ 3.6V		f _{ADC} = 42 MHz ⁽⁶⁾		-	-
		Resolution = 12 bits						-	-	1.00	-															
	Sampling rate for slow	Resolution = 10 bits	_	_	40.00 47 - 400.00	f _{ADC} = 15	SMP	-	-	1.28																
	channels	Resolution = 8 bits	-	-	-40 °C ≤ T _J ≤ 130 °C	f _{ADC} = 15 MHz ⁽⁶⁾	= 2.5	-	-	1.63																
		Resolution = 6 bits						-	-	2.08																
t _{TRIG}	External trigger period		Resolution = 12 bits						-	15	1/f _{ADC}															
V _{AIN}	Conversion voltage range	-						0	-	V _{REF+}																
V _{CMIV}	Common mode input voltage			-				V _{REF} /2- 10%	V _{REF} /2	V _{REF} /2 + 10%	V															



Table 86. 12-bit ADC characteristics⁽¹⁾⁽²⁾ (continued)

Sym- bol	Parameter	Conditions	Min	Тур	Max	Unit
		Resolution = 12 bits, T _J = 140 °C (tolerance 4 LSBs)	-	-	321	
		Resolution = 12 bits, T _J = 125 °C	-	-	220	
		Resolution = 10 bits, T _J = 140 °C	-	-	1039	
R _{AIN}	External	Resolution = 10 bits, T _J = 125 °C	-	-	2100	
(7)'	input impedance	Resolution = 8 bits, T _J = 140 °C	-	-	6327	Ω
		Resolution = 8 bits, T _J = 125 °C	-	-	12000	
		Resolution = 6 bits, T _J = 140 °C	-	-	47620	
		Resolution = 6 bits, T _J = 125 °C	-	-	80000	
C _{ADC}	Internal sample and hold capacitor	-	-	5	-	pF
t _{ADCV} REG_ STUP	ADC LDO startup time	-	-	5	10	μs
t _{STAB}	ADC power- up time	LDO already started	1	-	-	con- version cycle
t _{OFF} _ CAL	Offset calibration time	-		-	-	
	Trigger	CKMODE = 00	1.5	2	2.5	
	conversion latency for	CKMODE = 01	-	-	2.5	
t _{LATR}	regular and injected	CKMODE = 10	-	-	2.5	
	channels without aborting the conversion	CKMODE = 11	-	-	2.25	
	Trigger	CKMODE = 00	2.5	3	3.5	
	conversion latency for	CKMODE = 01	-	-	3.5	1/f _{ADC}
t _{LATR}	regular and injected	CKMODE = 10	-	-	3.5	· ···ADC
INJ	channels when a regular conversion is aborted	CKMODE = 11	-	-	3.25	
t _S	Sampling time	-	2.5	-	640.5	
tconv	Total conversion time (including sampling time) N-bits resolution		t _S + 0.5 + N	-	-	

Table 86. 12-bit ADC char	racteristics ⁽¹⁾⁽²⁾ (continued)
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Sym- bol	Parameter	Conditions	Min	Тур	Max	Unit
	ADC	f _S = 5 MSPS	-	430	-	
I _{DDA} _	consumption on V _{DDA} and	f _S = 1 MSPS	-	133	-	
D(ADC)	V _{REF} , Differential mode	f _S = 0.1 MSPS	-	51	-	
	ADC consumption on V _{DDA} and V _{REF} , Single-ended mode	f _S = 5 MSPS	-	350	-	μA
I _{DDA} _ SE		f _S = 1 MSPS	-	122	-	
(ADC)		f _S = 0.1 MSPS	-	47	-	
I _{DD} (ADC)	ADC consumption on V _{DD} per f _{ADC}	-	-	2.4	-	μΑ/ MHz

- 1. Guaranteed by design.
- 2. The voltage booster on ADC switches must be used for V_{DDA} < 2.4 V (embedded I/O switches).
- 3. Depending on the package, VREF+ can be internally connected to V_{DDA} and VREF- to V_{SSA} .
- 4. Guaranteed by characterization for BGA and CSP packages. The values for LQFP packages may be different.
- 5. The conversion of the first element in the group is excluded.
- f_{ADC} value corresponds to the maximum frequency that can be reached considering a 2.5 sampling period. For other SMPy sampling periods, the maximum frequency is f_{ADC} value * SMPy / 2.5 with a limitation to 75 MHz.
- 7. The tolerance is 2 LSBs for 12-bit, 10-bit and 8-bit resolutions. It is otherwise specified.

Table 87. Minimum sampling time vs R_{AIN} (12-bit ADC)⁽¹⁾⁽²⁾

Resolution	R _{AIN} (Ω)	Minimum sampling time (s)					
Resolution		Direct channels ⁽³⁾	Fast channels ⁽⁴⁾	Slow channels ⁽⁵⁾			
	47	5.55E-08	7.04E-08	1.03E-07			
	68	5.76E-08	7.22E-08	1.05E-07			
	100	6.17E-08	7.65E-08	1.07E-07			
12 bits	150	7.02E-08	8.45E-08	1.13E-07			
12 0105	220	8.59E-08	1.00E-07	1.22E-07			
	330	1.11E-07	1.26E-07	1.41E-07			
	470	1.46E-07	1.61E-07	1.69E-07			
	680	1.98E-07	2.17E-07	2.25E-07			



Table 87. Minimum sampling time vs R_{AIN} (12-bit ADC)⁽¹⁾⁽²⁾ (continued)

		Minim	um sampling time (s	
Resolution	R _{AIN} (Ω)	Direct channels ⁽³⁾	Fast channels ⁽⁴⁾	Slow channels ⁽⁵⁾
	47	4.90E-08	6.06E-08	8.77E-08
	68	5.07E-08	6.27E-08	8.95E-08
	100	5.41E-08	6.67E-08	9.22E-08
	150	6.18E-08	7.50E-08	9.59E-08
	220	7.51E-08	8.70E-08	1.04E-07
10 hita	330	9.46E-08	1.07E-07	1.17E-07
10 bits	470	1.22E-07	1.34E-07	1.42E-07
	680	1.63E-07	1.77E-07	1.86E-07
	1000	2.27E-07	2.42E-07	2.43E-07
	1500	3.27E-07	3.40E-07	3.35E-07
	2200	4.53E-07	4.86E-07	4.73E-07
	3300	6.56E-07	6.93E-07	6.72E-07
	47	4.35E-08	5.31E-08	7.36E-08
	68	4.47E-08	5.48E-08	7.47E-08
	100	4.72E-08	5.79E-08	7.63E-08
	150	5.33E-08	6.35E-08	7.88E-08
	220	6.26E-08	7.26E-08	8.47E-08
	330	7.84E-08	8.80E-08	9.48E-08
	470	9.80E-08	1.07E-07	1.14E-07
8 bits	680	1.28E-07	1.39E-07	1.43E-07
o bits	1000	1.76E-07	1.88E-07	1.90E-07
	1500	2.49E-07	2.66E-07	2.64E-07
	2200	3.50E-07	3.63E-07	3.63E-07
	3300	5.09E-07	5.27E-07	5.24E-07
	4700	7.00E-07	7.28E-07	7.09E-07
	6800	9.84E-07	1.03E-06	1.00E-06
	10000	1.43E-06	1.48E-06	1.44E-06
	15000	2.10E-06	2.18E-06	2.11E-06

Table 87. Minimum sampling time vs R_{AIN} (12-bit ADC)⁽¹⁾⁽²⁾ (continued)

Decelution.		Minimu	um sampling time (s)
Resolution	R _{AIN} (Ω)	Direct channels ⁽³⁾	Fast channels ⁽⁴⁾	Slow channels ⁽⁵⁾
	47	3.79E-08	4.58E-08	5.74E-08
	68	3.88E-08	4.69E-08	5.81E-08
	100	4.09E-08	4.89E-08	5.93E-08
	150	4.48E-08	5.25E-08	6.14E-08
	220	5.07E-08	5.81E-08	6.58E-08
	330	6.04E-08	6.79E-08	7.46E-08
	470	7.37E-08	8.10E-08	8.60E-08
6 bits	680	9.31E-08	1.01E-07	1.04E-07
o bits	1000	1.23E-07	1.32E-07	1.34E-07
	1500	1.71E-07	1.82E-07	1.82E-07
	2200	2.39E-07	2.50E-07	2.49E-07
	3300	3.43E-07	3.57E-07	3.49E-07
	4700	4.72E-07	4.92E-07	4.81E-07
	6800	6.65E-07	6.89E-07	6.68E-07
	10000	9.54E-07	9.88E-07	9.54E-07
	15000	1.40E-06	1.45E-06	1.39E-06

^{1.} Guaranteed by design.

^{2.} Data valid up to 130 °C, with a 22 pF PCB capacitor and V_{DDA} = 1.62 V.

^{3.} Direct channels are connected to analog I/Os (PA0_C, PA1_C, PC2_C and PC3_C) to optimize ADC performance.

^{4.} Fast channels correspond to ADCx_INx[0:5].

^{5.} Slow channels correspond to all ADC inputs except for the Direct and Fast channels.

Table 88. 12-bit ADC accuracy⁽¹⁾⁽²⁾

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
		Direct channel	Single ended	-	3.5	5	
			Differential	-	2.5	3	1
ET	Total unadjusted	Fast channel	Single ended	-	3.5	5	•
	error		Differential	-	2.5	3	
		Slow channel	Single ended	-	3.5	5	
			Differential	-	2.5	3	
EO	Offset error	ı		-	+/-2	+/-5	
EG	Gain error	-		-	TBD (3)	-	
ED	Differential linearity	Single ended		-	+/- 0.75	+1.5/- 1	±LSB
LD	error	Differential		-	+/-0.5	+1.25 /-1	
		Direct channel	Single ended	-	+/-1	+/-2.5	
			Differential	-	+/-1	+/-2	
EL	Integral linearity	Fast channel	Single ended	-	+/-1	+/-2.5	
	error		Differential	-	+/-1	+/-2	
		Slow channel	Single ended	-	+/-1	+/-2.5	
			Differential	-	+/-1	+/-2	
ENIOD	Effective	Single ended		-	11.2	-	1.11
ENOB	number of bits	Differential		-	11.5	-	bits
	Signal-to-	Single ended		-	68.9	-	
SINAD	noise and distortion ratio	Differential		-	71.1	-	
SNR	Signal-to-	Single ended		-	69.1	-	dB
SINK	noise ratio	Differential		-	71.4	-	
TUD	Total	Single ended				-	
THD	harmonic distortion	Differential		-	-81.8	-	

Guaranteed by characterization for BGA packages. The maximum values are preliminary data. The values for LQFP packages may be different.

^{2.} ADC DC accuracy values are measured after internal calibration in Continuous and Discontinuous mode.

^{3.} TBD stands for "to be defined".

6.3.24 DAC characteristics

Table 89. DAC characteristics⁽¹⁾

Symbol	Parameter	Condition	ıs	Min	Тур	Max	Unit
V_{DDA}	Analog supply voltage	-	-		3.3	3.6	
V _{REF+}	Positive reference voltage	-		1.80	-	V_{DDA}	V
V _{REF-}	Negative reference voltage	-		-	V_{SSA}	-	
R _I	Resistive Load	DAC output buffer	connected to V _{SSA}	5	-	-	
INL	ixesistive Load	ON	connected to V _{DDA}	25	-	-	kΩ
R _O	Output Impedance	DAC output buf	fer OFF	10.3	13	16	
	Output impedance	DAC output buffer	V _{DD} = 2.7 V	-	-	1.6	
R _{BON}	sample and hold mode, output buffer ON	ÓN	V _{DD} = 2.0 V	-	-	2.6	kΩ
	Output impedance	DAC output buffer	V _{DD} = 2.7 V	-	-	17.8	
R _{BOFF}	sample and hold mode, output buffer OFF	OFF $V_{DD} = 2.0$ V		-	-	18.7	kΩ
C _L	Capacitive Load	DAC output buf	fer OFF	-	-	50	pF
C _{SH}	Supuoliivo Loud	Sample and Hol	ld mode	-	0.1	1	μF
V _{DAC_OUT}	Voltage on DAC_OUT	DAC output but	ffer ON	0.2	-	V _{DDA} -0.2	V
	output	DAC output buf	fer OFF	0	-	V _{REF+}	
	Cattling times (full apple)		±0.5 LSB	-	2.05	3	
	Settling time (full scale: for a 12-bit code transition	Normal mode, DAC	±1 LSB	-	1.97	2.87	
	between the lowest and the highest input codes	output buffer ON, C _L ≤ 50 pF,	±2 LSB	-	1.67	2.84	
t _{SETTLING}	when DAC_OUT reaches	R _L ≥ 5 kΩ	±4 LSB	-	1.66	2.78	μs
	the final value of ±0.5LSB, ±1LSB, ±2LSB, ±4LSB,		±8 LSB	-	1.65	2.7	
	±8LSB)	Normal mode, DAC of OFF, ±1LSB C _L		1	1.7	2	
. (2)	Wakeup time from off state (setting the ENx bit	Normal mode, DAC output buffer ON, C _L ≤ 50 pF, R _L = 5 kΩ		-	5	7.5	
t _{WAKEUP} ⁽²⁾	in the DAC Control register) until the final value of ±1LSB is reached	Normal mode, DAC of OFF, C _L ≤ 1			2	5	μs
PSRR	DC V _{DDA} supply rejection ratio	Normal mode, DAC on $C_L \le 50 \text{ pF}$,		-	-80	-28	dB



Table 89. DAC characteristics⁽¹⁾ (continued)

Symbol	Parameter	9. DAC Characteris	•	Min	Тур	Max	Unit
	Sampling time in Sample and Hold mode	MODE<2:0>_V12 (BUFFER (ı	0.7	2.6	ms
t _{SAMP}	C _L =100 nF (code transition between the lowest input code and	MODE<2:0>_V (BUFFER C		-	11.5	18.7	1113
	the highest input code when DAC_OUT reaches the ±1LSB final value)		MODE<2:0>_V12=111 (INTERNAL BUFFER OFF)		0.3	0.6	μs
I _{leak}	Output leakage current	-			(3)		nA
C _{lint}	Internal sample and hold capacitor	-		1.8	2.2	2.6	pF
t _{TRIM}	Middle code offset trim time	Minimum time to ve code	rify the each	50	-	-	μs
	Middle code offset for 1	V _{REF+} = 3.	6 V	-	850	-	μV
V _{offset}	trim code step	V _{REF+} = 1.	8 V	-	425	-	μν
		DAC output buffer	No load, middle code (0x800)	-	360	-	
	DAC quiescent consumption from V _{DDA}	ON	No load, worst code (0xF1C)	-	490	-	
I _{DDA(DAC)}		DAC output buffer OFF	No load, middle/ worst code (0x800)	-	20	-	
		Sample and Hol C _{SH} =100		-	360*T _{ON} / (T _{ON} +T _{OFF})	-	
		DAC output buffer	No load, middle code (0x800)	-	170	-	μA
		ON	No load, worst code (0xF1C)	-	170	-	
I _{DDV} (DAC)	DAC consumption from V _{REF+}	DAC output buffer OFF	No load, middle/ worst code (0x800)	-	160	-	
		Sample and Hold m ON, C _{SH} =100 nF (v		-	170*T _{ON} / (T _{ON} +T _{OFF})	-	
		Sample and Hold m OFF, C _{SH} =100 nF (-	160*T _{ON} / (T _{ON} +T _{OFF})	-	

^{1.} Guaranteed by design unless otherwise specified.

- 2. In buffered mode, the output can overshoot above the final value for low input code (starting from the minimum value).
- 3. Refer to Table 54: I/O static characteristics.
- 4. T_{ON} is the refresh phase duration, while T_{OFF} is the hold phase duration. Refer to the product reference manual for more details.

Table 90. DAC accuracy⁽¹⁾

Symbol	Parameter	Cond	Conditions		Тур	Max	Unit
DNL	Differential non	DAC outpu	it buffer ON	-2	-	2	LSB
DINL	linearity ⁽²⁾	DAC outpu	t buffer OFF	-2	-	2	LOB
-	Monotonicity	10	bits	-	-	-	-
INII	Late and see the exit (3)		OAC output buffer ON, $C_L \le 50$ pF, $R_L \ge 5 \text{ k}\Omega$		-	4	LOD
INL	Integral non linearity ⁽³⁾		buffer OFF, pF, no R _L	-4	-	4	- LSB
		DAC output	V _{REF+} = 3.6 V	-	-	±12	
Offset	Offset error at code 0x800 (3)	buffer ON, C _L ≤ 50 pF, R _L ≥ 5 kΩ	V _{REF+} = 1.8 V	-	-	±25	LSB
			buffer OFF, pF, no R _L	-	-	±8	
Offset1	Offset error at code 0x001 ⁽⁴⁾		buffer OFF, pF, no R _L	-	-	±5	LSB
	Offset error at code	DAC output	V _{REF+} = 3.6 V	-	-	±5	
OffsetCal	0x800 after factory calibration	buffer ON, C _L ≤ 50 pF, R _L ≥ 5 kΩ	V _{REF+} = 1.8 V	-	-	±7	LSB
Gain	Gain error ⁽⁵⁾		er ON,C _L ≤ 50 pF, : 5 kΩ	-	-	±1	%
Gaili	Gain enor		buffer OFF, pF, no R _L	-	-	±1	70
TUE	Total unadjusted error		r ON, C _L ≤ 50 pF, 5 kΩ	-	-	±30	
TOE	Total unaujusted error		DAC output buffer OFF, C _L ≤ 50 pF, no R _L			±12	LSB
TUECal	Total unadjusted error after calibration	DAC output buffer ON, $C_L \le 50 \text{ pF}$, $R_L \ge 5 \text{ k}\Omega$		-	-	±23	
		DAC output buffe $R_L \ge 5 \text{ k}\Omega$, 1 kH	r ON,C _L ≤ 50 pF, z, BW = 500 KHz	-	67.8	-	
SNR	Signal-to-noise ratio ⁽⁶⁾	$C_L \le 50 \text{ pF, no}$	buffer OFF, R _L ,1 kHz, BW = KHz	-	67.8	-	dB



		3 (,			
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
THD	THD Total harmonic distortion ⁽⁶⁾	DAC output buffer ON, $C_L \le 50$ pF, $R_L \ge 5 \text{ k}\Omega$, 1 kHz	-	-78.6	-	dB
THD		DAC output buffer OFF, $C_L \le 50 \text{ pF, no R}_L, 1 \text{ kHz}$	-	-78.6	-	uв
SINAD	Signal-to-noise and	DAC output buffer ON, $C_L \le 50$ pF, $R_L \ge 5 \text{ k}\Omega$, 1 kHz	-	67.5	-	dB
SINAD	distortion ratio ⁽⁶⁾	DAC output buffer OFF, $C_L \le 50 \text{ pF, no R}_L, 1 \text{ kHz}$	-	67.5	-	ив
ENOR	Effective number of	DAC output buffer ON, $C_L \le 50 \text{ pF, } R_L \ge 5 \text{ k}\Omega$, 1 kHz	-	10.9	-	bits
ENOB	bits	DAC output buffer OFF, C _L ≤ 50 pF, no R _L , 1 kHz	-	10.9	-	DILS

Table 90. DAC accuracy⁽¹⁾ (continued)

- 1. Guaranteed by characterization results.
- 2. Difference between two consecutive codes minus 1 LSB.
- Difference between the value measured at Code i and the value measured at Code i on a line drawn between Code 0 and last Code 4095.
- 4. Difference between the value measured at Code (0x001) and the ideal value.
- Difference between the ideal slope of the transfer function and the measured slope computed from code 0x000 and 0xFFF when the buffer is OFF, and from code giving 0.2 V and $(V_{REF+}$ 0.2 V) when the buffer is ON.
- 6. Signal is -0.5 dBFS with $F_{sampling}$ =1 MHz.

Buffered/Non-buffered DAC Buffer(1) R_{I} DAC_OUTx 12-bit digital to analog converter $^{\rm C}$ $^{\rm L}$

Figure 50. 12-bit buffered /non-buffered DAC

The DAC integrates an output buffer that can be used to reduce the output impedance and to drive external loads directly without the use of an external operational amplifier. The buffer can be bypassed by configuring the BOFFx bit in the DAC_CR register.

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6.3.25 Voltage reference buffer characteristics

Table 91. VREFBUF characteristics⁽¹⁾

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
			VSCALE = 000	2.8	3.3	3.6	
		Normal mode,	VSCALE = 001	2.4	-	3.6	
		V _{DDA} = 3.3 V	VSCALE = 010	2.1	-	3.6	
\ \ <u>\</u>	Analog aunnhy valtage		VSCALE = 011	1.8	-	3.6	
V_{DDA}	Analog supply voltage		VSCALE = 000	1.62	-	2.80	
		Degraded mode ⁽²⁾	VSCALE = 001	1.62	-	2.40	
		Degraded mode.	VSCALE = 010	1.62	-	2.10	
		VS	VSCALE = 011	1.62	-	1.80	
			VSCALE = 000	2.4980	2.5000	2.5035	
		Normal mode at 30 °C,	VSCALE = 001	2.0460	2.0490	2.0520	V
		I _{load} = 100 μA	VSCALE = 010	1.8010	1.8040	1.8060	
	_OUT I _{load} = 100 μA		VSCALE = 011	1.4995	1.5015	1.5040	
V _{REFBUF}			VSCALE = 000	V _{DDA} - 150 mV	-	V_{DDA}	
_OUT		I _{load} = 100 μA Degraded mode ⁽²⁾	VSCALE = 001	V _{DDA} - 150 mV	-	V_{DDA}	
		•	VSCALE = 010	V _{DDA} - 150 mV	-	V_{DDA}	
			VSCALE = 011	V _{DDA} - 150 mV	-	V_{DDA}	
TRIM	Trim step resolution	-	-	-	±0.05	±0.1	%
C _L	Load capacitor	-	-	0.5	1	1.50	μF
esr	Equivalent Serial Resistor of C _L	-	-	-	-	2	Ω
I _{LOAD}	Static load current	-	-	-	-	4	mA
	l in a va sudation	201/41/4	I _{load} = 500 μA	-	200	-	Λ <i>(</i>
I _{line_reg}	Line regulation	2.8 V ≤ V _{DDA} ≤ 3.6 V	I _{load} = 4 mA	-	100	-	ppm/V
I _{load_reg}	Load regulation	500 μA ≤ I _{LOAD} ≤ 4 mA	Normal mode	-	50	-	ppm/ mA
T _{coeff}	Temperature coefficient	-40 °C < T _J <	+130 °C	-	-	T _{coeff} V _{REFINT} + 100	ppm/ °C
PSRR	Power supply rejection	DC	-	-	60	-	dB
I OILI	1 Swel Supply rejection	100KHz	-	-	40	-	QD.

Symbol	Parameter	Condition	ons	Min	Тур	Max	Unit
		C _L =0.5 μF	-	-	300	-	
t _{START}	Start-up time	C _L =1 μF	-	-	500	-	μs
		C _L =1.5 μF	-	-	650	-	
I _{INRUSH}	Control of maximum DC current drive on V _{REFBUF_OUT} during startup phase ⁽³⁾	-		-	8	-	mA
	VREFBUF	I _{LOAD} = 0 μA	-	-	15	25	
I _{DDA} (VREFBUF)	consumption from	I _{LOAD} = 500 μA	-	ı	16	30	μΑ
	V_{DDA}	I _{LOAD} = 4 mA	-	-	32	50	

- 1. Guaranteed by design, unless otherwise specified.
- 2. In degraded mode, the voltage reference buffer cannot accurately maintain the output voltage (V_{DDA}-drop voltage).
- 3. To properly control VREFBUF I_{INRUSH} current during the startup phase and the change of scaling, V_{DDA} voltage should be in the range of 1.8 V-3.6 V, 2.1 V-3.6 V, 2.4 V-3.6 V and 2.8 V-3.6 V for VSCALE = 011, 010, 001 and 000, respectively.

6.3.26 Analog temperature sensor characteristics

Table 92. Temperature sensor characteristics

Symbol	Parameter	Min	Тур	Max	Unit
T _L ⁽¹⁾	V _{SENSE} linearity with temperature	-	-	3	°C
Avg_Slope ⁽²⁾	Average slope	-	2	-	mV/°C
V ₃₀ ⁽³⁾	Voltage at 30°C ± 5 °C	-	0.62	-	٧
t _{start_run}	Startup time in Run mode (buffer startup)	-	-	25.2	116
t _{S_temp} ⁽¹⁾	ADC sampling time when reading the temperature	9	-	-	μs
I _{sens} ⁽¹⁾	Sensor consumption	-	0.18	0.31	μA
I _{sensbuf} ⁽¹⁾	Sensor buffer consumption	-	3.8	6.5	μΛ

- 1. Guaranteed by design.
- 2. Guaranteed by characterization results.
- 3. Measured at V_{DDA} = 3.3 V \pm 10 mV. The V_{30} ADC conversion result is stored in the TS_CAL1 byte.

Table 93. Temperature sensor calibration values

Symbol	Parameter	Memory address
TS_CAL1	Temperature sensor raw data acquired value at 30 °C, V _{DDA} =3.3 V	0x1FF1 E820 -0x1FF1 E821
TS_CAL2	Temperature sensor raw data acquired value at 110 °C, V _{DDA} =3.3 V	0x1FF1 E840 - 0x1FF1 E841

6.3.27 Digital temperature sensor characteristics

Table 94. Digital temperature sensor characteristics⁽¹⁾

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
f _{DTS} ⁽²⁾	Output Clock frequency	-	500	750	1150	kHz
T _{LC} ⁽²⁾	Temperature linearity coefficient	VOS2	1660	2100	2750	Hz/° C
T _{TOTAL} ERROR	Temperature offset	T _J = -40°C to 30°C	-13	-	4	°C
(2)	measurement, all VOS	T _J = 30°C to Tjmax	-7	-	2	
	Additional arror due to aupply	VOS2	0	-	0	
T _{VDD_CORE}	Additional error due to supply variation	VOS0, VOS1, VOS3	-1	-	1	°C
t _{TRIM}	Calibration time	-	-	-	2	ms
t _{WAKE_UP}	Wake-up time from off state until DTS ready bit is set	-	-	67	116.00	μs
I _{DDCORE_DTS}	DTS consumption on VDD_CORE	-	8.5	30	70.0	μA

^{1.} Guaranteed by design, unless otherwise specified.

6.3.28 Temperature and V_{BAT} monitoring

Table 95. V_{BAT} monitoring characteristics

Symbol	Parameter	Min	Тур	Max	Unit
R	Resistor bridge for V _{BAT}	-	26	-	ΚΩ
Q	Ratio on V _{BAT} measurement	-	4	-	-
Er ⁽¹⁾	Error on Q	-10	-	+10	%
t _{S_vbat} (1)	ADC sampling time when reading V _{BAT} input	9	-	-	μs
V _{BAThigh}	High supply monitoring		3.55	-	V
V _{BATIow}	Low supply monitoring	-	1.36	-	V

^{1.} Guaranteed by design.

Table 96. V_{BAT} charging characteristics

Symbol	Parameter	Condition	Min	Тур	Max	Unit
R _{BC}	Battery charging resistor -	VBRS in PWR_CR3= 0	-	5	-	ΚΩ
		VBRS in PWR_CR3= 1		1.5	-	1/22



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^{2.} Guaranteed by characterization results.

Table 97. Temperature monitoring characteristics

Symbol	Parameter	Min	Тур	Max	Unit
TEMP _{high}	High temperature monitoring	-	117	-	°C
TEMP _{low}	Low temperature monitoring	-	- 25	-	

6.3.29 Voltage booster for analog switch

Table 98. Voltage booster for analog switch characteristics⁽¹⁾

Symbol	Parameter	Condition	Min	Тур	Max	Unit
V_{DD}	Supply voltage	-	1.62	2.6	3.6	V
t _{SU(BOOST)}	Booster startup time	-	-	-	50	μs
I _{DD(BOOST)}	Booster consumption	1.62 V ≤ V _{DD} ≤ 2.7 V	-	-	125	μA
		2.7 V < V _{DD} < 3.6 V	-	-	250	μΑ

^{1.} Guaranteed by characterization results.

6.3.30 Comparator characteristics

Table 99. COMP characteristics⁽¹⁾

Symbol	Parameter	Conditions		Тур	Max	Unit	
V _{DDA}	Analog supply voltage	-	1.62	3.3	3.6		
V _{IN}	Comparator input voltage range	-	0	-	V_{DDA}	V	
V _{BG}	Scaler input voltage	-		(2)			
V _{SC}	Scaler offset voltage	-	-	±5	±10	mV	
1	Scaler static consumption	BRG_EN=0 (bridge disable)	-	0.2	0.3		
IDDA(SCALER)	from V _{DDA}	BRG_EN=1 (bridge enable)	-	8.0	1	μΑ	
t _{START_SCALER}	Scaler startup time	-		140	250	μs	
	Comparator startup time to reach propagation delay specification	High-speed mode	-	2	5		
t _{START}		Medium mode	-	5	20	μs	
		Ultra-low-power mode	-	15	80		
	Propagation delay for	High-speed mode	-	50	80	ns	
	200 mV step with 100 mV overdrive	Medium mode	-	0.5	0.9		
4 (3)		Ultra-low-power mode	-	2.5	7	μs	
t _D ⁽³⁾	Propagation delay for step > 200 mV with 100 mV overdrive only on positive inputs	High-speed mode	-	50	120	ns	
		Medium mode	-	0.5	1.2		
		Ultra-low-power mode	-	2.5	7	μs	
V _{offset}	Comparator offset error	Full common mode range	-	±5	±20	mV	

Symbol	Parameter	Co	Min	Тур	Max	Unit	
V		No	No hysteresis		0	-	
	Comparator hystorogia	Low	hysteresis	4	10	22	mV
V_{hys}	Comparator hysteresis	Mediu	m hysteresis	8	20	37	
		High hysteresis		16	30	52	
	Comparator consumption from V _{DDA}	Ultra-low- power mode	Static	-	400	600	nA
			With 50 kHz ±100 mV overdrive square signal	-	800	-	
		Medium mode	Static	-	5	7	
I _{DDA} (COMP)			With 50 kHz ±100 mV overdrive square signal	-	6	-	^
			Static	-	70	100	μA
		High-speed mode	With 50 kHz ±100 mV overdrive square signal	-	75	-	

Table 99. COMP characteristics⁽¹⁾ (continued)

6.3.31 Operational amplifier characteristics

Table 100. Operational amplifier characteristics⁽¹⁾

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V _{DDA} Analog supply voltage Range		-	2	3.3	3.6	V
CMIR	Common Mode Input Range	-	0	-	V_{DDA}	V
		25°C, no load on output	-	-	±1.5	
VI _{OFFSET}	Input offset voltage	All voltages and temperature, no load	-	-	±2.5	mV
ΔVI _{OFFSET}	Input offset voltage drift	-	-	±3.0	-	μV/°C
TRIMOFFSETP TRIMLPOFFSETP Offset trim step at low common input voltage (0.1*V _{DDA})		-	-	1.1	1.5	- mV
TRIMOFFSETN TRIMLPOFFSETN	Offset trim step at high common input voltage (0.9*V _{DDA})	-	-	1.1	1.5	1110
I _{LOAD}	Drive current	-		-	500	
I _{LOAD_PGA}	Drive current in PGA mode	-	-	-	270	μΑ

^{1.} Guaranteed by design, unless otherwise specified.

^{2.} Refer to Table 21: Embedded reference voltage.

^{3.} Guaranteed by characterization results.

Table 100. Operational amplifier characteristics⁽¹⁾ (continued)

Symbol	Parameter	С	onditions	Min	Тур	Max	Unit
C _{LOAD}	Capacitive load		-	-	-	50	pF
CMRR	Common mode rejection ratio		-	-	80	-	dB
PSRR	Power supply rejection ratio	R _{LOAD} ≥	$_{\text{OAD}}$ ≤ 50pf / 4 kΩ ⁽²⁾ at 1 kHz, $_{\text{om}}$ =V _{DDA} /2	50	66	-	dB
GBW	Gain bandwidth for high supply range		≤ Output dynamic ≤ V _{DDA} - 200 mV	4	7.3	12.3	MHz
SR	Slew rate (from 10% and	No	ormal mode	-	3	-	\//uc
3K	90% of output voltage)	High	-speed mode	-	24	-	V/µs
AO	Open loop gain		≤ Output dynamic ≤ V _{DDA} - 200 mV	59	90	129	dB
φm	Phase margin		-	-	55	-	۰
GM	Gain margin		-	-	12	-	dB
V _{OHSAT}	High saturation voltage	I _{load} =max or R _{LOAD} =min, Input at V _{DDA}		V _{DDA} -100 mV	-	-	mV
V _{OLSAT}	Low saturation voltage	I _{load} =max or R _{LOAD} =min, Input at 0 V		-	-	100	1110
•	Wake up time from OFF state	Normal mode	$C_{LOAD} \le 50 pf$, $R_{LOAD} \ge 4 k\Omega$, follower configuration	-	0.8	3.2	5
^t WAKEUP		High speed	$C_{LOAD} \le 50 pf$, $R_{LOAD} \ge 4 k\Omega$, follower configuration	-	0.9	2.8	- µs
		PC	GA gain = 2	-1	-	1	
	Non inverting gain error	PGA gain = 4		-2	-	2	
	value	PGA gain = 8		-2.5	-	2.5	
		PG	A gain = 16	-3	-	3	
		PC	GA gain = 2	-1	-	1	
DCAi-	Invention nois sees	PC	GA gain = 4	-1	-	1	0,
PGA gain	Inverting gain error value	PGA gain = 8		-2	-	2	- %
		PGA gain = 16		-3	-	3]
		PGA gain = 2		-1	-	1]
	External non-inverting gain	PGA gain = 4		-3	-	3	
	error value	PC	GA gain = 8	-3.5	-	3.5]
	Ī	PGA gain = 16		-4	_	4	

Table 100. Operational amplifier characteristics⁽¹⁾ (continued)

Symbol	Parameter	С	onditions	Min	Тур	Max	Unit	
		P	GA Gain=2	-	10/10	-		
	R2/R1 internal resistance	P	GA Gain=4	-	30/10	-		
	values in non-inverting PGA mode ⁽³⁾	P	GA Gain=8	1	70/10	-	-	
В		PC	GA Gain=16	-	150/10	-	kΩ/	
R _{network}		PG	GA Gain = -1	-	10/10	-	kΩ	
	R2/R1 internal resistance values in inverting PGA	PG	SA Gain = -3	-	30/10	-		
	mode ⁽³⁾	PG	SA Gain = -7	-	70/10	-		
		PG.	A Gain = -15	ı	150/10	ı		
Delta R	Resistance variation (R1 or R2)	-		-15	1	15	%	
			Gain=2	-	GBW/2	-		
	PGA bandwidth for different non inverting gain	PGA bandwidth for Gain=4		-	GBW/4	-	MHz	
		Gain=8		-	GBW/8	-		
PGA BW		Gain=16		ı	GBW/16	ı		
TOABW		Gain = -1		ı	5.00	i		
	PGA bandwidth for	Gain = -3		-	3.00	-	- MHz	
	different inverting gain	Gain = -7		-	1.50	-		
		(Gain = -15	1	0.80	ı		
on	Voltage noise density	at 1 KHz	output loaded	-	140	-	nV/√	
en	voltage hoise density	at 10 KHz	with 4 kΩ	-	55	-	Hz	
	ODAMD consumption for the	Normal mode	no Load,	-	570	1000		
I _{DDA(OPAMP)}	OPAMP consumption from - V _{DDA}	High- speed mode	quiescent mode, follower	-	610	1200	μA	

^{1.} Guaranteed by design, unless otherwise specified.

^{2.} R_{LOAD} is the resistive load connected to $V_{SSA} \, \text{or to} \, V_{DDA}.$

^{3.} R2 is the internal resistance between the OPAMP output and th OPAMP inverting input. R1 is the internal resistance between the OPAMP inverting input and ground. PGA gain = 1 + R2/R1.

6.3.32 Digital filter for Sigma-Delta Modulators (DFSDM) characteristics

Unless otherwise specified, the parameters given in *Table 101* for DFSDM are derived from tests performed under the ambient temperature, fPCLKx frequency and supply voltage conditions summarized in *Table 13: General operating conditions*.

- Output speed is set to OSPEEDRy[1:0] = 10
- Capacitive load C₁ = 30 pF
- Measurement points are done at CMOS levels: 0.5V_{DD}
- VOS level set to VOS0

Refer to Section 6.3.17: I/O port characteristics for more details on the input/output alternate function characteristics (DìFSDM_CKINx, DFSDM_DATINx, DFSDM_CKOUT for DFSDM).

Table 101. DFSDM measured timing

Symbol	Parameter	Cond	itions	Min	Тур	Max	Unit	
f _{DFSDMCLK}	DFSDM clock	1.62 < V _E	1.62 < V _{DD} < 3.6 V		-	f _{SYSCLK}		
f _{CKIN}	Input clock	(SITP[1: External o	mode 0] = 0,1), clock mode EL[1:0] = 0)	-	-	20	MHz	
(1/T _{CKIN})	frequency	(SITP[1: Internal c	mode 0] = 0,1), lock mode EL[1:0] # 0)	-	-	20	IVITZ	
f _{CKOUT}	Output clock frequency	1.62 < V _E	_{DD} < 3.6 V	-	-	20		
DuCv	Output clock		1.62 < V _{DD}	Even division, CKOUTDIV = n, 1, 3, 5	45	50	55	%
DuCy _{CKOUT}	frequency duty cycle < 3.6 V		Odd division, CKOUTDIV = n, 2, 4, 6	(((n/2+1)/(n+1)) *100)-5	(((n/2+1)/(n+1)) *100)	(((n/2+1)/(n+1)) *100)+5	/0	

Table 101. DFSDM measured timing (continued)

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
t _{wh(CKIN)}	Input clock high and low time	SPI mode (SITP[1:0] = 0,1), External clock mode (SPICKSEL[1:0] = 0)	T _{CKIN} /2-0.5	T _{CKIN} /2	-	
t _{su}	Data input setup time	SPI mode (SITP[1:0] = 0,1), External clock mode (SPICKSEL[1:0] = 0)	2	-	-	ns
t _h	Data input hold time	SPI mode (SITP[1:0] = 0,1), External clock mode (SPICKSEL[1:0] = 0)	1	-	-	115
T _{Manchester}	Manchester data period (recovered clock period)	Manchester mode (SITP[1:0] = 2,3), Internal clock mode (SPICKSEL[1:0] # 0)	(CKOUTDIV+1) * T _{DFSDMCLK}		(2*CKOUTDIV) * T _{DFSDMCLK}	

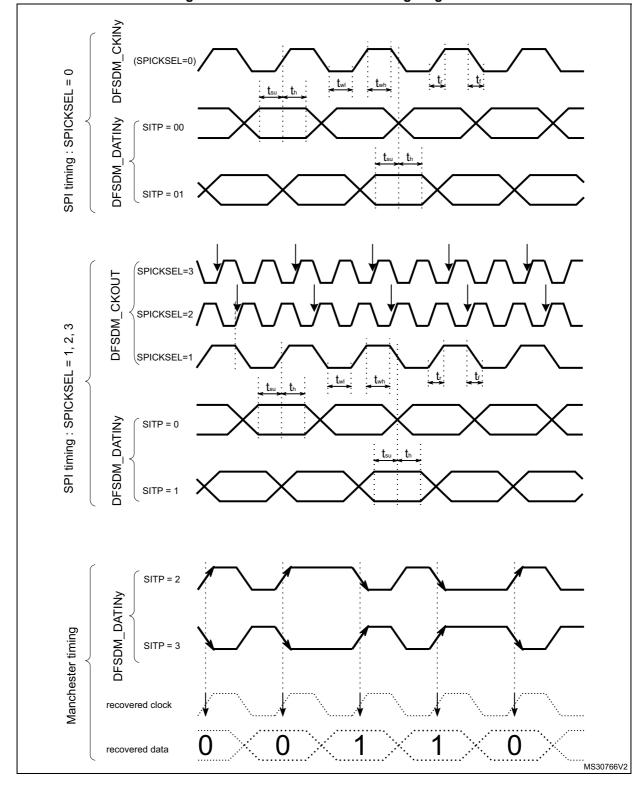


Figure 51. Channel transceiver timing diagrams



6.3.33 Camera interface (DCMI) timing specifications

Unless otherwise specified, the parameters given in *Table 102* for DCMI are derived from tests performed under the ambient temperature, f_{HCLK} frequency and VDD supply voltage summarized in *Table 13: General operating conditions*, with the following configuration:

- DCMI_PIXCLK polarity: falling
- DCMI_VSYNC and DCMI_HSYNC polarity: high
- Data formats: 14 bits
- Capacitive load C_L=30 pF
- Measurement points are done at CMOS levels: 0.5V_{DD}
- VOS level set to VOS0

Table 102. DCMI characteristics⁽¹⁾

Symbol	Parameter	Min	Max	Unit
-	Frequency ratio DCMI_PIXCLK/f _{HCLK}		0.4	-
DCMI_PIXCLK	Pixel Clock input		110	MHz
D _{pixel}	Pixel Clock input duty cycle	30	70	%
t _{su(} DATA)	Data input setup time	2	-	
t _h (DATA)	Data hold time	1	-	
tsu(HSYNC), tsu(VSYNC)	DCMI_HSYNC/ DCMI_VSYNC input setup time	2	-	ns
th(HSYNC), th(VSYNC)	DCMI_HSYNC/ DCMI_VSYNC input hold time	1	-	

^{1.} Guaranteed by characterization results.

DCMI_PIXCLK

DCMI_PIXCLK

DCMI_HSYNC

DCMI_HSYNC

DCMI_VSYNC

DATA[0:13]

MS32414V2

Figure 52. DCMI timing diagram

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6.3.34 Parallel synchronous slave interface (PSSI) characteristics

Unless otherwise specified, the parameters given in *Table 103* and *Table 104* for PSSI are derived from tests performed under the ambient temperature, f_{HCLK} frequency and VDD supply voltage summarized in *Table 13: General operating conditions*.

Table 103. PSSI transmit characteristics⁽¹⁾

Symbol	Parameter	Min	Max	Unit
-	Frequency ratio PSSI_PDCK/f _{HCLK}	-	0.4	-
Deel DDek	DCCI Clock input	-	50	MHz
PSSI_PDCK	PSSI Clock input	-	35 ⁽²⁾	IVITZ
D _{pixel}	PSSI Clock input duty cycle	30	70	%
t _{ov} (DATA)	Data output valid time	-	10	
-	-	-	14 ⁽²⁾	
t _{oh} (DATA)	Data output hold time	4.5	-	
t _{ov(} (DE)	DE output valid time	-	10	ns
t _{oh} (DE)	DE output hold time	4	-	
tsu(RDY)	RDY input setup time	0	-	
th(RDY)	RDY input hold time	0	-	

^{1.} Guaranteed by characterization results.

Table 104. PSSI receive characteristics⁽¹⁾

Symbol	Parameter	Min	Max	Unit
-	Frequency ratio PSSI_PDCK/f _{HCLK}		0.4	-
PSSI_PDCK	PSSI Clock input	-	110	MHz
D _{pixel}	PSSI Clock input duty cycle	30	70	%
t _{su} (DATA)	Data input setup time	1.5	-	
t _h (DATA)	Data input hold time	0.5	-	
t _{su(} (DE)	DE input setup time	2	-	ns
t _h (DE)	t _h (DE) DE input hold time		-	115
tov(RDY)	tov(RDY) RDY output valid time		15	
toh(RDY)	RDY output hold time	5.5	-	

^{1.} Guaranteed by characterization results.

^{2.} This value is obtained by using PA9, PA10 or PH4 I/O.

6.3.35 LCD-TFT controller (LTDC) characteristics

Unless otherwise specified, the parameters given in *Table 105* for LCD-TFT are derived from tests performed under the ambient temperature, f_{HCLK} frequency and VDD supply voltage summarized in *Table 13: General operating conditions*, with the following configuration:

- LCD_CLK polarity: high
- LCD_DE polarity: low
- LCD_VSYNC and LCD_HSYNC polarity: high
- Pixel formats: 24 bits
- Output speed is set to OSPEEDRy[1:0] = 11
- Capacitive load C_L=30 pF
- Measurement points are done at CMOS levels: 0.5VDD
- IO Compensation cell activated.
- HSLV activated when V_{DD} ≤ 2.7 V
- VOS level set to VOS0

Table 105. LTDC characteristics⁽¹⁾

Symbol	Parameter			Min	Max	Unit
	LTDC clock	2.7 <v<sub>DD<3.6 V, 20 pF</v<sub>		150		
f _{CLK}	output	2.7<\	V _{DD} <3.6 V	-	133	MHz
	frequency	1.62<	V _{DD} <3.6 V		90/76.5 ⁽²⁾	
D _{CLK}	LTD	C clock output	duty cycle	45	55	%
t _{w(CLKH),} t _{w(CLKL)}	Clo	Clock High time, low time			t _{w(CLK)} /2+0.5	
+	Data outpu	Data output valid time $ \frac{2.7 < V_{DD} < 3.6 \text{ V}}{1.62 < V_{DD} < 3.6 \text{ V}} $			2.0	
t _{v(DATA)}	Data outpu			-	2.5/6.5 ⁽²⁾	
t _{h(DATA)}	Г	Data output hol	d time	0	-	
t _{v(HSYNC),}	HSYNCA/SY	NC/DE output	2.7 <v<sub>DD<3.6 V</v<sub>	-	1.5	ns
$t_{v(VSYNC),} \ t_{v(DE)}$		HSYNC/VSYNC/DE output valid time		-	2.0	
$\begin{matrix} t_{h(HSYNC),} \\ t_{h(VSYNC),} \\ t_{h(DE)} \end{matrix}$	HSYNC/	HSYNC/VSYNC/DE output hold time		0	-	

^{1.} Guaranteed by characterization results.

This value is valid when PA[9], PA[10], PA[11], PA[12], PA[15], PB[11], PH[4], PJ[8], PJ[9], PJ[10], PJ[11], PK[0], PK[1] or PK[2] is used.

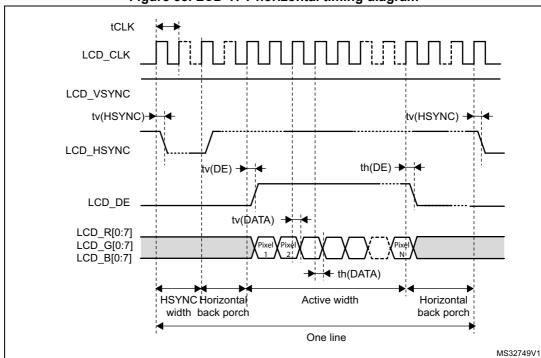
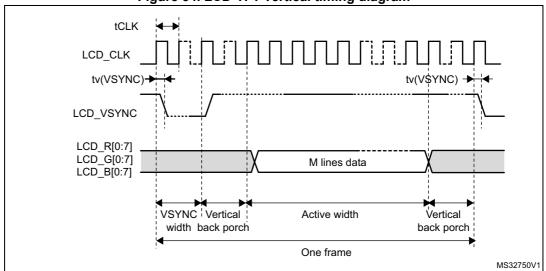


Figure 53. LCD-TFT horizontal timing diagram





6.3.36 Timer characteristics

The parameters given in *Table 106* are guaranteed by design.

Refer to Section 6.3.17: I/O port characteristics for details on the input/output alternate function characteristics (output compare, input capture, external clock, PWM output).

Symbol	Parameter	Conditions ⁽³⁾	Min	Max	Unit
t _{res(TIM)}	Timer resolution time	AHB/APBx prescaler=1 or 2 or 4, f _{TIMxCLK} = 275 MHz	1	-	t _{TIMxCLK}
	Time resolution time	AHB/APBx prescaler>4, f _{TIMxCLK} = 137.5 MHz	1	-	t _{TIMxCLK}
f _{EXT}	Timer external clock frequency on CH1 to CH4	f _{TIMxCLK} = 240 MHz	0	f _{TIMxCLK} /2	MHz
Res _{TIM}	Timer resolution		-	16/32	bit
t _{MAX_COUNT}	Maximum possible count with 32-bit counter	-	-	65536 × 65536	t _{TIMxCLK}

Table 106. TIMx characteristics⁽¹⁾⁽²⁾

6.3.37 Low-power timer characteristics

The parameters given in *Table 107* are guaranteed by design.

Refer to Section 6.3.17: I/O port characteristics for details on the input/output alternate function characteristics (output compare, input capture, external clock, PWM output).

Symbol	Parameter	Min	Max	Unit
t _{res(TIM)}	Timer resolution time	1	-	t _{TIMxCLK}
f _{LPTIMxCLK}	Timer kernel clock	0	137.5	
f _{EXT}	f _{EXT} Timer external clock frequency on Input1 and Input2		f _{LPTIMxCLK} /2	MHz
Res _{TIM}	Timer resolution	-	16	bit
t _{MAX_COUNT}	Maximum possible count	-	65536	t _{TIMxCLK}

Table 107. LPTIMx characteristics⁽¹⁾⁽²⁾

^{1.} TIMx is used as a general term to refer to the TIM1 to TIM17 timers.

^{2.} Guaranteed by design.

^{3.} The maximum timer frequency on APB1 or APB2 is up to 275 MHz, by setting the TIMPRE bit in the RCC_CFGR register, if APBx prescaler is 1 or 2 or 4, then TIMxCLK = rcc_hclk1, otherwise TIMxCLK = $4x F_{rcc_pclkx1}$ or TIMxCLK = $4x F_{rcc_pclkx2}$.

^{1.} LPTIMx is used as a general term to refer to the LPTIM1 to LPTIM5 timers.

^{2.} Guaranteed by design.

6.3.38 Communication interfaces

I²C interface characteristics

The I²C interface meets the timings requirements of the I₂C-bus specification and user manual revision 03 for:

- Standard-mode (Sm): with a bit rate up to 100 kbit/s
- Fast-mode (Fm): with a bit rate up to 400 kbit/s
- Fast-mode Plus (Fm+): with a bit rate up to 1 Mbit/s.

The I²C timings requirements are guaranteed by design when the I²C peripheral is properly configured (refer to RM0399 reference manual) and when the i2c_ker_ck frequency is greater than the minimum shown in the table below:

Table 108. Millimum izc_ker_ck frequency in all 1 C modes						
Symbol	Parameter	Cond	dition	Min	Unit	
		Standard-mode	-	2		
		Fast mode	Analog Filtre ON DNF=0	8		
f(I2CCLK)	I2CCLK frequency Fast-mode P	LK	Analog Filtre OFF DNF=1	9	MHz	
		Fact made Divis	Analog Filtre ON DNF=0	17		
		rast-mode Plus	Analog Filtre OFF DNF=1	16	-	

Table 108. Minimum i2c ker ck frequency in all I²C modes

The SDA and SCL I/O requirements are met with the following restrictions:

- The SDA and SCL I/O pins are not "true" open-drain. When configured as open-drain, the PMOS connected between the I/O pin and V_{DD} is disabled, but still present.
- The 20 mA output drive requirement in Fast-mode Plus is not supported. This limits the maximum load C_{Load} supported in Fm+, which is given by these formulas:

$$t_{r(SDA/SCL)}$$
=0.8473xR_P * C_{Load}

$$R_{P(min)} = (V_{DD} - V_{OL(max)}) / I_{OL(max)}$$

Where R_P is the I2C lines pull-up. Refer to Section 6.3.17: I/O port characteristics for the I²C I/Os characteristics.

All I²C SDA and SCL I/Os embed an analog filter. Refer to the table below for the analog filter characteristics:

Table 109. I²C analog filter characteristics⁽¹⁾

Symbol	Parameter	Min	Max	Unit
t _{AF}	Maximum pulse width of spikes that are suppressed by analog filter	50 ⁽²⁾	80 ⁽³⁾	ns

^{1.} Guaranteed by characterization results.

^{2.} Spikes with widths below $t_{AF(min)}$ are filtered.

3. Spikes with widths above $t_{AF(max)}$ are not filtered.

USART interface characteristics

Unless otherwise specified, the parameters given in *Table 110* for USART are derived from tests performed under the ambient temperature, f_{PCLKx} frequency and V_{DD} supply voltage conditions summarized in *Table 13: General operating conditions*, with the following configuration:

- Output speed is set to OSPEEDRy[1:0] = 11
- Capacitive load C_I = 30 pF
- Measurement points are done at CMOS levels: 0.5V_{DD}
- IO Compensation cell activated.
- VOS level set to VOS0

Refer to Section 6.3.17: I/O port characteristics for more details on the input/output alternate function characteristics (NSS, CK, TX, RX for USART).

Table 110. USART characteristics⁽¹⁾

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
		Master mode, 1.62 V < V _{DD} < 3.6 V			17.0	
fск	USART clock frequency	Slave receiver mode, 1.62 V < V _{DD} < 3.6 V	-	-	45.0	MHz
'CK	OSAINT CLOCK TEQUENCY	Slave transmitter mode, 1.62 V < V _{DD} < 3.6 V			27.0	IVIIIZ
		Slave transmitter mode, 2.5 V < V _{DD} < 3.6 V	-	-	37.0	
t _{su(NSS)}	NSS setup time	Slave mode	t _{ker} +1	-	-	
t _{h(NSS)}	NSS hold time CK high and low time	Slave mode	2	-	-	
t _{w(SCKH)} , t _{w(SCKL)}		Master mode	1/f _{CK} /2-2	1/f _{CK} /2	1/f _{CK} /2+2	
	Data input setup time	Master mode	16	-	-	
t _{su(RX)}		Slave mode	1.0	-	-	
4	Data input hold time	Master mode	0	-	-	
t _{h(RX)}	Data input hold time	Slave mode	2.0	-	-	ns
		Slave mode, , 1.62 V < V _{DD} < 3.6 V	-	12.0	18	
t _{v(TX)}	Data output valid time	Slave mode, , 2.5 V < V _{DD} < 3.6 V	-	12.0	13.5	
		Master mode	-	0.5	1	
4	Data output hold time	Slave mode	9	-	-	
t _{h(TX)}	Data output hold time	Master mode	0	-	-	

^{1.} Guaranteed by characterization results.



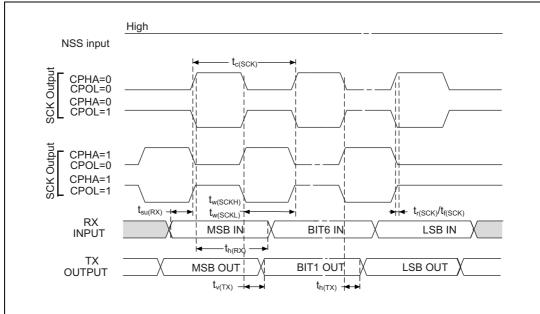


Figure 55. USART timing diagram in Master mode

1. Measurement points are done at $0.5V_{DD}$ and with external C_L = 30 pF.

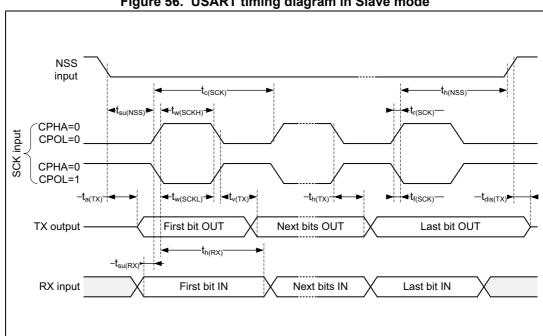


Figure 56. USART timing diagram in Slave mode

SPI interface characteristics

Unless otherwise specified, the parameters given in *Table 111* for SPI are derived from tests performed under the ambient temperature, f_{PCLKx} frequency and V_{DD} supply voltage conditions summarized in *Table 13: General operating conditions*, with the following configuration:

- Output speed is set to OSPEEDRy[1:0] = 11
- Capacitive load C_I = 30 pF
- Measurement points are done at CMOS levels: 0.5V_{DD}
- IO Compensation cell activated.
- HSLV activated when VDD ≤ 2.7 V
- VOS level set to VOS0

Refer to Section 6.3.17: I/O port characteristics for more details on the input/output alternate function characteristics (NSS, SCK, MOSI, MISO for SPI).

Table 111. SPI characteristics⁽¹⁾⁽²⁾

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
		Master mode, 2.7 V < V _{DD} < 3.6 V, SPI1, 2, 3			125	
		Master mode, 1.62 V < V _{DD} < 3.6 V, SPI1, 2, 3			80/66 ⁽³⁾	
	f _{SCK} SPI clock frequency	Master mode, 1.62 V < V _{DD} < 3.6 V, SPI4, 5, 6			68.5	
f _{SCK}		Slave receiver mode, 1.62 V < V _{DD} < 3.6 V, SPI1, 2, 3	-	-	100	MHz
		Slave receiver mode, 1.62 V < V _{DD} < 3.6 V, SPI4, 5, 6	68.5			
		Slave mode transmitter/full duplex, 2.7 V < V _{DD} < 3.6 V			45	
		Slave mode transmitter/full duplex, 1.62 V < V _{DD} < 3.6 V			42.5/31 ⁽⁴⁾	
t _{su(NSS)}	NSS setup time	Slave mode	2	-	-	
t _{h(NSS)}	NSS hold time	Slave mode	1	-	-	_
t _{w(SCKH)} , t _{w(SCKL)}	SCK high and low time	Master mode	t _{SCK} /2-1 ⁽⁵⁾	t _{SCK} /2 ⁽⁵⁾	t _{SCK} /2+1 ⁽⁵⁾	

Table 111. SPI characteristics⁽¹⁾⁽²⁾ (continued)

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
t _{su(MI)}	Data input setup time	Master mode	2.5	-	-	
t _{su(SI)}	Data input setup time	Slave mode	1	-	-	
t _{h(MI)}	Data input hold time	Master mode	3	-	-	
t _{h(SI)}	Data input noid time	Slave mode	1.5	-	-	
t _{a(SO)}	Data output access time	Slave mode	9	13	27	
t _{dis(SO)}	Data output disable time	Slave mode	0	1	5	
4		Slave mode, 2.7 V < V _{DD} < 3.6 V	-	7.5	11	ns
t _{v(SO)}	Data output valid time	Slave mode, 1.62 V < V _{DD} < 3.6 V	-	7.5	12/16 ⁽⁴⁾	
t _{v(MO)}		Master mode, 1.62 V < V _{DD} < 3.6 V	-	1	1.5/5.5 ⁽⁶⁾	
t _{h(SO)}	Data output hold time	Slave mode	7	-	-	
t _{h(MO)}	Data output noid time	Master mode	0.5	-	-	

- 1. Guaranteed by characterization results.
- 2. The values given in the above table might be degraded when PC3_C/PC2_C I/Os are used (not available on all packages).
- 3. This value is obtained by using PA9 or PA12 I/O.
- 4. This value is obtained by using PC2 or PJ11 I/O.
- 5. $t_{SCK} = t_{ker_ck} * baud rate prescaler$.
- 6. This value is obtained by using PC3 or PJ10 I/O.

NSS input t_{h(NSS)} −t_{w(SCKH)}
− $-t_{r(SCK)}$ CPHA=0 SCK input CPOL=0 CPHA=0 CPOL=1 $-t_{h(SO)}$ -t_{dis(SO)}► MISO output First bit OUT Next bits OUT Last bit OUT t_{h(SI)} -t_{su(SI)} MOSI input First bit IN Last bit IN Next bits IN

Figure 57. SPI timing diagram - slave mode and CPHA = 0

MSv41658V1

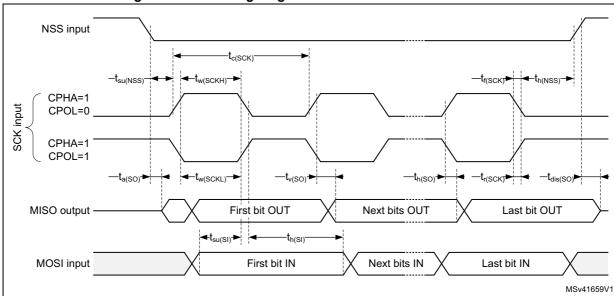
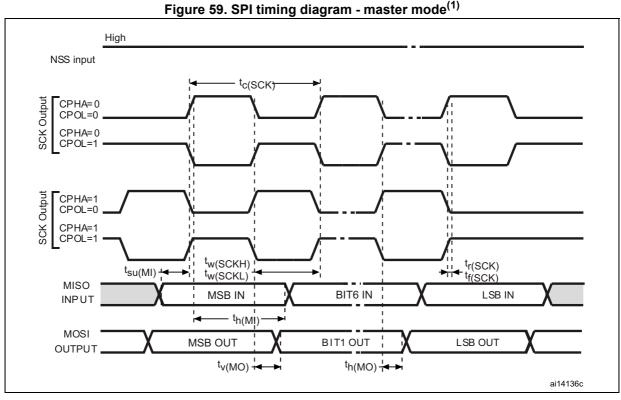


Figure 58. SPI timing diagram - slave mode and CPHA = 1⁽¹⁾

1. Measurement points are done at $0.5V_{DD}$ and with external C_L = 30 pF.



1. Measurement points are done at $0.5V_{DD}$ and with external C_L = 30 pF.

I²S Interface characteristics

Unless otherwise specified, the parameters given in *Table 112* for I^2S are derived from tests performed under the ambient temperature, f_{PCLKx} frequency and V_{DD} supply voltage conditions summarized in *Table 13: General operating conditions*, with the following configuration:

- Output speed is set to OSPEEDRy[1:0] = 11
- Capacitive load C_I = 30 pF
- Measurement points are done at CMOS levels: 0.5V_{DD}
- IO Compensation cell activated.
- HSLV activated when VDD ≤ 2.7 V
- VOS level set to VOS0

Refer to Section 6.3.17: I/O port characteristics for more details on the input/output alternate function characteristics (CK,SD,WS).

Table 112. I²S dynamic characteristics⁽¹⁾

Symbol	Parameter	Conditions	Min	Max	Unit
		-	-	50	
		Master transmitter	-	50/40 ⁽²⁾	
f _{MCK}	I ² S main clock output	Master receiver	-	50/40 ⁽²⁾	MHz
		Slave transmitter	-	41.5/31 ⁽³⁾	
		Slave receiver	-	50	
t _{v(WS)}	WS valid time	ime Master mode		2/6 ⁽⁴⁾	
t _{h(WS)}	WS hold time	- Master mode	1	-	
t _{su(WS)}	WS setup time	Clave made	3	-	
t _{h(WS)}	WS hold time	- Slave mode	1	-	
t _{su(SD_MR)}	Data input actual time	Master receiver	2.5	-	
t _{su(SD_SR)}	Data input setup time	Slave receiver	1	-	
t _{h(SD_MR)}	Data input hold time	Master receiver	3	-	
t _{h(SD_SR)}	Data iriput riolu tirrie	Slave receiver	1.5	-	ns
t _{v(SD_ST)}	Data output valid time	Slave transmitter (after enable edge)	-	12/16 ⁽³⁾	
t _{v(SD_MT)}	Data output valid time	Master transmitter (after enable edge)	-	2/6 ⁽⁵⁾	
t _{h(SD_ST)}	Data output hold fire	Slave transmitter (after enable edge)	6.5	-	
t _{h(SD_MT)}	Data output hold time	Master transmitter (after enable edge)	0.5	-	

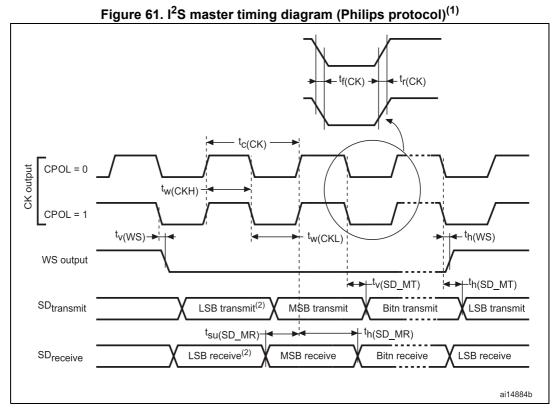
- 1. Guaranteed by characterization results.
- 2. This value is obtained when PA9 or PA12 are used.
- 3. This value is obtained when PC2 is used.
- 4. This value is obtained when PA11 or PA15 are used.

5. This value is obtained when PC3 is used.

t_{c(CK)} CK Input CPOL = 1 -th(WS) tw(CKH) tw(CKL) WS input <mark>'→→</mark>tv(SD_ST) . |◀▶|-^th(SD_ST) $t_{su(WS)}$ $\mathsf{SD}_{transmit}$ LSB transmit⁽²⁾ MSB transmit Bitn transmit LSB transmit ┿^th(SD_SR) tsu(SD_SR) LSB receive(2) MSB receive Bitn receive LSB receive SD_{receive} ai14881b

Figure 60. I²S slave timing diagram (Philips protocol)⁽¹⁾

LSB transmit/receive of the previously transmitted byte. No LSB transmit/receive is sent before the first byte.



LSB transmit/receive of the previously transmitted byte. No LSB transmit/receive is sent before the first byte.

SAI characteristics

Unless otherwise specified, the parameters given in *Table 113* for SAI are derived from tests performed under the ambient temperature, f_{PCLKx} frequency and VDD supply voltage conditions summarized in *Table 13: General operating conditions*, with the following configuration:

- Output speed is set to OSPEEDRy[1:0] = 10
- Capacitive load C_I = 30 pF
- IO Compensation cell activated.
- Measurement points are done at CMOS levels: 0.5V_{DD}
- VOS level set to VOS0

Refer to Section 6.3.17: I/O port characteristics for more details on the input/output alternate function characteristics (SCK,SD,WS).

Table 113. SAI characteristics⁽¹⁾

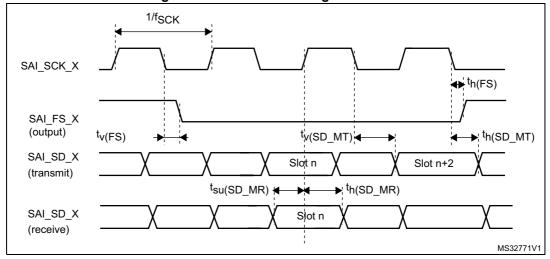
Symbol	Parameter	Conditions	Min	Max	Unit
f _{MCK}	SAI Main clock output	-	-	50	
	SAI Main clock output fCK SAI clock frequency ⁽²⁾	Master transmitter, 2.7 V ≤ V _{DD} ≤ 3.6 V	-	45	
		Master transmitter, 1.62 V ≤ V _{DD} ≤ 3.6 V	-	32	
f		Master receiver, 1.62 V ≤ V _{DD} ≤ 3.6 V	-	32	MHz
'CK		Slave transmitter, 2.7 V ≤ V _{DD} ≤ 3.6 V	-	47.5	
		Slave transmitter, 1.62 V ≤ V _{DD} ≤ 3.6 V	-	41.5	
		Slave receiver, 1.62 V ≤ V _{DD} ≤ 3.6 V	-	50	

Table 113. SAI characteristics⁽¹⁾ (continued)

Symbol	Parameter	Conditions	Min	Max	Unit
4	C valid time	Master mode, 2.7 V ≤ V _{DD} ≤ 3.6 V	-	11	
t _{v(FS)}	F _S valid time	Master mode, 1.62 V ≤ V _{DD} ≤ 3.6 V	-	15.5	
t _{su(FS)}	F _S setup time	Slave mode	2.5	-	
4	E hold time	Master mode	6	-	
t _{h(FS)}	F _S hold time	Slave mode	0.5	-	
t _{su(SD_A_MR)}	Data input actus time	Master receiver	3	-	
t _{su(SD_B_SR)}	Data input setup time	Slave receiver	3.5	-	
t _{h(SD_A_MR)}	Data input hold time	Master receiver	3.5	-	
t _{h(SD_B_SR)}	Data input noid time	Slave receiver	0	-	ns
+	Dete cuteurt valid time	Slave transmitter (after enable edge), $2.7 \text{ V} \leq \text{V}_{\text{DD}} \leq 3.6 \text{ V}$	-	10.5	
t _{v(SD_B_ST)}	Data output valid time	Slave transmitter (after enable edge), $1.62 \text{ V} \leq \text{V}_{DD} \leq 3.6 \text{ V}$	-	12	
t _{h(SD_B_ST)}	Data output hold time	Slave transmitter (after enable edge)	6.5	-	
+	Data output valid time	Master transmitter (after enable edge), $2.7 \text{ V} \le \text{V}_{\text{DD}} \le 3.6 \text{ V}$	-	10.5	
^t v(SD_A_MT)	Data output valid time	Master transmitter (after enable edge), $1.62 \text{ V} \leq \text{V}_{DD} \leq 3.6 \text{ V}$	-	14.5	
t _{h(SD_A_MT)}	Data output hold time	Master transmitter (after enable edge)	6	-	1

- 1. Guaranteed by characterization results.
- 2. APB clock frequency must be at least twice SAI clock frequency.

Figure 62. SAI master timing waveforms



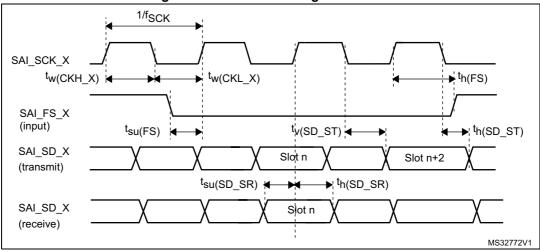


Figure 63. SAI slave timing waveforms

MDIO characteristics

Unless otherwise specified, the parameters given in *Table 114* for the MDIO are derived from tests performed under the ambient temperature, f_{PCLKx} frequency and VDD supply voltage conditions summarized in *Table 13: General operating conditions*, with the following configuration:

- Output speed is set to OSPEEDRy[1:0] = 10
- I/O Compensation cell activated.
- Measurement points are done at CMOS levels: 0.5V_{DD}
- HSLV activated when V_{DD} ≤ 2.7 V
- VOS level set to VOS0

Table 114. MDIO Slave timing parameters

Symbol	Parameter		Тур	Max	Unit
F _{MDC}	Management Data Clock	-	-	30	MHz
t _{d(MDIO)}	Management Data Iput/output output valid time	8	10	18	
t _{su(MDIO)}	Management Data Iput/output setup time	1	-	-	ns
t _{h(MDIO)}	Management Data Iput/output hold time	1	-	-	

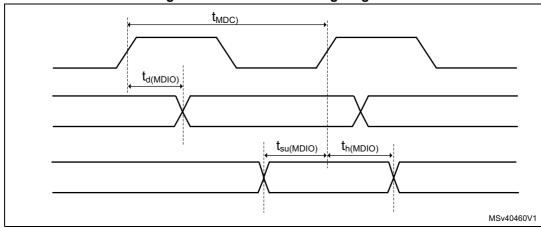


Figure 64. MDIO Slave timing diagram

SD/SDIO MMC card host interface (SDMMC) characteristics

Unless otherwise specified, the parameters given in *Table 115* and *Table 116* for SDIO are derived from tests performed under the ambient temperature, f_{PCLKx} frequency and VDD supply voltage summarized in *Table 13: General operating conditions*, with the following configuration:

- Output speed is set to OSPEEDRy[1:0] = 11
- Capacitive load C_I =30 pF
- Measurement points are done at CMOS levels: 0.5V_{DD}
- IO Compensation cell activated.
- HSLV activated when V_{DD} ≤ 2.7 V
- VOS level set to VOS0

Refer to Section 6.3.17: I/O port characteristics for more details on the input/output characteristics.

Table 115. Dynamics characteristics: SD / MMC characteristics, V_{DD}=2.7 to 3.6 V⁽¹⁾⁽²⁾

Symbol	Parameter	Conditions	Min	Тур	Max	Unit		
f _{PP}	Clock frequency in data transfer mode	-	0	-	120	MHz		
-	SDIO_CK/fPCLK2 frequency ratio	-	-	-	8/3	-		
t _{W(CKL)}	Clock low time	f _{PP} =52MHz	8.5	9.5	-	ns		
t _{W(CKH)}	Clock high time	1PP -321VII 12	8.5	9.5	ı	115		
CMD, D inp	uts (referenced to CK) in eMMC lega	cy/SDR/DDR and	SD HS/	SDR/DD	R mode)		
t _{ISU}	Input setup time HS	-	2.5	-	-			
t _{IH}	Input hold time HS	-	0.5	-	-	ns		
t _{IDW} (3)	Input valid window (variable window)	-	1.5	-	-			
CMD, D out	CMD, D outputs (referenced to CK) in eMMC legacy/SDR/DDR and SD HS/SDR/DDR mode							
t _{OV}	Output valid time HS	-	-	5.5	6	ns		
t _{OH}	Output hold time HS	-	4.5	-	-	113		



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Table 115. Dynamics characteristics: SD / MMC characteristics, V_{DD} =2.7 to 3.6 $V^{(1)(2)}$

Symbol	Parameter	Conditions	Min	Тур	Max	Unit	
CMD, D inputs (referenced to CK) in SD default mode							
t _{ISUD}	Input setup time SD	-	1.5		-	ne	
t _{IHD}	Input hold time SD	-	0.5		-	ns	
CMD, D out	puts (referenced to CK) in SD defau	It mode					
t _{OVD}	Output valid default time SD	-	-	1	1	ns	
t _{OHD}	Output hold default time SD	-	0	-	-	113	

^{1.} Guaranteed by characterization results.

Table 116. Dynamics characteristics: eMMC characteristics VDD=1.71V to 1.9V⁽¹⁾⁽²⁾

Symbol	Parameter	Conditions	Min	Тур	Max	Unit		
f _{PP}	Clock frequency in data transfer mode	-	0	-	85	MHz		
-	SDIO_CK/fPCLK2 frequency ratio	-	-	-	8/3	-		
t _{W(CKL)}	Clock low time	f _{PP} =52 MHz	8.5	9.5	-	ns		
t _{W(CKH)}	Clock high time	1pp =32 Wil 12	8.5	9.5	-	113		
CMD, D in	outs (referenced to CK) in eMMC m	ode						
t _{ISU}	Input setup time HS	-	1.5	i	-			
t _{IH}	Input hold time HS	-	1.5	1	-	ns		
t _{IDW} (3)	Input valid window (variable window)	-	3.5	-	-			
CMD, D ou	CMD, D outputs (referenced to CK) in eMMC mode							
t _{OVD}	Output valid time HS	-	-	6	6.5	ns		
t _{OHD}	Output hold time HS	-	5.5	-	-	113		

^{1.} Guaranteed by characterization results.

^{2.} Above 100 MHz, $C_L = 20 pF$.

^{3.} The minimum window of time where the data needs to be stable for proper sampling in tuning mode.

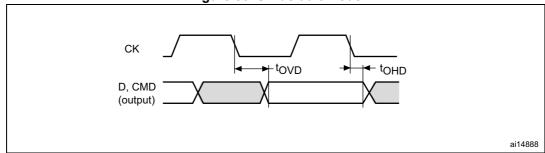
^{2.} $C_L = 20 pF$.

^{3.} The minimum window of time where the data needs to be stable for proper sampling in tuning mode.

tW(CKH) ^tW(CKL) CK tov ^tOH D, CMD (output) tisu D, CMD (input) ai14887

Figure 65. SDIO high-speed mode

Figure 66. SD default mode



 $t_{\text{w(CLKL)}} \\$ $t_{\text{f(CLK)}}$ $t_{\text{r}(\text{CLK})}$ $t_{(\text{CLK})} \\$ $t_{\text{w(CLKH)}} \\$ Clock $t_{\text{hr}(OUT)}$ t_{hf(OUT)} Data output 100 102 101 IO3 104 105 $t_{\text{sr(IN)}}t_{\text{hr(IN)}}$ Data input 100 Ιφ1 102 103 104 105 MSv36879V3

Figure 67. DDR mode

USB OTG FS characteristics

Unless otherwise specified, the parameters given in *Table 118* for ULPI are derived from tests performed under the ambient temperature, f_{PCLKx} frequency and V_{DD} supply voltage summarized in *Table 13: General operating conditions*, with the following configuration:

- Output speed is set to OSPEEDRy[1:0] = 11
- Capacitive load C_I =20 pF
- Measurement points are done at CMOS levels: 0.5V_{DD}
- IO Compensation cell activated.
- VOS level set to VOS0

Refer to Section 6.3.17: I/O port characteristics for more details on the input/output characteristics.

Symbol	Parameter	Condition	Min	Тур	Max	Unit
V _{DD33US}	USB transceiver operating voltage	-	3.0 ⁽¹⁾	-	3.6	V
R _{PUI}	Embedded USB_DP pull-up value during idle	-	900	1250	1600	
R _{PUR}	Embedded USB_DP pull-up value during reception	-	1400	2300	3200	Ω
Z _{DRV}	Output driver impedance ⁽²⁾	Driver high and low	28	36	44	

Table 117. USB OTG_FS electrical characteristics

USB OTG HS characteristics

Unless otherwise specified, the parameters given in *Table 118* for ULPI are derived from tests performed under the ambient temperature, f_{PCLKx} frequency and V_{DD} supply voltage summarized in *Table 13: General operating conditions*, with the following configuration:

- Output speed is set to OSPEEDRy[1:0] = 11
- Capacitive load C_I =20 pF
- Measurement points are done at CMOS levels: 0.5V_{DD}
- IO Compensation cell activated.
- VOS level set to VOS0

Refer to Section 6.3.17: I/O port characteristics for more details on the input/output characteristics.

The USB functionality is ensured down to 2.7 V. However, not all USB electrical characteristics are degraded in the 2.7 to 3.0 V voltage range.

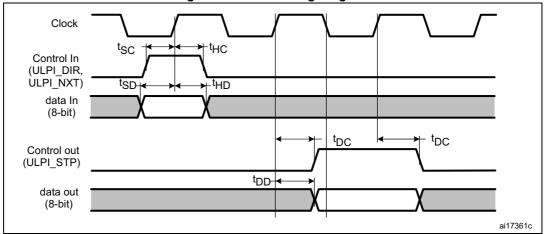
^{2.} No external termination series resistors are required on USB_DP (D+) and USB_DM (D-); the matching impedance is already included in the embedded driver.

Table 118. Dynamics characteristics: USB ULPI⁽¹⁾

Symbol	Parameter	Condition	Min	Тур	Max	Unit
t _{SC}	Control in (ULPI_DIR , ULPI_NXT) setup time	-	5.5	-	-	
t _{HC}	Control in (ULPI_DIR, ULPI_NXT) hold time	-	0	-	-	
t _{SD}	Data in setup time	-	2.5	-	-	ns
t _{HD}	Data in hold time	-	0	-	-	115
+ /+	Control/Datal output delay	$2.7 \text{ V} < \text{V}_{DD} < 3.6 \text{ V},$ $\text{C}_{L} = 20 \text{ pF}$	-	6.0	8.0	
t _{DC} /t _{DD}	Control Data output delay	1.71 V < V _{DD} < 3.6 V , C _L = 15 pF	-	6.0	12	

^{1.} Guaranteed by characterization results.

Figure 68. ULPI timing diagram



Ethernet interface characteristics

Unless otherwise specified, the parameters given in *Table 119*, *Table 120* and *Table 121* for SMI, RMII and MII are derived from tests performed under the ambient temperature, $f_{rcc_c_ck}$ frequency and V_{DD} supply voltage conditions summarized in *Table 13: General operating conditions*, with the following configuration:

- Output speed is set to OSPEEDRy[1:0] = 10
- Capacitive load C_I =20 pF
- Measurement points are done at CMOS levels: 0.5V_{DD}
- IO Compensation cell activated.
- HSLV activated when VDD ≤ 2.7 V
- VOS level set to VOS1

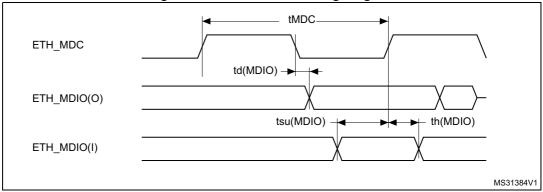
Refer to Section 6.3.17: I/O port characteristics for more details on the input/output characteristics:

Table 119. Dynamics characteristics: Ethernet MAC signals for SMI (1)

Symbol	Parameter	Min	Тур	Max	Unit
t _{MDC}	MDC cycle time(2.5 MHz)	400	400	403	
T _{d(MDIO)}	Write data valid time	0.5	1.5	4	ne
t _{su(MDIO)}	Read data setup time	12.5	-	-	ns
t _{h(MDIO)}	Read data hold time	0	-	-	

^{1.} Guaranteed by characterization results.

Figure 69. Ethernet SMI timing diagram



9.5

243/276

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Symbol	Parameter	Min	Тур	Max	Unit			
t _{su(RXD)}	Receive data setup time	2	-	-				
t _{ih(RXD)}	Receive data hold time	2	-	-				
t _{su(CRS)}	Carrier sense setup time	1.5	-	-	ns			
t _{ih(CRS)}	Carrier sense hold time	1.5	-	-	115			
t _{d(TXEN)}	Transmit enable valid delay time	8	0	10.5				

7

Table 120. Dynamics characteristics: Ethernet MAC signals for RMII (1)

 $t_{d(TXD)}$

Transmit data valid delay time

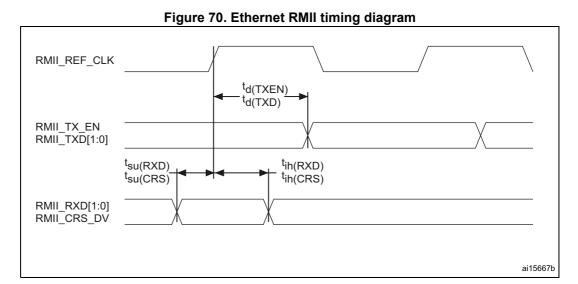


Table 121. Dynamics characteristics: Ethernet MAC signals for MII ⁽¹⁾

Symbol	Parameter	Min	Тур	Max	Unit
t _{su(RXD)}	Receive data setup time	2.0	-	-	
t _{ih(RXD)}	Receive data hold time	2.0	-	-	
t _{su(DV)}	Data valid setup time	1.5	-	-	
t _{ih(DV)}	Data valid hold time	1.5	-	-	ne
t _{su(ER)}	Error setup time	1.5	-	-	ns
t _{ih(ER)}	Error hold time	0.5	-	-	
t _{d(TXEN)}	Transmit enable valid delay time	9.0	11	19	
t _{d(TXD)}	Transmit data valid delay time	8.5	10	19	

^{1.} Guaranteed by characterization results.

^{1.} Guaranteed by characterization results.

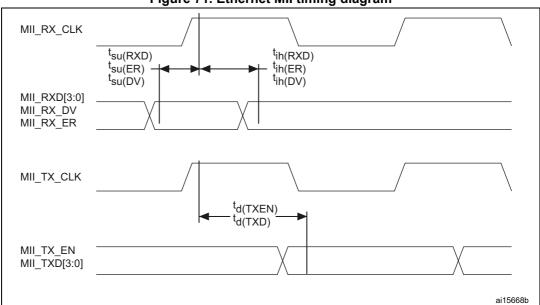


Figure 71. Ethernet MII timing diagram

JTAG/SWD interface characteristics

Unless otherwise specified, the parameters given in *Table 122* and *Table 123* for JTAG/SWD are derived from tests performed under the ambient temperature, $f_{rcc_c_ck}$ frequency and V_{DD} supply voltage summarized in *Table 13: General operating conditions*, with the following configuration:

- Output speed is set to OSPEEDRy[1:0] = 11
- Capacitive load C_I =30 pF
- Measurement points are done at CMOS levels: 0.5V_{DD}
- VOS level set to VOS0

Refer to Section 6.3.17: I/O port characteristics for more details on the input/output characteristics:

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
F _{pp}	T _{CK} clock frequency	2.7V <v<sub>DD< 3.6 V</v<sub>	-	-	37	
1/t _{c(TCK)}	1 CK clock frequency	1.62 <v<sub>DD< 3.6 V</v<sub>	-	-	27.5	MHz
ti _{su(TMS)}	TMS input setup time	-	2.5	-	-	IVII IZ
ti _{h(TMS)}	TMS input hold time	-	1	-	-	
ti _{su(TDI)}	TDI input setup time	-	1.5	-	-	-
ti _{h(TDI)}	TDI input hold time	-	1	-	-	-
+	TDO output valid time	2.7V <v<sub>DD< 3.6 V</v<sub>	-	8	13.5	-
t _{ov(TDO)}	TDO output valid time	1.62 <v<sub>DD< 3.6 V</v<sub>	-	8	18	-
t _{oh(TDO)}	TDO output hold time	-	7	-	-	-

Table 122. Dynamics JTAG characteristics

Table 123. Dynamics SWD characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
F _{pp}	SWCLK clock frequency	2.7V <v<sub>DD< 3.6 V</v<sub>	-	-	71	MHz
1/t _{c(SWCLK)}	SWOLK GOOK Hequency	1.62 <v<sub>DD< 3.6 V</v<sub>	-	-	52.5	IVII IZ
ti _{su(SWDIO)}	SWDIO input setup time	-	2.5	-	-	
ti _{h(SWDIO)}	SWDIO input hold time	-	1	-	-	-
		2.7V <v<sub>DD< 3.6 V</v<sub>	-	8.5	14	
t _{ov(SWDIO)}	SWDIO output valid time	1.62 <v<sub>DD< 3.6 V</v<sub>	-	8.5	19	-
t _{oh(SWDIO)}	SWDIO output hold time	-	8	-	-	-

Figure 72. JTAG timing diagram

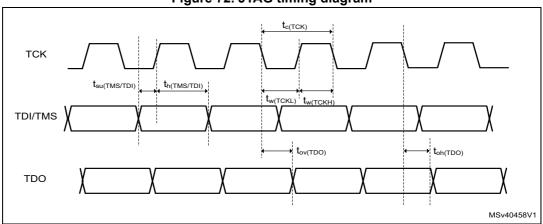
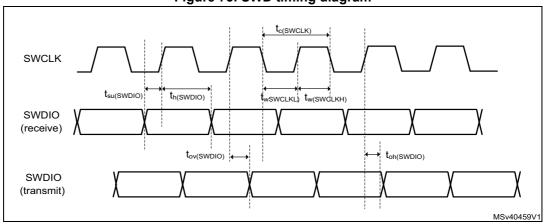


Figure 73. SWD timing diagram



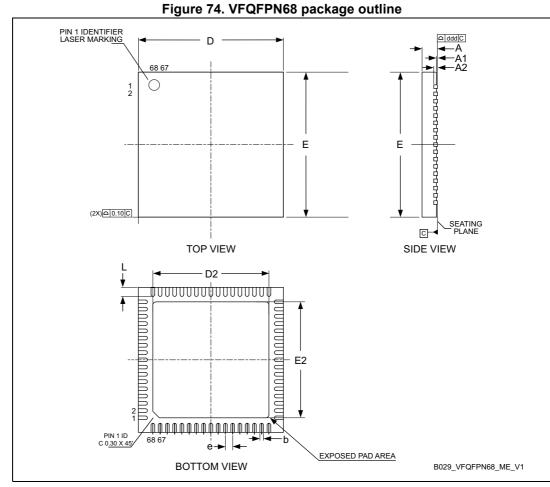
Package information STM32H725xE/G

7 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK packages, depending on their level of environmental compliance. ECOPACK specifications, grade definitions and product status *are available at www.st.com.* ECOPACK is an ST trademark.

7.1 VFQFPN68 package information

VFQFPN68 is a 68-pin, 8 x 8 mm, 0.4 mm pitch, very thin fine pitch quad flat package.



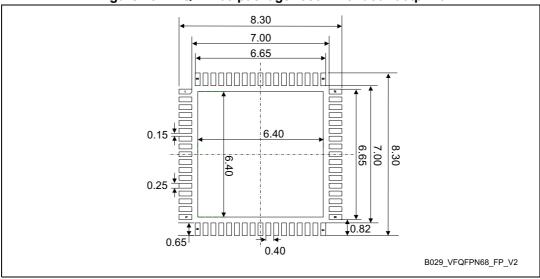
- 1. VFQFPN stands for Thermally Enhanced Very thin Fine pitch Quad Flat Packages No lead. Sawed version. Very thin profile: $0.80 < A \le 1.00$ mm.
- 2. The pin #1 identifier must be existed on the top surface of the package by using indentation mark or other feature of package body. Exact shape and size of this feature is optional.

Table 124. VFQFPN68 package mechanical data

Symbol		millimeters			inches ⁽¹⁾	
	Min	Тур	Max	Min	Тур	Max
А	0.80	0.90	1.00	0.0315	0.0354	0.0394
A1	0	0.02	0.05	0	0.0008	0.0020
A3	-	0.20	-	-	0.0008	-
b	0.15	0.20	0.25	0.0059	0.0079	0.0098
D	7.85	8.00	8.15	0.3091	0.3150	0.3209
D2	6.30	6.40	6.50	0.2480	0.2520	0.2559
Е	7.85	8.00	8.15	0.3091	0.3150	0.3209
E2	6.30	6.40	6.50	0.2480	0.2520	0.2559
е	-	0.40	-	-	0.0157	-
L	0.40	0.50	0.60	0.0157	0.0197	0.0236
ddd	-	-	0.08	-	-	0.0031

^{1.} Values in inches are converted from mm and rounded to 4 decimal digits.

Figure 75. VFQFPN68 package recommended footprint



1. Dimensions are expressed in millimeters.

Package information STM32H725xE/G

Device marking for VFQFPN68

The following figure gives an example of topside marking versus ball A1 position identifier location.

The printed markings may differ depending on the supply chain.

Other optional marking or inset/upset marks, which depend on supply chain operations, are not indicated below.

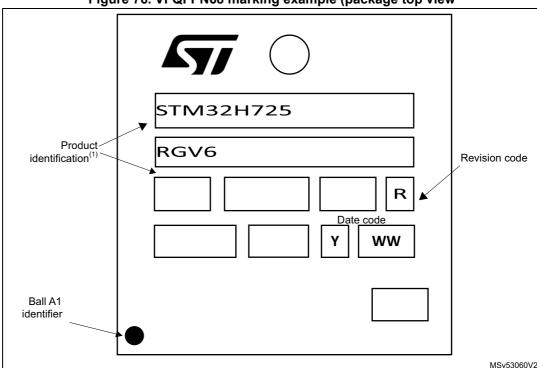


Figure 76. VFQFPN68 marking example (package top view

1. Parts marked as "ES", "E" or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not approved for use in production. ST is not responsible for any consequences resulting from such use. In no event will ST be liable for the customer using any of these engineering samples in production. ST's Quality department must be contacted prior to any decision to use these engineering samples to run a qualification activity.

STM32H725xE/G **Package information**

LQFP100 package information 7.2

LQFP100 is a 100-pin, 14 x 14 mm low-profile quad flat package.

SEATING PLANE С 0.25 mm GAUGE PLANE □ ccc C D D1 E3 PIN 1 **IDENTIFICATION** 1L_ME_V5

Figure 77. LQFP100 package outline

1. Drawing is not to scale.

Table 125. LQPF100 package mechanical data

Symbol		millimeters	llimeters		inches ⁽¹⁾		
	Min	Тур	Max	Min	Тур	Max	
А	-	-	1.600	-	-	0.0630	
A1	0.050	-	0.150	0.0020	-	0.0059	
A2	1.350	1.400	1.450	0.0531	0.0551	0.0571	
b	0.170	0.220	0.270	0.0067	0.0087	0.0106	
С	0.090	-	0.200	0.0035	-	0.0079	
D	15.800	16.000	16.200	0.6220	0.6299	0.6378	

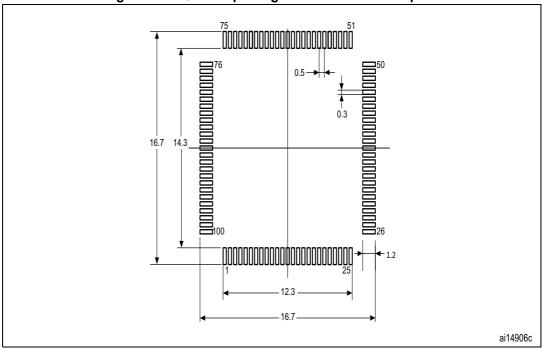
Package information STM32H725xE/G

Table 125. LQPF100	package m	echanical data	(continued)
---------------------------	-----------	----------------	-------------

Symbol		millimeters		inches ⁽¹⁾			
	Min	Тур	Max	Min	Тур	Max	
D1	13.800	14.000	14.200	0.5433	0.5512	0.5591	
D3	-	12.000	-	-	0.4724	-	
E	15.800	16.000	16.200	0.6220	0.6299	0.6378	
E1	13.800	14.000	14.200	0.5433	0.5512	0.5591	
E3	-	12.000	-	-	0.4724	-	
е	-	0.500	-	-	0.0197	-	
L	0.450	0.600	0.750	0.0177	0.0236	0.0295	
L1	-	1.000	-	-	0.0394	-	
k	0.0°	3.5°	7.0°	0.0°	3.5°	7.0°	
ccc	-	-	0.080	-	-	0.0031	

^{1.} Values in inches are converted from mm and rounded to 4 decimal digits.

Figure 78. LQFP100 package recommended footprint



1. Dimensions are expressed in millimeters.

STM32H725xE/G Package information

Device marking for LQFP100

The following figure gives an example of topside marking versus pin 1 position identifier location.

The printed markings may differ depending on the supply chain.

Other optional marking or inset/upset marks, which depend on supply chain operations, are not indicated below.

Product identification⁽¹⁾ TM32H725 GT6 Revision code R Date code Pin 1 indentifier MSv53062V3

Figure 79. LQFP100 marking example (package top view)

Parts marked as "ES", "E" or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not approved for use in production. ST is not responsible for any consequences resulting from such use. In no event will ST be liable for the customer using any of these engineering samples in production. ST's Quality department must be contacted prior to any decision to use these engineering samples to run a qualification activity.

DS13311 Rev 2 251/276 **Package information** STM32H725xE/G

TFBGA100 package information 7.3

TFBGA100 is a 100-ball, 8 x 8 mm, 0.8 mm pitch, thin fine-pitch ball grid array package.

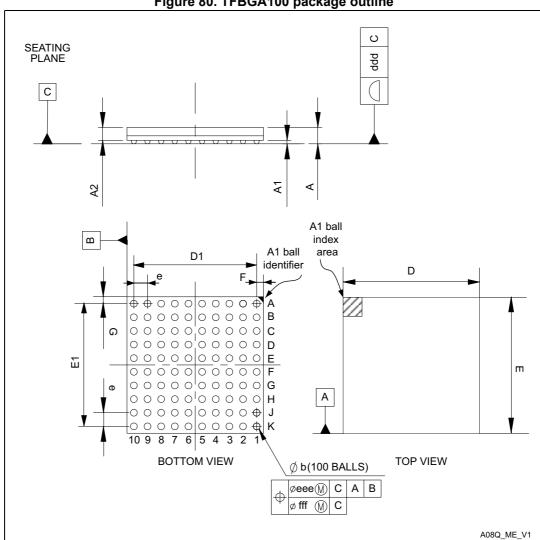


Figure 80. TFBGA100 package outline

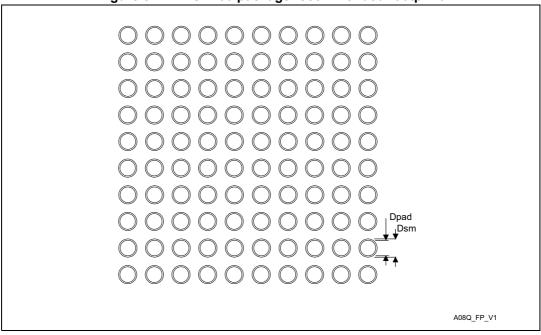
1. Drawing is not to scale.

Table 126. TFBGA100 package mechanical data

Symbol		millimeters		inches ⁽¹⁾		
Symbol	Min	Тур	Max	Min	Тур	Max
А	-	-	1.100	-	-	0.0433
A1	0.150	-	-	0.0059	-	-
A2	-	0.760	-	-	0.0299	-
b	0.350	0.400	0.450	0.0138	0.0157	0.0177
D	7.850	8.000	8.150	0.3091	0.3150	0.3209
D1	-	7.200		-	0.2835	-
E	7.850	8.000	8.150	0.3091	0.3150	0.3209
E1	-	7.200	-	-	0.2835	-
е	-	0.800	-	-	0.0315	-
F	-	0.400	-	-	0.0157	-
G	-	0.400	-	-	0.0157	-
ddd	-	-	0.100	-	-	0.0039
eee	-	-	0.150	-	-	0.0059
fff	-	-	0.080	-	-	0.0031

^{1.} Values in inches are converted from mm and rounded to 4 decimal digits.

Figure 81. TFBGA100 package recommended footprint



^{1.} Dimensions are expressed in millimeters.

Table 127. TFBGA100 recommended PCB design rules (0.8 mm pitch BGA)

Dimension	Recommended values
Pitch	0.8
Dpad	0.400 mm
Dsm	0.470 mm typ (depends on the soldermask registration tolerance)
Stencil opening	0.400 mm
Stencil thickness	Between 0.100 mm and 0.125 mm
Pad trace width	0.120 mm

Device marking for TFBGA100

The following figure gives an example of topside marking versus pin 1 position identifier location.

The printed markings may differ depending on the supply chain.

Other optional marking or inset/upset marks, which depend on supply chain operations, are not indicated below.

Product identification⁽¹⁾

STM32H725

Revision code

Ball Alidentifier

Revision code

Figure 82. TFBGA100 marking example (package top view)

1. Parts marked as "ES", "E" or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not approved for use in production. ST is not responsible for any consequences resulting from such use. In no event will ST be liable for the customer using any of these engineering samples in production. ST's Quality department must be contacted prior to any decision to use these engineering samples to run a qualification activity.

7.4 WLCSP115 package information

WLCSP115 is a 115-ball, 3.73 x 4.15 mm, 0.35 mm pitch, wafer level chip scale package.

// bbb Z -A1 A1 Ball location E e2 D △ aaa SIDE VIEW BOTTOM VIEW FRONT VIEW BUMP △eeeZ A1 orientation reference øb (115x) Øccc @ ZXY

øddd @ Z Seating plane TOP VIEW Detail A B08U_WLCSP115_ME_V1

Figure 83. WLCSP115 package outline

- 1. Drawing is not to scale.
- 2. Dimension is measured at the maximum bump diameter parallel to primary datum Z.
- 3. Primary datum Z and seating plane are defined by the spherical crowns of the bump.
- 4. Bump position designation per JESD 95-1, SPP-010.

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Table 128. WLCSP115 package mechanical data

O. mala al	millimeters			inches ⁽¹⁾		
Symbol	Min	Тур	Max	Min	Тур	Max
A ⁽²⁾	-	-	0.58	-	-	0.023
A1	-	0.17	-	-	0.007	-
A2	-	0.38	-	-	0.015	-
A3 ⁽³⁾	-	0.025	-	-	0.001	-
b	0.21	0.24	0.27	0.008	0.009	0.011
D	3.71	3.73	3.75	0.146	0.147	0.148
Е	4.13	4.15	4.17	0.163	0.163	0.164
е	-	0.35	-	-	0.014	-
e1	-	3.03	-	-	0.119	-
e2	-	3.15	-	-	0.124	-
F ⁽⁴⁾	-	0.36	-	-	0.014	-
G ⁽⁴⁾	-	0.51	-	-	0.020	-
aaa	-	-	0.10	-	-	0.004
bbb	-	-	0.10	-	-	0.004
ccc	-	-	0.10	-	-	0.004
ddd	-	-	0.05	-	-	0.002
eee	-	-	0.05	-	-	0.002

- 1. Values in inches are converted from mm and rounded to 4 decimal digits.
- 2. The maximum total package height is calculated by the RSS method (Root Sum Square) using nominal and tolerances values of A1 and A2.
- Back side coating. Nominal dimension is rounded to the 3rd decimal place resulting from process capability.
- 4. Calculated dimensions are rounded to the 3rd decimal place

Figure 84. WLCSP115 package recommended footprint

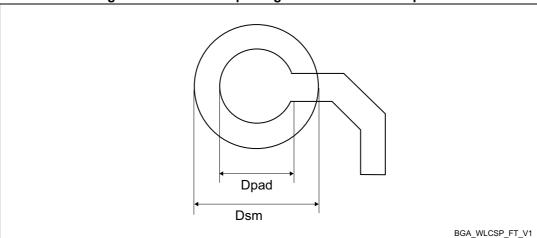


Table 129. WLCSP115 recommended PCB design rules

	<u> </u>
Dimension	Recommended values
Pitch	0.35 mm
Dpad	0,225 mm
Dsm	0.250 mm typ. (depends on soldermask registration tolerance)
Stencil opening	0.250 mm
Stencil thickness	0.080 mm

Device marking for WLSCP115

The following figure gives an example of topside marking versus ball A1 position identifier location.

The printed markings may differ depending on the supply chain.

Other optional marking or inset/upset marks, which depend on supply chain operations, are not indicated below.

Ball A1 identifier

Product identification(1)

Date code

Y WW

Revision code

Figure 85. WLCSP115 marking example (package top view

1. Parts marked as "ES", "E" or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not approved for use in production. ST is not responsible for any consequences resulting from such use. In no event will ST be liable for the customer using any of these engineering samples in production. ST's Quality department must be contacted prior to any decision to use these engineering samples to run a qualification activity.

7.5 LQFP144 package information

LQFP144 is a 144-pin, 20 x 20 mm low-profile quad flat package.

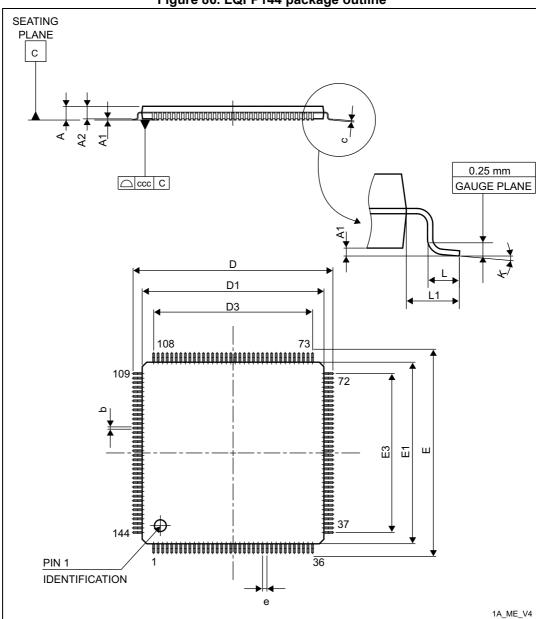


Figure 86. LQFP144 package outline

1. Drawing is not to scale.

Table 130. LQFP144 package mechanical data

Comple of		millimeters		inches ⁽¹⁾		
Symbol	Min	Тур	Max	Min	Тур	Max
Α	-	-	1.600	-	-	0.0630
A1	0.050	-	0.150	0.0020	-	0.0059
A2	1.350	1.400	1.450	0.0531	0.0551	0.0571
b	0.170	0.220	0.270	0.0067	0.0087	0.0106
С	0.090	-	0.200	0.0035	-	0.0079
D	21.800	22.000	22.200	0.8583	0.8661	0.8740
D1	19.800	20.000	20.200	0.7795	0.7874	0.7953
D3	-	17.500	-	-	0.6890	-
Е	21.800	22.000	22.200	0.8583	0.8661	0.8740
E1	19.800	20.000	20.200	0.7795	0.7874	0.7953
E3	-	17.500	-	-	0.6890	-
е	-	0.500	-	-	0.0197	-
L	0.450	0.600	0.750	0.0177	0.0236	0.0295
L1	-	1.000	-	-	0.0394	-
k	0°	3.5°	7°	0°	3.5°	7°
ccc	-	-	0.080	-	-	0.0031

^{1.} Values in inches are converted from mm and rounded to 4 decimal digits.

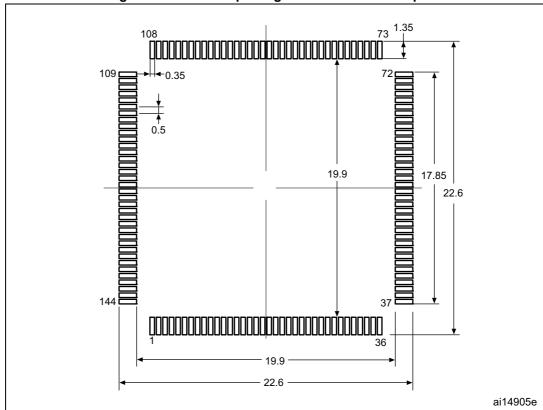


Figure 87. LQFP144 package recommended footprint

1. Dimensions are expressed in millimeters.

STM32H725xE/G Package information

Device marking for LQFP144

The following figure gives an example of topside marking versus pin 1 position identifier location.

The printed markings may differ depending on the supply chain.

Other optional marking or inset/upset marks, which depend on supply chain operations, are not indicated below.

Product identification⁽¹⁾

STM32H725ZGTL

Revision code

Y W W

MSv53066V2

Figure 88. LQFP144 marking example (package top view)

1. Parts marked as "ES", "E" or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not approved for use in production. ST is not responsible for any consequences resulting from such use. In no event will ST be liable for the customer using any of these engineering samples in production. ST's Quality department must be contacted prior to any decision to use these engineering samples to run a qualification activity.

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7.6 UFBGA169 package information

UFBGA169 is a 169-pin, 7 x 7 mm, 0.50 mm pitch, ultra fine pitch ball grid array package.

Z Seating plane Ā A3 SIDE VIEW A1 ball A1 ball - X identifier index area D **BOTTOM VIEW TOP VIEW** Øb (169 balls) ⊕ | Ø eee(M) | Z | X | Y | Øfff | (M) | Z | A0YV_ME_V2

Figure 89. UFBGA169 package outline

1. Drawing is not in scale.

Table 131. UFBGA169 package mechanical data

	Table	101. 01 00/	troo packag	e illechanica	i data	
Symbol	millimeters			inches ⁽¹⁾		
	Min.	Тур.	Max.	Min.	Тур.	Max.
Α	0.460	0.530	0.600	0.0181	0.0209	0.0236
A1	0.050	0.080	0.110	0.0020	0.0031	0.0043
A2	0.400	0.450	0.500	0.0157	0.0177	0.0197
A3	-	0.130	-	-	0.0051	-
A4	0.270	0.320	0.370	0.0106	0.0126	0.0146
b	0.230	0.280	0.330	0.0091	0.0110	0.0130
D	6.950	7.000	7.050	0.2736	0.2756	0.2776
D1	5.950	6.000	6.050	0.2343	0.2362	0.2382
E	6.950	7.000	7.050	0.2736	0.2756	0.2776
E1	5.950	6.000	6.050	0.2343	0.2362	0.2382
е	-	0.500	-	-	0.0197	-
F	0.450	0.500	0.550	0.0177	0.0197	0.0217

		millimeters		inches ⁽¹⁾		
Symbol	Min.	Тур.	Max.	Min.	Тур.	Max.
ddd	-	-	0.100	-	-	0.0039
eee	-	-	0.150	-	-	0.0059
fff	-	-	0.050	-	-	0.0020

^{1.} Values in inches are converted from mm and rounded to 4 decimal digits.

Figure 90. UFBGA169 recommended footprint

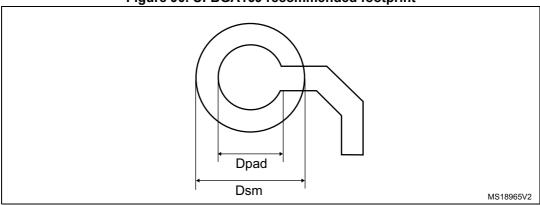


Table 132. UFBGA169 recommended PCB design rules (0.5 mm pitch BGA)

Dimension	Recommended values		
Pitch	0.5		
Dpad	0.27 mm		
Dsm	0.35 mm typ. (depends on the soldermask registration tolerance)		
Solder paste	0.27 mm aperture diameter.		

Note: Non-solder mask defined (NSMD) pads are recommended.

Note: 4 to 6 mils solder paste screen printing process.

Device marking for UFBGA169

The following figure gives an example of topside marking versus ball A1 position identifier location.

The printed markings may differ depending on the supply chain.

Other optional marking or inset/upset marks, which depend on supply chain operations, are not indicated below.

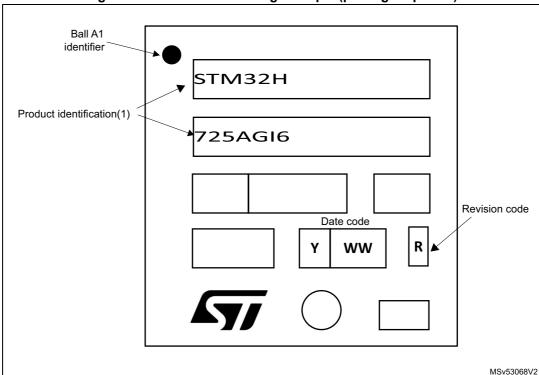


Figure 91. UFBGA169 marking example (package top view)

^{1.} Parts marked as "ES", "E" or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not approved for use in production. ST is not responsible for any consequences resulting from such use. In no event will ST be liable for the customer using any of these engineering samples in production. ST's Quality department must be contacted prior to any decision to use these engineering samples to run a qualification activity.

7.7 LQFP176 package information

LQFP176 is a 176-pin, 24 x 24 mm low profile quad flat package.

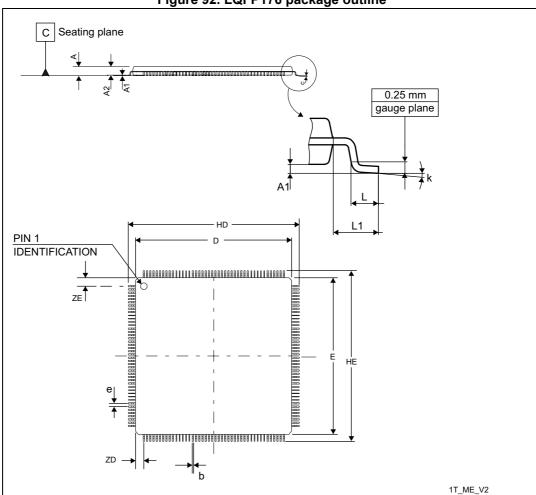


Figure 92. LQFP176 package outline

1. Drawing is not to scale.

Table 133. LQFP176 package mechanical data

	Dimensions							
Ref.		Millimeters			Inches ⁽¹⁾			
	Min.	Тур.	Max.	Min.	Тур.	Max.		
Α	-	-	1.600	-	-	0.0630		
A1	0.050	-	0.150	0.0020	-	0.0059		
A2	1.350	-	1.450	0.0531	-	0.0571		
b	0.170	-	0.270	0.0067	-	0.0106		
С	0.090	-	0.200	0.0035	-	0.0079		
D	23.900	-	24.100	0.9409	-	0.9488		
HD	25.900	-	26.100	1.0197	-	1.0276		
ZD	-	1.250	-	-	0.0492	-		
Е	23.900	-	24.100	0.9409	-	0.9488		
HE	25.900	-	26.100	1.0197	-	1.0276		
ZE	-	1.250	-	-	0.0492	-		
е	-	0.500	-	-	0.0197	-		
L ⁽²⁾	0.450	-	0.750	0.0177	-	0.0295		
L1	-	1.000	-	-	0.0394	-		
k	0°	-	7°	0°	-	7°		
ccc	-	-	0.080	-	-	0.0031		

^{1.} Values in inches are converted from mm and rounded to 4 decimal digits.

^{2.} $\,$ L dimension is measured at gauge plane at 0.25 mm above the seating plane.

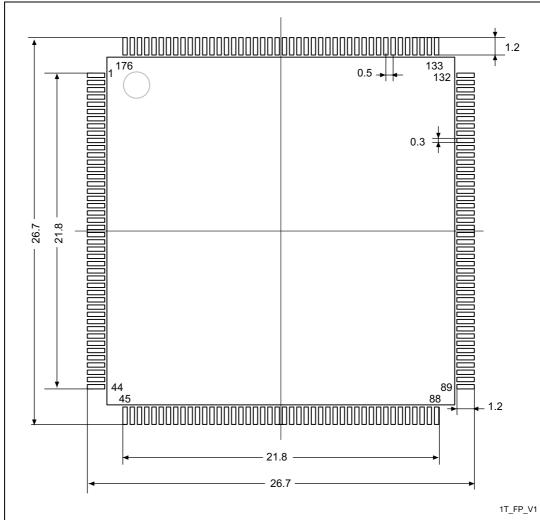


Figure 93. LQFP176 package recommended footprint

1. Dimensions are expressed in millimeters.

Device marking for LQFP176

The following figure gives an example of topside marking versus pin 1 position identifier location.

The printed markings may differ depending on the supply chain.

Other optional marking or inset/upset marks, which depend on supply chain operations, are not indicated below.

Product identification⁽¹⁾

STM32H725IGT6

Revision code

Pin 1 identifier

MSv62539V2

Figure 94. LQFP176 marking example (package top view

1. Parts marked as "ES", "E" or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not approved for use in production. ST is not responsible for any consequences resulting from such use. In no event will ST be liable for the customer using any of these engineering samples in production. ST's Quality department must be contacted prior to any decision to use these engineering samples to run a qualification activity.

STM32H725xE/G Package information

7.8 UFBGA176+25 package information

UFBGA176+25 is a 201-ball, 10 x 10 mm, 0.65 mm pitch, ultra fine pitch ball grid array package.

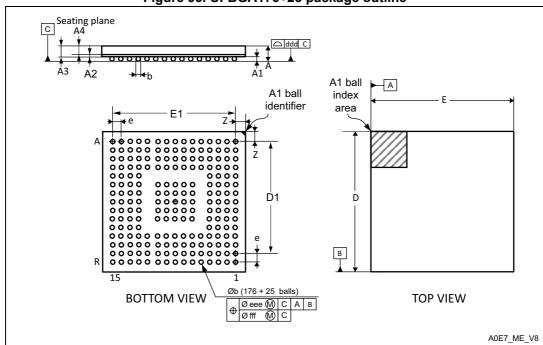


Figure 95. UFBGA176+25 package outline

1. Drawing is not to scale.

Table 134. UFBGA176+25 package mechanical data

Counch of	millimeters			inches ⁽¹⁾		
Symbol	Min.	Тур.	Max.	Min.	Тур.	Max.
Α	-	-	0.600	-	-	0.0236
A1	-	-	0.110	-	-	0.0043
A2	-	0.130	-	-	0.0051	-
A3	-	0.450	-	-	0.0177	-
A4	-	0.320	-	-	0.0126	-
b	0.240	0.290	0.340	0.0094	0.0114	0.0134
D	9.850	10.000	10.150	0.3878	0.3937	0.3996
D1	-	9.100	-	-	0.3583	-
E	9.850	10.000	10.150	0.3878	0.3937	0.3996
E1	-	9.100	-	-	0.3583	-
е	-	0.650	-	-	0.0256	-
Z	-	0.450	-	-	0.0177	-
ddd	-	-	0.080	-	-	0.0031

Table 134. UFBGA176+25 package mechanical data (continued)

Symbol		millimeters		inches ⁽¹⁾		
Symbol Min.		Тур.	Max.	Min.	Тур.	Max.
eee	-	-	0.150	-	-	0.0059
fff	-	-	0.050	-	-	0.0020

^{1.} Values in inches are converted from mm and rounded to 4 decimal digits.

Figure 96. UFBGA176+25 package recommended footprint

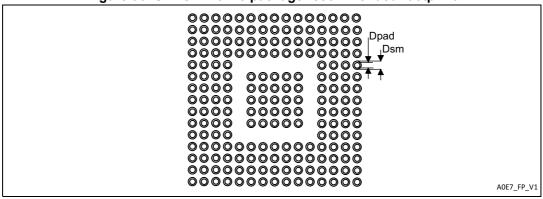


Table 135. UFBGA176+25 recommended PCB design rules (0.65 mm pitch BGA)

	• • • • • • • • • • • • • • • • • • • •
Dimension	Recommended values
Pitch	0.65 mm
Dpad	0.300 mm
Dsm	0.400 mm typ. (depends on the soldermask registration tolerance)
Stencil opening	0.300 mm
Stencil thickness	Between 0.100 mm and 0.125 mm
Pad trace width	0.100 mm

Device marking for UFBGA176+25

The following figure gives an example of topside marking versus ball A1 position identifier location.

The printed markings may differ depending on the supply chain.

Other optional marking or inset/upset marks, which depend on supply chain operations, are not indicated below.

Product identification⁽¹⁾

STM32H725

Revision code

Ball Alidentifier

MSv53070V2

Figure 97. UFBGA176+25 marking example (package top view

 Parts marked as "ES", "E" or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not approved for use in production. ST is not responsible for any consequences resulting from such use. In no event will ST be liable for the customer using any of these engineering samples in production. ST's Quality department must be contacted prior to any decision to use these engineering samples to run a qualification activity.

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7.9 Thermal characteristics

The maximum chip-junction temperature, T_J max, in degrees Celsius, may be calculated using the following equation:

 $T_J \max = T_A \max + (P_D \max \times \Theta_{JA})$

Where:

- T_A max is the maximum ambient temperature in °C,
- Θ_{JA} is the package junction-to-ambient thermal resistance, in °C/W,
- P_D max is the sum of P_{INT} max and $P_{I/O}$ max (P_D max = P_{INT} max + $P_{I/O}$ max),
- P_{INT} max is the product of I_{DD} and V_{DD}, expressed in Watts. This is the maximum chip internal power.

P_{I/O} max represents the maximum power dissipation on output pins where:

$$\mathsf{P}_{\mathsf{I/O}} \; \mathsf{max} = \Sigma \; (\mathsf{V}_{\mathsf{OL}} \times \mathsf{I}_{\mathsf{OL}}) + \Sigma ((\mathsf{V}_{\mathsf{DD}} - \mathsf{V}_{\mathsf{OH}}) \times \mathsf{I}_{\mathsf{OH}}),$$

taking into account the actual V_{OL} / I_{OL} and V_{OH} / I_{OH} of the I/Os at low and high level in the application.

Symbol	Definition	Parameter	Value	Unit	
$\Theta_{\sf JA}$	Thermal resistance junction-ambient	Thermal resistance junction-ambient VFQFPN68 - 8 x 8 mm / 0.4 mm pitch	26.1	- °C/W	
		Thermal resistance junction-ambient LQFP100 - 14 x 14 mm	43.8		
		Thermal resistance junction-ambient TFBGA100 - 8 x 8 mm /0.8 mm pitch	43.2		
		Thermal resistance junction-ambient WLCSP115 3.73 x 4.15 mm, 0.35 mm pitch	44.2		
		Thermal resistance junction-ambient LQFP144 - 20 x 20 mm / 0.5 mm pitch	44.8	38	
		Thermal resistance junction-ambient UFBGA169 - 7 x 7 mm / 0.5 mm pitch	38		
		Thermal resistance junction-ambient LQFP176 - 24 x 24 mm / 0.5 mm pitch	48.3		
		Thermal resistance junction-ambient UFBGA176+25 - 10 x 10 mm / 0.65 mm pitch	38		

Table 136. Thermal characteristics

Table 136. Thermal characteristics (continued)

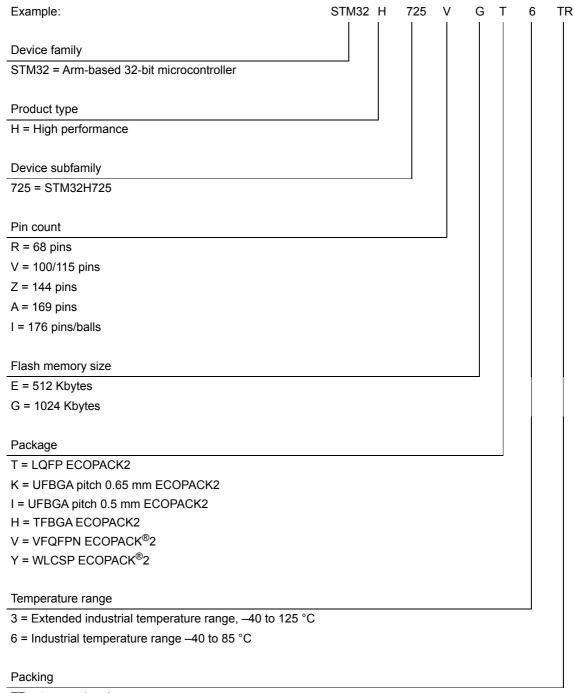
Symbol	Definition	Parameter	Value	Unit	
ΘJB	Thermal resistance junction-board	Thermal resistance junction-board VFQFPN68 - 8 x 8 mm / 0.4 mm pitch	5.6	°C/W	
		Thermal resistance junction-board LQFP100 - 14 x 14 mm	19.8		
		Thermal resistance junction-ambient TFBGA100 - 8 x 8 mm /0.8 mm pitch	24.8		
		Thermal resistance junction-ambient WLCSP115 3.73 x 4.15 mm, 0.35 mm pitch	17.6		
		Thermal resistance junction-board LQFP144 - 20 x 20 mm /0.5 mm pitch	24.4		
		Thermal resistance junction-board UFBGA169 - 7 x 7 mm /0.5 mm pitch	18		
		Thermal resistance junction-board LQFP176 - 24 x 24 mm /0.5 mm pitch	29.1		
		Thermal resistance junction-board UFBGA176+25 - 10 x 10 mm /0.65 mm pitch	20		
ΘJС	Thermal resistance junction-case	Thermal resistance junction-case VFQFPN68 - 8 x 8 mm / 0.4 mm pitch	3.1		
		Thermal resistance junction-case LQFP100 - 14 x 14 mm	7.3		
		Thermal resistance junction-ambient TFBGA100 - 8 x 8 mm /0.8 mm pitch	13.2		
		Thermal resistance junction-ambient WLCSP115 3.73 x 4.15 mm / 0.35 mm pitch	1.7	°C/W	
		Thermal resistance junction-case LQFP144 - 20 x 20 mm /0.5 mm pitch	7.4		
		Thermal resistance junction-case UFBGA169 - 7 x 7 mm / 0.5 mm pitch	11		
		Thermal resistance junction-case LQFP176 - 24 x 24 mm / 0.5 mm pitch	7.9		
		Thermal resistance junction-case UFBGA176+25 - 10 x 10 mm / 0.65 mm pitch	24		

7.9.1 Reference documents

- JESD51-2 Integrated Circuits Thermal Test Method Environment Conditions Natural Convection (Still Air). Available from www.jedec.org.
- For information on thermal management, refer to application note "Thermal management guidelines for STM32 applications" (AN5036) available from www.st.com.

Ordering information STM32H725xE/G

8 Ordering information



TR = tape and reel

No character = tray or tube

For a list of available options (speed, package, etc.) or for further information on any aspect of this device, please contact your nearest ST sales office.

STM32H725xE/G Revision history

9 Revision history

Table 137. Document revision history

Date	Revision	Changes
10-Jul-2020	1	Initial release.
03-Sep-2020	2	Distinction made between LQFP100 (STM32H725VGT) and TFBGA100 (STM32H725VGH) packages in Table 2: STM32H725xE/G features and peripheral counts.
		Renamed Section 3.30 into True random number generator (RNG).
		Replaced V _{DDIOx} by V _{DD} in <i>Section 6: Electrical characteristics</i> .
		Updated I _{IO} in <i>Table 11: Current characteristics</i> and <i>Table 18: Inrush current and inrush electric charge characteristics for LDO and SMPS.</i>
		Removed Table 14: Supply voltage and maximum temperature configuration.
		Updated Table 28: Typical current consumption in Autonomous mode, Table 31: Typical current consumption in Standby mode and Table 32: Typical and maximum current consumption in VBAT mode.
		Added Section 6.3.16: I/O current injection characteristics.
		Removed reference to PI8 in <i>Table 55: Output voltage</i> characteristics for all I/Os except PC13, PC14 and PC15 and <i>Table 56: Output voltage characteristics for PC13, PC14 and PC15.</i>
		Added Section : Analog switch between ports Pxy_C and Pxy.
		Added Figure 93: LQFP176 package recommended footprint and Table 132: UFBGA169 recommended PCB design rules (0.5 mm pitch BGA).

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